Radiation Report

TPS7H5006-SEP and TPS7H5002-SP QMLP Neutron Displacement Damage (NDD) Characterization Report

ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the TPS7H5006-SEP and TPS7H5002-SP QMLP PWM controller. Both the TPS7H5006-SEP and TPS7H5002-SP QMLP showed a strong degree of hardness to neutron irradiation up to fluence level 1 × 10^{13} n/cm^2.

The neutron irradiation test is a destructive test. Test procedure follows MIL-STD-883 method 1017 as guidance. The purpose of this test is to determine the device susceptibility to non-ionizing energy loss (NIEL) degradation. Objectives of the test are, to detect and measure the degradation of critical device parameters as a function of neutron fluence and to determine if these parameters are within specified limits after exposure to a specified level of neutron fluence.

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1 Device Information

1.1 Product Description

The TPS7H5006-SEP and TPS7H5002-SP QMLP are 4-V to 14-V, current mode, a single output PWM controller that supports buck applications and single ended isolated topologies optimized for DC-DC converters. The high switching frequency capability of the TPS7H5006-SEP and TPS7H5002-SP QMLP, small footprint, and low-current consumption makes the device ideal for fully exploiting the area reduction and high-efficiency benefits of

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DC-DC converters. These devices feature integrated synchronous rectification output optimized for GaN power semiconductor based applications, the controller has configurable dead time and configurable leading edge blank time.

The TPS7H5006-SEP and TPS7H5002-SP QMLP controller can be configured for maximum duty cycle of 75% or 100%. As such, the DCL pin can be left floating or connected to VLDO. These devices are packaged in a very small 24-pin TSSOP (thin-shrink small outline package) package. As the TPS7H5002-SP QMLP uses the same material set, the results are applicable to both devices.

1.2 Device Details

Device and Exposure Details lists the device information and test conditions used in the NDD characterization.

Table 1-1. Device and Exposure Details

NDD Exposure Details	
TI Devices	TPS7H5006-SEP
TI Part Name	TPS7H5006MPWTSEP
Device Function	PWM controller
Package	24-pin TSSOP
Technology	LBC7
Lot Number / Lot Trace Code	1805055 / 1AC5PSK
Sample Quantity	9 + 1 control unit
Exposure Facility	Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor (UMLRR)
Neutron Fluence (1-MeV equivalent) Level	1×10^{12}, 5×10^{12}, 1×10^{13} n/cm^2
Irradiation Temperature	25°C

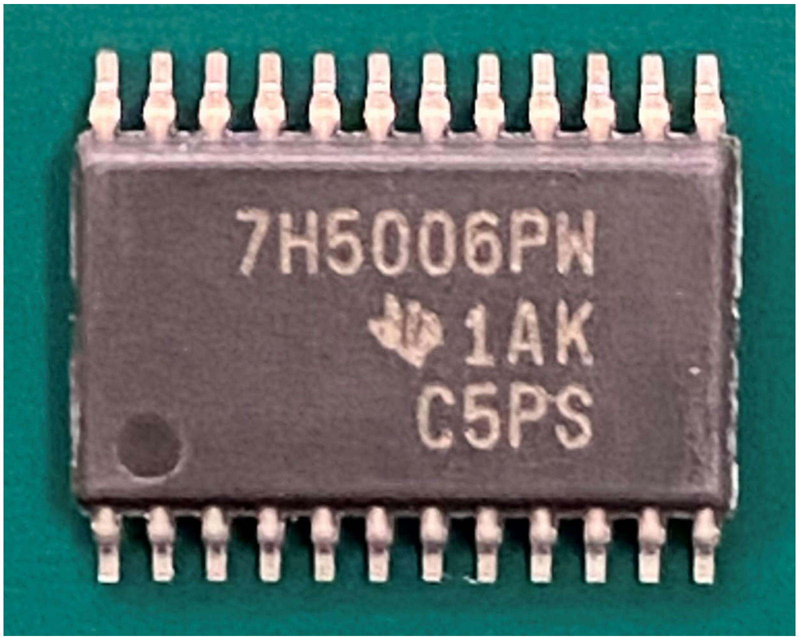

Figure 1-1. TPS7H5006-SEP Device

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2 Total Dose Test Setup

2.1 Test Overview

General test procedures adhere to MIL-STD-883, Method 1017 as a guide for neutron irradiation. The TPS7H5006-SEP was electrically tested using the production automated test equipment (ATE) program at an ambient room temperature of 25°C before and after neutron irradiation.

2.2 Test Facility

The utilized test facility is the Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor. The neutron fluence for this irradiation was measured utilizing ASTM E-265 "Measuring Reaction Rates and Fast Neutron Fluence by Radioactivation of Sulfur-32" and correlated to the measured reactor power level. All irradiation conditions required under ASTM 722 were met, this includes: neutron fluence, distribution and uncertainty. The Average Integrated Neutron Fluence, 1-MeV(Si) equivalent, reflects these factors.

Detailed information of the radiation facility is available at the following link:

https://www.uml.edu/docs/FNI%20Brochure_tcm18-90375.pdf

2.3 Test Setup Details

Devices were irradiated at three fluence levels in unbiased conditions: 1.0×10^{12} n/cm^2, 5.0×10^{12} n/cm^2 and 1.0×10^{13} n/cm^2.

Table 2-1. Neutron Irradiation Conditions

GROUP	SAMPLE QTY	NEUTRON FLUENCE (n/cm^2)	BIAS
A	3	1.0×10^{12}	Unbias
B	3	5.0×10^{12}	Unbias
C	3	1.0×10^{13}	Unbias
Control Unit	1	N/A	N/A

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3 Test Results

3.1 NDD Characterization Summary

The results show that all devices were fully functional and within specification limits. A sample size of nine units was exposed for neutron irradiation and an additional unirradiated control unit was used as correlation.

Overall, the TPS7H5006-SEP showed a strong degree of hardness to Neutron irradiation up to fluence level 1 × 10^{13} n/cm^2. As the TPS7H5002-SP QMLP uses the same material set, the results are applicable to this orderable as well. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each fluence level. The parameters that showed a greater degree of change between pre- and post- irradiation were still within the Electrical Performance Characteristics specified in the Data Sheet Electrical Parameters table. See Table 3-1 for the Data Sheet Electrical Parameters and Associated Tests.

Electrical testing is done for pre- and post- neutron irradiation by ATE. ATE electrical test is done at an ambient room temperature of 25°C. Parameters not listed in the Table 3-1 are omitted either because there is no parametric data or because verification was done through bench testing.

See Appendix A for NDD report up to 1.0 × 10^{13} n/cm^2.

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3.2 Data Sheet Electrical Parameters and Associated Tests

Table 3-1. TPS7H5006-SEP and TPS7H5002-SP QMLPElectrical Parameters Table

PARAMETER	TEST CONDITION	TPS7H5006-SEP and TPS7H5002-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
SUPPLY VOLTAGES AND CURRENTS						
IDD Operating supply current	f_{SW} = 500 kHz, No load for OUTA, OUTB, SRA, and SRB		6.25	8	mA	5.24 __IDD_ACT_500K_NOLOAD_4V, 5.25 __IDD_ACT_500K_NOLOAD_5V, 5.26 __IDD_ACT_500K_NOLOAD_12V, 5.27 __IDD_ACT_500K_NOLOAD_14V
	f_{SW} = 1 MHz, No load for OUTA, OUTB, SRA, and SRB		6.75	9.5	mA	5.28 __IDD_ACT_1M_NOLOAD_4V, 5.29 __IDD_ACT_1M_NOLOAD_5V, 5.30 __IDD_ACT_1M_NOLOAD_12V, 5.31 __IDD_ACT_1M_NOLOAD_14V
	f_{SW} = 2 MHz, No load for OUTA, OUTB, SRA, and SRB		8.5	13.5	mA	5.36 __IDD_ACT_2M_NOLOAD_4V, 5.37 __IDD_ACT_2M_NOLOAD_5V, 5.38 __IDD_ACT_2M_NOLOAD_12V, 5.39 __IDD_ACT_2M_NOLOAD_14V
	f_{SW} = 500 kHz, C_{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		7.5	9.5	mA	5.48 __IDD_ACT_500K_4V, 5.49 __IDD_ACT_500K_5V, 5.50 __IDD_ACT_500K_12V, 5.51 __IDD_ACT_500K_14V
	f_{SW} = 1 MHz, C_{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		9	12	mA	5.52 __IDD_ACT_1M_4V, 5.53 __IDD_ACT_1M_5V, 5.54 __IDD_ACT_1M_12V, 5.55 __IDD_ACT_1M_14V
	f_{SW} = 2 MHz, C_{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		14	19.5	mA	5.60 __IDD_ACT_2M_4V, 5.61 __IDD_ACT_2M_5V, 5.62 __IDD_ACT_2M_12V, 5.63 __IDD_ACT_2M_14V
$I_{DD(dis)}$ Standby current	EN = 0 V			3	mA	5.1 __IDD_DIS_4V, 5.2 __IDD_DIS_5V, 5.3 __IDD_DIS_12V 5.4 __IDD_DIS_14V
VLDO Internal linear regulator output voltage	5 V ≤VIN ≤ 14 V, fsw ≤ 1 MHz	4.75	5	5.2	V	5.65 __V_LDO_100K_5V, 5.66 __V_LDO_100K_12V, 5.67 __V_LDO_100K_14V, 5.69 __V_LDO_200K_5V, 5.70 __V_LDO_200K_12V, 5.71 __V_LDO_200K_14V, 5.73 __V_LDO_500K_5V, 5.74 __V_LDO_500K_12V, 5.75 __V_LDO_500K_14V, 5.77 __V_LDO_1M_5V, 5.78 __V_LDO_1M_12V, 5.79 __V_LDO_1M_14V
	5 V ≤ VIN ≤ 14 V, fsw = 2 MHz	4.65	5	5.2	V	5.85 __V_LDO_2M_5V, 5.86 __V_LDO_2M_12V, 5.87 __V_LDO_2M_14V
ENABLE AND UNDERVOLTAGE LOCKOUT						
V_{ENR} EN threshold rising		0.57	0.6	0.65	V	6.5 __V_EN_RISE_4V, 6.8 __V_EN_RISE_5V, 6.11 __V_EN_RISE_12V, 6.14 __V_EN_RISE_14V
V_{ENF} EN threshold falling		0.47	0.5	0.55	V	6.6 __V_EN_FALL_4V, 6.9 __V_EN_FALL_5V, 6.12 __V_EN_FALL_12V, 6.15 __V_EN_FALL_14V
V_{ENH} EN hysteresis voltage		85	95	105	mV	6.7 __V_EN_HYS_4V, 6.10 __V_EN_HYS_5V, 6.13 __V_EN_HYS_12V, 6.16 __V_EN_HYS_14V
I_{EN} EN pin input leakage current	VIN = 14 V, EN = 5V		5	50	nA	6.1 __I_EN_LEAK_4V, 6.2 __I_EN_LEAK_5V, 6.3 __I_EN_LEAK_12V, 6.4 __I_EN_LEAK_14V
$VLDO_{UVLOR}$ VLDO UVLO rising		3.44	3.55	3.66	V	6.34 __UVLO_VLDO_RISE_1MHz, 6.37 __UVLO_VLDO_RISE_100kHz, 6.40 __UVLO_VLDO_RISE_200kHz, 6.43 __UVLO_VLDO_RISE_500kHz, 6.46 __UVLO_VLDO_RISE_2MHz
$VLDO_{UVLOF}$ VLDO UVLO falling		3.29	3.4	3.51	V	6.35 __UVLO_VLDO_FALL_1MHz, 6.38 __UVLO_VLDO_FALL_100kHz, 6.41 __UVLO_VLDO_FALL_200kHz, 6.44 __UVLO_VLDO_FALL_500kHz, 6.47 __UVLO_VLDO_FALL_2MHz
$VLDO_{UVLOH}$ VLDO UVLO hysteresis		115	135	160	mV	6.36 __UVLO_VLDO_HYS_1MHz, 6.39 __UVLO_VLDO_HYS_100kHz, 6.42 __UVLO_VLDO_HYS_200kHz, 6.45 __UVLO_VLDO_HYS_500kHz, 6.48 __UVLO_VLDO_HYS_2MHz
SOFT START						
I_{SS} Soft-start current	SS = 0.3 V	1.98	2.7	3.32	µA	7.1 __I_SS_4V, 7.3 __I_SS_5V, 7.5 __I_SS_12V, 7.7 __I_SS_14V
ERROR AMPLIFIER						
EA_{gm} Transconductance	-2 µA < I_{COMP} < 2 µA, $V_{(COMP)}$ = 1 V	1150	1800	2500	µA/V	8.9 __EA_GM_4V, 8.10 __EA_GM_5V, 8.11 __EA_GM_12V, 8.12 __EA_GM_14V

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Table 3-1. TPS7H5006-SEP and TPS7H5002-SP QMLPElectrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5006-SEP and TPS7H5002-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
EA_{ISRC} Error amplifier source current	$V_{(COMP)}$ = 1 V, 100-mV input overdrive	100		190	µA	8.13 __EA_I_SOURCE_4V, 8.14 __EA_I_SOURCE_5V, 8.15 __EA_I_SOURCE_12V, 8.16 __EA_I_SOURCE_14V
EA_{ISNK} Error amplifier sink current	$V_{(COMP)}$ = 1 V, 100-mV input overdrive	100		190	µA	8.17 __EA_I_SINK_4V, 8.18 __EA_I_SINK_5V, 8.19 __EA_I_SINK_12V, 8.20 __EA_I_SINK_14V
EA_{OS} Error amplifier offset voltage		–2		2	mV	8.5 __EA_OS_4V, 8.6 __EA_OS_5V, 8.7 __EA_OS_12V, 8.8 __EA_OS_14V
OSCILLATOR						
$SYNC_{RT}$ SYNC out low-to-high rise time (10%/90%)	C_{LOAD} = 25 pF		6	15	ns	9.1 __T_SYNC_RISE_100kHz_4V, 9.5 __T_SYNC_RISE_200kHz_4V, 9.9 __T_SYNC_RISE_500kHz_4V, 9.13 __T_SYNC_RISE_1MHz_4V, 9.17 __T_SYNC_RISE_1p5MHz_4V, 9.21 __T_SYNC_RISE_2MHz_4V, 9.25 __T_SYNC_RISE_100kHz_5V, 9.29 __T_SYNC_RISE_200kHz_5V, 9.33 __T_SYNC_RISE_500kHz_5V, 9.37 __T_SYNC_RISE_1MHz_5V, 9.41 __T_SYNC_RISE_1p5MHz_5V, 9.45 __T_SYNC_RISE_2MHz_5V, 9.49 __T_SYNC_RISE_100kHz_12V, 9.53 __T_SYNC_RISE_200kHz_12V, 9.57 __T_SYNC_RISE_500kHz_12V, 9.61 __T_SYNC_RISE_1MHz_12V, 9.65 __T_SYNC_RISE_1p5MHz_12V, 9.69 __T_SYNC_RISE_2MHz_12V, 9.73 __T_SYNC_RISE_100kHz_14V, 9.77 __T_SYNC_RISE_200kHz_14V, 9.81 __T_SYNC_RISE_500kHz_14V, 9.85 __T_SYNC_RISE_1MHz_14V, 9.89 __T_SYNC_RISE_1p5MHz_14V, 9.93 __T_SYNC_RISE_2MHz_14V
$SYNC_{FT}$ SYNC out high-to-low fall time (10%/90%)	C_{LOAD} = 25 pF		6	17	ns	9.2 __T_SYNC_FALL_100kHz_4V, 9.14 __T_SYNC_FALL_1MHz_4V, 9.22 __T_SYNC_FALL_2MHz_4V, 9.26 __T_SYNC_FALL_100kHz_5V, 9.38 __T_SYNC_FALL_1MHz_5V, 9.46 __T_SYNC_FALL_2MHz_5V, 9.74 __T_SYNC_FALL_100kHz_14V, 9.86 __T_SYNC_FALL_1MHz_14V, 9.94 __T_SYNC_FALL_2MHz_14V
$SYNC_{OL}$ SYNC out low level	I_{OL}= 10 mA			500	mV	9.186__SYNC_VOL_4V, 9.187__SYNC_VOL_5V, 9.188__SYNC_VOL_12V, 9.189__SYNC_VOL_14V
EXT_{DT} Externally set frequency detection time	RT = Open, f = 200 kHz			20	µs	9.185__T_SYNC_DETECT
FSW_{EXT} Externally set frequency	RT = 1.07 MΩ	95	105	115	kHz	9.4 __FSW_EXT_RT_100kHz_4V, 9.28 __FSW_EXT_RT_100kHz_5V, 9.52 __FSW_EXT_RT_100kHz_12V, 9.76 __FSW_EXT_RT_100kHz_14V
	RT = 511 kΩ	190	210	230	kHz	9.8 __FSW_EXT_RT_200kHz_4V, 9.32 __FSW_EXT_RT_200kHz_5V, 9.56 __FSW_EXT_RT_200kHz_12V, 9.80 __FSW_EXT_RT_200kHz_14V
	RT =90.9 kΩ	900	1000	1100	kHz	9.16 __FSW_EXT_RT_1MHz_4V, 9.40 __FSW_EXT_RT_1MHz_5V, 9.64 __FSW_EXT_RT_1MHz_12V, 9.88 __FSW_EXT_RT_1MHz_14V
	RT = 34.8 kΩ	1700	2000	2300	kHz	9.24 __FSW_EXT_RT_2MHz_4V, 9.48 __FSW_EXT_RT_2MHz_5V, 9.72 __FSW_EXT_RT_2MHz_12V, 9.96 __FSW_EXT_RT_2MHz_14V
VOLTAGE REFERENCE						
VREF Internal voltage reference initial tolerance	Measured at COMP, 25°C	0.609	0.613	0.615	V	8.1 __VREF_4V, 8.2 __VREF_5V, 8.3 __VREF_12V, 8.4 __VREF_14V

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Table 3-1. TPS7H5006-SEP and TPS7H5002-SP QMLPElectrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5006-SEP and TPS7H5002-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
REFCAP REFCAP voltage	REFCAP = 470 nF	1.213	1.225	1.237	V	5.88 __V_REFCAP_100K_4V, 5.89 __V_REFCAP_100K_5V, 5.90 __V_REFCAP_100K_12V, 5.91 __V_REFCAP_100K_14V, 5.92 __V_REFCAP_200K_4V, 5.93 __V_REFCAP_200K_5V, 5.94 __V_REFCAP_200K_12V, 5.95 __V_REFCAP_200K_14V, 5.96 __V_REFCAP_500K_4V, 5.97 __V_REFCAP_500K_5V, 5.98 __V_REFCAP_500K_12V, 5.99 __V_REFCAP_500K_14V, 5.100__V_REFCAP_1M_4V, 5.101__V_REFCAP_1M_5V, 5.102__V_REFCAP_1M_12V, 5.103__V_REFCAP_1M_14V, 5.104__V_REFCAP_1P5M_4V, 5.105__V_REFCAP_1P5M_5V, 5.106__V_REFCAP_1P5M_12V, 5.107__V_REFCAP_1P5M_14V, 5.108__V_REFCAP_2M_4V, 5.109__V_REFCAP_2M_5V, 5.110__V_REFCAP_2M_12V, 5.111__V_REFCAP_2M_14V
CURRENT SENSE, CURRENT LIMIT, AND HICCUP						
CCSR	COMP to CS_ILIM ratio	2.00	2.06	2.12		10.49 __CCSR_Ratio
V_{CS_ILIM} Current limit (over-current) threshold			1.05	1.09	V	10.1 __V_CS_ILIM_OC_Rise_4V, 10.3 __V_CS_ILIM_OC_Rise_5V, 10.5 __V_CS_ILIM_OC_Rise_12V, 10.7 __V_CS_ILIM_OC_Rise_14V
FAULT						
V_{FLTR} FLT threshold rising		0.57	0.6	0.65	V	12.1 __V_FAULT_RISE_4V, 12.4 __V_FAULT_RISE_5V, 12.7 __V_FAULT_RISE_12V, 12.10 __V_FAULT_RISE_14V
V_{FLTF} FLT threshold falling		0.47	0.5	0.55	V	12.2 __V_FAULT_FALL_4V, 12.5 __V_FAULT_FALL_5V, 12.8 __V_FAULT_FALL_12V, 12.11 __V_FAULT_FALL_14V
V_{FLTH} FLT hysteresis voltage		90	100	110	mV	12.3 __V_FAULT_HYS_4V, 12.6 __V_FAULT_HYS_5V, 12.9 __V_FAULT_HYS_12V, 12.12 __V_FAULT_HYS_14V
T_{FLT} FLT minimum pulse width	V_{FLT} = 1 V	0.4		1.4	µs	12.14 __T_FAULT_MIN
t_{DFLT} FLT delay duration	f_{sw} = 100 kHz	140	152	169	µs	12.15 __T_FAULT_DELAY_100kHz
	f_{sw} = 200 kHz	66	78	86	µs	12.17 __T_FAULT_DELAY_200kHz
	f_{sw} = 1 MHz	14	17	21	µs	12.21 __T_FAULT_DELAY_1MHz
	f_{sw} = 2 MHz	7	11	14	µs	12.23 __T_FAULT_DELAY_2MHz
PRIMARY AND SYNCHRONOUS RECTIFIER OUTPUTS						
Rise/fall time	R_{LOAD} = 50 kΩ, C_{LOAD} = 100 pF, 10% to 90%		10	17	ns	13.1 __OUTA_RISE_1MHz_4V, 13.9 __OUTA_RISE_1MHz_5V, 13.17 __OUTA_RISE_1MHz_12V, 13.25 __OUTA_RISE_1MHz_14V, 13.3 __OUTA_FALL_1MHz_4V, 13.11 __OUTA_FALL_1MHz_5V, 13.19 __OUTA_FALL_1MHz_12V, 13.27 __OUTA_FALL_1MHz_14V
t_{MIN} Minimum on-time LEB = 10 kΩ	LEB = 10 kΩ, 5 V ≤ VIN ≤ 14 V			85	ns	13.145__OUT_T_ON_MIN

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Table 3-1. TPS7H5006-SEP and TPS7H5002-SP QMLPElectrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5006-SEP and TPS7H5002-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
TD_{PS} Primary off to secondary on dead time	PS = floating, 5 V ≤ VIN ≤ 14 V, 90% of OUTx falling edge to 10% of SRx rising edge with OUTx and SRx floating	5	8	11	ns	13.37 __PSA_DT_0ns_1M_5V, 13.41 __PSA_DT_0ns_1M_12V, 13.45 __PSA_DT_0ns_1M_14V
	PS = 49.9 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of OUTx falling edge to 10% of SRx rising edge with OUTx and SRx floating	43	50	55	ns	13.53 __PSA_DT_50ns_1M_5V, 13.57 __PSA_DT_50ns_1M_12V, 13.61 __PSA_DT_50ns_1M_14V
	PS = 107 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of OUTx falling edge to 10% of SRx rising edge with OUTx and SRx floating	85	100	110	ns	13.69 __PSA_DT_100ns_1M_5V, 13.73 __PSA_DT_100ns_1M_12V, 13.77 __PSA_DT_100ns_1M_14V
TD_{SP} Secondary off to primary on dead time	SP = floating, 5 V ≤ VIN ≤ 14 V, 90% of SRx falling edge to 10% of OUTx rising edge with OUTx and SRx floating	5	8	11	ns	13.39 __SPA_DT_0ns_1M_5V, 13.43 __SPA_DT_0ns_1M_12V, 13.47 __SPA_DT_0ns_1M_14V
	SP = 49.9 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of SRx falling edge to 10% of OUTx rising edge with OUTx and SRx floating	43	50	55	ns	13.55 __SPA_DT_50ns_1M_5V, 13.59 __SPA_DT_50ns_1M_12V, 13.63 __SPA_DT_50ns_1M_14V
	SP = 100 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of SRx falling edge to 10% of OUTx rising edge with OUTx and SRx floating	85	100	110	ns	13.71 __SPA_DT_100ns_1M_5V, 13.75 __SPA_DT_100ns_1M_12V, 13.79 __SPA_DT_100ns_1M_14V
DUTY CYCLE						
D_{MAX} Maximum duty cycle	DCL = floating	70	75	80	%	13.163__MAX_DC_DCL_OPEN
	DCL =VLDO			100	%	13.166__MAX_DC_DCL_VLDO

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4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H5006-SEP Radiation-Hardness-Assured Si and GaN Dual Output Controller* data sheet
- Texas Instruments, TPS7H500x-SP Radiation-Hardness-Assured 2-MHz Current Mode PWM Controllers
- Texas Instruments, *TPS7H500x-SEP Evaluation Module (EVM)*
- Texas Instruments, *TPS7H500x-SEP Single-Event Effects (SEE)* Radiation Report

4.2 Reference Documents

Texas Instruments neutron irradiation test follow the guideline from MIL-STD-883 TM 1017. The document is available in Defense Logistic Agency's website.

A Appendix: NDD Report Data

This appendix contains the NDD report data.

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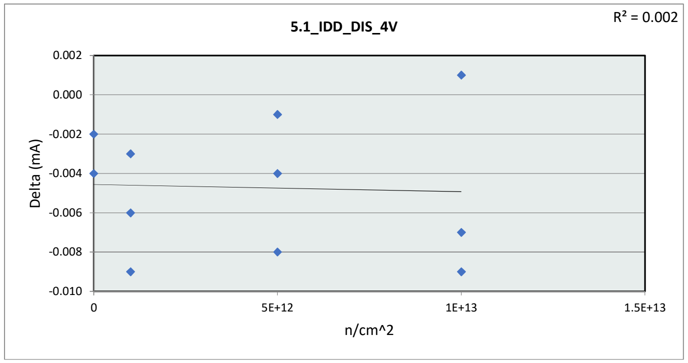
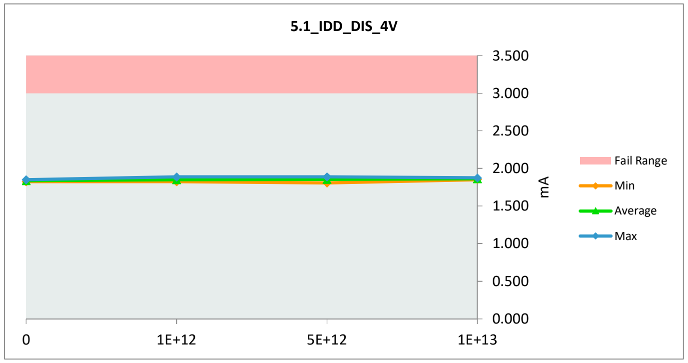
NDD Characterization Report
TPS7H5006-SEP

NDD Characterization Report
TPS7H5006-SEP

		5.1_IDD_DIS_4V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		2.6	3	
Min Limit		1		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.827	1.825	-0.002
0	49	1.855	1.851	-0.004
1E+12	11	1.888	1.885	-0.003
1E+12	12	1.855	1.846	-0.009
1E+12	13	1.830	1.824	-0.006
5E+12	14	1.812	1.808	-0.004
5E+12	15	1.867	1.866	-0.001
5E+12	16	1.896	1.888	-0.008
1E+13	17	1.883	1.874	-0.009
1E+13	18	1.865	1.866	0.001
1E+13	19	1.859	1.852	-0.007
	Max	1.896	1.888	0.001
	Average	1.858	1.853	-0.005
	Min	1.812	1.808	-0.009
	Std Dev	0.026	0.026	0.003



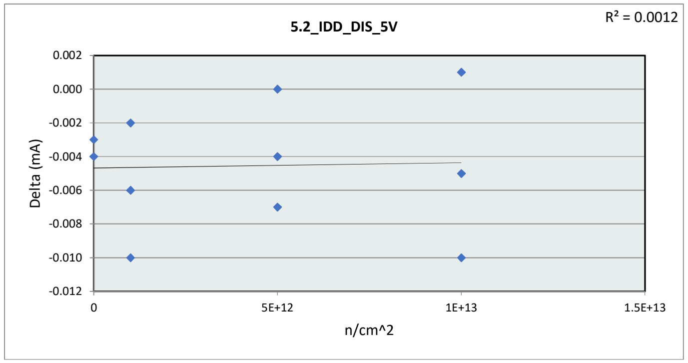
	5.1_IDD_DIS_4V			
Test Site				
Tester				
Test Number				
Max Limit	3	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.825	1.824	1.808	1.852
Average	1.838	1.852	1.854	1.864
Max	1.851	1.885	1.888	1.874
UL	3.000	3.000	3.000	3.000



NDD Characterization Report
TPS7H5006-SEP

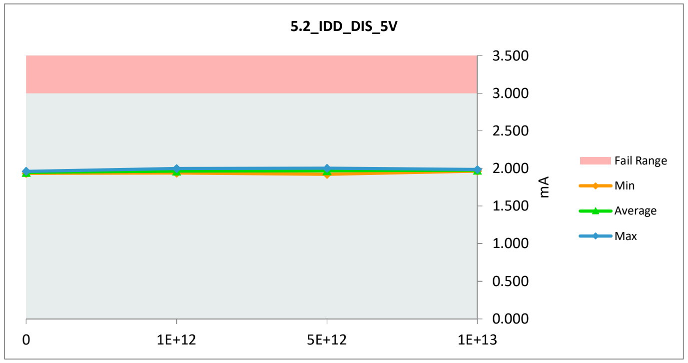
	5.2_IDD_DIS_5V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	2.8	3
Min Limit	1	

n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.937	1.934	-0.003
0	49	1.966	1.962	-0.004
1E+12	11	2.000	1.998	-0.002
1E+12	12	1.967	1.957	-0.010
1E+12	13	1.943	1.937	-0.006
5E+12	14	1.925	1.921	-0.004
5E+12	15	1.980	1.980	0.000
5E+12	16	2.009	2.002	-0.007
1E+13	17	1.995	1.985	-0.010
1E+13	18	1.977	1.978	0.001
1E+13	19	1.971	1.966	-0.005
	Max	2.009	2.002	0.001
	Average	1.970	1.965	-0.005
	Min	1.925	1.921	-0.010
	Std Dev	0.027	0.026	0.004



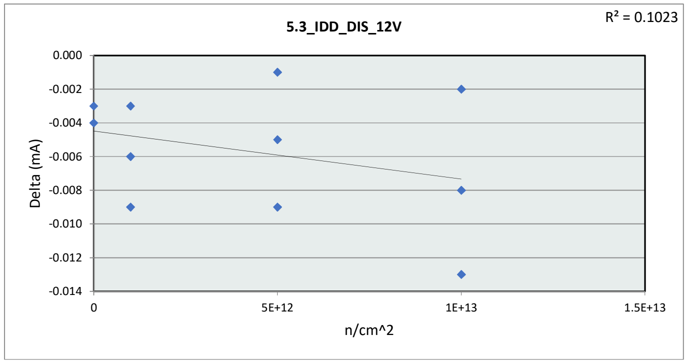
	5.2_IDD_DIS_5V	
Test Site		
Tester		
Test Number		
Max Limit	3	mA
Min Limit		mA

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.934	1.937	1.921	1.966
Average	1.948	1.964	1.968	1.976
Max	1.962	1.998	2.002	1.985
UL	3.000	3.000	3.000	3.000

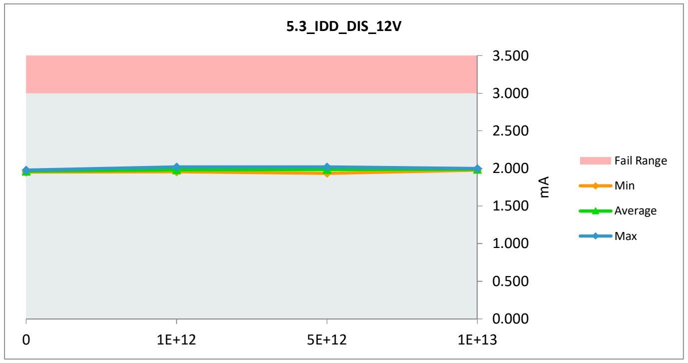


NDD Characterization Report
TPS7H5006-SEP

		5.3_IDD_DIS_12V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		2.8	3	
Min Limit		1		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.956	1.952	-0.004
0	49	1.980	1.977	-0.003
1E+12	11	2.023	2.020	-0.003
1E+12	12	1.984	1.975	-0.009
1E+12	13	1.960	1.954	-0.006
5E+12	14	1.942	1.937	-0.005
5E+12	15	1.999	1.998	-0.001
5E+12	16	2.028	2.019	-0.009
1E+13	17	2.012	1.999	-0.013
1E+13	18	1.992	1.990	-0.002
1E+13	19	1.987	1.979	-0.008
	Max	2.028	2.020	-0.001
	Average	1.988	1.982	-0.006
	Min	1.942	1.937	-0.013
	Std Dev	0.027	0.027	0.004

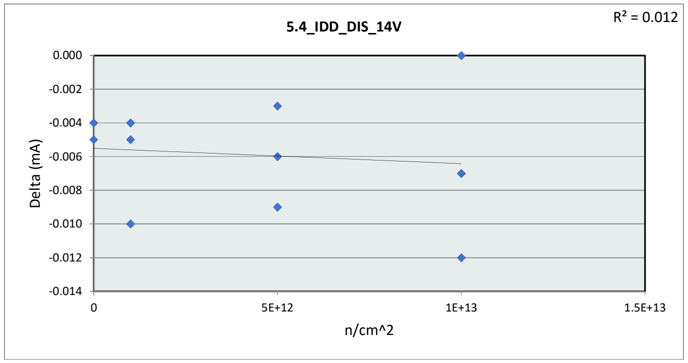


5.3_IDD_DIS_12V				
Test Site				
Tester				
Test Number				
Max Limit	3	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.952	1.954	1.937	1.979
Average	1.965	1.983	1.985	1.989
Max	1.977	2.020	2.019	1.999
UL	3.000	3.000	3.000	3.000

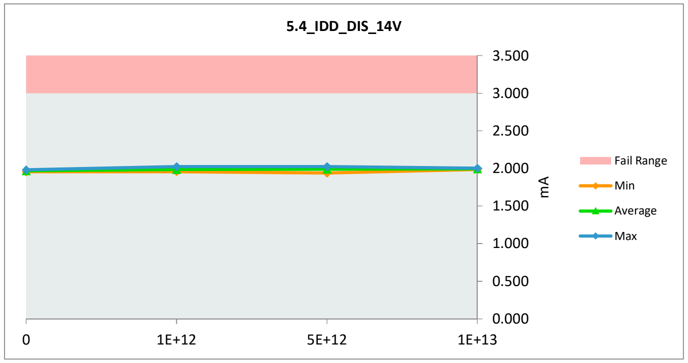


NDD Characterization Report
TPS7H5006-SEP

		5.4_IDD_DIS_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	2.8	3	
	Min Limit	1		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.960	1.956	-0.004
0	49	1.985	1.980	-0.005
1E+12	11	2.028	2.024	-0.004
1E+12	12	1.989	1.979	-0.010
1E+12	13	1.963	1.958	-0.005
5E+12	14	1.947	1.941	-0.006
5E+12	15	2.004	2.001	-0.003
5E+12	16	2.033	2.024	-0.009
1E+13	17	2.016	2.004	-0.012
1E+13	18	1.995	1.995	0.000
1E+13	19	1.992	1.985	-0.007
	Max	2.033	2.024	0.000
	Average	1.992	1.986	-0.006
	Min	1.947	1.941	-0.012
	Std Dev	0.028	0.027	0.003

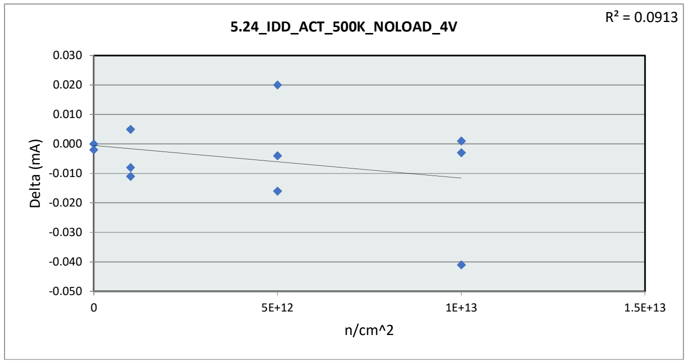


	5.4_IDD_DIS_14V			
Test Site				
Tester				
Test Number				
Max Limit	3	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.956	1.958	1.941	1.985
Average	1.968	1.987	1.989	1.995
Max	1.980	2.024	2.024	2.004
UL	3.000	3.000	3.000	3.000

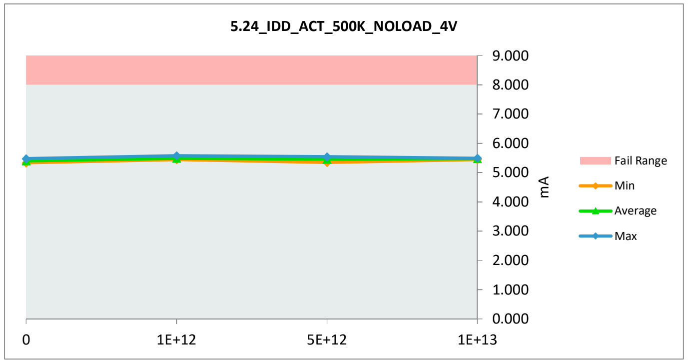


NDD Characterization Report
TPS7H5006-SEP

		5.24_IDD_ACT_500K_NOLOAD_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	7.8	8	
	Min Limit	2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.334	5.332	-0.002
0	49	5.475	5.475	0.000
1E+12	11	5.574	5.579	0.005
1E+12	12	5.453	5.442	-0.011
1E+12	13	5.466	5.458	-0.008
5E+12	14	5.352	5.348	-0.004
5E+12	15	5.518	5.538	0.020
5E+12	16	5.496	5.480	-0.016
1E+13	17	5.452	5.449	-0.003
1E+13	18	5.483	5.484	0.001
1E+13	19	5.533	5.492	-0.041
	Max	5.574	5.579	0.020
	Average	5.467	5.462	-0.005
	Min	5.334	5.332	-0.041
	Std Dev	0.071	0.072	0.015

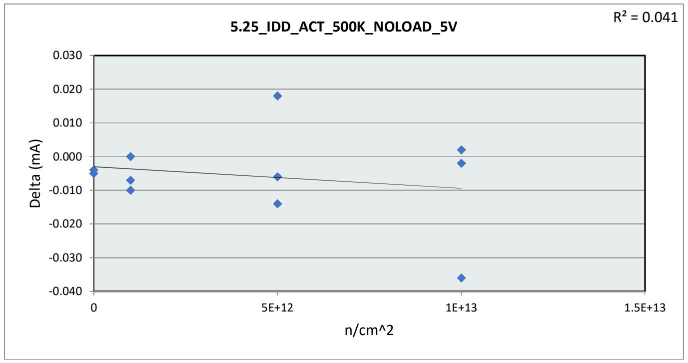


	5.24_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	5.332	5.442	5.348	5.449
Average	5.404	5.493	5.455	5.475
Max	5.475	5.579	5.538	5.492
UL	8.000	8.000	8.000	8.000

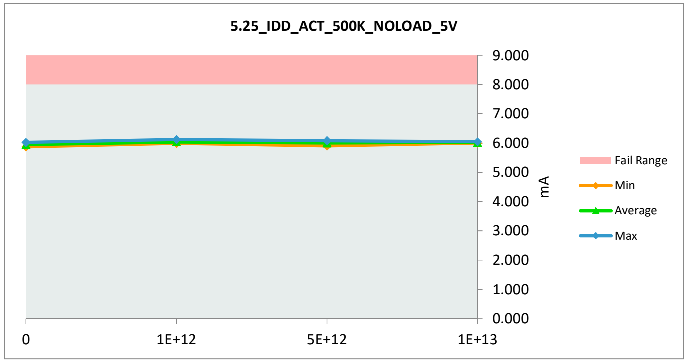


NDD Characterization Report
TPS7H5006-SEP

		5.25_IDD_ACT_500K_NOLOAD_5V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		7.8	8	
Min Limit		2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.879	5.875	-0.004
0	49	6.029	6.024	-0.005
1E+12	11	6.124	6.124	0.000
1E+12	12	6.002	5.992	-0.010
1E+12	13	6.016	6.009	-0.007
5E+12	14	5.904	5.898	-0.006
5E+12	15	6.069	6.087	0.018
5E+12	16	6.050	6.036	-0.014
1E+13	17	6.001	5.999	-0.002
1E+13	18	6.032	6.034	0.002
1E+13	19	6.082	6.046	-0.036
	Max	6.124	6.124	0.018
	Average	6.017	6.011	-0.006
	Min	5.879	5.875	-0.036
	Std Dev	0.072	0.073	0.013

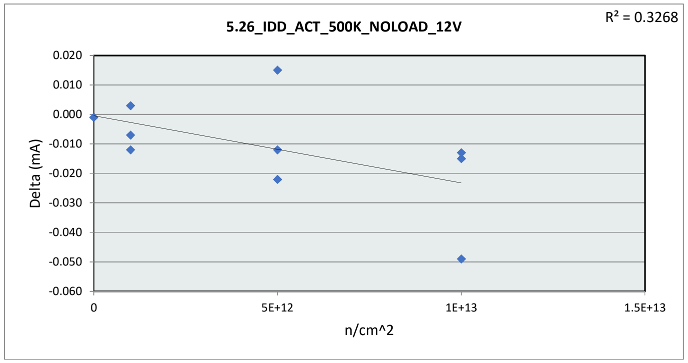


	5.25_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	5.875	5.992	5.898	5.999
Average	5.950	6.042	6.007	6.026
Max	6.024	6.124	6.087	6.046
UL	8.000	8.000	8.000	8.000

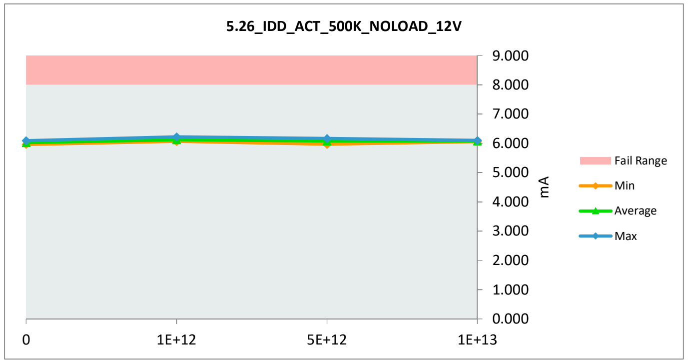


NDD Characterization Report
TPS7H5006-SEP

		5.26_IDD_ACT_500K_NOLOAD_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	7.8	8	
	Min Limit	2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.965	5.964	-0.001
0	49	6.089	6.088	-0.001
1E+12	11	6.219	6.222	0.003
1E+12	12	6.079	6.067	-0.012
1E+12	13	6.086	6.079	-0.007
5E+12	14	5.978	5.966	-0.012
5E+12	15	6.146	6.161	0.015
5E+12	16	6.134	6.112	-0.022
1E+13	17	6.072	6.057	-0.015
1E+13	18	6.098	6.085	-0.013
1E+13	19	6.153	6.104	-0.049
	Max	6.219	6.222	0.015
	Average	6.093	6.082	-0.010
	Min	5.965	5.964	-0.049
	Std Dev	0.074	0.075	0.016

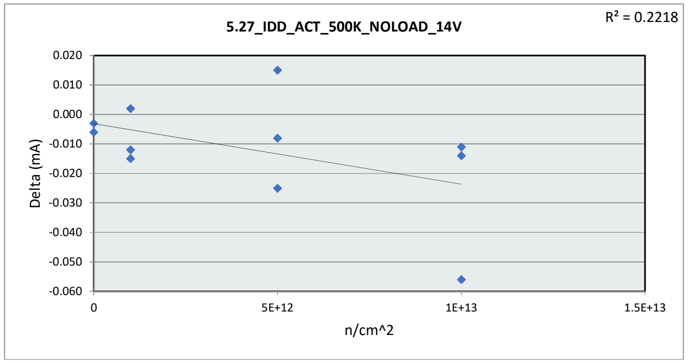


	5.26_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	5.964	6.067	5.966	6.057
Average	6.026	6.123	6.080	6.082
Max	6.088	6.222	6.161	6.104
UL	8.000	8.000	8.000	8.000

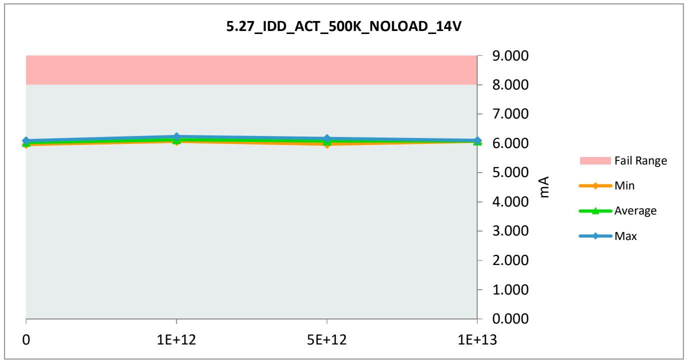


NDD Characterization Report
TPS7H5006-SEP

		5.27_IDD_ACT_500K_NOLOAD_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		7.8	8	
Min Limit		2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.970	5.964	-0.006
0	49	6.096	6.093	-0.003
1E+12	11	6.227	6.229	0.002
1E+12	12	6.084	6.069	-0.015
1E+12	13	6.092	6.080	-0.012
5E+12	14	5.978	5.970	-0.008
5E+12	15	6.151	6.166	0.015
5E+12	16	6.141	6.116	-0.025
1E+13	17	6.076	6.062	-0.014
1E+13	18	6.102	6.091	-0.011
1E+13	19	6.161	6.105	-0.056
	Max	6.227	6.229	0.015
	Average	6.098	6.086	-0.012
	Min	5.970	5.964	-0.056
	Std Dev	0.075	0.076	0.018

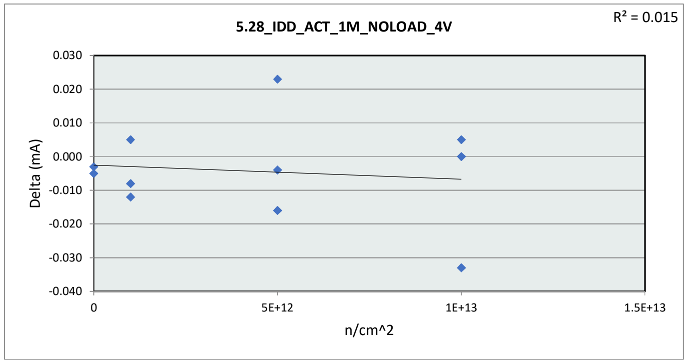


	5.27_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	5.964	6.069	5.970	6.062
Average	6.029	6.126	6.084	6.086
Max	6.093	6.229	6.166	6.105
UL	8.000	8.000	8.000	8.000

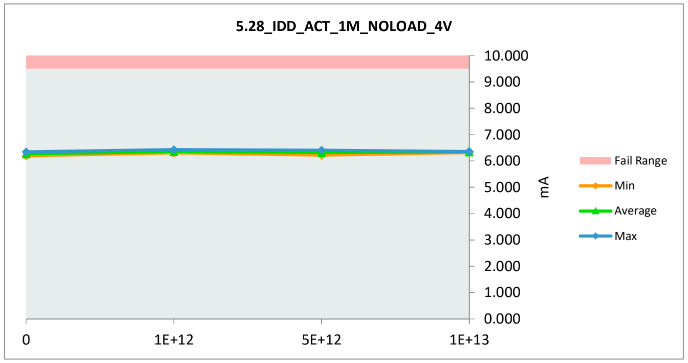


NDD Characterization Report
TPS7H5006-SEP

		5.28_IDD_ACT_1M_NOLOAD_4V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.1	9.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.198	6.195	-0.003
0	49	6.351	6.346	-0.005
1E+12	11	6.423	6.428	0.005
1E+12	12	6.320	6.308	-0.012
1E+12	13	6.333	6.325	-0.008
5E+12	14	6.221	6.217	-0.004
5E+12	15	6.377	6.400	0.023
5E+12	16	6.368	6.352	-0.016
1E+13	17	6.319	6.319	0.000
1E+13	18	6.347	6.352	0.005
1E+13	19	6.393	6.360	-0.033
	Max	6.423	6.428	0.023
	Average	6.332	6.327	-0.004
	Min	6.198	6.195	-0.033
	Std Dev	0.068	0.069	0.014

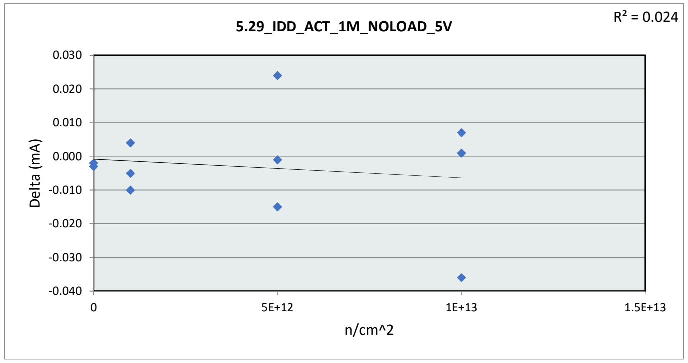


	5.28_IDD_ACT_1M_NOLOAD_4			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.195	6.308	6.217	6.319
Average	6.271	6.354	6.323	6.344
Max	6.346	6.428	6.400	6.360
UL	9.500	9.500	9.500	9.500

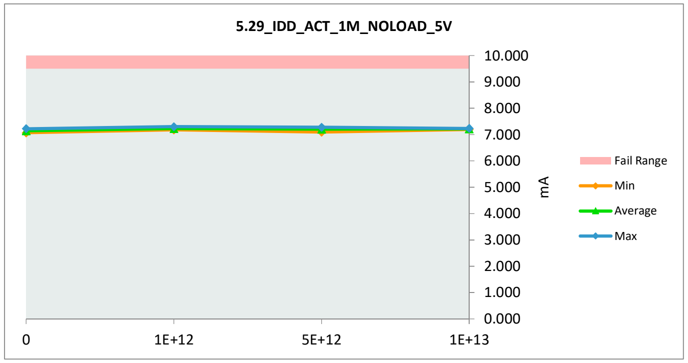


NDD Characterization Report
TPS7H5006-SEP

		5.29_IDD_ACT_1M_NOLOAD_5V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.1	9.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.071	7.069	-0.002
0	49	7.226	7.223	-0.003
1E+12	11	7.296	7.300	0.004
1E+12	12	7.190	7.180	-0.010
1E+12	13	7.206	7.201	-0.005
5E+12	14	7.096	7.095	-0.001
5E+12	15	7.250	7.274	0.024
5E+12	16	7.251	7.236	-0.015
1E+13	17	7.196	7.197	0.001
1E+13	18	7.225	7.232	0.007
1E+13	19	7.273	7.237	-0.036
	Max	7.296	7.300	0.024
	Average	7.207	7.204	-0.003
	Min	7.071	7.069	-0.036
	Std Dev	0.069	0.069	0.015

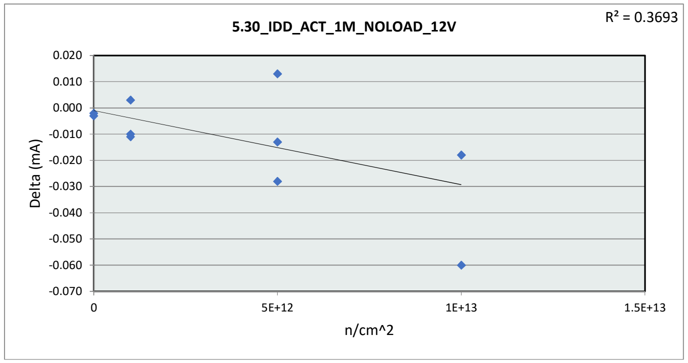


	5.29_IDD_ACT_1M_NOLOAD_			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.069	7.180	7.095	7.197
Average	7.146	7.227	7.202	7.222
Max	7.223	7.300	7.274	7.237
UL	9.500	9.500	9.500	9.500

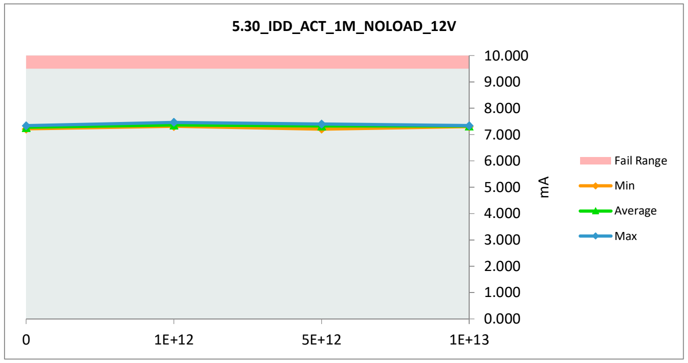


NDD Characterization Report
TPS7H5006-SEP

		5.30_IDD_ACT_1M_NOLOAD_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	9.1	9.5	
	Min Limit	5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.214	7.212	-0.002
0	49	7.337	7.334	-0.003
1E+12	11	7.461	7.464	0.003
1E+12	12	7.319	7.309	-0.010
1E+12	13	7.327	7.316	-0.011
5E+12	14	7.224	7.211	-0.013
5E+12	15	7.387	7.400	0.013
5E+12	16	7.394	7.366	-0.028
1E+13	17	7.316	7.298	-0.018
1E+13	18	7.337	7.319	-0.018
1E+13	19	7.396	7.336	-0.060
	Max	7.461	7.464	0.013
	Average	7.337	7.324	-0.013
	Min	7.214	7.211	-0.060
	Std Dev	0.073	0.073	0.019

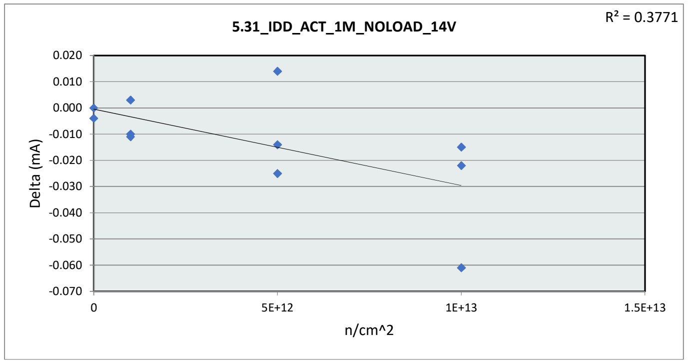


	5.30_IDD_ACT_1M_NOLOAD_			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.212	7.309	7.211	7.298
Average	7.273	7.363	7.326	7.318
Max	7.334	7.464	7.400	7.336
UL	9.500	9.500	9.500	9.500

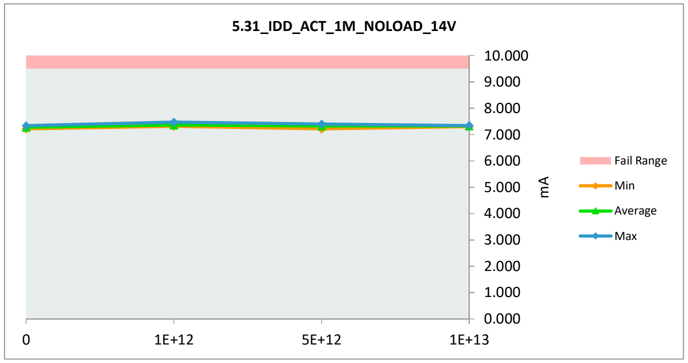


NDD Characterization Report
TPS7H5006-SEP

		5.31_IDD_ACT_1M_NOLOAD_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.1	9.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.220	7.216	-0.004
0	49	7.337	7.337	0.000
1E+12	11	7.466	7.469	0.003
1E+12	12	7.324	7.313	-0.011
1E+12	13	7.332	7.322	-0.010
5E+12	14	7.228	7.214	-0.014
5E+12	15	7.391	7.405	0.014
5E+12	16	7.397	7.372	-0.025
1E+13	17	7.323	7.301	-0.022
1E+13	18	7.339	7.324	-0.015
1E+13	19	7.403	7.342	-0.061
	Max	7.466	7.469	0.014
	Average	7.342	7.329	-0.013
	Min	7.220	7.214	-0.061
	Std Dev	0.073	0.074	0.019

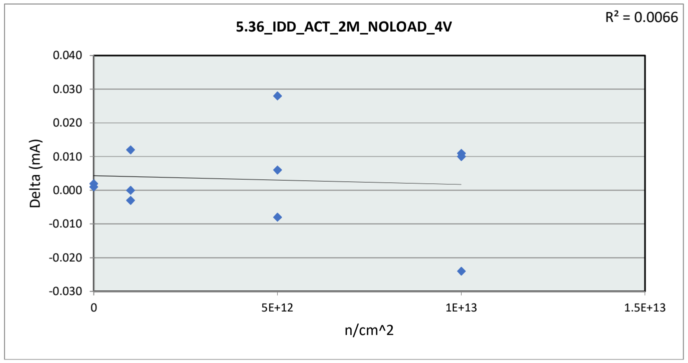


	5.31_IDD_ACT_1M_NOLOAD_			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.216	7.313	7.214	7.301
Average	7.277	7.368	7.330	7.322
Max	7.337	7.469	7.405	7.342
UL	9.500	9.500	9.500	9.500

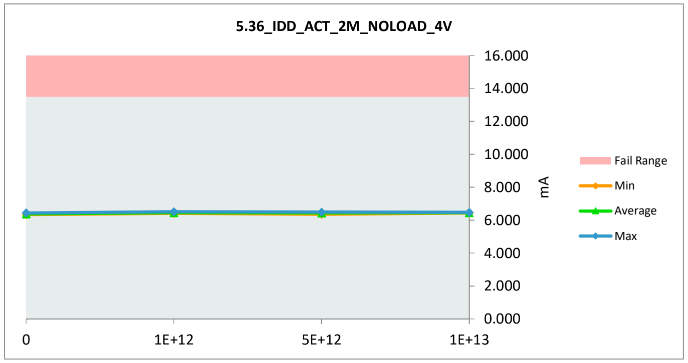


NDD Characterization Report
TPS7H5006-SEP

		5.36_IDD_ACT_2M_NOLOAD_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	9.5	13.5	
	Min Limit	5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.330	6.331	0.001
0	49	6.440	6.442	0.002
1E+12	11	6.495	6.507	0.012
1E+12	12	6.407	6.404	-0.003
1E+12	13	6.442	6.442	0.000
5E+12	14	6.353	6.359	0.006
5E+12	15	6.460	6.488	0.028
5E+12	16	6.479	6.471	-0.008
1E+13	17	6.422	6.433	0.011
1E+13	18	6.465	6.475	0.010
1E+13	19	6.484	6.460	-0.024
	Max	6.495	6.507	0.028
	Average	6.434	6.437	0.003
	Min	6.330	6.331	-0.024
	Std Dev	0.053	0.054	0.013

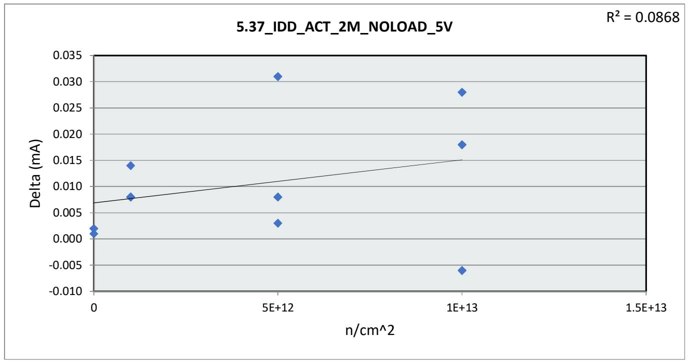


	5.36_IDD_ACT_2M_NOLOAD_4			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.331	6.404	6.359	6.433
Average	6.387	6.451	6.439	6.456
Max	6.442	6.507	6.488	6.475
UL	13.500	13.500	13.500	13.500

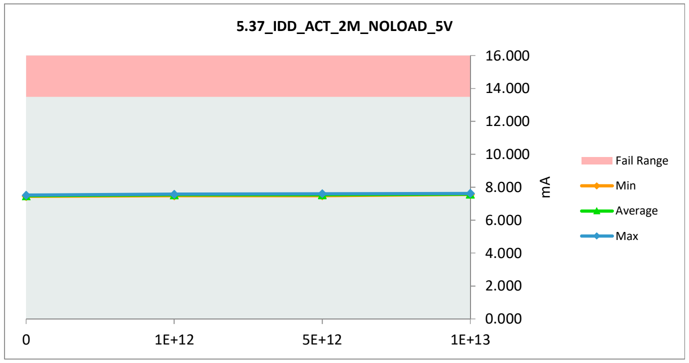


NDD Characterization Report
TPS7H5006-SEP

		5.37_IDD_ACT_2M_NOLOAD_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	12	13.5	
	Min Limit	5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.443	7.444	0.001
0	49	7.518	7.520	0.002
1E+12	11	7.552	7.566	0.014
1E+12	12	7.475	7.483	0.008
1E+12	13	7.560	7.568	0.008
5E+12	14	7.476	7.484	0.008
5E+12	15	7.527	7.558	0.031
5E+12	16	7.600	7.603	0.003
1E+13	17	7.535	7.563	0.028
1E+13	18	7.608	7.626	0.018
1E+13	19	7.575	7.569	-0.006
	Max	7.608	7.626	0.031
	Average	7.534	7.544	0.010
	Min	7.443	7.444	-0.006
	Std Dev	0.053	0.055	0.011

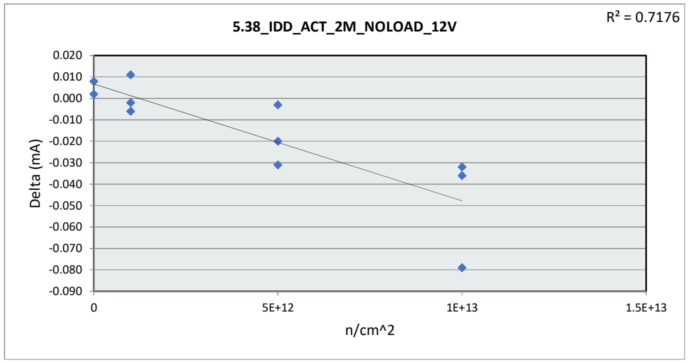


	5.37_IDD_ACT_2M_NOLOAD_5			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.444	7.483	7.484	7.563
Average	7.482	7.539	7.548	7.586
Max	7.520	7.568	7.603	7.626
UL	13.500	13.500	13.500	13.500

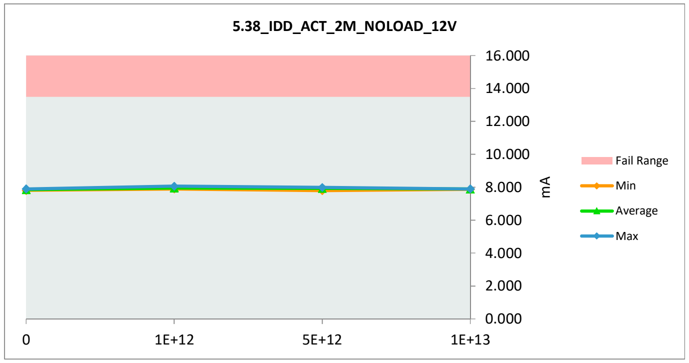


NDD Characterization Report
TPS7H5006-SEP

		5.38_IDD_ACT_2M_NOLOAD_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	12	13.5	
	Min Limit	5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.809	7.811	0.002
0	49	7.888	7.896	0.008
1E+12	11	8.052	8.063	0.011
1E+12	12	7.901	7.899	-0.002
1E+12	13	7.918	7.912	-0.006
5E+12	14	7.811	7.791	-0.020
5E+12	15	7.979	7.976	-0.003
5E+12	16	8.028	7.997	-0.031
1E+13	17	7.916	7.880	-0.036
1E+13	18	7.916	7.884	-0.032
1E+13	19	7.975	7.896	-0.079
	Max	8.052	8.063	0.011
	Average	7.927	7.910	-0.017
	Min	7.809	7.791	-0.079
	Std Dev	0.078	0.078	0.026



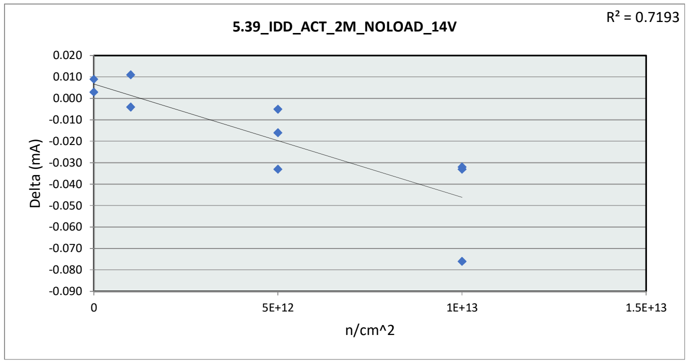
	5.38_IDD_ACT_2M_NOLOAD_			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.811	7.899	7.791	7.880
Average	7.854	7.958	7.921	7.887
Max	7.896	8.063	7.997	7.896
UL	13.500	13.500	13.500	13.500



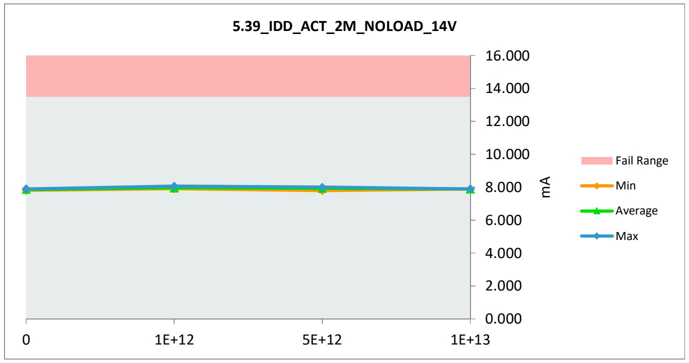
NDD Characterization Report
TPS7H5006-SEP

	5.39_IDD_ACT_2M_NOLOAD_14V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	12	13.5
Min Limit	5	

n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.813	7.816	0.003
0	49	7.893	7.902	0.009
1E+12	11	8.056	8.067	0.011
1E+12	12	7.907	7.903	-0.004
1E+12	13	7.920	7.916	-0.004
5E+12	14	7.812	7.796	-0.016
5E+12	15	7.984	7.979	-0.005
5E+12	16	8.035	8.002	-0.033
1E+13	17	7.919	7.886	-0.033
1E+13	18	7.920	7.888	-0.032
1E+13	19	7.978	7.902	-0.076
	Max	8.056	8.067	0.011
	Average	7.931	7.914	-0.016
	Min	7.812	7.796	-0.076
	Std Dev	0.079	0.078	0.026

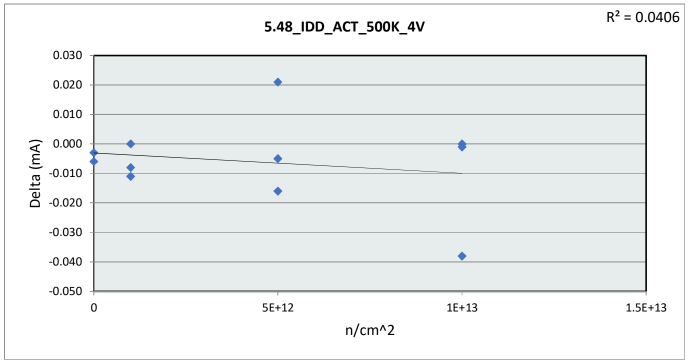


	5.39_IDD_ACT_2M_NOLOAD_			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.816	7.903	7.796	7.886
Average	7.859	7.962	7.926	7.892
Max	7.902	8.067	8.002	7.902
UL	13.500	13.500	13.500	13.500

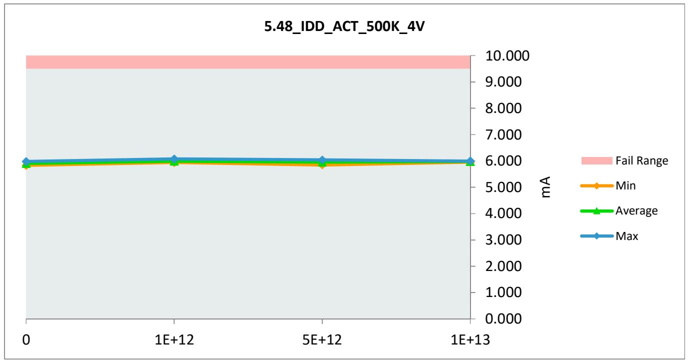


NDD Characterization Report
TPS7H5006-SEP

		5.48_IDD_ACT_500K_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	9.2	9.5	
	Min Limit	2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.837	5.831	-0.006
0	49	5.980	5.977	-0.003
1E+12	11	6.076	6.076	0.000
1E+12	12	5.956	5.945	-0.011
1E+12	13	5.969	5.961	-0.008
5E+12	14	5.856	5.851	-0.005
5E+12	15	6.019	6.040	0.021
5E+12	16	5.999	5.983	-0.016
1E+13	17	5.954	5.953	-0.001
1E+13	18	5.983	5.983	0.000
1E+13	19	6.034	5.996	-0.038
	Max	6.076	6.076	0.021
	Average	5.969	5.963	-0.006
	Min	5.837	5.831	-0.038
	Std Dev	0.071	0.072	0.014

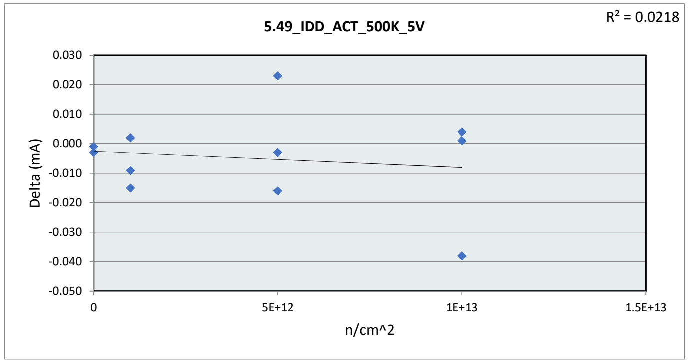


	5.48_IDD_ACT_500K_4V			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	5.831	5.945	5.851	5.953
Average	5.904	5.994	5.958	5.977
Max	5.977	6.076	6.040	5.996
UL	9.500	9.500	9.500	9.500

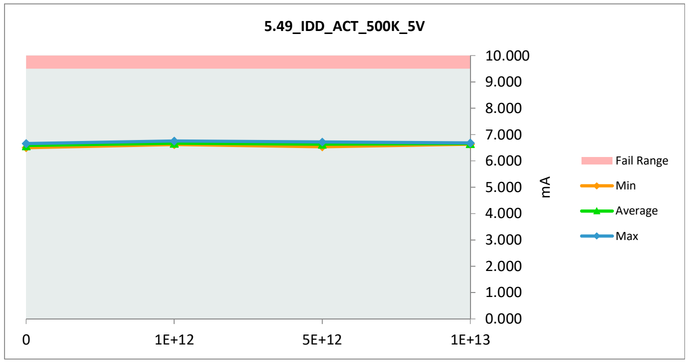


NDD Characterization Report
TPS7H5006-SEP

		5.49_IDD_ACT_500K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	9.2	9.5	
	Min Limit	2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.509	6.506	-0.003
0	49	6.657	6.656	-0.001
1E+12	11	6.753	6.755	0.002
1E+12	12	6.636	6.621	-0.015
1E+12	13	6.650	6.641	-0.009
5E+12	14	6.535	6.532	-0.003
5E+12	15	6.696	6.719	0.023
5E+12	16	6.683	6.667	-0.016
1E+13	17	6.632	6.633	0.001
1E+13	18	6.663	6.667	0.004
1E+13	19	6.719	6.681	-0.038
	Max	6.753	6.755	0.023
	Average	6.648	6.643	-0.005
	Min	6.509	6.506	-0.038
	Std Dev	0.072	0.073	0.015

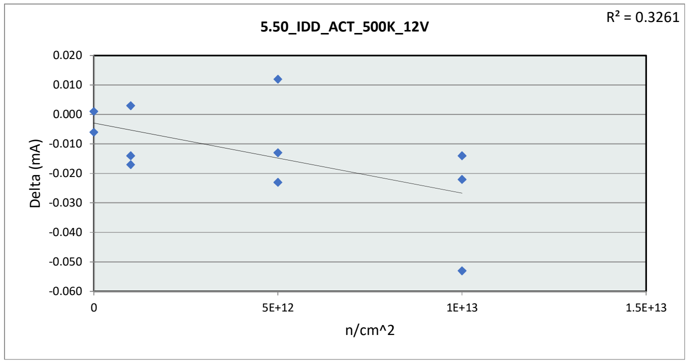


	5.49_IDD_ACT_500K_5V			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.506	6.621	6.532	6.633
Average	6.581	6.672	6.639	6.660
Max	6.656	6.755	6.719	6.681
UL	9.500	9.500	9.500	9.500

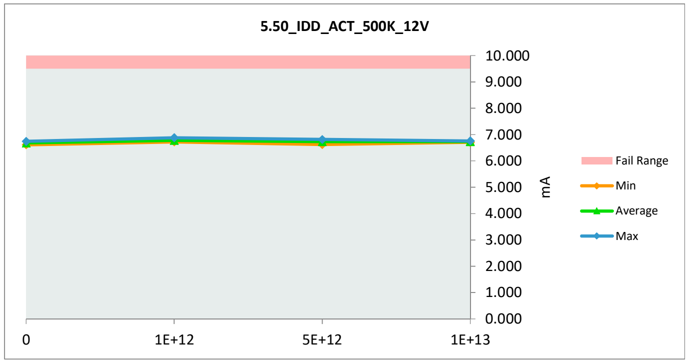


NDD Characterization Report
TPS7H5006-SEP

		5.50_IDD_ACT_500K_12V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.2	9.5	
Min Limit		2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.621	6.615	-0.006
0	49	6.741	6.742	0.001
1E+12	11	6.879	6.882	0.003
1E+12	12	6.738	6.721	-0.017
1E+12	13	6.744	6.730	-0.014
5E+12	14	6.631	6.618	-0.013
5E+12	15	6.804	6.816	0.012
5E+12	16	6.792	6.769	-0.023
1E+13	17	6.729	6.707	-0.022
1E+13	18	6.748	6.734	-0.014
1E+13	19	6.812	6.759	-0.053
	Max	6.879	6.882	0.012
	Average	6.749	6.736	-0.013
	Min	6.621	6.615	-0.053
	Std Dev	0.075	0.077	0.017

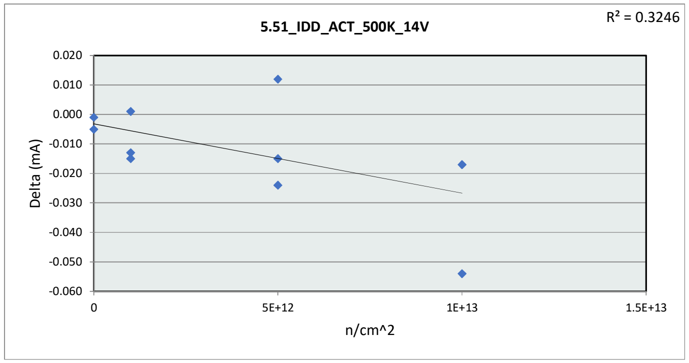


	5.50_IDD_ACT_500K_12V			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.615	6.721	6.618	6.707
Average	6.679	6.778	6.734	6.733
Max	6.742	6.882	6.816	6.759
UL	9.500	9.500	9.500	9.500

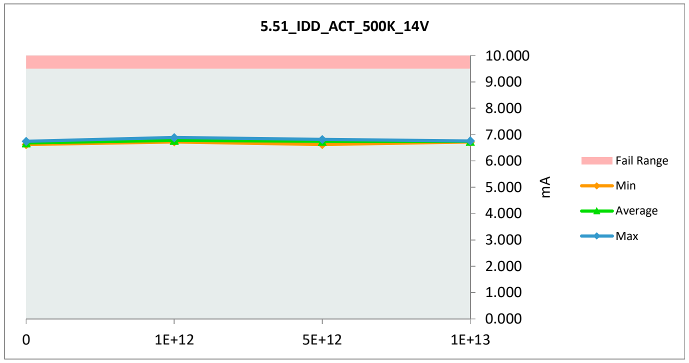


NDD Characterization Report
TPS7H5006-SEP

		5.51_IDD_ACT_500K_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.2	9.5	
Min Limit		2		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.626	6.621	-0.005
0	49	6.747	6.746	-0.001
1E+12	11	6.885	6.886	0.001
1E+12	12	6.740	6.725	-0.015
1E+12	13	6.749	6.736	-0.013
5E+12	14	6.637	6.622	-0.015
5E+12	15	6.808	6.820	0.012
5E+12	16	6.798	6.774	-0.024
1E+13	17	6.732	6.715	-0.017
1E+13	18	6.754	6.737	-0.017
1E+13	19	6.816	6.762	-0.054
	Max	6.885	6.886	0.012
	Average	6.754	6.740	-0.013
	Min	6.626	6.621	-0.054
	Std Dev	0.075	0.076	0.017

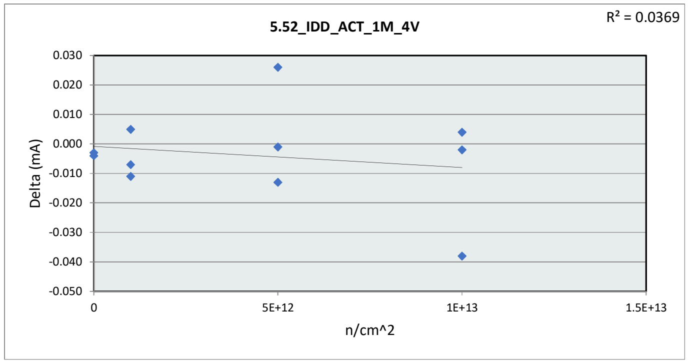


	5.51_IDD_ACT_500K_14V			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.621	6.725	6.622	6.715
Average	6.684	6.782	6.739	6.738
Max	6.746	6.886	6.820	6.762
UL	9.500	9.500	9.500	9.500

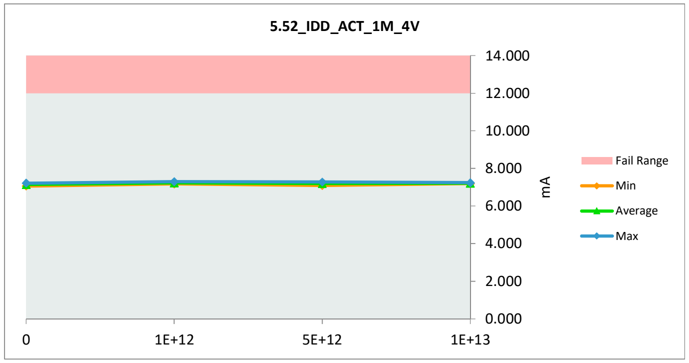


NDD Characterization Report
TPS7H5006-SEP

		5.52_IDD_ACT_1M_4V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		11.7	12	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.071	7.067	-0.004
0	49	7.223	7.220	-0.003
1E+12	11	7.295	7.300	0.005
1E+12	12	7.192	7.181	-0.011
1E+12	13	7.207	7.200	-0.007
5E+12	14	7.094	7.093	-0.001
5E+12	15	7.250	7.276	0.026
5E+12	16	7.240	7.227	-0.013
1E+13	17	7.195	7.193	-0.002
1E+13	18	7.221	7.225	0.004
1E+13	19	7.272	7.234	-0.038
	Max	7.295	7.300	0.026
	Average	7.205	7.201	-0.004
	Min	7.071	7.067	-0.038
	Std Dev	0.069	0.069	0.015

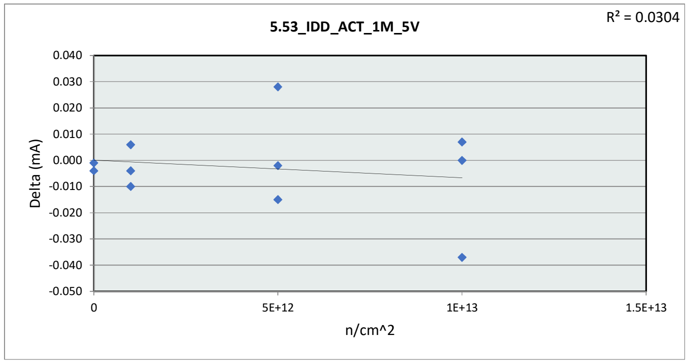


	5.52_IDD_ACT_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.067	7.181	7.093	7.193
Average	7.144	7.227	7.199	7.217
Max	7.220	7.300	7.276	7.234
UL	12.000	12.000	12.000	12.000

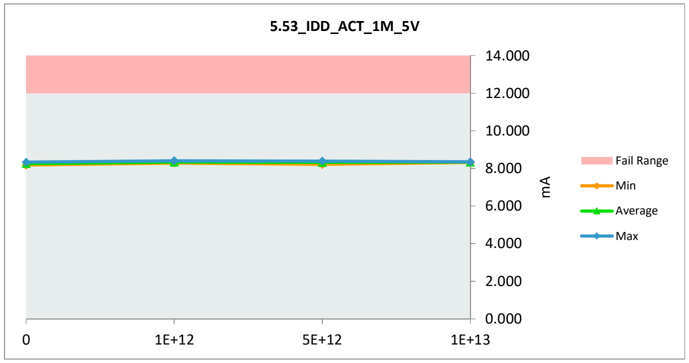


NDD Characterization Report
TPS7H5006-SEP

		5.53_IDD_ACT_1M_5V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		11.7	12	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.177	8.176	-0.001
0	49	8.338	8.334	-0.004
1E+12	11	8.405	8.411	0.006
1E+12	12	8.302	8.292	-0.010
1E+12	13	8.317	8.313	-0.004
5E+12	14	8.206	8.204	-0.002
5E+12	15	8.360	8.388	0.028
5E+12	16	8.361	8.346	-0.015
1E+13	17	8.311	8.311	0.000
1E+13	18	8.335	8.342	0.007
1E+13	19	8.390	8.353	-0.037
	Max	8.405	8.411	0.028
	Average	8.318	8.315	-0.003
	Min	8.177	8.176	-0.037
	Std Dev	0.071	0.071	0.016

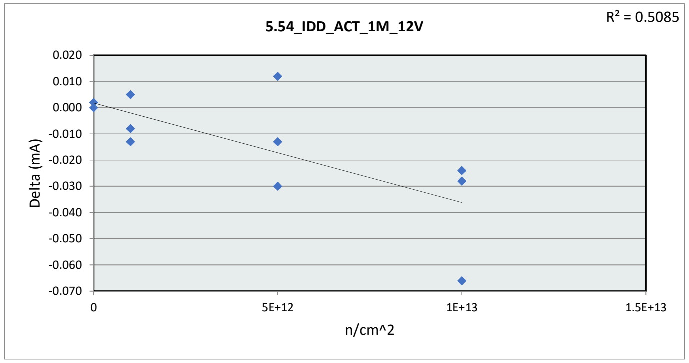


	5.53_IDD_ACT_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.176	8.292	8.204	8.311
Average	8.255	8.339	8.313	8.335
Max	8.334	8.411	8.388	8.353
UL	12.000	12.000	12.000	12.000

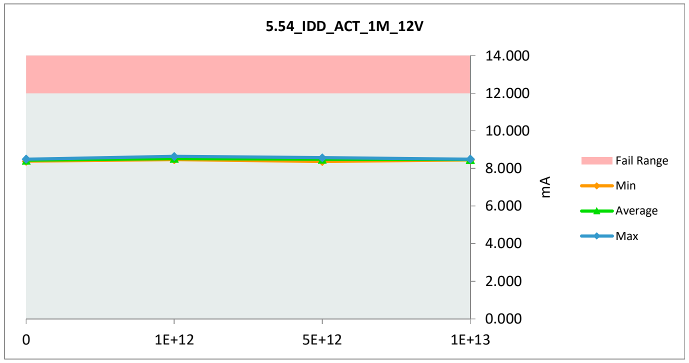


NDD Characterization Report
TPS7H5006-SEP

		5.54_IDD_ACT_1M_12V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		11.7	12	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.377	8.377	0.000
0	49	8.492	8.494	0.002
1E+12	11	8.633	8.638	0.005
1E+12	12	8.485	8.472	-0.013
1E+12	13	8.488	8.480	-0.008
5E+12	14	8.383	8.370	-0.013
5E+12	15	8.553	8.565	0.012
5E+12	16	8.561	8.531	-0.030
1E+13	17	8.482	8.454	-0.028
1E+13	18	8.494	8.470	-0.024
1E+13	19	8.564	8.498	-0.066
	Max	8.633	8.638	0.012
	Average	8.501	8.486	-0.015
	Min	8.377	8.370	-0.066
	Std Dev	0.076	0.076	0.022

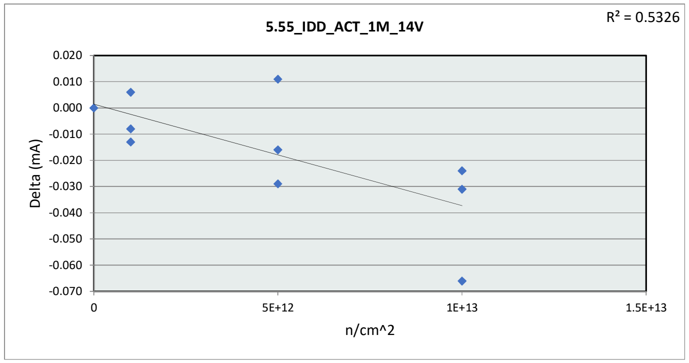


	5.54_IDD_ACT_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.377	8.472	8.370	8.454
Average	8.436	8.530	8.489	8.474
Max	8.494	8.638	8.565	8.498
UL	12.000	12.000	12.000	12.000

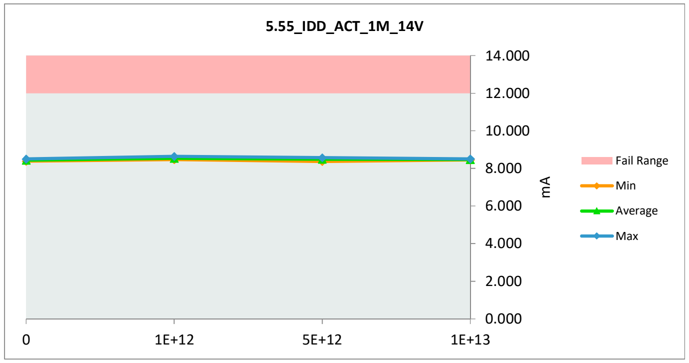


NDD Characterization Report
TPS7H5006-SEP

		5.55_IDD_ACT_1M_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		11.7	12	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.380	8.380	0.000
0	49	8.498	8.498	0.000
1E+12	11	8.635	8.641	0.006
1E+12	12	8.490	8.477	-0.013
1E+12	13	8.493	8.485	-0.008
5E+12	14	8.387	8.371	-0.016
5E+12	15	8.559	8.570	0.011
5E+12	16	8.565	8.536	-0.029
1E+13	17	8.488	8.457	-0.031
1E+13	18	8.499	8.475	-0.024
1E+13	19	8.568	8.502	-0.066
	Max	8.635	8.641	0.011
	Average	8.506	8.490	-0.015
	Min	8.380	8.371	-0.066
	Std Dev	0.076	0.077	0.022

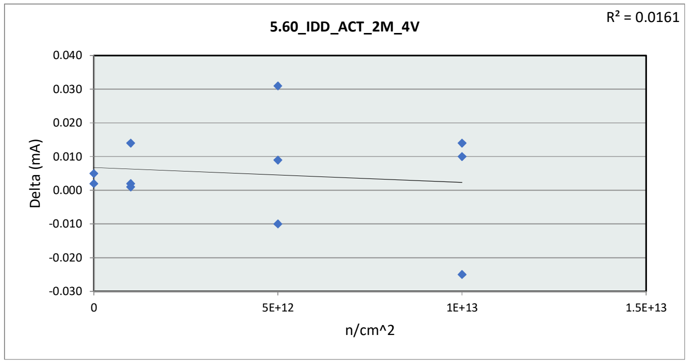


	5.55_IDD_ACT_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.380	8.477	8.371	8.457
Average	8.439	8.534	8.492	8.478
Max	8.498	8.641	8.570	8.502
UL	12.000	12.000	12.000	12.000

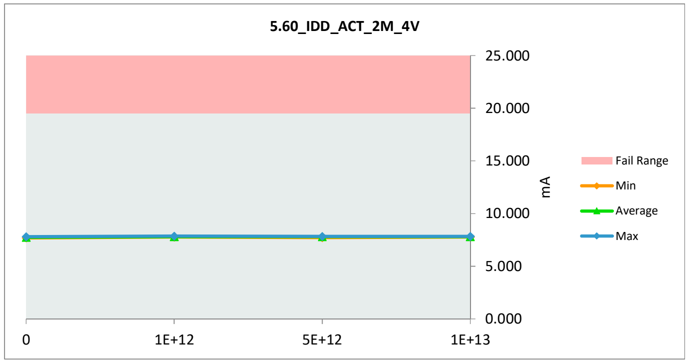


NDD Characterization Report
TPS7H5006-SEP

		5.60_IDD_ACT_2M_4V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		13	19.5	
Min Limit		5		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.684	7.689	0.005
0	49	7.795	7.797	0.002
1E+12	11	7.846	7.860	0.014
1E+12	12	7.763	7.764	0.001
1E+12	13	7.803	7.805	0.002
5E+12	14	7.712	7.721	0.009
5E+12	15	7.817	7.848	0.031
5E+12	16	7.834	7.824	-0.010
1E+13	17	7.776	7.786	0.010
1E+13	18	7.822	7.836	0.014
1E+13	19	7.845	7.820	-0.025
	Max	7.846	7.860	0.031
	Average	7.791	7.795	0.005
	Min	7.684	7.689	-0.025
	Std Dev	0.053	0.053	0.014

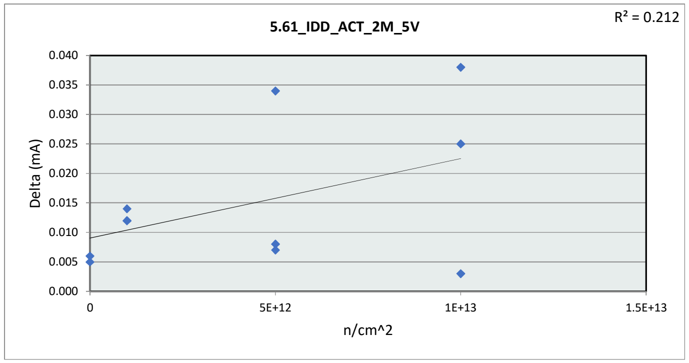


5.60_IDD_ACT_2M_4V				
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.689	7.764	7.721	7.786
Average	7.743	7.810	7.798	7.814
Max	7.797	7.860	7.848	7.836
UL	19.500	19.500	19.500	19.500

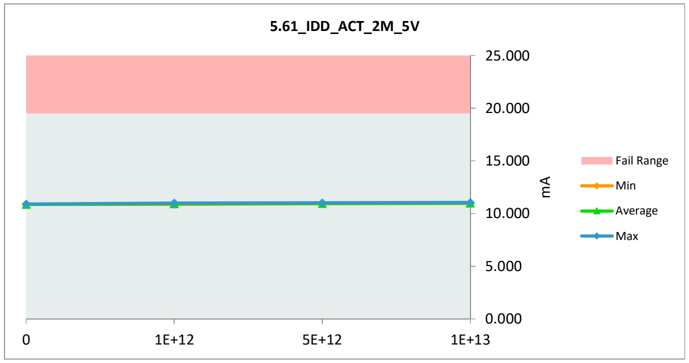


NDD Characterization Report
TPS7H5006-SEP

		5.61_IDD_ACT_2M_5V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		18	19.5	
Min Limit		10		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	10.860	10.866	0.006
0	49	10.906	10.911	0.005
1E+12	11	10.946	10.958	0.012
1E+12	12	10.868	10.880	0.012
1E+12	13	10.976	10.990	0.014
5E+12	14	10.906	10.914	0.008
5E+12	15	10.922	10.956	0.034
5E+12	16	11.001	11.008	0.007
1E+13	17	10.933	10.971	0.038
1E+13	18	11.021	11.046	0.025
1E+13	19	10.983	10.986	0.003
	Max	11.021	11.046	0.038
	Average	10.938	10.953	0.015
	Min	10.860	10.866	0.003
	Std Dev	0.053	0.055	0.012

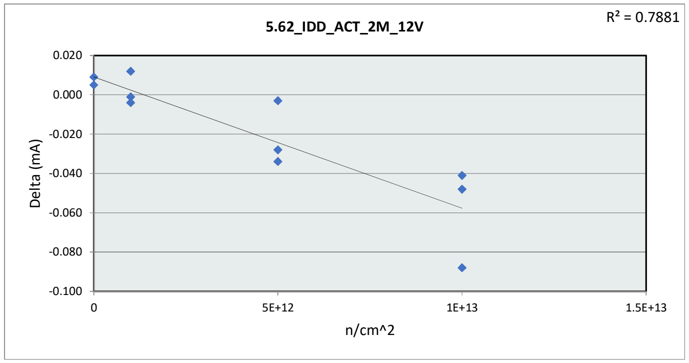


	5.61_IDD_ACT_2M_5V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	10.866	10.880	10.914	10.971
Average	10.889	10.943	10.959	11.001
Max	10.911	10.990	11.008	11.046
UL	19.500	19.500	19.500	19.500

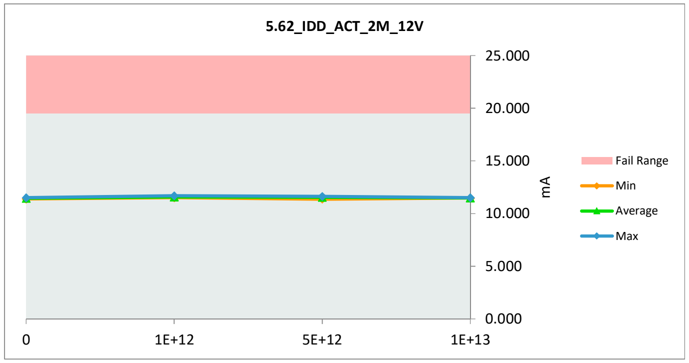


NDD Characterization Report
TPS7H5006-SEP

		5.62_IDD_ACT_2M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	18	19.5	
	Min Limit	10		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	11.390	11.395	0.005
0	49	11.492	11.501	0.009
1E+12	11	11.678	11.690	0.012
1E+12	12	11.514	11.513	-0.001
1E+12	13	11.537	11.533	-0.004
5E+12	14	11.404	11.376	-0.028
5E+12	15	11.605	11.602	-0.003
5E+12	16	11.660	11.626	-0.034
1E+13	17	11.536	11.488	-0.048
1E+13	18	11.515	11.474	-0.041
1E+13	19	11.594	11.506	-0.088
	Max	11.678	11.690	0.012
	Average	11.539	11.519	-0.020
	Min	11.390	11.376	-0.088
	Std Dev	0.092	0.093	0.031

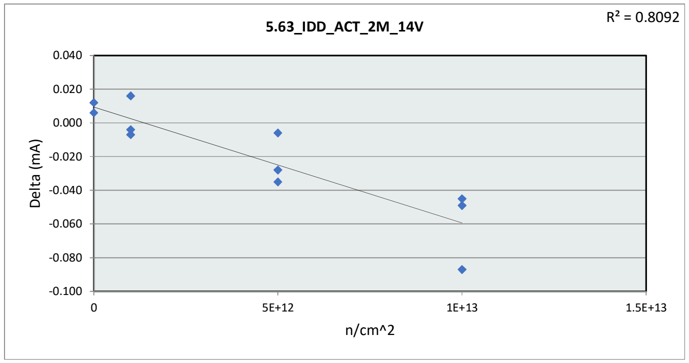


	5.62_IDD_ACT_2M_12V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	11.395	11.513	11.376	11.474
Average	11.448	11.579	11.535	11.489
Max	11.501	11.690	11.626	11.506
UL	19.500	19.500	19.500	19.500

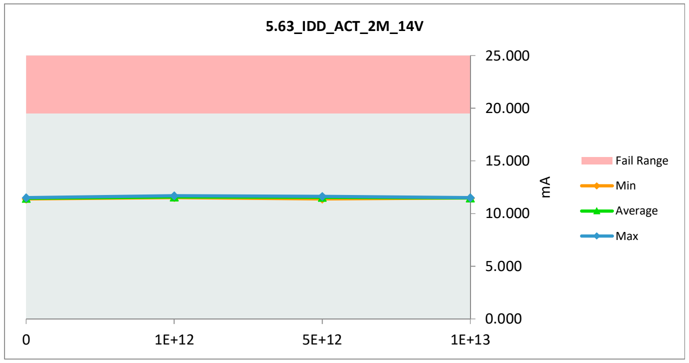


NDD Characterization Report
TPS7H5006-SEP

		5.63_IDD_ACT_2M_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		18	19.5	
Min Limit		10		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	11.395	11.401	0.006
0	49	11.494	11.506	0.012
1E+12	11	11.678	11.694	0.016
1E+12	12	11.521	11.517	-0.004
1E+12	13	11.543	11.536	-0.007
5E+12	14	11.410	11.382	-0.028
5E+12	15	11.610	11.604	-0.006
5E+12	16	11.664	11.629	-0.035
1E+13	17	11.541	11.492	-0.049
1E+13	18	11.522	11.477	-0.045
1E+13	19	11.598	11.511	-0.087
	Max	11.678	11.694	0.016
	Average	11.543	11.523	-0.021
	Min	11.395	11.382	-0.087
	Std Dev	0.091	0.092	0.031

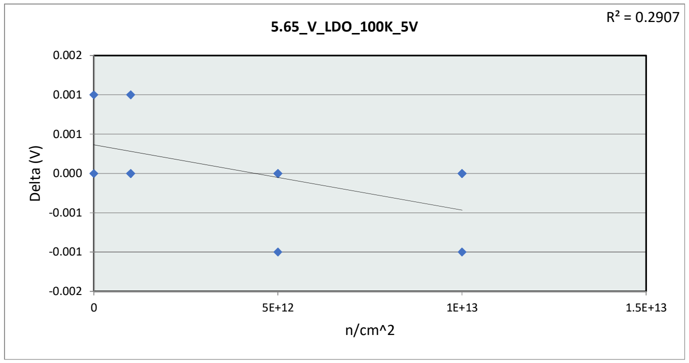


	5.63_IDD_ACT_2M_14V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	11.401	11.517	11.382	11.477
Average	11.454	11.582	11.538	11.493
Max	11.506	11.694	11.629	11.511
UL	19.500	19.500	19.500	19.500

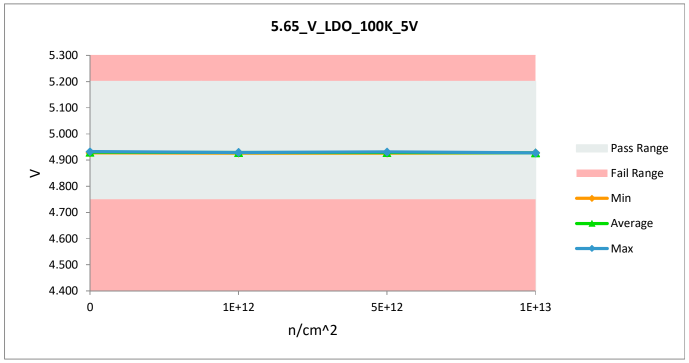


NDD Characterization Report
TPS7H5006-SEP

		5.65_V_LDO_100K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.1	5.2	
	Min Limit	4.85	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	4.931	4.932	0.001
0	49	4.928	4.928	0.000
1E+12	11	4.927	4.927	0.000
1E+12	12	4.929	4.929	0.000
1E+12	13	4.928	4.929	0.001
5E+12	14	4.931	4.931	0.000
5E+12	15	4.928	4.928	0.000
5E+12	16	4.928	4.927	-0.001
1E+13	17	4.929	4.928	-0.001
1E+13	18	4.928	4.928	0.000
1E+13	19	4.928	4.928	0.000
	Max	4.931	4.932	0.001
	Average	4.929	4.929	0.000
	Min	4.927	4.927	-0.001
	Std Dev	0.001	0.002	0.001

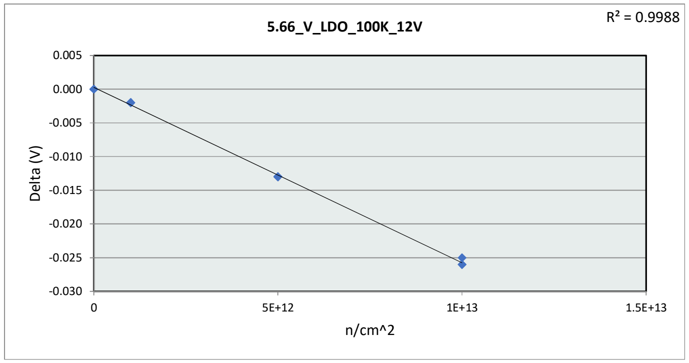


	5.65_V_LDO_100K_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.928	4.927	4.927	4.928
Average	4.930	4.928	4.929	4.928
Max	4.932	4.929	4.931	4.928
UL	5.200	5.200	5.200	5.200

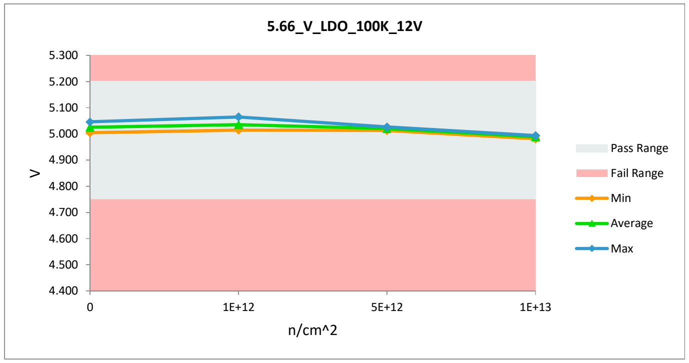


NDD Characterization Report
TPS7H5006-SEP

		5.66_V_LDO_100K_12V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.15	5.2	
Min Limit		4.85	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.046	5.046	0.000
0	49	5.005	5.005	0.000
1E+12	11	5.067	5.065	-0.002
1E+12	12	5.029	5.027	-0.002
1E+12	13	5.017	5.015	-0.002
5E+12	14	5.026	5.013	-0.013
5E+12	15	5.034	5.021	-0.013
5E+12	16	5.040	5.027	-0.013
1E+13	17	5.018	4.992	-0.026
1E+13	18	5.007	4.981	-0.026
1E+13	19	5.019	4.994	-0.025
	Max	5.067	5.065	0.000
	Average	5.028	5.017	-0.011
	Min	5.005	4.981	-0.026
	Std Dev	0.018	0.024	0.011

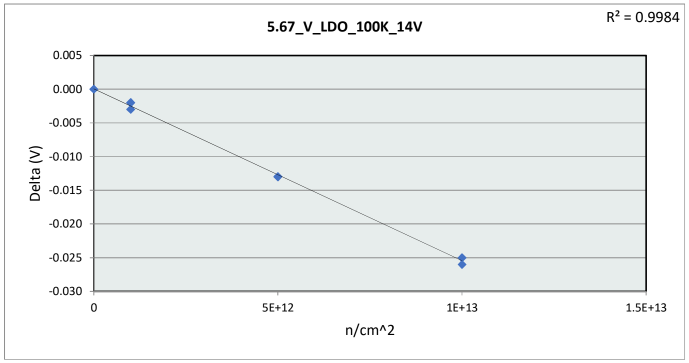


	5.66_V_LDO_100K_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.005	5.015	5.013	4.981
Average	5.026	5.036	5.020	4.989
Max	5.046	5.065	5.027	4.994
UL	5.200	5.200	5.200	5.200

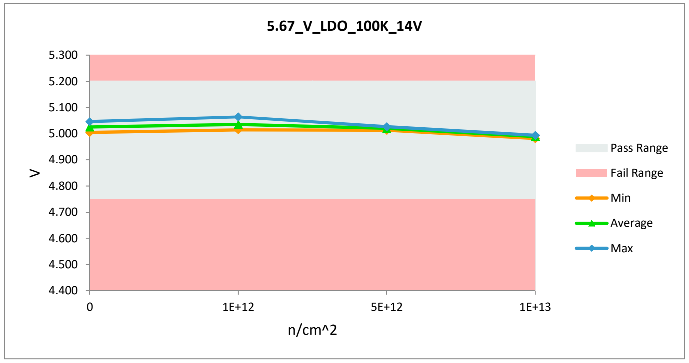


NDD Characterization Report
TPS7H5006-SEP

		5.67_V_LDO_100K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.85	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.046	5.046	0.000
0	49	5.005	5.005	0.000
1E+12	11	5.067	5.064	-0.003
1E+12	12	5.029	5.027	-0.002
1E+12	13	5.017	5.015	-0.002
5E+12	14	5.026	5.013	-0.013
5E+12	15	5.034	5.021	-0.013
5E+12	16	5.040	5.027	-0.013
1E+13	17	5.018	4.993	-0.025
1E+13	18	5.007	4.981	-0.026
1E+13	19	5.019	4.994	-0.025
	Max	5.067	5.064	0.000
	Average	5.028	5.017	-0.011
	Min	5.005	4.981	-0.026
	Std Dev	0.018	0.024	0.010

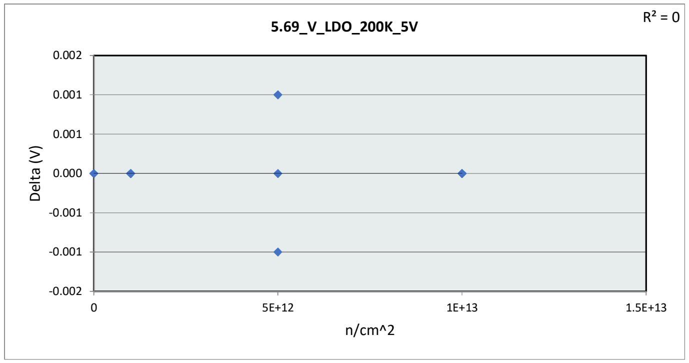


	5.67_V_LDO_100K_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.005	5.015	5.013	4.981
Average	5.026	5.035	5.020	4.989
Max	5.046	5.064	5.027	4.994
UL	5.200	5.200	5.200	5.200

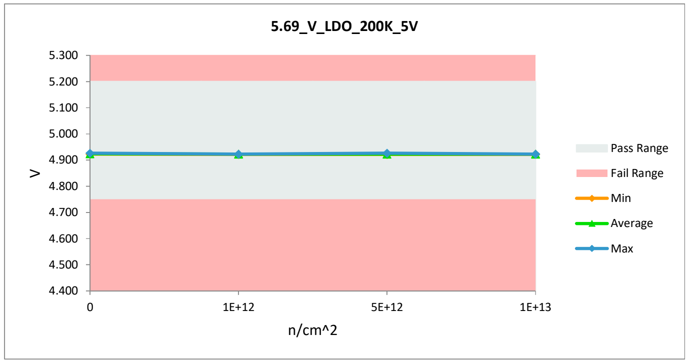


NDD Characterization Report
TPS7H5006-SEP

		5.69_V_LDO_200K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.1	5.2	
	Min Limit	4.84	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	4.926	4.926	0.000
0	49	4.923	4.923	0.000
1E+12	11	4.921	4.921	0.000
1E+12	12	4.923	4.923	0.000
1E+12	13	4.923	4.923	0.000
5E+12	14	4.925	4.926	0.001
5E+12	15	4.922	4.922	0.000
5E+12	16	4.922	4.921	-0.001
1E+13	17	4.923	4.923	0.000
1E+13	18	4.922	4.922	0.000
1E+13	19	4.922	4.922	0.000
	Max	4.926	4.926	0.001
	Average	4.923	4.923	0.000
	Min	4.921	4.921	-0.001
	Std Dev	0.001	0.002	0.000

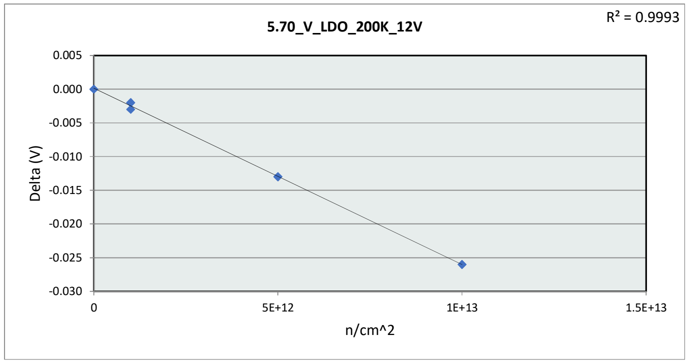


	5.69_V_LDO_200K_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.923	4.921	4.921	4.922
Average	4.925	4.922	4.923	4.922
Max	4.926	4.923	4.926	4.923
UL	5.200	5.200	5.200	5.200

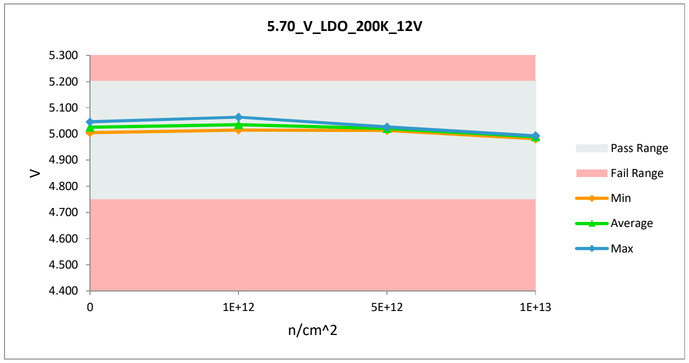


NDD Characterization Report
TPS7H5006-SEP

n/cm^2	Serial #	5.70_V_LDO_200K_12V		Delta
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.84	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.046	5.046	0.000
0	49	5.005	5.005	0.000
1E+12	11	5.067	5.064	-0.003
1E+12	12	5.029	5.027	-0.002
1E+12	13	5.017	5.015	-0.002
5E+12	14	5.026	5.013	-0.013
5E+12	15	5.034	5.021	-0.013
5E+12	16	5.040	5.027	-0.013
1E+13	17	5.018	4.992	-0.026
1E+13	18	5.007	4.981	-0.026
1E+13	19	5.019	4.993	-0.026
	Max	5.067	5.064	0.000
	Average	5.028	5.017	-0.011
	Min	5.005	4.981	-0.026
	Std Dev	0.018	0.024	0.011

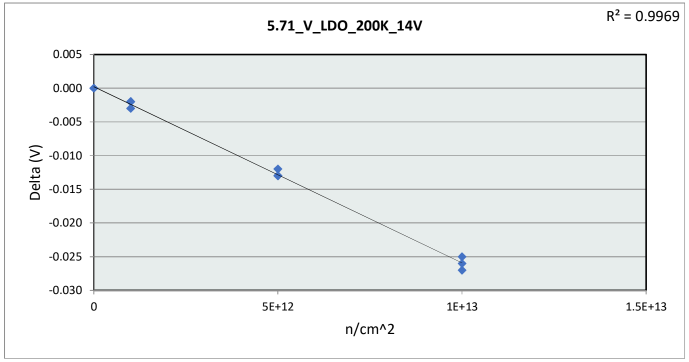


	5.70_V_LDO_200K_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.005	5.015	5.013	4.981
Average	5.026	5.035	5.020	4.989
Max	5.046	5.064	5.027	4.993
UL	5.200	5.200	5.200	5.200

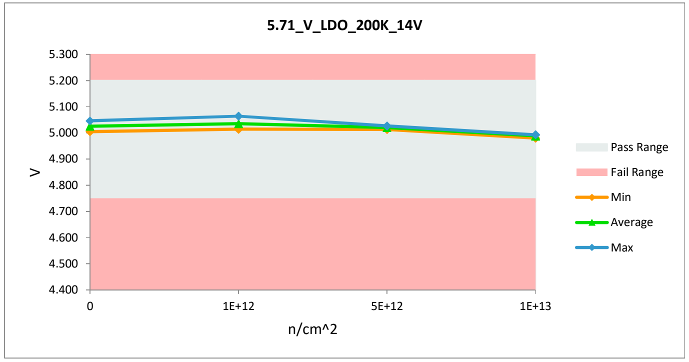


NDD Characterization Report
TPS7H5006-SEP

		5.71_V_LDO_200K_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.15	5.2	
Min Limit		4.84	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.046	5.046	0.000
0	49	5.005	5.005	0.000
1E+12	11	5.066	5.064	-0.002
1E+12	12	5.029	5.026	-0.003
1E+12	13	5.016	5.014	-0.002
5E+12	14	5.025	5.013	-0.012
5E+12	15	5.034	5.021	-0.013
5E+12	16	5.040	5.027	-0.013
1E+13	17	5.018	4.992	-0.026
1E+13	18	5.007	4.980	-0.027
1E+13	19	5.018	4.993	-0.025
	Max	5.066	5.064	0.000
	Average	5.028	5.016	-0.011
	Min	5.005	4.980	-0.027
	Std Dev	0.018	0.024	0.011

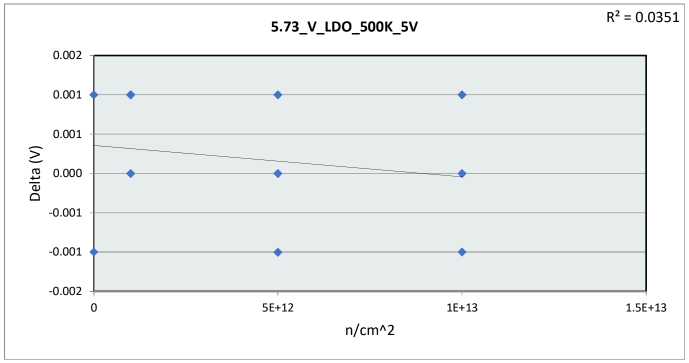


	5.71_V_LDO_200K_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.005	5.014	5.013	4.980
Average	5.026	5.035	5.020	4.988
Max	5.046	5.064	5.027	4.993
UL	5.200	5.200	5.200	5.200

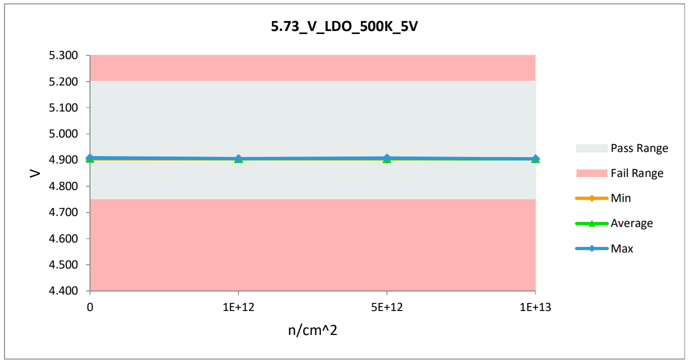


NDD Characterization Report
TPS7H5006-SEP

		5.73_V_LDO_500K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.1	5.2	
	Min Limit	4.81	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	4.908	4.909	0.001
0	49	4.906	4.905	-0.001
1E+12	11	4.904	4.905	0.001
1E+12	12	4.906	4.906	0.000
1E+12	13	4.905	4.906	0.001
5E+12	14	4.907	4.908	0.001
5E+12	15	4.905	4.905	0.000
5E+12	16	4.905	4.904	-0.001
1E+13	17	4.906	4.905	-0.001
1E+13	18	4.905	4.905	0.000
1E+13	19	4.904	4.905	0.001
	Max	4.908	4.909	0.001
	Average	4.906	4.906	0.000
	Min	4.904	4.904	-0.001
	Std Dev	0.001	0.001	0.001

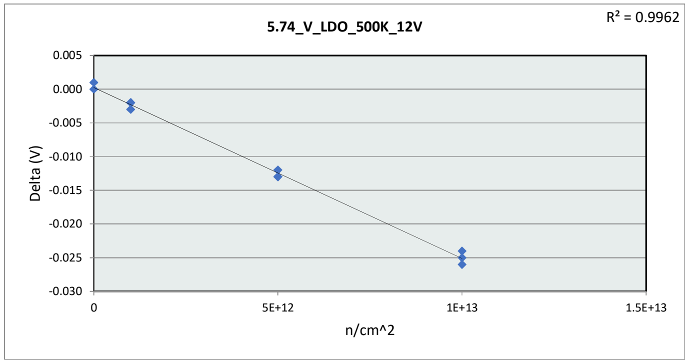


	5.73_V_LDO_500K_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.905	4.905	4.904	4.905
Average	4.907	4.906	4.906	4.905
Max	4.909	4.906	4.908	4.905
UL	5.200	5.200	5.200	5.200

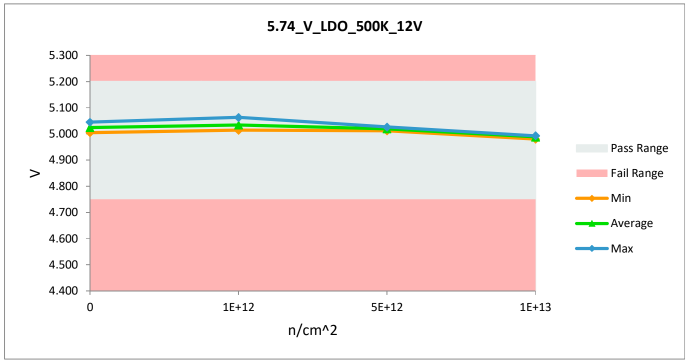


NDD Characterization Report
TPS7H5006-SEP

		5.74_V_LDO_500K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.81	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.045	5.045	0.000
0	49	5.004	5.005	0.001
1E+12	11	5.065	5.063	-0.002
1E+12	12	5.028	5.025	-0.003
1E+12	13	5.016	5.014	-0.002
5E+12	14	5.024	5.012	-0.012
5E+12	15	5.034	5.021	-0.013
5E+12	16	5.039	5.026	-0.013
1E+13	17	5.017	4.992	-0.025
1E+13	18	5.006	4.980	-0.026
1E+13	19	5.017	4.993	-0.024
	Max	5.065	5.063	0.001
	Average	5.027	5.016	-0.011
	Min	5.004	4.980	-0.026
	Std Dev	0.018	0.024	0.010

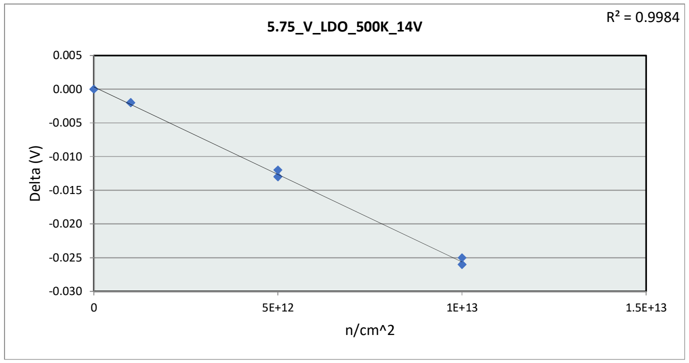


	5.74_V_LDO_500K_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.005	5.014	5.012	4.980
Average	5.025	5.034	5.020	4.988
Max	5.045	5.063	5.026	4.993
UL	5.200	5.200	5.200	5.200

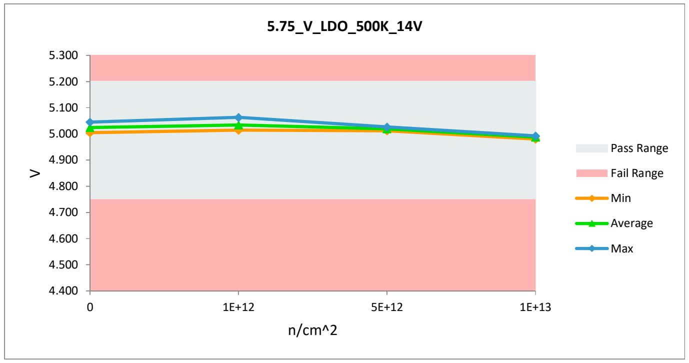


NDD Characterization Report
TPS7H5006-SEP

		5.75_V_LDO_500K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.81	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.045	5.045	0.000
0	49	5.004	5.004	0.000
1E+12	11	5.065	5.063	-0.002
1E+12	12	5.028	5.026	-0.002
1E+12	13	5.016	5.014	-0.002
5E+12	14	5.024	5.012	-0.012
5E+12	15	5.033	5.020	-0.013
5E+12	16	5.039	5.026	-0.013
1E+13	17	5.017	4.991	-0.026
1E+13	18	5.006	4.980	-0.026
1E+13	19	5.017	4.992	-0.025
	Max	5.065	5.063	0.000
	Average	5.027	5.016	-0.011
	Min	5.004	4.980	-0.026
	Std Dev	0.018	0.024	0.011

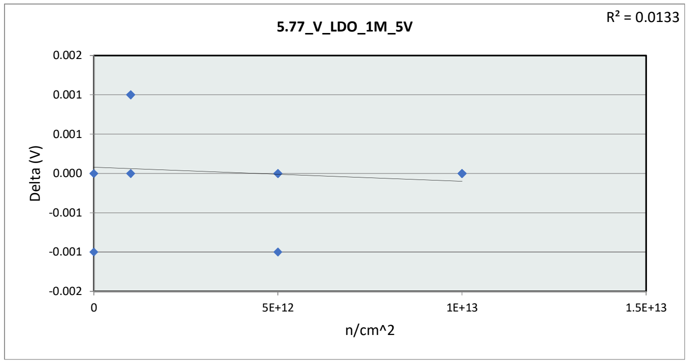


	5.75_V_LDO_500K_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.004	5.014	5.012	4.980
Average	5.025	5.034	5.019	4.988
Max	5.045	5.063	5.026	4.992
UL	5.200	5.200	5.200	5.200

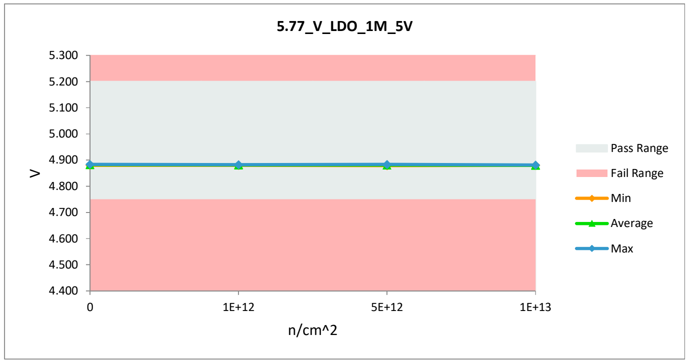


NDD Characterization Report
TPS7H5006-SEP

		5.77_V_LDO_1M_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.1	5.2	
Min Limit		4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	4.884	4.884	0.000
0	49	4.881	4.880	-0.001
1E+12	11	4.880	4.880	0.000
1E+12	12	4.881	4.882	0.001
1E+12	13	4.881	4.882	0.001
5E+12	14	4.883	4.883	0.000
5E+12	15	4.880	4.880	0.000
5E+12	16	4.880	4.879	-0.001
1E+13	17	4.881	4.881	0.000
1E+13	18	4.880	4.880	0.000
1E+13	19	4.880	4.880	0.000
	Max	4.884	4.884	0.001
	Average	4.881	4.881	0.000
	Min	4.880	4.879	-0.001
	Std Dev	0.001	0.002	0.001

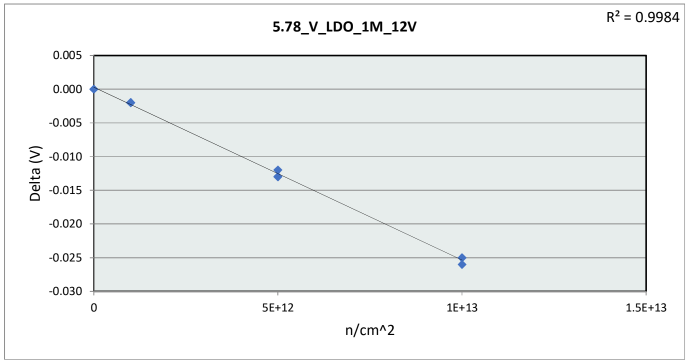


	5.77_V_LDO_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.880	4.880	4.879	4.880
Average	4.882	4.881	4.881	4.880
Max	4.884	4.882	4.883	4.881
UL	5.200	5.200	5.200	5.200

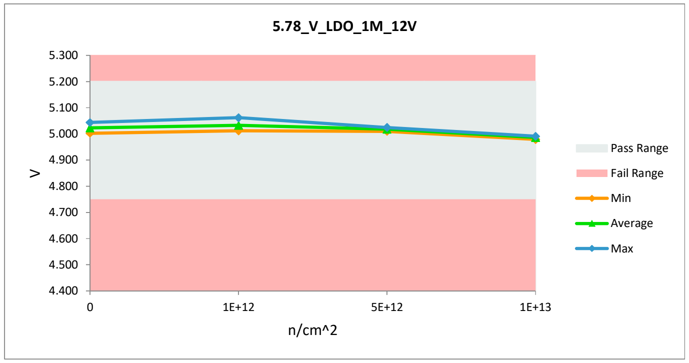


NDD Characterization Report
TPS7H5006-SEP

		5.78_V_LDO_1M_12V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.15	5.2	
Min Limit		4.85	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.044	5.044	0.000
0	49	5.003	5.003	0.000
1E+12	11	5.064	5.062	-0.002
1E+12	12	5.026	5.024	-0.002
1E+12	13	5.014	5.012	-0.002
5E+12	14	5.023	5.010	-0.013
5E+12	15	5.032	5.019	-0.013
5E+12	16	5.037	5.025	-0.012
1E+13	17	5.015	4.990	-0.025
1E+13	18	5.005	4.979	-0.026
1E+13	19	5.016	4.991	-0.025
	Max	5.064	5.062	0.000
	Average	5.025	5.014	-0.011
	Min	5.003	4.979	-0.026
	Std Dev	0.018	0.024	0.011

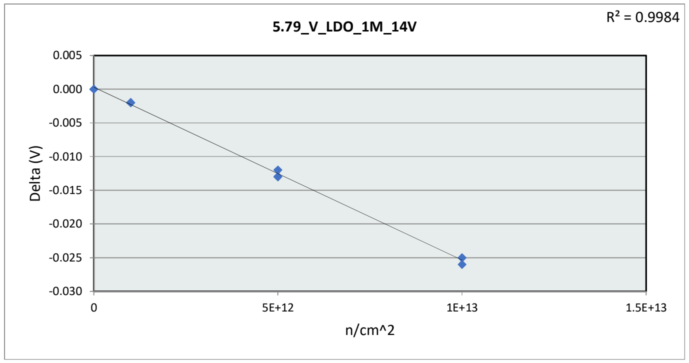


	5.78_V_LDO_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.003	5.012	5.010	4.979
Average	5.024	5.033	5.018	4.987
Max	5.044	5.062	5.025	4.991
UL	5.200	5.200	5.200	5.200

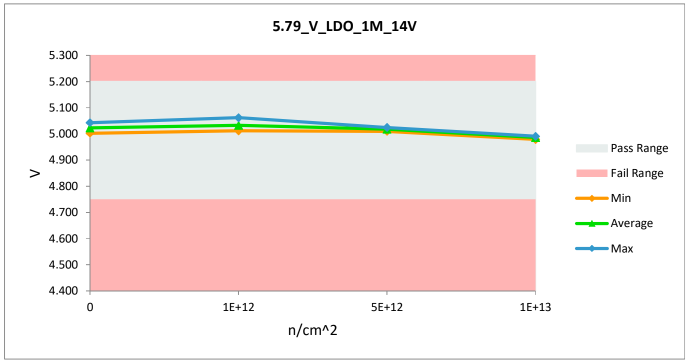


NDD Characterization Report
TPS7H5006-SEP

		5.79_V_LDO_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.85	4.75	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.043	5.043	0.000
0	49	5.003	5.003	0.000
1E+12	11	5.064	5.062	-0.002
1E+12	12	5.026	5.024	-0.002
1E+12	13	5.014	5.012	-0.002
5E+12	14	5.023	5.010	-0.013
5E+12	15	5.032	5.019	-0.013
5E+12	16	5.037	5.025	-0.012
1E+13	17	5.015	4.990	-0.025
1E+13	18	5.005	4.979	-0.026
1E+13	19	5.016	4.991	-0.025
	Max	5.064	5.062	0.000
	Average	5.025	5.014	-0.011
	Min	5.003	4.979	-0.026
	Std Dev	0.018	0.024	0.011

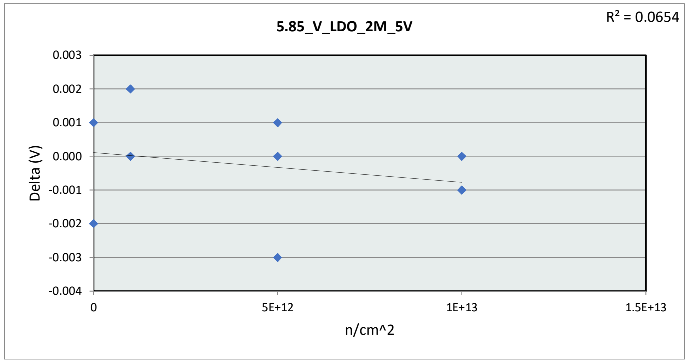


	5.79_V_LDO_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.003	5.012	5.010	4.979
Average	5.023	5.033	5.018	4.987
Max	5.043	5.062	5.025	4.991
UL	5.200	5.200	5.200	5.200

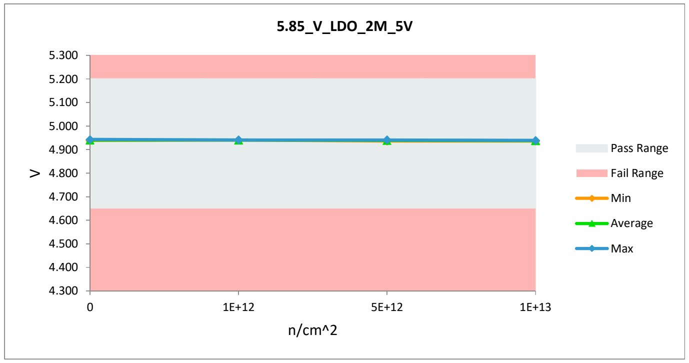


NDD Characterization Report
TPS7H5006-SEP

		5.85_V_LDO_2M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.1	5.2	
	Min Limit	4.8	4.65	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	4.942	4.943	0.001
0	49	4.941	4.939	-0.002
1E+12	11	4.940	4.940	0.000
1E+12	12	4.941	4.941	0.000
1E+12	13	4.938	4.940	0.002
5E+12	14	4.940	4.941	0.001
5E+12	15	4.940	4.940	0.000
5E+12	16	4.939	4.936	-0.003
1E+13	17	4.940	4.939	-0.001
1E+13	18	4.938	4.937	-0.001
1E+13	19	4.938	4.938	0.000
	Max	4.942	4.943	0.002
	Average	4.940	4.939	0.000
	Min	4.938	4.936	-0.003
	Std Dev	0.001	0.002	0.001

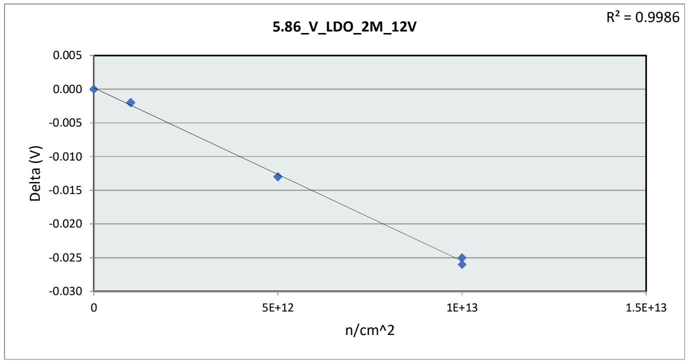


	5.85_V_LDO_2M_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	4.939	4.940	4.936	4.937
Average	4.941	4.940	4.939	4.938
Max	4.943	4.941	4.941	4.939
UL	5.200	5.200	5.200	5.200

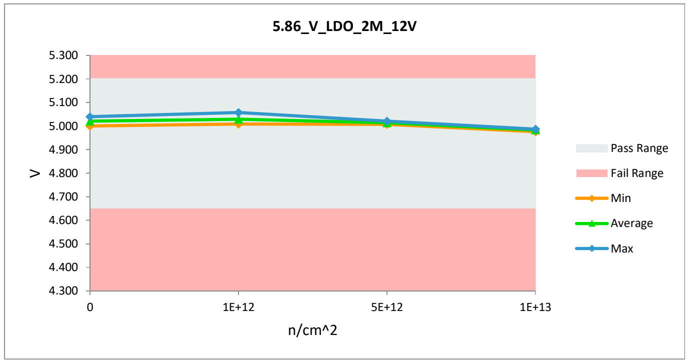


NDD Characterization Report
TPS7H5006-SEP

		5.86_V_LDO_2M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.8	4.65	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.040	5.040	0.000
0	49	5.000	5.000	0.000
1E+12	11	5.060	5.058	-0.002
1E+12	12	5.022	5.020	-0.002
1E+12	13	5.011	5.009	-0.002
5E+12	14	5.020	5.007	-0.013
5E+12	15	5.029	5.016	-0.013
5E+12	16	5.034	5.021	-0.013
1E+13	17	5.012	4.987	-0.025
1E+13	18	5.002	4.976	-0.026
1E+13	19	5.012	4.987	-0.025
	Max	5.060	5.058	0.000
	Average	5.022	5.011	-0.011
	Min	5.000	4.976	-0.026
	Std Dev	0.018	0.024	0.011

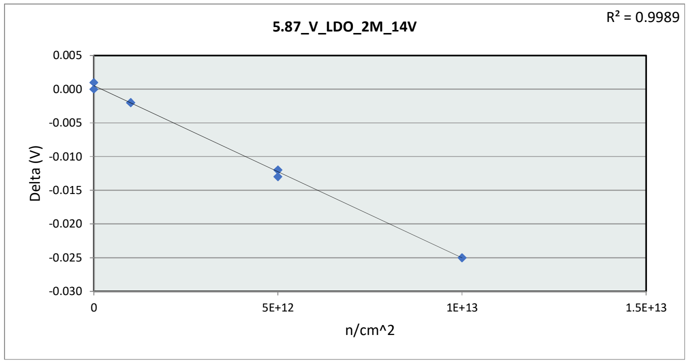


	5.86_V_LDO_2M_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	5.000	5.009	5.007	4.976
Average	5.020	5.029	5.015	4.983
Max	5.040	5.058	5.021	4.987
UL	5.200	5.200	5.200	5.200

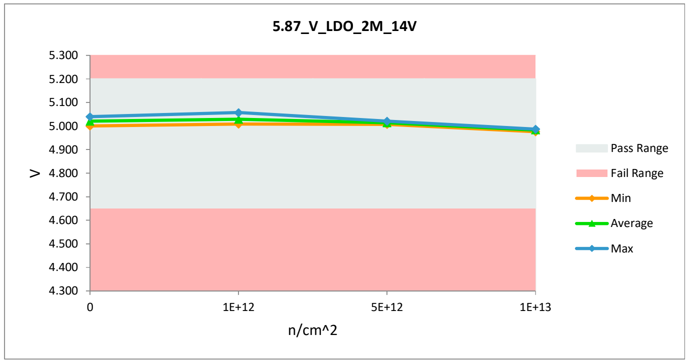


NDD Characterization Report
TPS7H5006-SEP

		5.87_V_LDO_2M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.15	5.2	
	Min Limit	4.8	4.65	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.040	5.040	0.000
0	49	4.999	5.000	0.001
1E+12	11	5.059	5.057	-0.002
1E+12	12	5.022	5.020	-0.002
1E+12	13	5.011	5.009	-0.002
5E+12	14	5.019	5.007	-0.012
5E+12	15	5.028	5.016	-0.012
5E+12	16	5.034	5.021	-0.013
1E+13	17	5.012	4.987	-0.025
1E+13	18	5.001	4.976	-0.025
1E+13	19	5.012	4.987	-0.025
	Max	5.059	5.057	0.001
	Average	5.022	5.011	-0.011
	Min	4.999	4.976	-0.025
	Std Dev	0.018	0.024	0.010

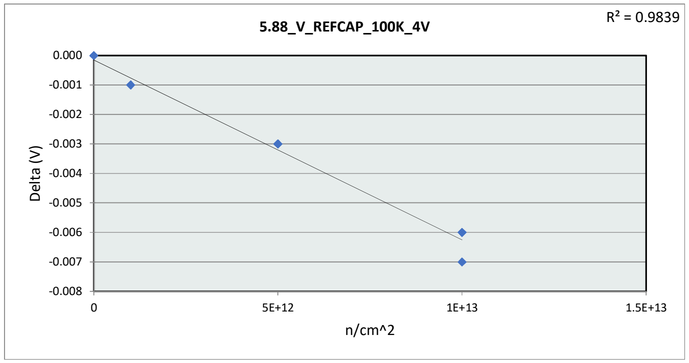


	5.87_V_LDO_2M_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	5.000	5.009	5.007	4.976
Average	5.020	5.029	5.015	4.983
Max	5.040	5.057	5.021	4.987
UL	5.200	5.200	5.200	5.200

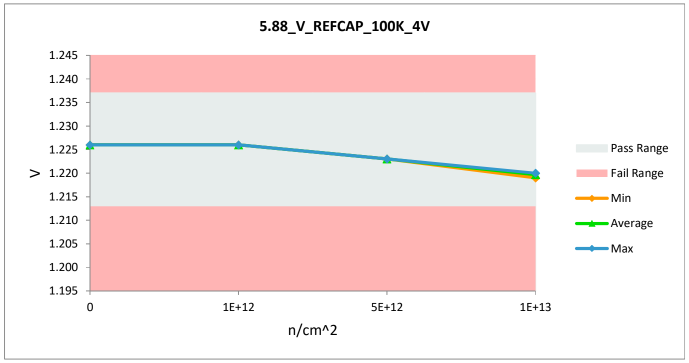


NDD Characterization Report
TPS7H5006-SEP

		5.88_V_REFCAP_100K_4V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.226	-0.001
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.219	-0.007
1E+13	18	1.226	1.220	-0.006
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.226	0.000
	Average	1.226	1.223	-0.003
	Min	1.226	1.219	-0.007
	Std Dev	0.000	0.003	0.003

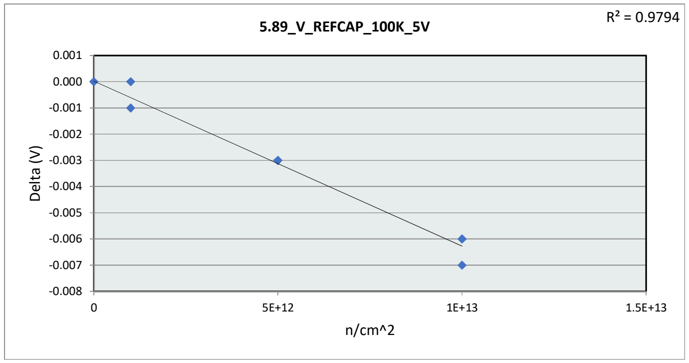


	5.88_V_REFCAP_100K_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.219
Average	1.226	1.226	1.223	1.220
Max	1.226	1.226	1.223	1.220
UL	1.237	1.237	1.237	1.237

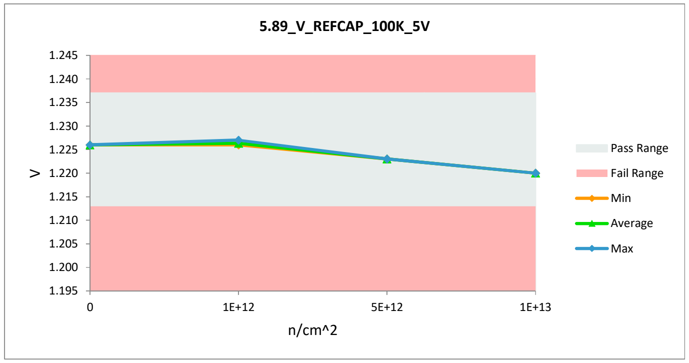


NDD Characterization Report
TPS7H5006-SEP

		5.89_V_REFCAP_100K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

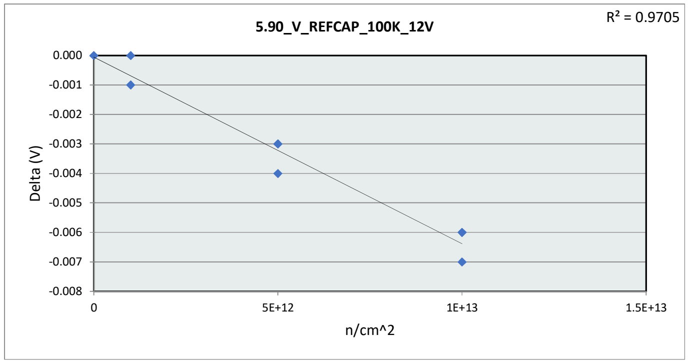


	5.89_V_REFCAP_100K_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

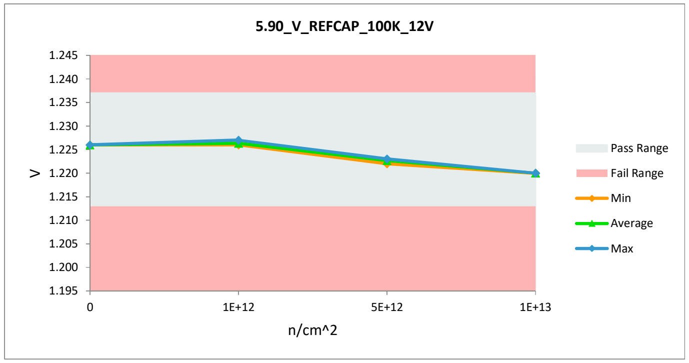


NDD Characterization Report
TPS7H5006-SEP

		5.90_V_REFCAP_100K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.222	-0.004
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

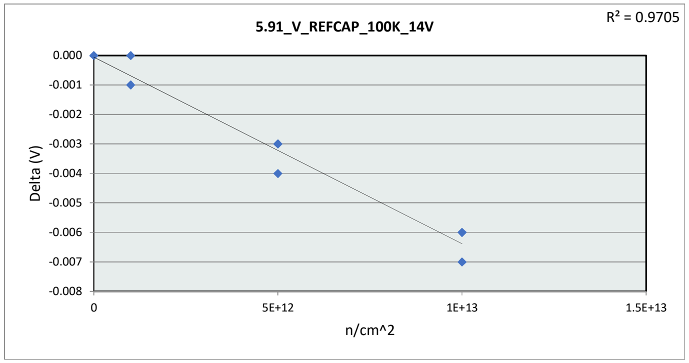


	5.90_V_REFCAP_100K_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.222	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

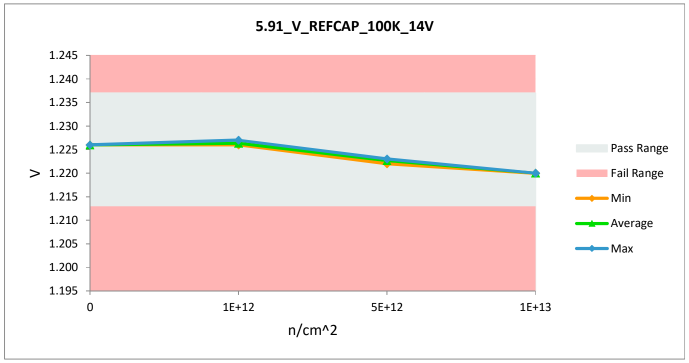


NDD Characterization Report
TPS7H5006-SEP

		5.91_V_REFCAP_100K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.222	-0.004
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

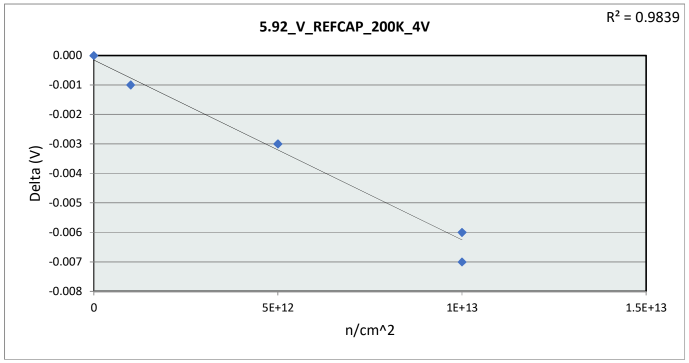


	5.91_V_REFCAP_100K_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237 V			
Min Limit	1.213 V			
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.222	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

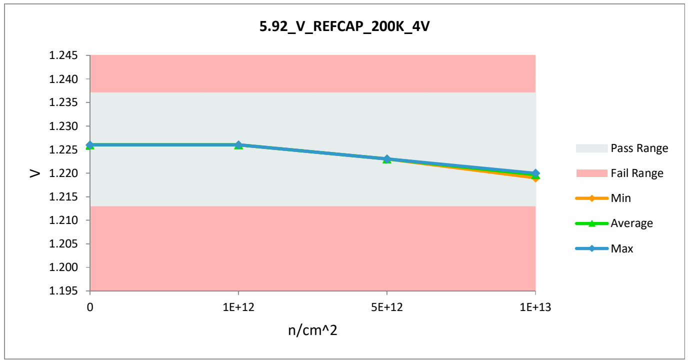


NDD Characterization Report
TPS7H5006-SEP

		5.92_V_REFCAP_200K_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.226	-0.001
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.219	-0.007
1E+13	18	1.226	1.220	-0.006
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.226	0.000
	Average	1.226	1.223	-0.003
	Min	1.226	1.219	-0.007
	Std Dev	0.000	0.003	0.003

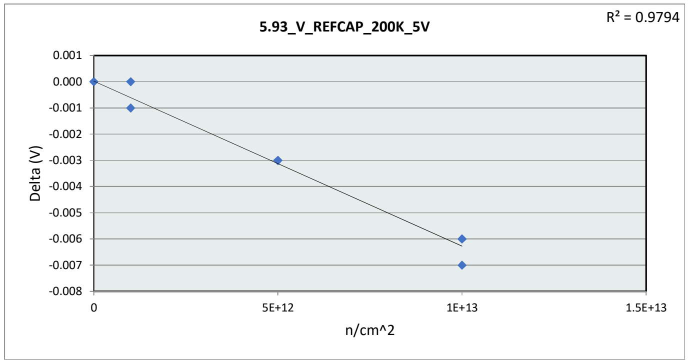


	5.92_V_REFCAP_200K_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237 V			
Min Limit	1.213 V			
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.219
Average	1.226	1.226	1.223	1.220
Max	1.226	1.226	1.223	1.220
UL	1.237	1.237	1.237	1.237

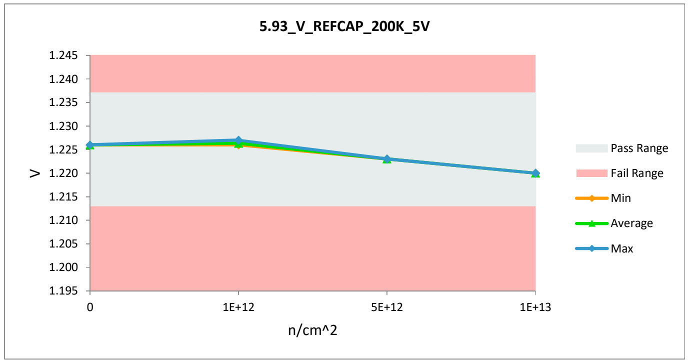


NDD Characterization Report
TPS7H5006-SEP

	5.93_V_REFCAP_200K_5V			
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

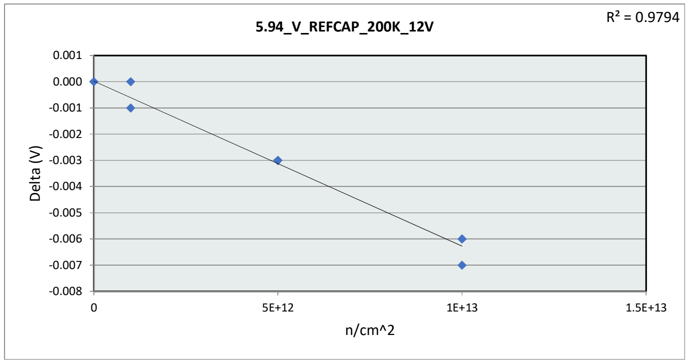


	5.93_V_REFCAP_200K_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

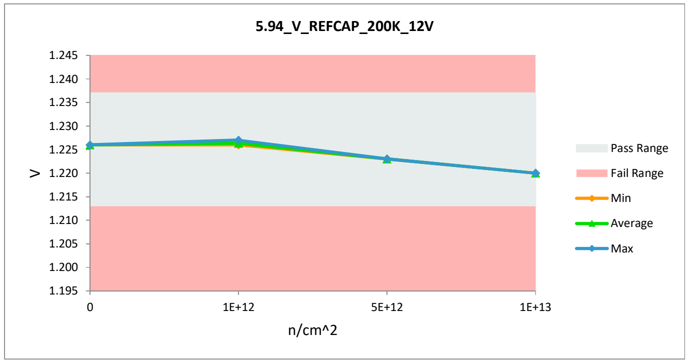


NDD Characterization Report
TPS7H5006-SEP

		5.94_V_REFCAP_200K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

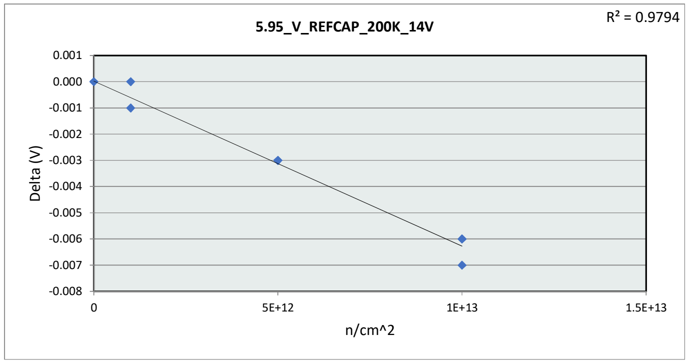


	5.94_V_REFCAP_200K_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

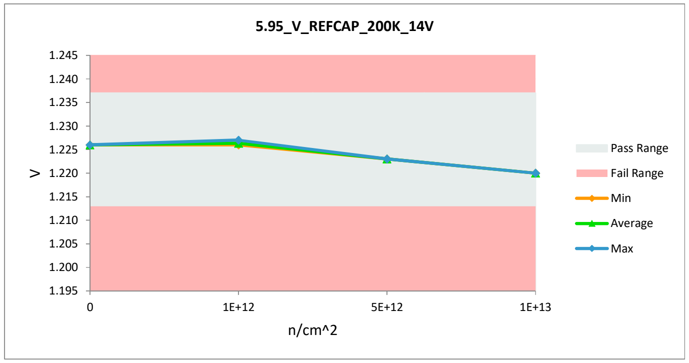


NDD Characterization Report
TPS7H5006-SEP

		5.95_V_REFCAP_200K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

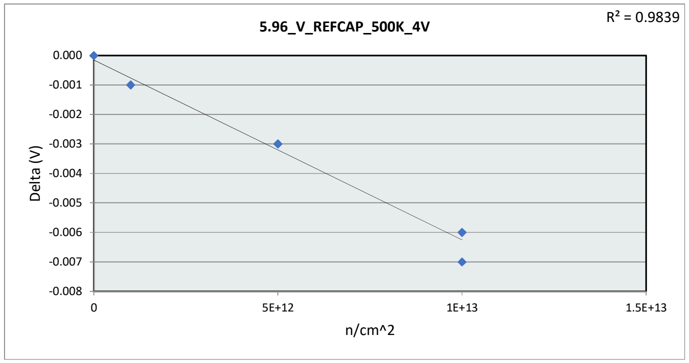


	5.95_V_REFCAP_200K_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

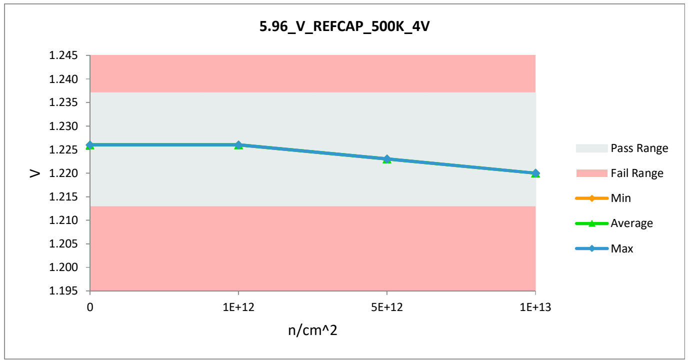


NDD Characterization Report
TPS7H5006-SEP

		5.96_V_REFCAP_500K_4V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.226	-0.001
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.226	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

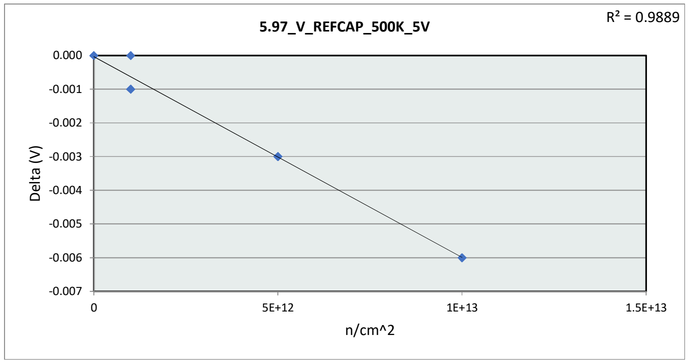


	5.96_V_REFCAP_500K_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.226	1.223	1.220
UL	1.237	1.237	1.237	1.237

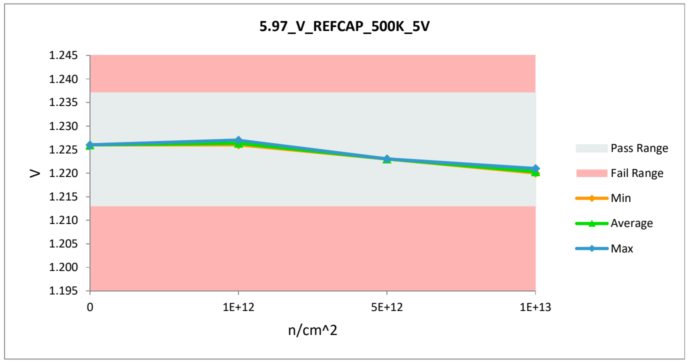


NDD Characterization Report
TPS7H5006-SEP

		5.97_V_REFCAP_500K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.002

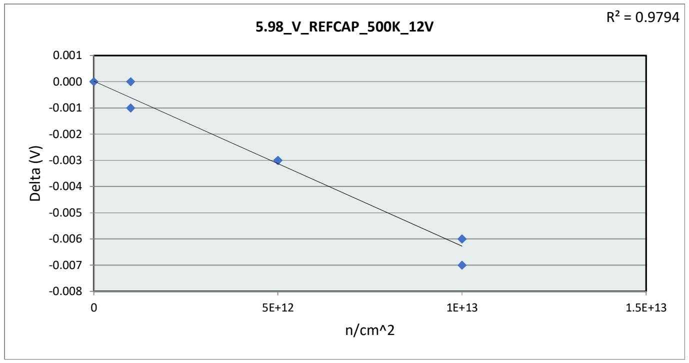


	5.97_V_REFCAP_500K_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237 V			
Min Limit	1.213 V			
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.221
UL	1.237	1.237	1.237	1.237

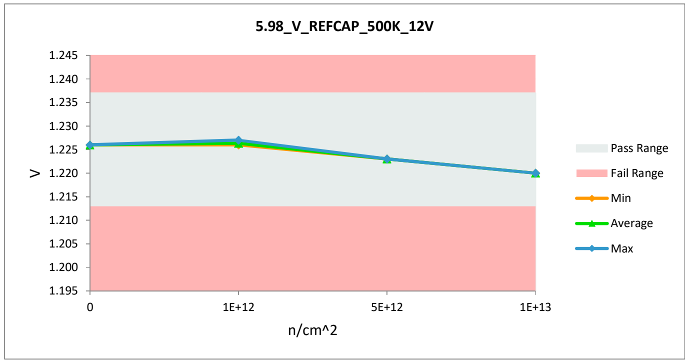


NDD Characterization Report
TPS7H5006-SEP

		5.98_V_REFCAP_500K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

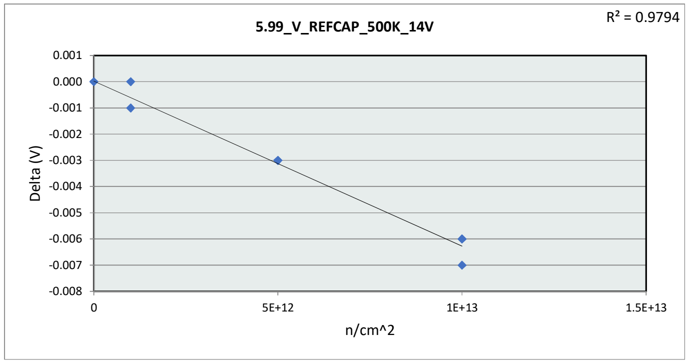


	5.98_V_REFCAP_500K_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

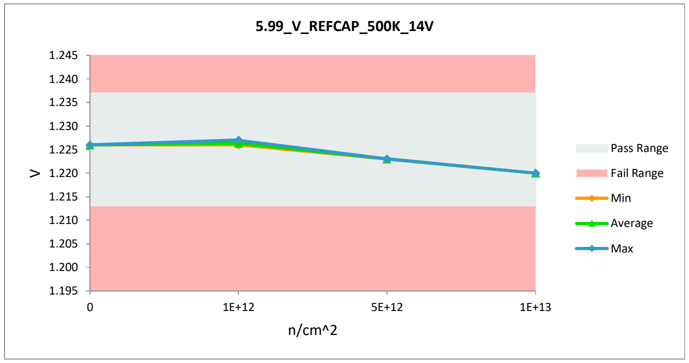


NDD Characterization Report
TPS7H5006-SEP

		5.99_V_REFCAP_500K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.220	-0.007
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.007
	Std Dev	0.001	0.003	0.003

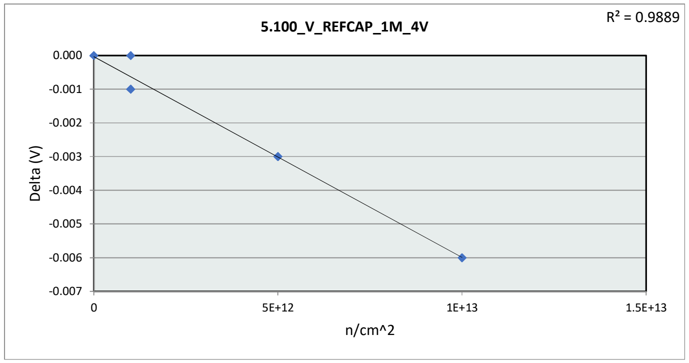


	5.99_V_REFCAP_500K_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.220
UL	1.237	1.237	1.237	1.237

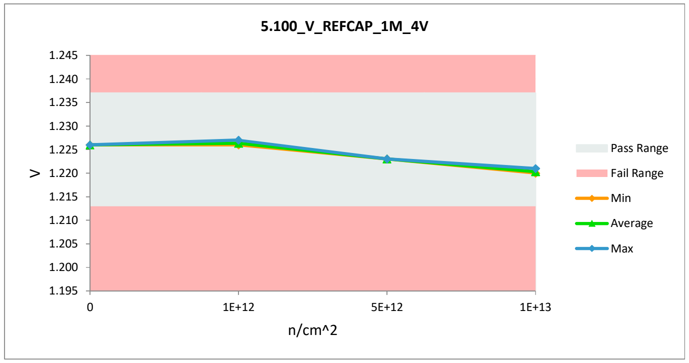


NDD Characterization Report
TPS7H5006-SEP

		5.100_V_REFCAP_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.226	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.223	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.002

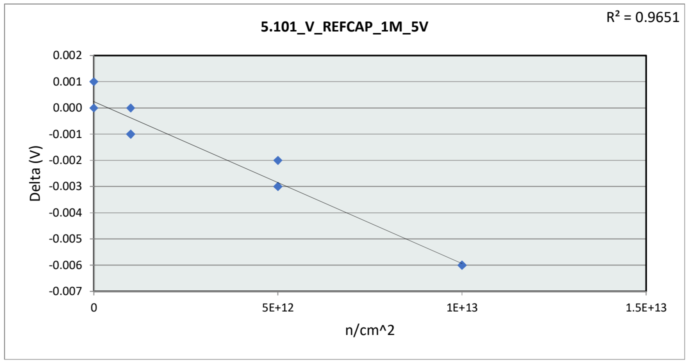


	5.100_V_REFCAP_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.226	1.226	1.223	1.220
Max	1.226	1.227	1.223	1.221
UL	1.237	1.237	1.237	1.237

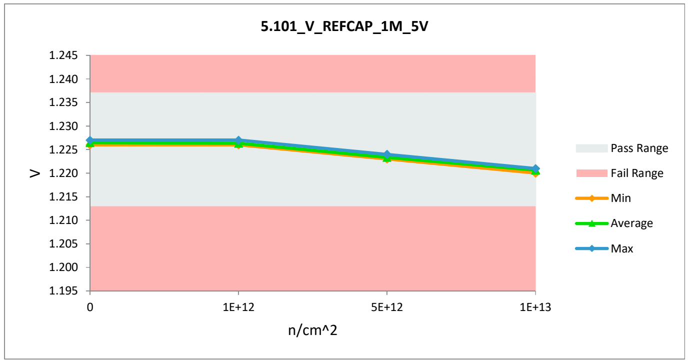


NDD Characterization Report
TPS7H5006-SEP

		5.101_V_REFCAP_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.224	-0.002
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

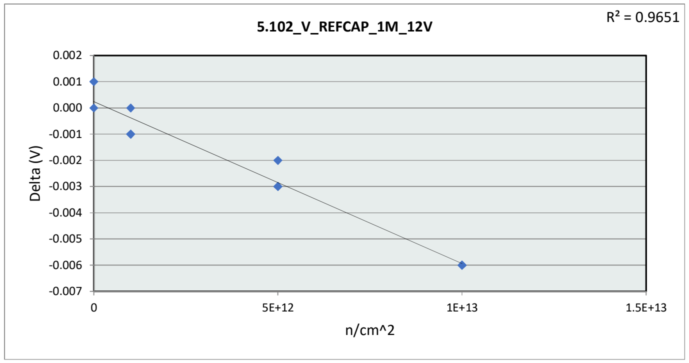


	5.101_V_REFCAP_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

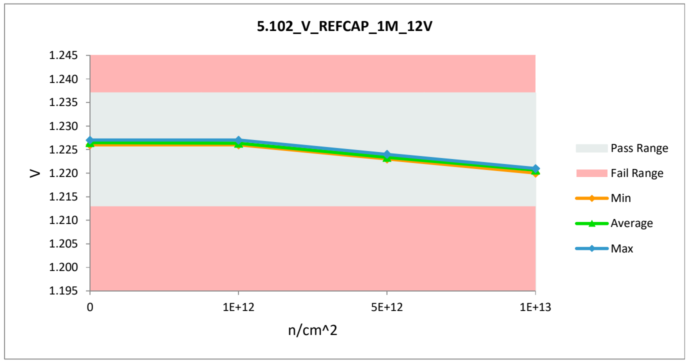


NDD Characterization Report
TPS7H5006-SEP

		5.102_V_REFCAP_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.224	-0.002
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

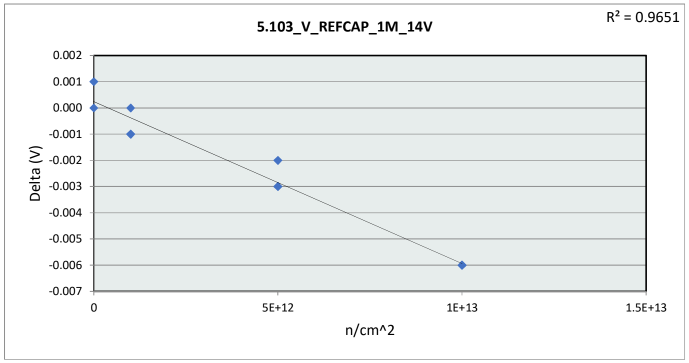


	5.102_V_REFCAP_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

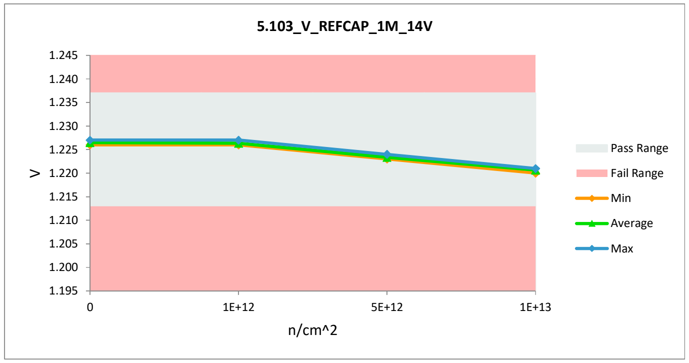


NDD Characterization Report
TPS7H5006-SEP

		5.103_V_REFCAP_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.224	-0.002
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

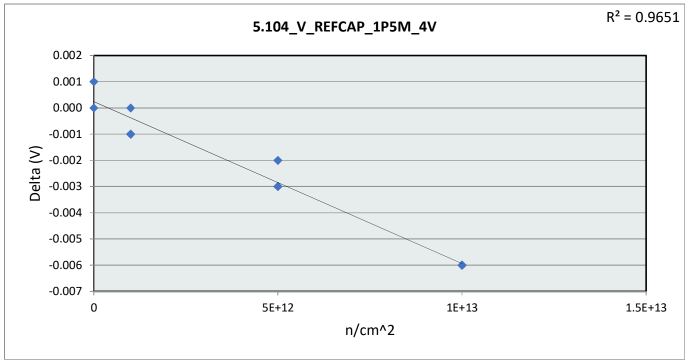


	5.103_V_REFCAP_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.226	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

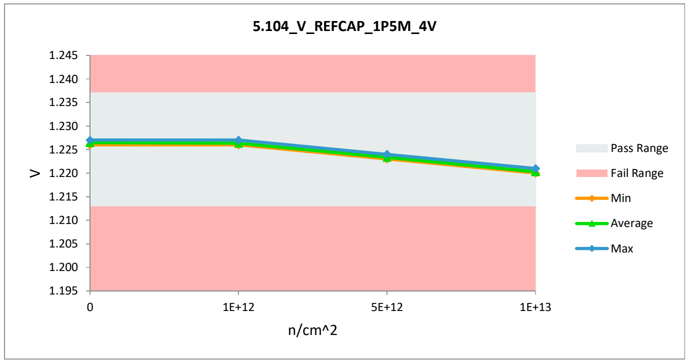


NDD Characterization Report
TPS7H5006-SEP

		5.104_V_REFCAP_1P5M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.226	-0.001
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.224	-0.002
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.226	1.220	-0.006
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

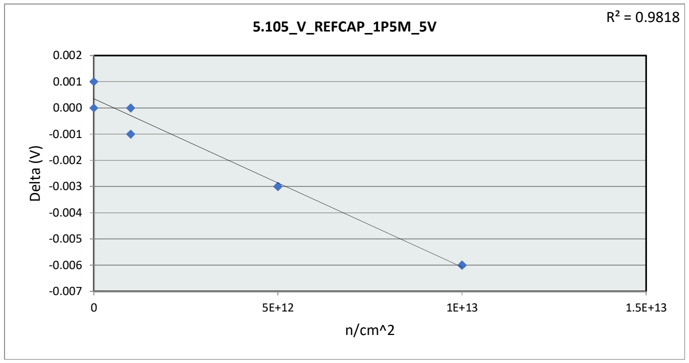


	5.104_V_REFCAP_1P5M_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.226	1.223	1.220
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

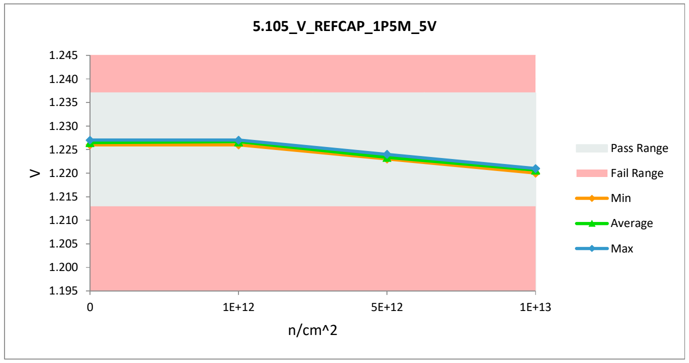


NDD Characterization Report
TPS7H5006-SEP

		5.105_V_REFCAP_1P5M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
	Max	1.227	1.227	0.001
	Average	1.227	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

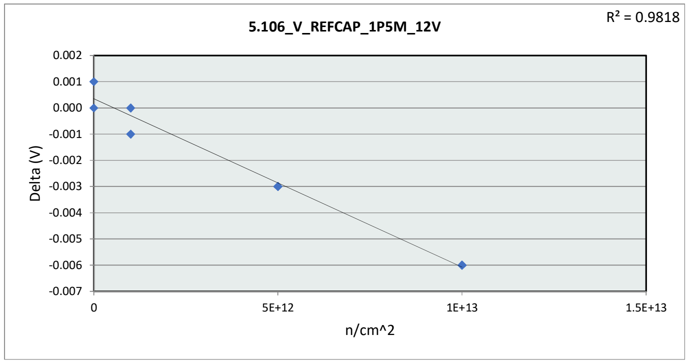


	5.105_V_REFCAP_1P5M_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

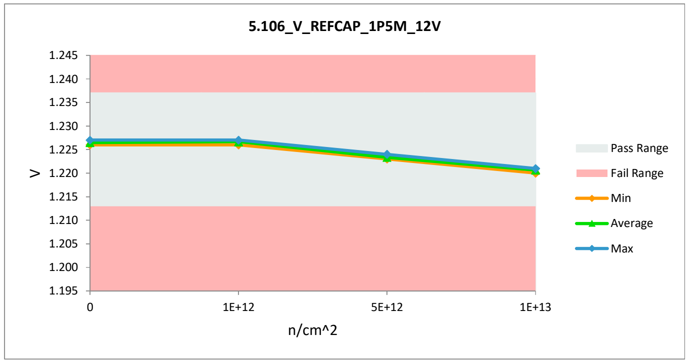


NDD Characterization Report
TPS7H5006-SEP

		5.106_V_REFCAP_1P5M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
	Max	1.227	1.227	0.001
	Average	1.227	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

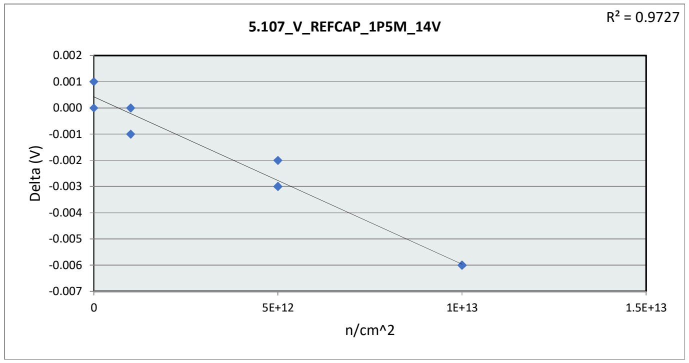


	5.106_V_REFCAP_1P5M_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

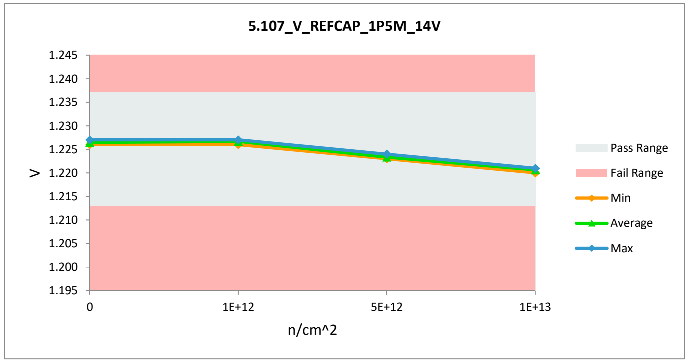


NDD Characterization Report
TPS7H5006-SEP

		5.107_V_REFCAP_1P5M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.226	1.224	-0.002
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
	Max	1.227	1.227	0.001
	Average	1.226	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

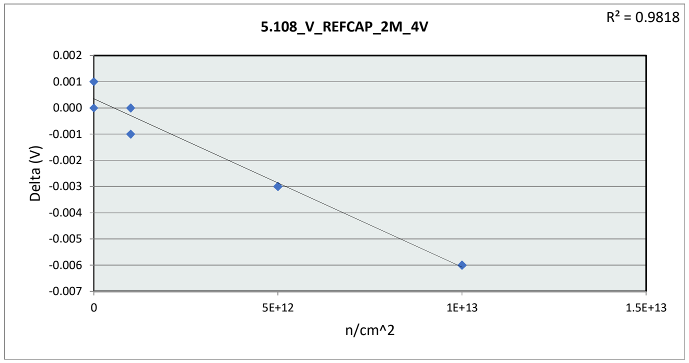


	5.107_V_REFCAP_1P5M_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

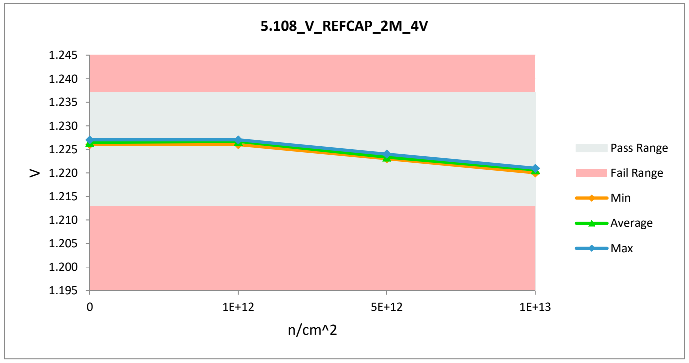


NDD Characterization Report
TPS7H5006-SEP

		5.108_V_REFCAP_2M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.226	0.000
0	49	1.226	1.227	0.001
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.226	-0.001
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
	Max	1.227	1.227	0.001
	Average	1.227	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

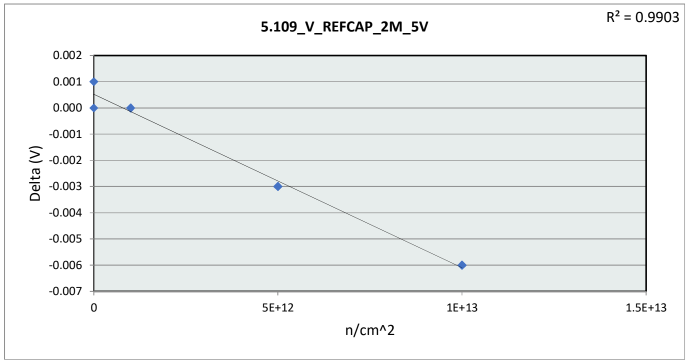


	5.108_V_REFCAP_2M_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

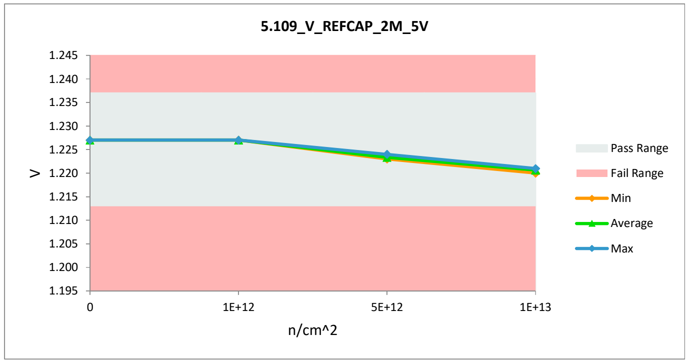


NDD Characterization Report
TPS7H5006-SEP

		5.109_V_REFCAP_2M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.227	0.001
0	49	1.227	1.227	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.227	0.000
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
	Max	1.227	1.227	0.001
	Average	1.227	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

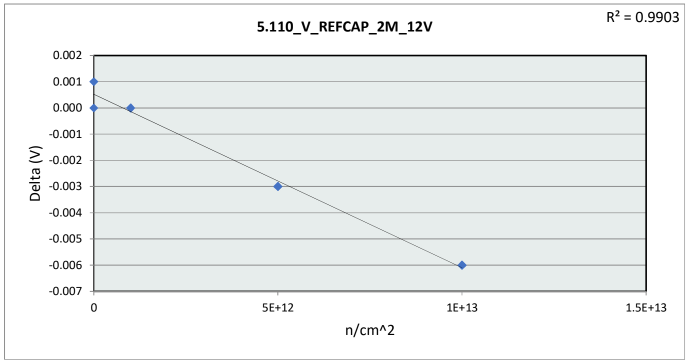


	5.109_V_REFCAP_2M_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.227	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

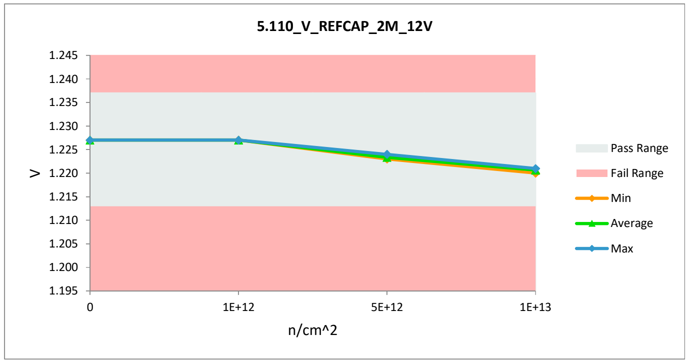


NDD Characterization Report
TPS7H5006-SEP

		5.110_V_REFCAP_2M_12V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.227	0.001
0	49	1.227	1.227	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.227	0.000
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
	Max	1.227	1.227	0.001
	Average	1.227	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

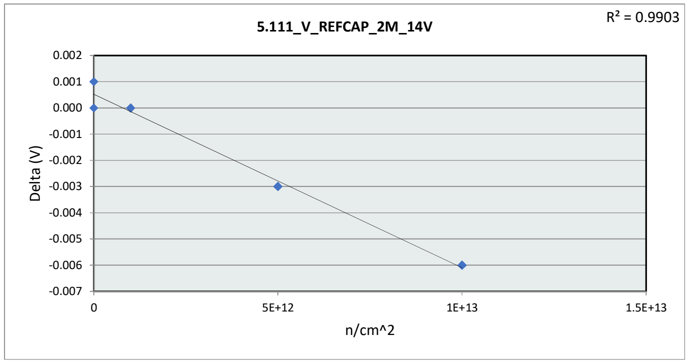


	5.110_V_REFCAP_2M_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.227	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

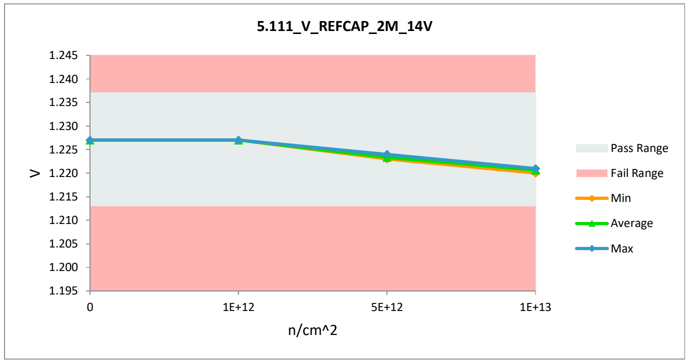


NDD Characterization Report
TPS7H5006-SEP

		5.111_V_REFCAP_2M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.226	1.227	0.001
0	49	1.227	1.227	0.000
1E+12	11	1.227	1.227	0.000
1E+12	12	1.227	1.227	0.000
1E+12	13	1.227	1.227	0.000
5E+12	14	1.226	1.223	-0.003
5E+12	15	1.227	1.224	-0.003
5E+12	16	1.226	1.223	-0.003
1E+13	17	1.226	1.220	-0.006
1E+13	18	1.227	1.221	-0.006
1E+13	19	1.227	1.221	-0.006
	Max	1.227	1.227	0.001
	Average	1.227	1.224	-0.002
	Min	1.226	1.220	-0.006
	Std Dev	0.001	0.003	0.003

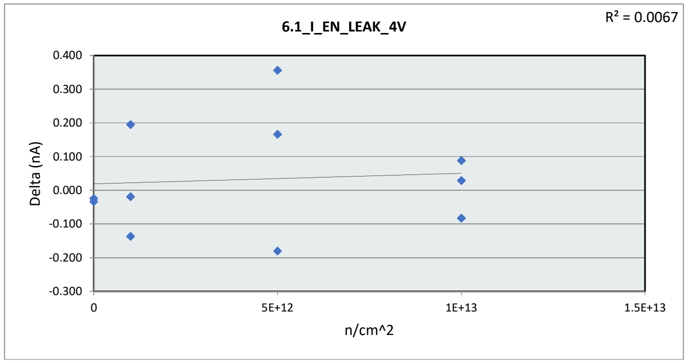


	5.111_V_REFCAP_2M_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.227	1.223	1.220
Average	1.227	1.227	1.223	1.221
Max	1.227	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

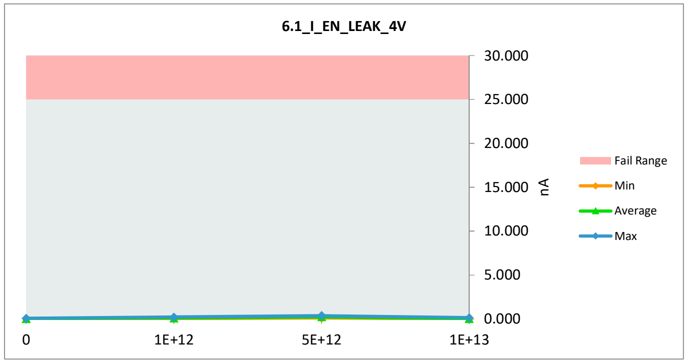


NDD Characterization Report
TPS7H5006-SEP

		6.1_I_EN_LEAK_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	nA	nA	
	Max Limit	5	25	
	Min Limit	-0.1		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.095	0.071	-0.024
0	49	0.056	0.022	-0.034
1E+12	11	0.012	0.207	0.195
1E+12	12	0.051	0.032	-0.019
1E+12	13	0.203	0.066	-0.137
5E+12	14	0.290	0.110	-0.180
5E+12	15	0.027	0.383	0.356
5E+12	16	0.051	0.217	0.166
1E+13	17	0.085	0.002	-0.083
1E+13	18	0.012	0.041	0.029
1E+13	19	0.041	0.129	0.088
	Max	0.290	0.383	0.356
	Average	0.084	0.116	0.032
	Min	0.012	0.002	-0.180
	Std Dev	0.087	0.114	0.158

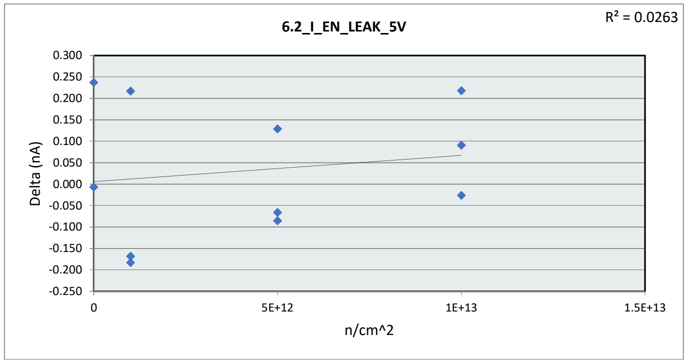


	6.1_I_EN_LEAK_4V			
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit		nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.022	0.032	0.110	0.002
Average	0.047	0.102	0.237	0.057
Max	0.071	0.207	0.383	0.129
UL	25.000	25.000	25.000	25.000

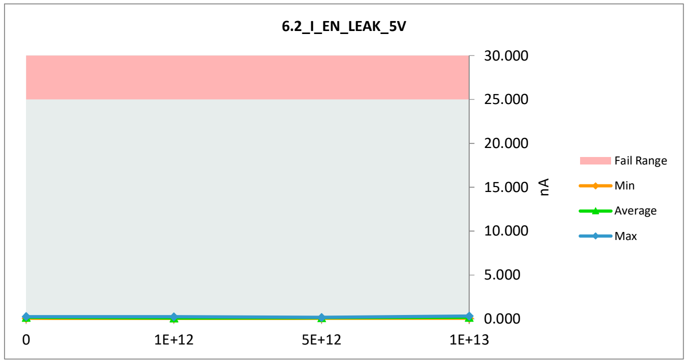


NDD Characterization Report
TPS7H5006-SEP

		6.2_I_EN_LEAK_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	nA	nA	
	Max Limit	5	25	
	Min Limit	-0.1		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.029	0.266	0.237
0	49	0.088	0.081	-0.007
1E+12	11	0.029	0.246	0.217
1E+12	12	0.185	0.017	-0.168
1E+12	13	0.244	0.061	-0.183
5E+12	14	0.195	0.129	-0.066
5E+12	15	0.166	0.081	-0.085
5E+12	16	0.039	0.168	0.129
1E+13	17	0.107	0.081	-0.026
1E+13	18	0.107	0.325	0.218
1E+13	19	0.068	0.159	0.091
	Max	0.244	0.325	0.237
	Average	0.114	0.147	0.032
	Min	0.029	0.017	-0.183
	Std Dev	0.074	0.097	0.154

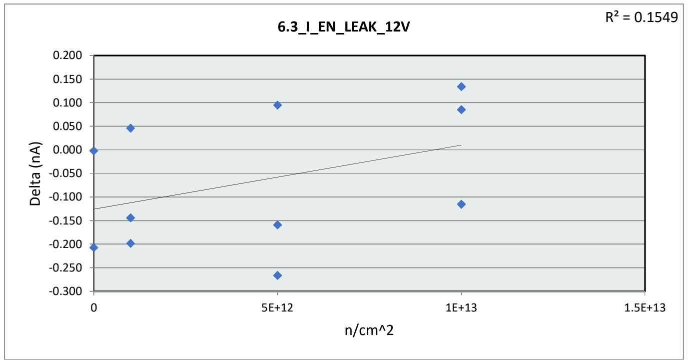


	6.2_I_EN_LEAK_5V			
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit		nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.081	0.017	0.081	0.081
Average	0.174	0.108	0.126	0.188
Max	0.266	0.246	0.168	0.325
UL	25.000	25.000	25.000	25.000

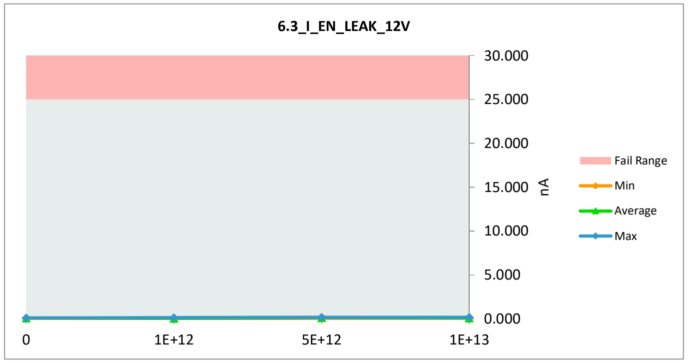


NDD Characterization Report
TPS7H5006-SEP

		6.3_I_EN_LEAK_12V		
Test Site				
Tester				
Test Number				
Unit		nA	nA	
Max Limit		5	25	
Min Limit		-0.1		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.273	0.066	-0.207
0	49	0.107	0.105	-0.002
1E+12	11	0.088	0.134	0.046
1E+12	12	0.283	0.085	-0.198
1E+12	13	0.156	0.012	-0.144
5E+12	14	0.342	0.183	-0.159
5E+12	15	0.078	0.173	0.095
5E+12	16	0.342	0.076	-0.266
1E+13	17	0.176	0.061	-0.115
1E+13	18	0.000	0.085	0.085
1E+13	19	0.049	0.183	0.134
	Max	0.342	0.183	0.134
	Average	0.172	0.106	-0.066
	Min	0.000	0.012	-0.266
	Std Dev	0.121	0.056	0.141

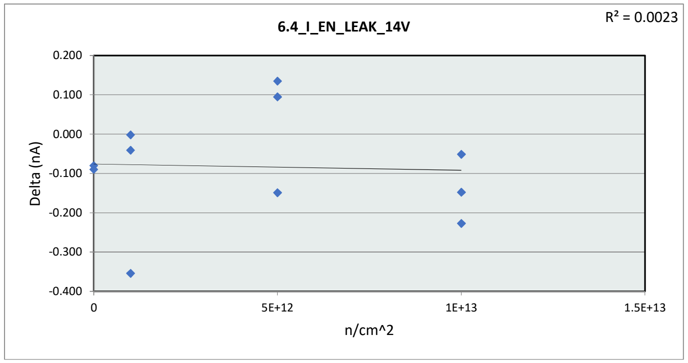


	6.3_I_EN_LEAK_12V			
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit		nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.066	0.012	0.076	0.061
Average	0.086	0.077	0.144	0.110
Max	0.105	0.134	0.183	0.183
UL	25.000	25.000	25.000	25.000

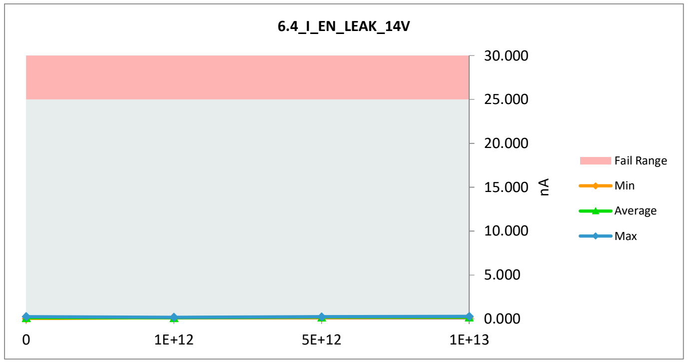


NDD Characterization Report
TPS7H5006-SEP

		6.4_I_EN_LEAK_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	nA	nA	
	Max Limit	5	25	
	Min Limit	-0.1		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.127	0.037	-0.090
0	49	0.351	0.271	-0.080
1E+12	11	0.488	0.134	-0.354
1E+12	12	0.156	0.154	-0.002
1E+12	13	0.234	0.193	-0.041
5E+12	14	0.107	0.242	0.135
5E+12	15	0.283	0.134	-0.149
5E+12	16	0.137	0.232	0.095
1E+13	17	0.429	0.281	-0.148
1E+13	18	0.410	0.183	-0.227
1E+13	19	0.254	0.203	-0.051
	Max	0.488	0.281	0.135
	Average	0.271	0.188	-0.083
	Min	0.107	0.037	-0.354
	Std Dev	0.134	0.071	0.138

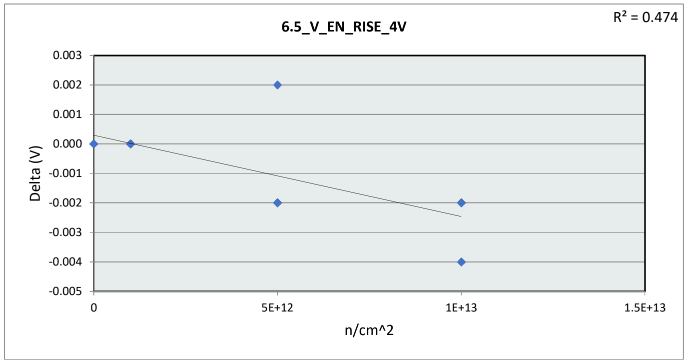


	6.4_I_EN_LEAK_14V			
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit		nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.037	0.134	0.134	0.183
Average	0.154	0.160	0.203	0.222
Max	0.271	0.193	0.242	0.281
UL	25.000	25.000	25.000	25.000

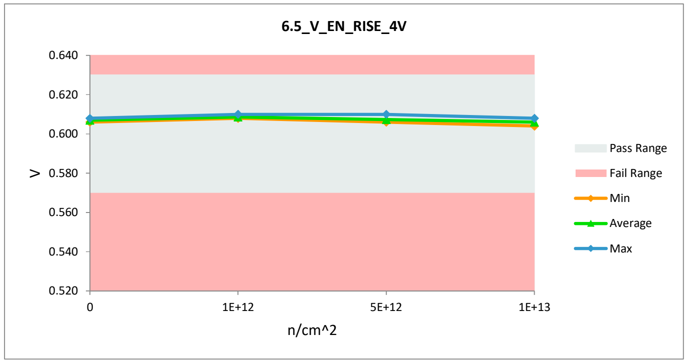


NDD Characterization Report
TPS7H5006-SEP

		6.5_V_EN_RISE_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.606	0.606	0.000
0	49	0.608	0.608	0.000
1E+12	11	0.608	0.608	0.000
1E+12	12	0.610	0.610	0.000
1E+12	13	0.608	0.608	0.000
5E+12	14	0.608	0.606	-0.002
5E+12	15	0.608	0.610	0.002
5E+12	16	0.608	0.606	-0.002
1E+13	17	0.608	0.604	-0.004
1E+13	18	0.608	0.606	-0.002
1E+13	19	0.610	0.608	-0.002
	Max	0.610	0.610	0.002
	Average	0.608	0.607	-0.001
	Min	0.606	0.604	-0.004
	Std Dev	0.001	0.002	0.002

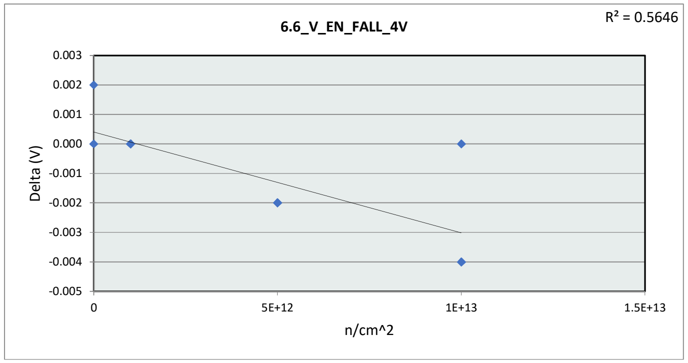


	6.5_V_EN_RISE_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.606	0.608	0.606	0.604
Average	0.607	0.609	0.607	0.606
Max	0.608	0.610	0.610	0.608
UL	0.630	0.630	0.630	0.630

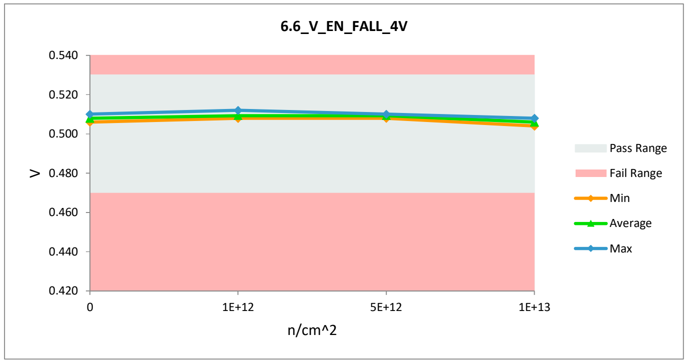


NDD Characterization Report
TPS7H5006-SEP

		6.6_V_EN_FALL_4V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.53	0.53	
Min Limit		0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.506	0.506	0.000
0	49	0.508	0.510	0.002
1E+12	11	0.508	0.508	0.000
1E+12	12	0.512	0.512	0.000
1E+12	13	0.508	0.508	0.000
5E+12	14	0.510	0.508	-0.002
5E+12	15	0.512	0.510	-0.002
5E+12	16	0.512	0.510	-0.002
1E+13	17	0.508	0.504	-0.004
1E+13	18	0.510	0.506	-0.004
1E+13	19	0.508	0.508	0.000
	Max	0.512	0.512	0.002
	Average	0.509	0.508	-0.001
	Min	0.506	0.504	-0.004
	Std Dev	0.002	0.002	0.002

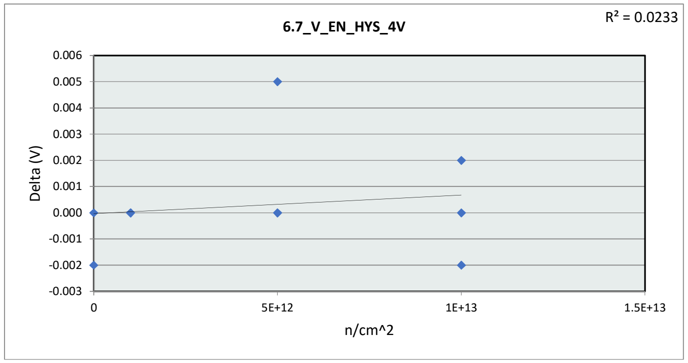


	6.6_V_EN_FALL_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.504
Average	0.508	0.509	0.509	0.506
Max	0.510	0.512	0.510	0.508
UL	0.530	0.530	0.530	0.530

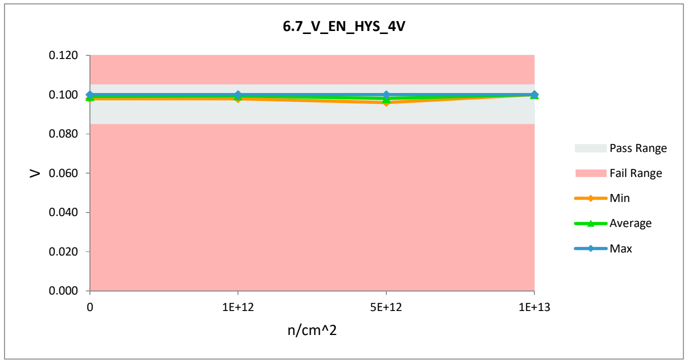


NDD Characterization Report
TPS7H5006-SEP

		6.7_V_EN_HYS_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.100	0.100	0.000
0	49	0.100	0.098	-0.002
1E+12	11	0.100	0.100	0.000
1E+12	12	0.098	0.098	0.000
1E+12	13	0.100	0.100	0.000
5E+12	14	0.098	0.098	0.000
5E+12	15	0.095	0.100	0.005
5E+12	16	0.096	0.096	0.000
1E+13	17	0.100	0.100	0.000
1E+13	18	0.098	0.100	0.002
1E+13	19	0.102	0.100	-0.002
	Max	0.102	0.100	0.005
	Average	0.099	0.099	0.000
	Min	0.095	0.096	-0.002
	Std Dev	0.002	0.001	0.002

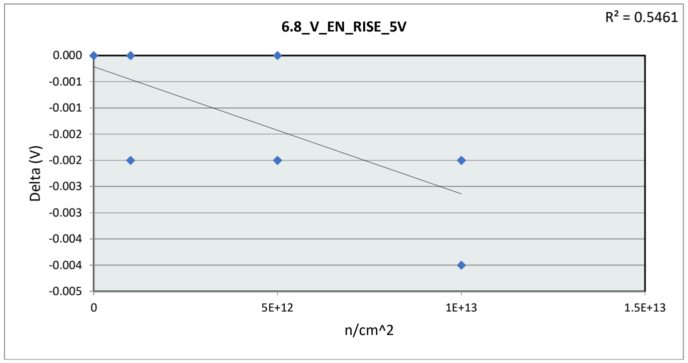


6.7_V_EN_HYS_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.098	0.098	0.096	0.100
Average	0.099	0.099	0.098	0.100
Max	0.100	0.100	0.100	0.100
UL	0.105	0.105	0.105	0.105

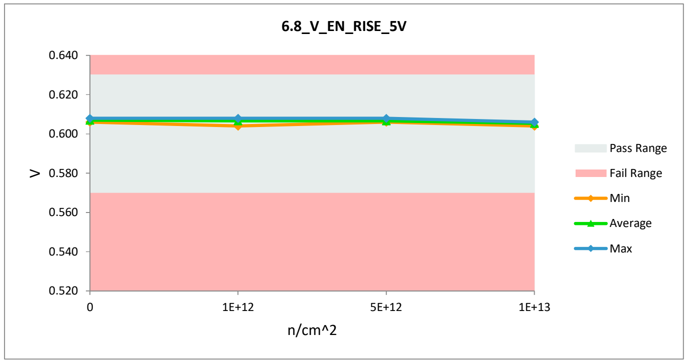


NDD Characterization Report
TPS7H5006-SEP

		6.8_V_EN_RISE_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.606	0.606	0.000
0	49	0.608	0.608	0.000
1E+12	11	0.604	0.604	0.000
1E+12	12	0.608	0.608	0.000
1E+12	13	0.610	0.608	-0.002
5E+12	14	0.608	0.606	-0.002
5E+12	15	0.608	0.606	-0.002
5E+12	16	0.608	0.608	0.000
1E+13	17	0.608	0.606	-0.002
1E+13	18	0.610	0.606	-0.004
1E+13	19	0.606	0.604	-0.002
	Max	0.610	0.608	0.000
	Average	0.608	0.606	-0.001
	Min	0.604	0.604	-0.004
	Std Dev	0.002	0.002	0.001

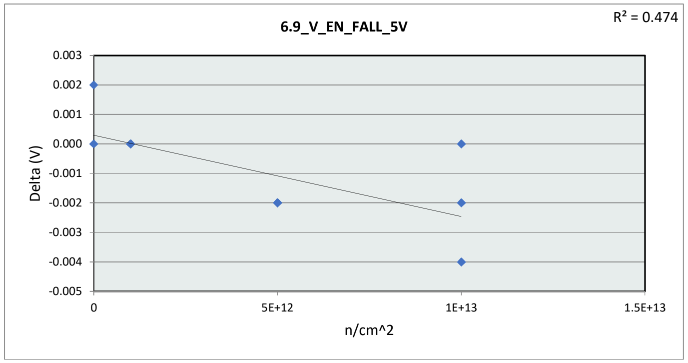


	6.8_V_EN_RISE_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.606	0.604	0.606	0.604
Average	0.607	0.607	0.607	0.605
Max	0.608	0.608	0.608	0.606
UL	0.630	0.630	0.630	0.630

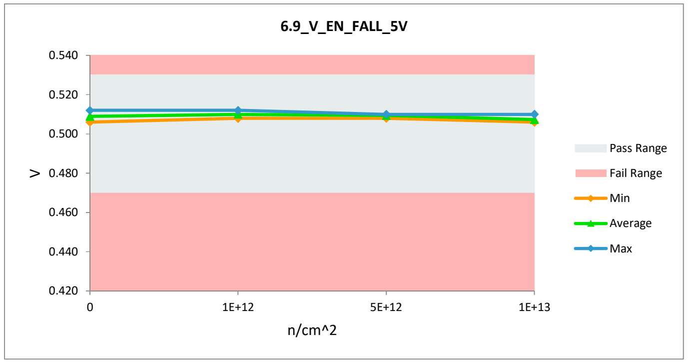


NDD Characterization Report
TPS7H5006-SEP

		6.9_V_EN_FALL_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.506	0.506	0.000
0	49	0.510	0.512	0.002
1E+12	11	0.508	0.508	0.000
1E+12	12	0.512	0.512	0.000
1E+12	13	0.510	0.510	0.000
5E+12	14	0.510	0.508	-0.002
5E+12	15	0.512	0.510	-0.002
5E+12	16	0.512	0.510	-0.002
1E+13	17	0.508	0.506	-0.002
1E+13	18	0.510	0.506	-0.004
1E+13	19	0.510	0.510	0.000
	Max	0.512	0.512	0.002
	Average	0.510	0.509	-0.001
	Min	0.506	0.506	-0.004
	Std Dev	0.002	0.002	0.002

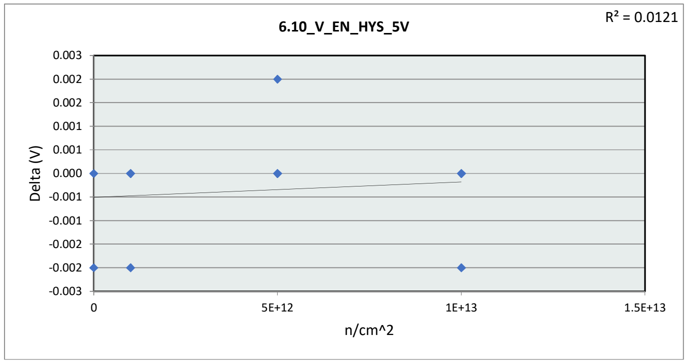


	6.9_V_EN_FALL_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.53 V			
Min Limit	0.47 V			
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.506
Average	0.509	0.510	0.509	0.507
Max	0.512	0.512	0.510	0.510
UL	0.530	0.530	0.530	0.530

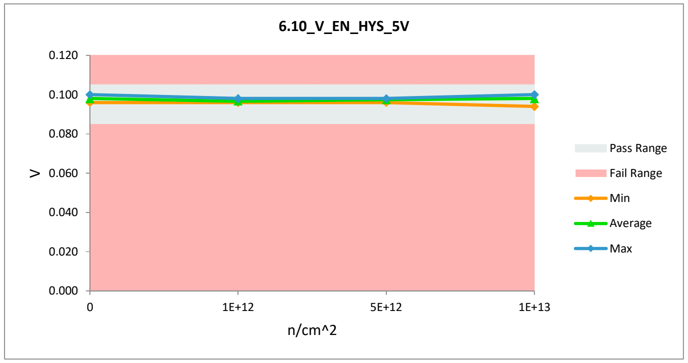


NDD Characterization Report
TPS7H5006-SEP

		6.10_V_EN_HYS_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.100	0.100	0.000
0	49	0.098	0.096	-0.002
1E+12	11	0.096	0.096	0.000
1E+12	12	0.096	0.096	0.000
1E+12	13	0.100	0.098	-0.002
5E+12	14	0.098	0.098	0.000
5E+12	15	0.096	0.096	0.000
5E+12	16	0.096	0.098	0.002
1E+13	17	0.100	0.100	0.000
1E+13	18	0.100	0.100	0.000
1E+13	19	0.096	0.094	-0.002
	Max	0.100	0.100	0.002
	Average	0.098	0.097	0.000
	Min	0.096	0.094	-0.002
	Std Dev	0.002	0.002	0.001

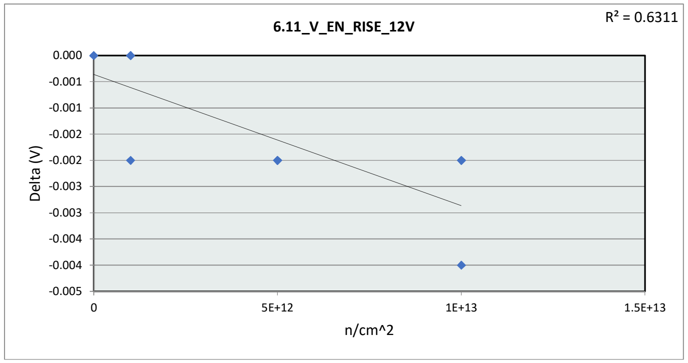


	6.10_V_EN_HYS_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.096	0.096	0.096	0.094
Average	0.098	0.097	0.097	0.098
Max	0.100	0.098	0.098	0.100
UL	0.105	0.105	0.105	0.105

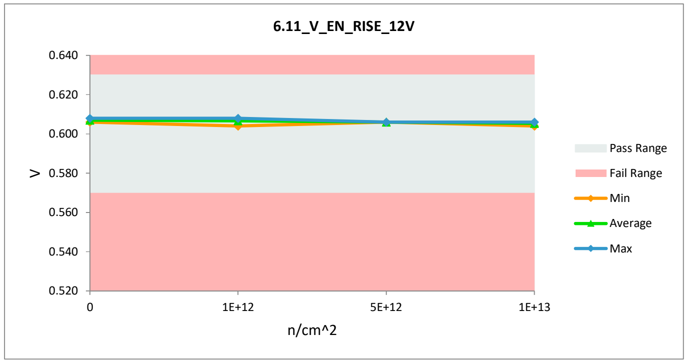


NDD Characterization Report
TPS7H5006-SEP

		6.11_V_EN_RISE_12V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.63	0.63	
Min Limit		0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.606	0.606	0.000
0	49	0.608	0.608	0.000
1E+12	11	0.604	0.604	0.000
1E+12	12	0.608	0.608	0.000
1E+12	13	0.610	0.608	-0.002
5E+12	14	0.608	0.606	-0.002
5E+12	15	0.608	0.606	-0.002
5E+12	16	0.608	0.606	-0.002
1E+13	17	0.608	0.606	-0.002
1E+13	18	0.610	0.606	-0.004
1E+13	19	0.606	0.604	-0.002
	Max	0.610	0.608	0.000
	Average	0.608	0.606	-0.001
	Min	0.604	0.604	-0.004
	Std Dev	0.002	0.001	0.001

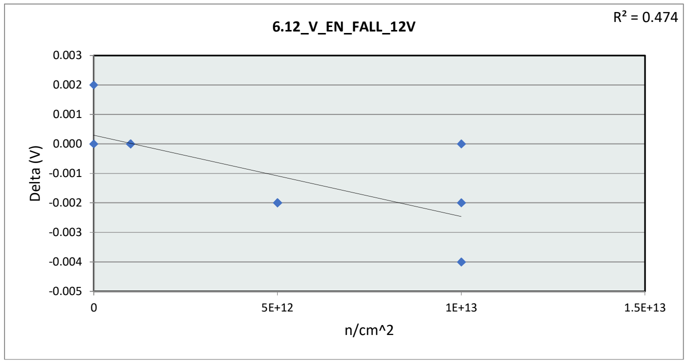


	6.11_V_EN_RISE_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.63 V			
Min Limit	0.57 V			
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.606	0.604	0.606	0.604
Average	0.607	0.607	0.606	0.605
Max	0.608	0.608	0.606	0.606
UL	0.630	0.630	0.630	0.630

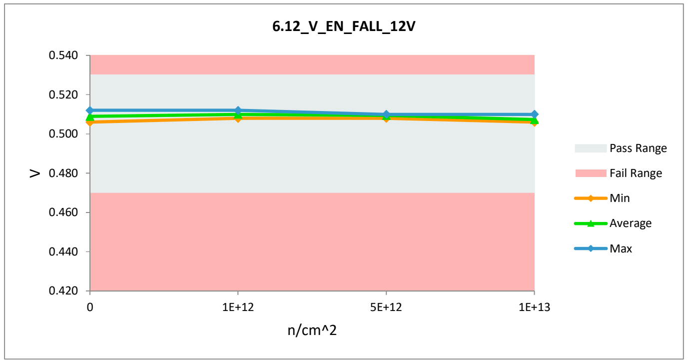


NDD Characterization Report
TPS7H5006-SEP

		6.12_V_EN_FALL_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.506	0.506	0.000
0	49	0.510	0.512	0.002
1E+12	11	0.508	0.508	0.000
1E+12	12	0.512	0.512	0.000
1E+12	13	0.510	0.510	0.000
5E+12	14	0.510	0.508	-0.002
5E+12	15	0.512	0.510	-0.002
5E+12	16	0.512	0.510	-0.002
1E+13	17	0.508	0.506	-0.002
1E+13	18	0.510	0.506	-0.004
1E+13	19	0.510	0.510	0.000
	Max	0.512	0.512	0.002
	Average	0.510	0.509	-0.001
	Min	0.506	0.506	-0.004
	Std Dev	0.002	0.002	0.002



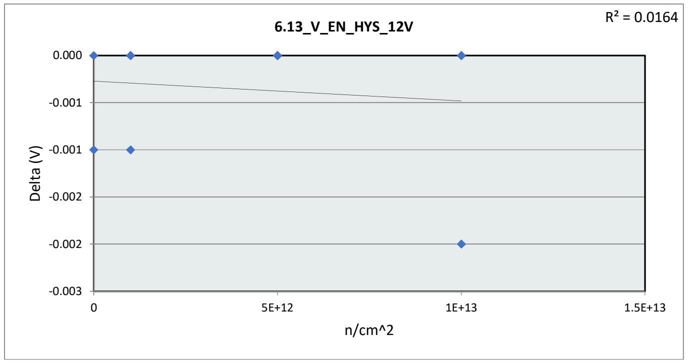
	6.12_V_EN_FALL_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.506
Average	0.509	0.510	0.509	0.507
Max	0.512	0.512	0.510	0.510
UL	0.530	0.530	0.530	0.530



NDD Characterization Report
TPS7H5006-SEP

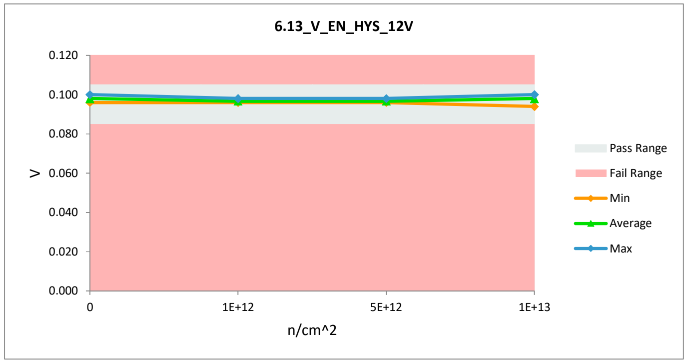
	6.13_V_EN_HYS_12V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.105	0.105
Min Limit	0.085	0.085

n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.100	0.100	0.000
0	49	0.097	0.096	-0.001
1E+12	11	0.096	0.096	0.000
1E+12	12	0.096	0.096	0.000
1E+12	13	0.099	0.098	-0.001
5E+12	14	0.098	0.098	0.000
5E+12	15	0.096	0.096	0.000
5E+12	16	0.096	0.096	0.000
1E+13	17	0.100	0.100	0.000
1E+13	18	0.100	0.100	0.000
1E+13	19	0.096	0.094	-0.002
	Max	0.100	0.100	0.000
	Average	0.098	0.097	0.000
	Min	0.096	0.094	-0.002
	Std Dev	0.002	0.002	0.001



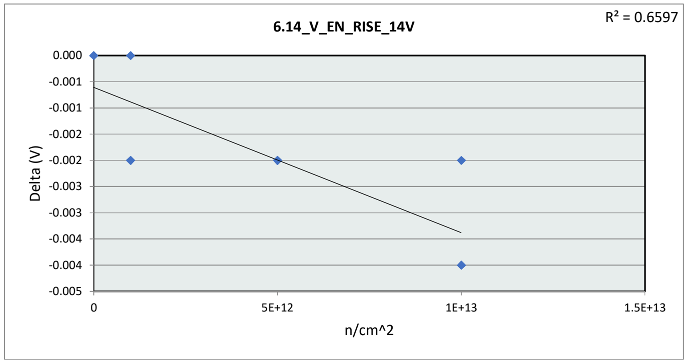
	6.13_V_EN_HYS_12V	
Test Site		
Tester		
Test Number		
Max Limit	0.105	V
Min Limit	0.085	V

n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.096	0.096	0.096	0.094
Average	0.098	0.097	0.097	0.098
Max	0.100	0.098	0.098	0.100
UL	0.105	0.105	0.105	0.105

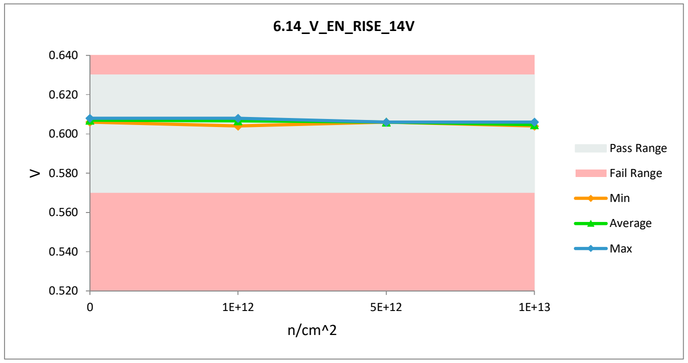


NDD Characterization Report
TPS7H5006-SEP

		6.14_V_EN_RISE_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.606	0.606	0.000
0	49	0.608	0.608	0.000
1E+12	11	0.606	0.604	-0.002
1E+12	12	0.608	0.608	0.000
1E+12	13	0.610	0.608	-0.002
5E+12	14	0.608	0.606	-0.002
5E+12	15	0.608	0.606	-0.002
5E+12	16	0.608	0.606	-0.002
1E+13	17	0.608	0.604	-0.004
1E+13	18	0.610	0.606	-0.004
1E+13	19	0.606	0.604	-0.002
	Max	0.610	0.608	0.000
	Average	0.608	0.606	-0.002
	Min	0.606	0.604	-0.004
	Std Dev	0.001	0.002	0.001

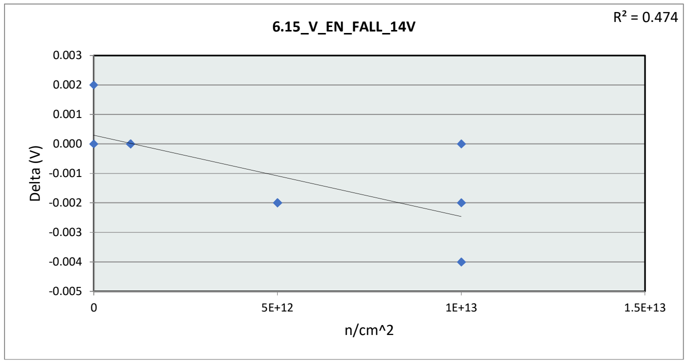


	6.14_V_EN_RISE_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.606	0.604	0.606	0.604
Average	0.607	0.607	0.606	0.605
Max	0.608	0.608	0.606	0.606
UL	0.630	0.630	0.630	0.630

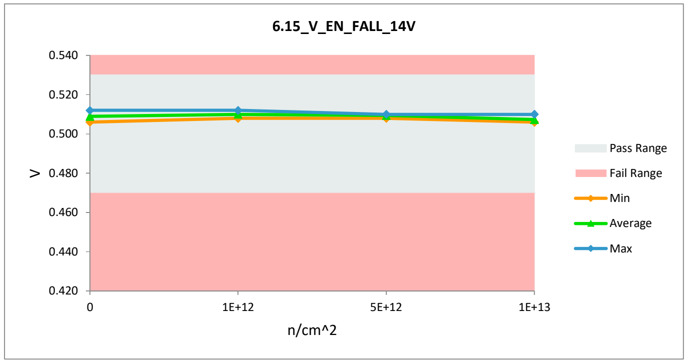


NDD Characterization Report
TPS7H5006-SEP

		6.15_V_EN_FALL_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.506	0.506	0.000
0	49	0.510	0.512	0.002
1E+12	11	0.508	0.508	0.000
1E+12	12	0.512	0.512	0.000
1E+12	13	0.510	0.510	0.000
5E+12	14	0.510	0.508	-0.002
5E+12	15	0.512	0.510	-0.002
5E+12	16	0.512	0.510	-0.002
1E+13	17	0.508	0.506	-0.002
1E+13	18	0.510	0.506	-0.004
1E+13	19	0.510	0.510	0.000
	Max	0.512	0.512	0.002
	Average	0.510	0.509	-0.001
	Min	0.506	0.506	-0.004
	Std Dev	0.002	0.002	0.002

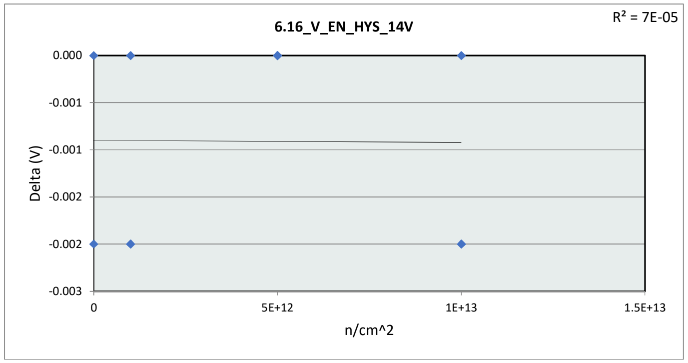


	6.15_V_EN_FALL_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.506
Average	0.509	0.510	0.509	0.507
Max	0.512	0.512	0.510	0.510
UL	0.530	0.530	0.530	0.530

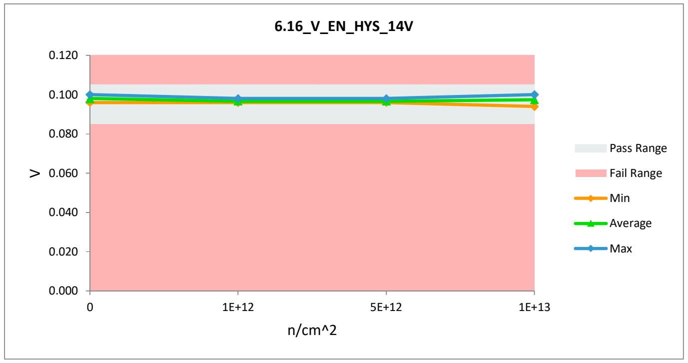


NDD Characterization Report
TPS7H5006-SEP

		6.16_V_EN_HYS_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.100	0.100	0.000
0	49	0.098	0.096	-0.002
1E+12	11	0.098	0.096	-0.002
1E+12	12	0.096	0.096	0.000
1E+12	13	0.100	0.098	-0.002
5E+12	14	0.098	0.098	0.000
5E+12	15	0.096	0.096	0.000
5E+12	16	0.096	0.096	0.000
1E+13	17	0.100	0.098	-0.002
1E+13	18	0.100	0.100	0.000
1E+13	19	0.096	0.094	-0.002
	Max	0.100	0.100	0.000
	Average	0.098	0.097	-0.001
	Min	0.096	0.094	-0.002
	Std Dev	0.002	0.002	0.001

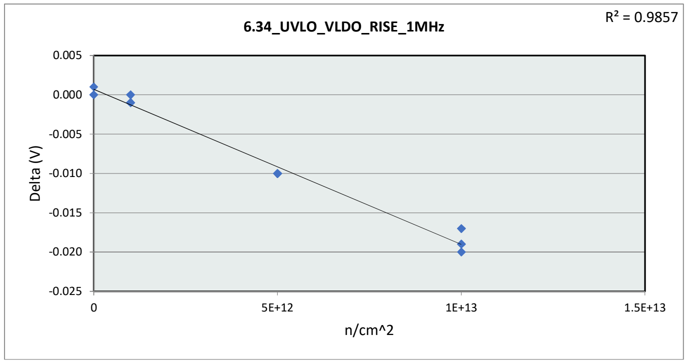


	6.16_V_EN_HYS_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.096	0.096	0.096	0.094
Average	0.098	0.097	0.097	0.097
Max	0.100	0.098	0.098	0.100
UL	0.105	0.105	0.105	0.105

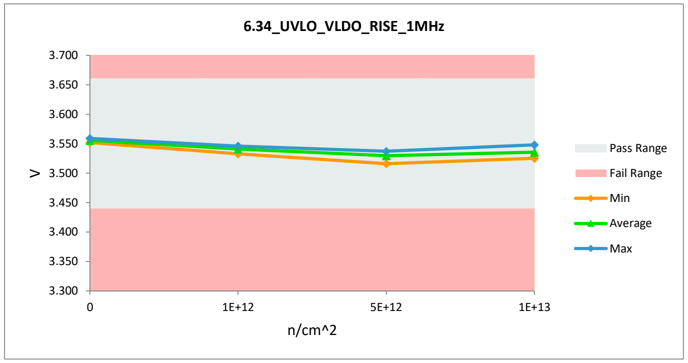


NDD Characterization Report
TPS7H5006-SEP

		6.34_UVLO_VLDO_RISE_1MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.66	3.66	
	Min Limit	3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.558	3.559	0.001
0	49	3.552	3.552	0.000
1E+12	11	3.533	3.533	0.000
1E+12	12	3.544	3.543	-0.001
1E+12	13	3.547	3.546	-0.001
5E+12	14	3.546	3.536	-0.010
5E+12	15	3.547	3.537	-0.010
5E+12	16	3.526	3.516	-0.010
1E+13	17	3.568	3.548	-0.020
1E+13	18	3.544	3.525	-0.019
1E+13	19	3.551	3.534	-0.017
	Max	3.568	3.559	0.001
	Average	3.547	3.539	-0.008
	Min	3.526	3.516	-0.020
	Std Dev	0.011	0.012	0.008

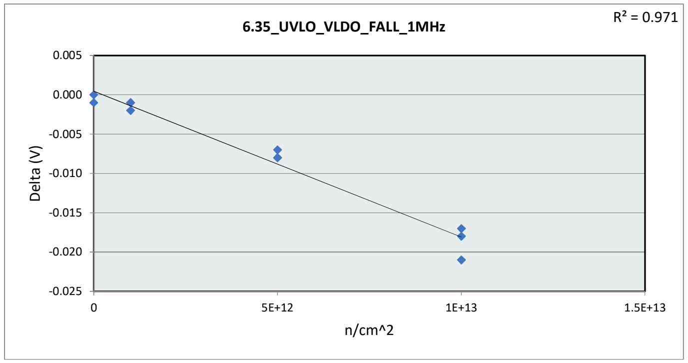


	6.34_UVLO_VLDO_RISE_1MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.552	3.533	3.516	3.525
Average	3.556	3.541	3.530	3.536
Max	3.559	3.546	3.537	3.548
UL	3.660	3.660	3.660	3.660

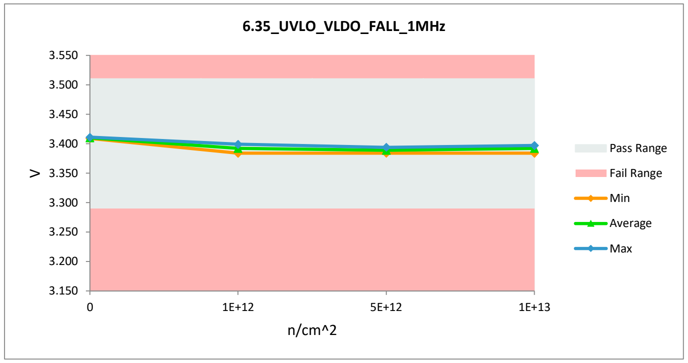


NDD Characterization Report
TPS7H5006-SEP

		6.35_UVLO_VLDO_FALL_1MHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.51	3.51	
Min Limit		3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.410	3.409	-0.001
0	49	3.411	3.411	0.000
1E+12	11	3.385	3.384	-0.001
1E+12	12	3.395	3.393	-0.002
1E+12	13	3.400	3.399	-0.001
5E+12	14	3.395	3.388	-0.007
5E+12	15	3.402	3.394	-0.008
5E+12	16	3.392	3.384	-0.008
1E+13	17	3.418	3.397	-0.021
1E+13	18	3.413	3.395	-0.018
1E+13	19	3.401	3.384	-0.017
	Max	3.418	3.411	0.000
	Average	3.402	3.394	-0.008
	Min	3.385	3.384	-0.021
	Std Dev	0.010	0.009	0.008

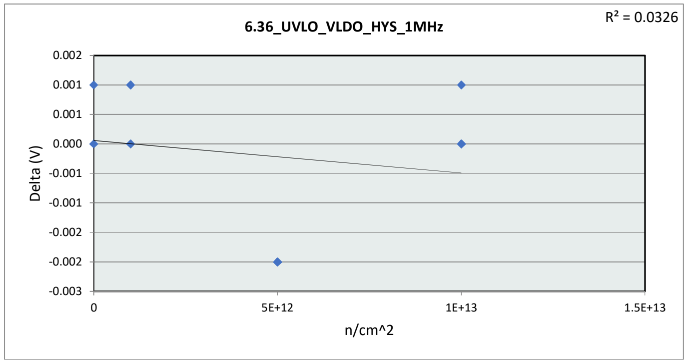


6.35_UVLO_VLDO_FALL_1MHz				
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.409	3.384	3.384	3.384
Average	3.410	3.392	3.389	3.392
Max	3.411	3.399	3.394	3.397
UL	3.510	3.510	3.510	3.510



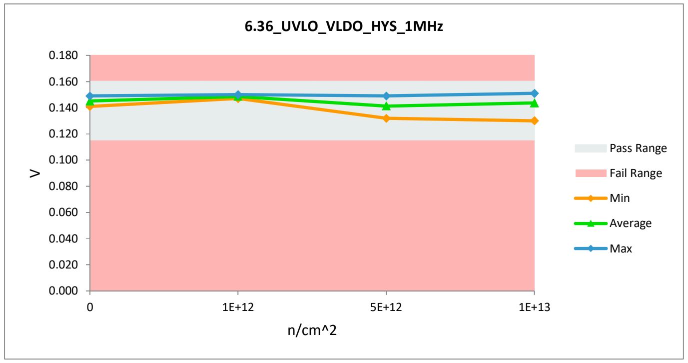
NDD Characterization Report
TPS7H5006-SEP

		6.36_UVLO_VLDO_HYS_1MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.158	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.148	0.149	0.001
0	49	0.141	0.141	0.000
1E+12	11	0.148	0.149	0.001
1E+12	12	0.149	0.150	0.001
1E+12	13	0.147	0.147	0.000
5E+12	14	0.151	0.149	-0.002
5E+12	15	0.145	0.143	-0.002
5E+12	16	0.134	0.132	-0.002
1E+13	17	0.150	0.151	0.001
1E+13	18	0.130	0.130	0.000
1E+13	19	0.150	0.150	0.000
	Max	0.151	0.151	0.001
	Average	0.145	0.145	0.000
	Min	0.130	0.130	-0.002
	Std Dev	0.007	0.007	0.001



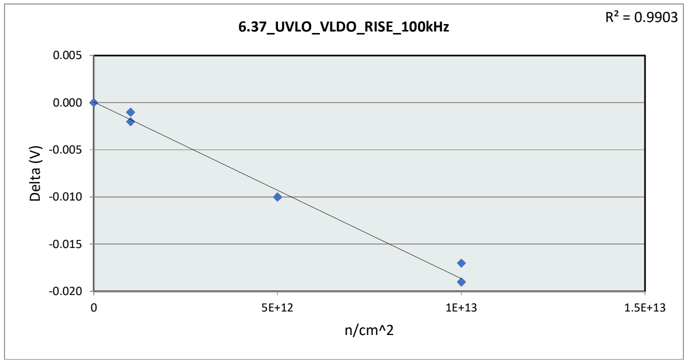
	6.36_UVLO_VLDO_HYS_1MHz	
Test Site		
Tester		
Test Number		
Max Limit	0.16	V
Min Limit	0.115	V

n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.141	0.147	0.132	0.130
Average	0.145	0.149	0.141	0.144
Max	0.149	0.150	0.149	0.151
UL	0.160	0.160	0.160	0.160

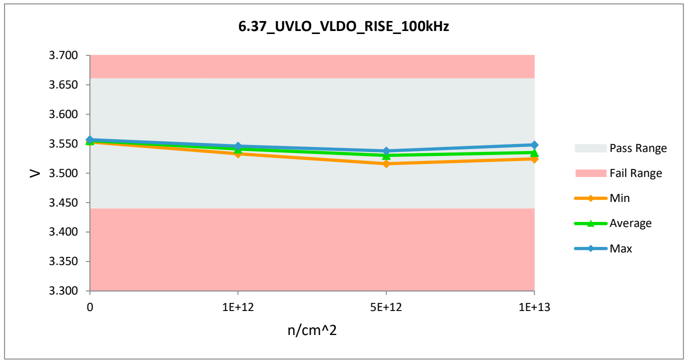


NDD Characterization Report
TPS7H5006-SEP

		6.37_UVLO_VLDO_RISE_100kHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.66	3.66	
Min Limit		3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.557	3.557	0.000
0	49	3.553	3.553	0.000
1E+12	11	3.534	3.533	-0.001
1E+12	12	3.544	3.543	-0.001
1E+12	13	3.548	3.546	-0.002
5E+12	14	3.546	3.536	-0.010
5E+12	15	3.548	3.538	-0.010
5E+12	16	3.526	3.516	-0.010
1E+13	17	3.567	3.548	-0.019
1E+13	18	3.543	3.524	-0.019
1E+13	19	3.551	3.534	-0.017
	Max	3.567	3.557	0.000
	Average	3.547	3.539	-0.008
	Min	3.526	3.516	-0.019
	Std Dev	0.011	0.012	0.008

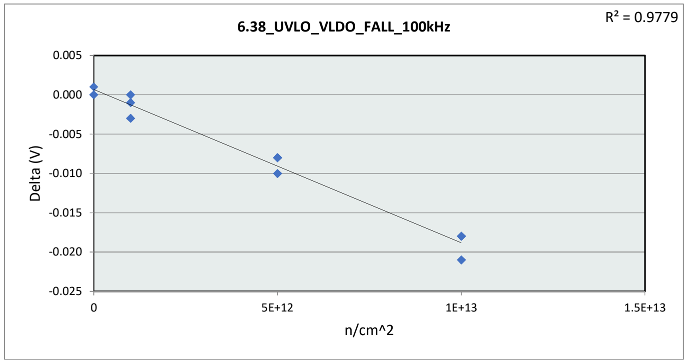


	6.37_UVLO_VLDO_RISE_100k			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.553	3.533	3.516	3.524
Average	3.555	3.541	3.530	3.535
Max	3.557	3.546	3.538	3.548
UL	3.660	3.660	3.660	3.660

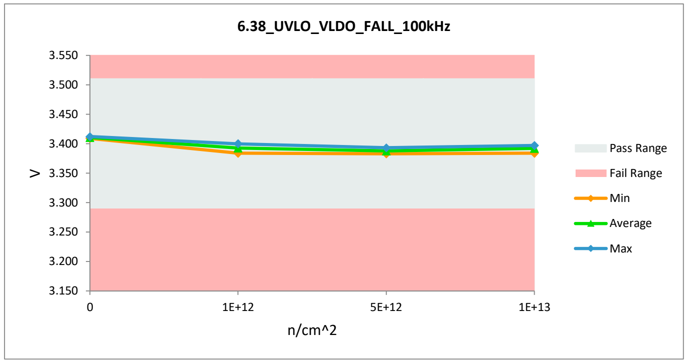


NDD Characterization Report
TPS7H5006-SEP

		6.38_UVLO_VLDO_FALL_100kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.409	3.409	0.000
0	49	3.411	3.412	0.001
1E+12	11	3.387	3.384	-0.003
1E+12	12	3.394	3.394	0.000
1E+12	13	3.401	3.400	-0.001
5E+12	14	3.395	3.387	-0.008
5E+12	15	3.401	3.393	-0.008
5E+12	16	3.393	3.383	-0.010
1E+13	17	3.418	3.397	-0.021
1E+13	18	3.413	3.395	-0.018
1E+13	19	3.402	3.384	-0.018
	Max	3.418	3.412	0.001
	Average	3.402	3.394	-0.008
	Min	3.387	3.383	-0.021
	Std Dev	0.010	0.010	0.008

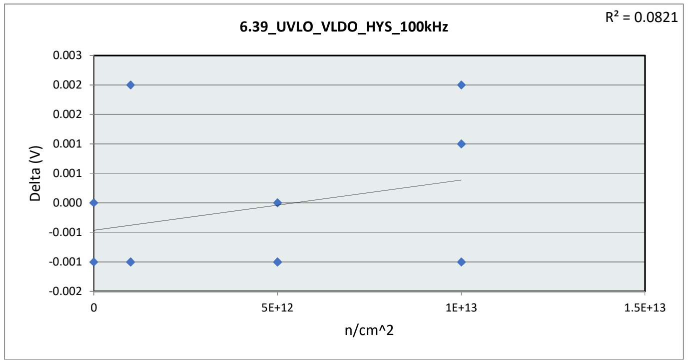


	6.38_UVLO_VLDO_FALL_100k			
Test Site				
Tester				
Test Number				
Max Limit	3.51 V			
Min Limit	3.29 V			
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.409	3.384	3.383	3.384
Average	3.411	3.393	3.388	3.392
Max	3.412	3.400	3.393	3.397
UL	3.510	3.510	3.510	3.510

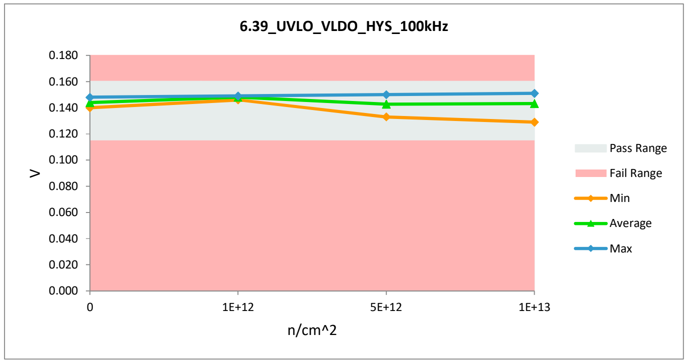


NDD Characterization Report
TPS7H5006-SEP

		6.39_UVLO_VLDO_HYS_100kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.158	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.148	0.148	0.000
0	49	0.141	0.140	-0.001
1E+12	11	0.147	0.149	0.002
1E+12	12	0.150	0.149	-0.001
1E+12	13	0.147	0.146	-0.001
5E+12	14	0.151	0.150	-0.001
5E+12	15	0.146	0.145	-0.001
5E+12	16	0.133	0.133	0.000
1E+13	17	0.149	0.151	0.002
1E+13	18	0.130	0.129	-0.001
1E+13	19	0.149	0.150	0.001
	Max	0.151	0.151	0.002
	Average	0.145	0.145	0.000
	Min	0.130	0.129	-0.001
	Std Dev	0.007	0.007	0.001

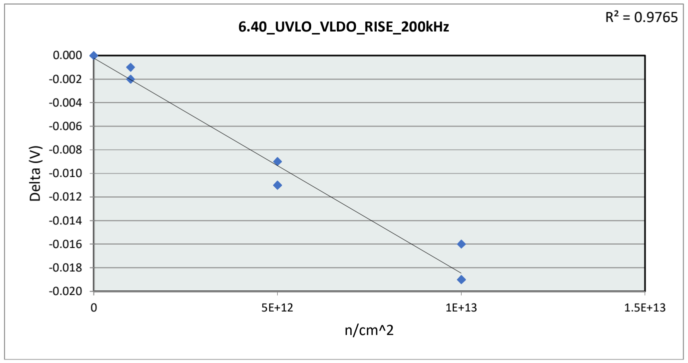


	6.39_UVLO_VLDO_HYS_100kH			
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.140	0.146	0.133	0.129
Average	0.144	0.148	0.143	0.143
Max	0.148	0.149	0.150	0.151
UL	0.160	0.160	0.160	0.160

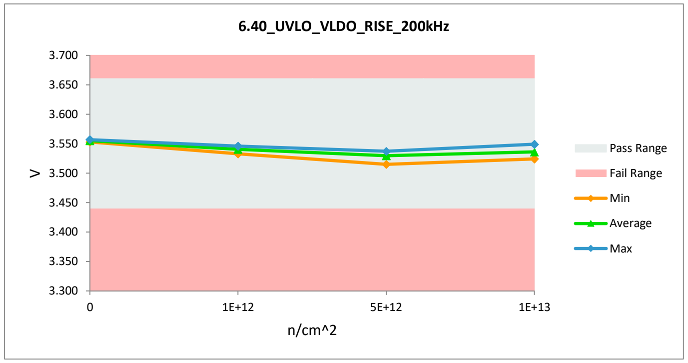


NDD Characterization Report
TPS7H5006-SEP

		6.40_UVLO_VLDO_RISE_200kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.66	3.66	
	Min Limit	3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.557	3.557	0.000
0	49	3.553	3.553	0.000
1E+12	11	3.534	3.533	-0.001
1E+12	12	3.544	3.542	-0.002
1E+12	13	3.548	3.546	-0.002
5E+12	14	3.546	3.537	-0.009
5E+12	15	3.548	3.537	-0.011
5E+12	16	3.526	3.515	-0.011
1E+13	17	3.568	3.549	-0.019
1E+13	18	3.543	3.524	-0.019
1E+13	19	3.551	3.535	-0.016
	Max	3.568	3.557	0.000
	Average	3.547	3.539	-0.008
	Min	3.526	3.515	-0.019
	Std Dev	0.011	0.012	0.008

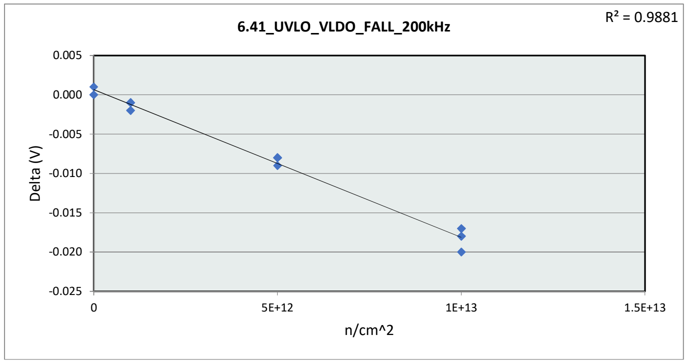


	6.40_UVLO_VLDO_RISE_200k			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.553	3.533	3.515	3.524
Average	3.555	3.540	3.530	3.536
Max	3.557	3.546	3.537	3.549
UL	3.660	3.660	3.660	3.660

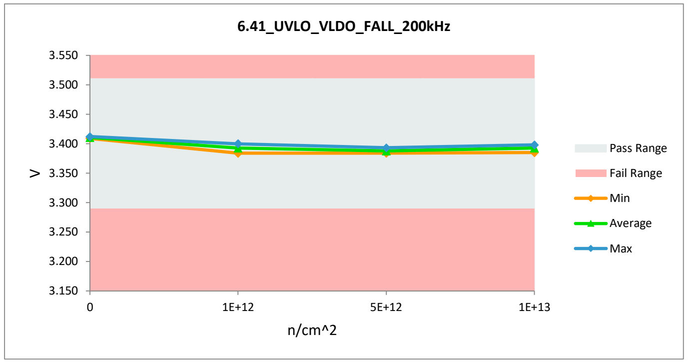


NDD Characterization Report
TPS7H5006-SEP

		6.41_UVLO_VLDO_FALL_200kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.409	3.409	0.000
0	49	3.411	3.412	0.001
1E+12	11	3.385	3.384	-0.001
1E+12	12	3.395	3.393	-0.002
1E+12	13	3.401	3.400	-0.001
5E+12	14	3.395	3.387	-0.008
5E+12	15	3.402	3.393	-0.009
5E+12	16	3.392	3.384	-0.008
1E+13	17	3.418	3.398	-0.020
1E+13	18	3.413	3.395	-0.018
1E+13	19	3.402	3.385	-0.017
	Max	3.418	3.412	0.001
	Average	3.402	3.395	-0.008
	Min	3.385	3.384	-0.020
	Std Dev	0.010	0.010	0.008

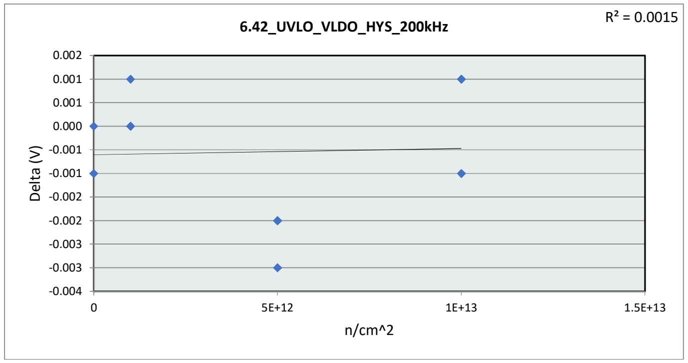


	6.41_UVLO_VLDO_FALL_200k			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.409	3.384	3.384	3.385
Average	3.411	3.392	3.388	3.393
Max	3.412	3.400	3.393	3.398
UL	3.510	3.510	3.510	3.510



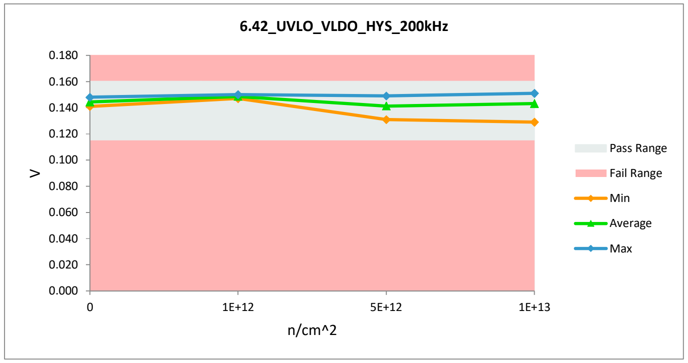
NDD Characterization Report
TPS7H5006-SEP

		6.42_UVLO_VLDO_HYS_200kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.158	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.148	0.148	0.000
0	49	0.142	0.141	-0.001
1E+12	11	0.149	0.149	0.000
1E+12	12	0.149	0.150	0.001
1E+12	13	0.147	0.147	0.000
5E+12	14	0.151	0.149	-0.002
5E+12	15	0.146	0.144	-0.002
5E+12	16	0.134	0.131	-0.003
1E+13	17	0.150	0.151	0.001
1E+13	18	0.130	0.129	-0.001
1E+13	19	0.149	0.150	0.001
	Max	0.151	0.151	0.001
	Average	0.145	0.144	-0.001
	Min	0.130	0.129	-0.003
	Std Dev	0.007	0.008	0.001



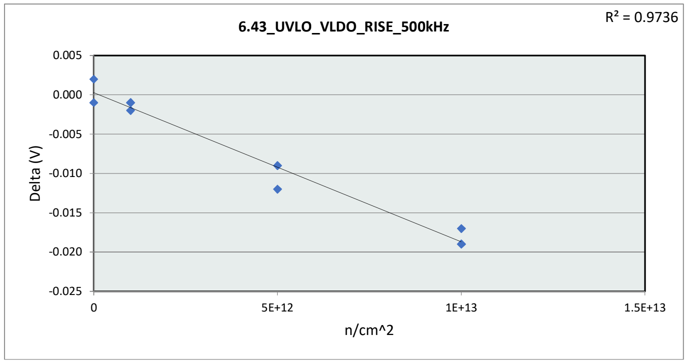
6.42_UVLO_VLDO_HYS_200kH		
Test Site		
Tester		
Test Number		
Max Limit	0.16	V
Min Limit	0.115	V

n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.141	0.147	0.131	0.129
Average	0.145	0.149	0.141	0.143
Max	0.148	0.150	0.149	0.151
UL	0.160	0.160	0.160	0.160

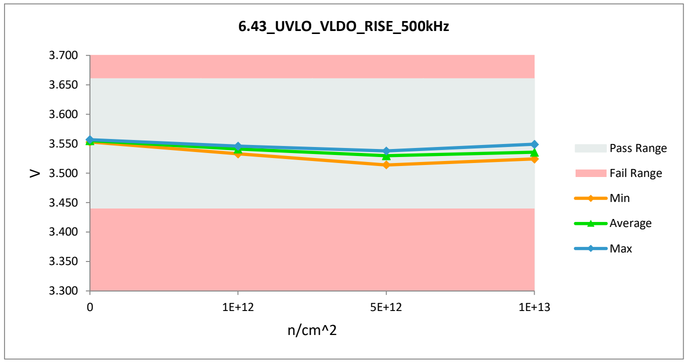


NDD Characterization Report
TPS7H5006-SEP

		6.43_UVLO_VLDO_RISE_500kHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.66	3.66	
Min Limit		3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.558	3.557	-0.001
0	49	3.551	3.553	0.002
1E+12	11	3.534	3.533	-0.001
1E+12	12	3.545	3.543	-0.002
1E+12	13	3.547	3.546	-0.001
5E+12	14	3.546	3.537	-0.009
5E+12	15	3.547	3.538	-0.009
5E+12	16	3.526	3.514	-0.012
1E+13	17	3.568	3.549	-0.019
1E+13	18	3.543	3.524	-0.019
1E+13	19	3.551	3.534	-0.017
	Max	3.568	3.557	0.002
	Average	3.547	3.539	-0.008
	Min	3.526	3.514	-0.019
	Std Dev	0.011	0.013	0.008

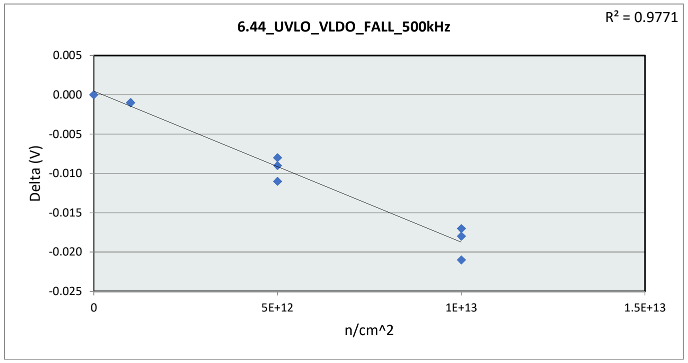


	6.43_UVLO_VLDO_RISE_500k			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.553	3.533	3.514	3.524
Average	3.555	3.541	3.530	3.536
Max	3.557	3.546	3.538	3.549
UL	3.660	3.660	3.660	3.660

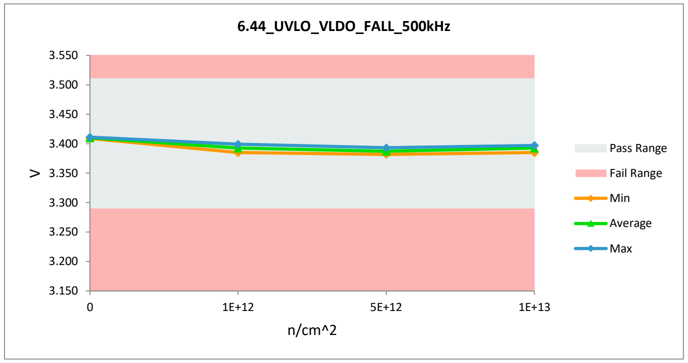


NDD Characterization Report
TPS7H5006-SEP

		6.44_UVLO_VLDO_FALL_500kHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.51	3.51	
Min Limit		3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.409	3.409	0.000
0	49	3.411	3.411	0.000
1E+12	11	3.386	3.385	-0.001
1E+12	12	3.394	3.393	-0.001
1E+12	13	3.400	3.399	-0.001
5E+12	14	3.395	3.387	-0.008
5E+12	15	3.402	3.393	-0.009
5E+12	16	3.393	3.382	-0.011
1E+13	17	3.418	3.397	-0.021
1E+13	18	3.413	3.395	-0.018
1E+13	19	3.402	3.385	-0.017
	Max	3.418	3.411	0.000
	Average	3.402	3.394	-0.008
	Min	3.386	3.382	-0.021
	Std Dev	0.010	0.010	0.008



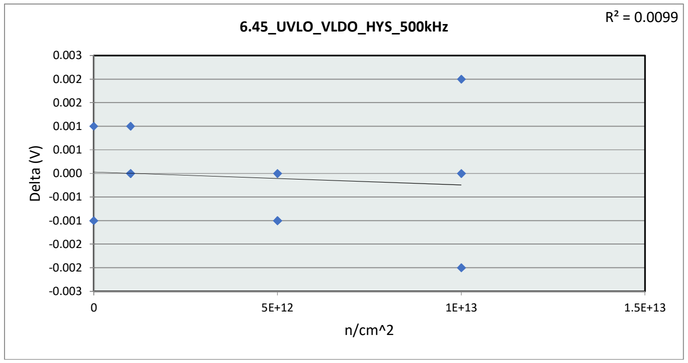
	6.44_UVLO_VLDO_FALL_500k			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.409	3.385	3.382	3.385
Average	3.410	3.392	3.387	3.392
Max	3.411	3.399	3.393	3.397
UL	3.510	3.510	3.510	3.510



NDD Characterization Report
TPS7H5006-SEP

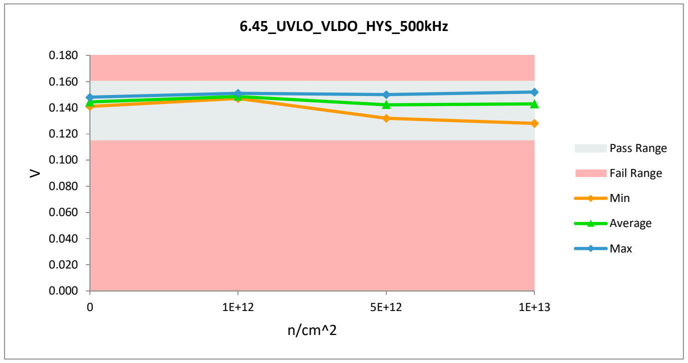
	6.45_UVLO_VLDO_HYS_500kHz	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.158	0.16
Min Limit	0.115	0.115

n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.149	0.148	-0.001
0	49	0.140	0.141	0.001
1E+12	11	0.148	0.148	0.000
1E+12	12	0.150	0.151	0.001
1E+12	13	0.147	0.147	0.000
5E+12	14	0.151	0.150	-0.001
5E+12	15	0.145	0.145	0.000
5E+12	16	0.133	0.132	-0.001
1E+13	17	0.150	0.152	0.002
1E+13	18	0.130	0.128	-0.002
1E+13	19	0.149	0.149	0.000
	Max	0.151	0.152	0.002
	Average	0.145	0.145	0.000
	Min	0.130	0.128	-0.002
	Std Dev	0.007	0.008	0.001



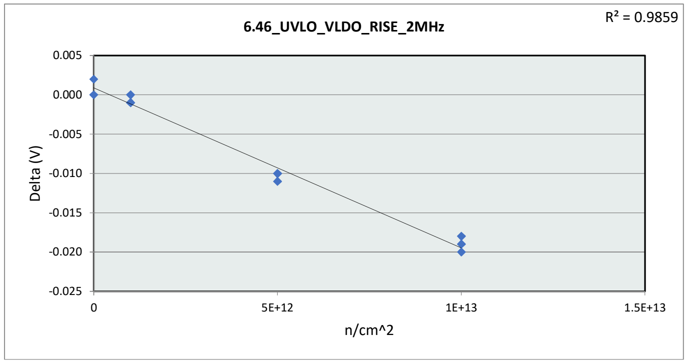
	6.45_UVLO_VLDO_HYS_500kH	
Test Site		
Tester		
Test Number		
Max Limit	0.16	V
Min Limit	0.115	V

n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.141	0.147	0.132	0.128
Average	0.145	0.149	0.142	0.143
Max	0.148	0.151	0.150	0.152
UL	0.160	0.160	0.160	0.160

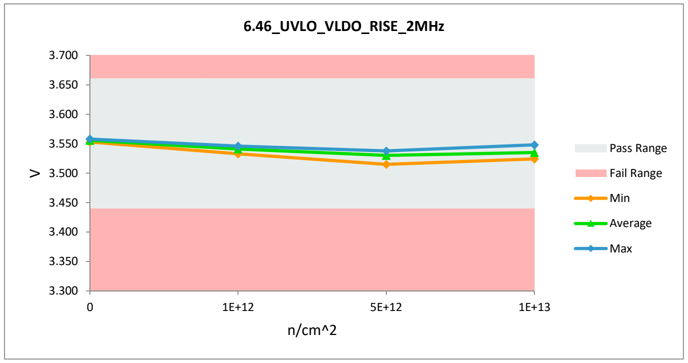


NDD Characterization Report
TPS7H5006-SEP

		6.46_UVLO_VLDO_RISE_2MHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.66	3.66	
Min Limit		3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.558	3.558	0.000
0	49	3.551	3.553	0.002
1E+12	11	3.533	3.533	0.000
1E+12	12	3.544	3.543	-0.001
1E+12	13	3.547	3.546	-0.001
5E+12	14	3.547	3.537	-0.010
5E+12	15	3.548	3.538	-0.010
5E+12	16	3.526	3.515	-0.011
1E+13	17	3.568	3.548	-0.020
1E+13	18	3.543	3.524	-0.019
1E+13	19	3.551	3.533	-0.018
	Max	3.568	3.558	0.002
	Average	3.547	3.539	-0.008
	Min	3.526	3.515	-0.020
	Std Dev	0.011	0.013	0.008

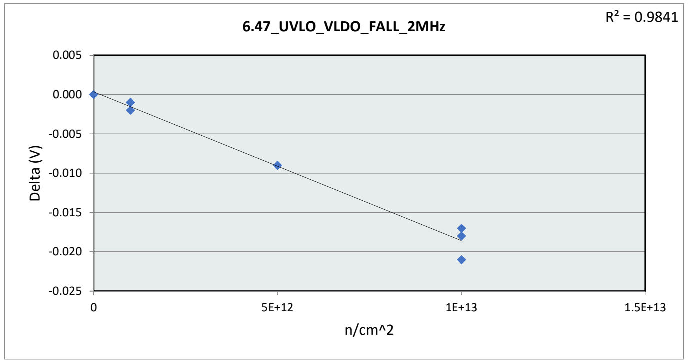


	6.46_UVLO_VLDO_RISE_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.553	3.533	3.515	3.524
Average	3.556	3.541	3.530	3.535
Max	3.558	3.546	3.538	3.548
UL	3.660	3.660	3.660	3.660

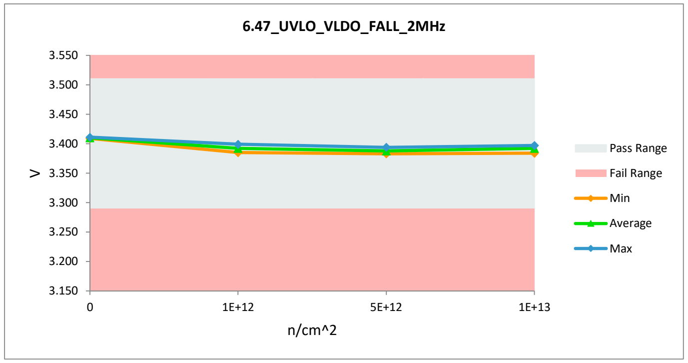


NDD Characterization Report
TPS7H5006-SEP

		6.47_UVLO_VLDO_FALL_2MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	3.409	3.409	0.000
0	49	3.411	3.411	0.000
1E+12	11	3.386	3.385	-0.001
1E+12	12	3.394	3.392	-0.002
1E+12	13	3.400	3.399	-0.001
5E+12	14	3.395	3.386	-0.009
5E+12	15	3.403	3.394	-0.009
5E+12	16	3.392	3.383	-0.009
1E+13	17	3.418	3.397	-0.021
1E+13	18	3.413	3.395	-0.018
1E+13	19	3.401	3.384	-0.017
	Max	3.418	3.411	0.000
	Average	3.402	3.394	-0.008
	Min	3.386	3.383	-0.021
	Std Dev	0.010	0.010	0.008

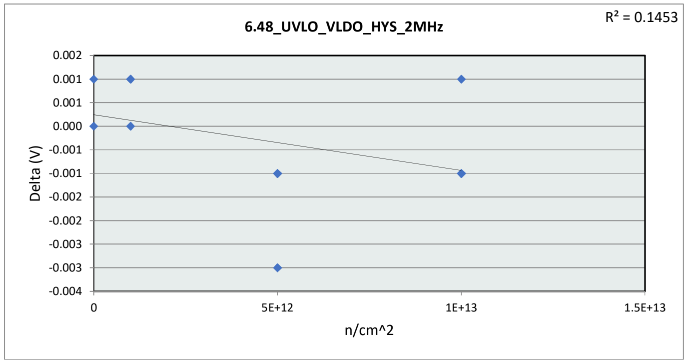


	6.47_UVLO_VLDO_FALL_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.409	3.385	3.383	3.384
Average	3.410	3.392	3.388	3.392
Max	3.411	3.399	3.394	3.397
UL	3.510	3.510	3.510	3.510

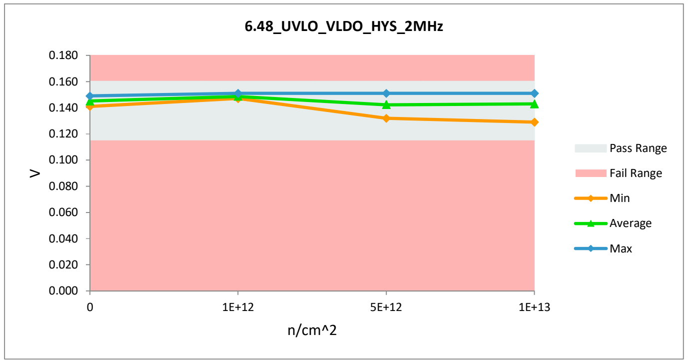


NDD Characterization Report
TPS7H5006-SEP

		6.48_UVLO_VLDO_HYS_2MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.158	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.149	0.149	0.000
0	49	0.140	0.141	0.001
1E+12	11	0.147	0.148	0.001
1E+12	12	0.150	0.151	0.001
1E+12	13	0.147	0.147	0.000
5E+12	14	0.152	0.151	-0.001
5E+12	15	0.145	0.144	-0.001
5E+12	16	0.135	0.132	-0.003
1E+13	17	0.150	0.151	0.001
1E+13	18	0.130	0.129	-0.001
1E+13	19	0.150	0.149	-0.001
	Max	0.152	0.151	0.001
	Average	0.145	0.145	0.000
	Min	0.130	0.129	-0.003
	Std Dev	0.007	0.008	0.001

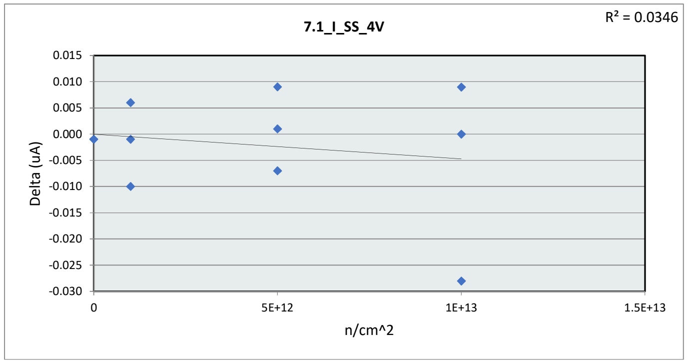


	6.48_UVLO_VLDO_HYS_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.141	0.147	0.132	0.129
Average	0.145	0.149	0.142	0.143
Max	0.149	0.151	0.151	0.151
UL	0.160	0.160	0.160	0.160

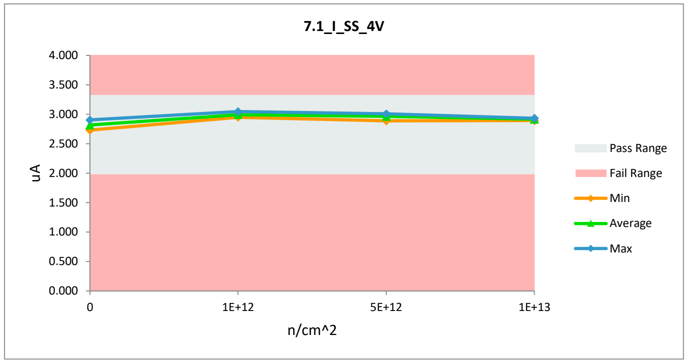


NDD Characterization Report
TPS7H5006-SEP

		7.1_I_SS_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	3.2	3.32	
	Min Limit	2.2	1.98	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2.732	2.731	-0.001
0	49	2.905	2.904	-0.001
1E+12	11	3.039	3.045	0.006
1E+12	12	2.996	2.986	-0.010
1E+12	13	2.952	2.951	-0.001
5E+12	14	2.885	2.886	0.001
5E+12	15	2.988	2.997	0.009
5E+12	16	3.016	3.009	-0.007
1E+13	17	2.894	2.894	0.000
1E+13	18	2.913	2.922	0.009
1E+13	19	2.960	2.932	-0.028
	Max	3.039	3.045	0.009
	Average	2.935	2.932	-0.002
	Min	2.732	2.731	-0.028
	Std Dev	0.085	0.084	0.010

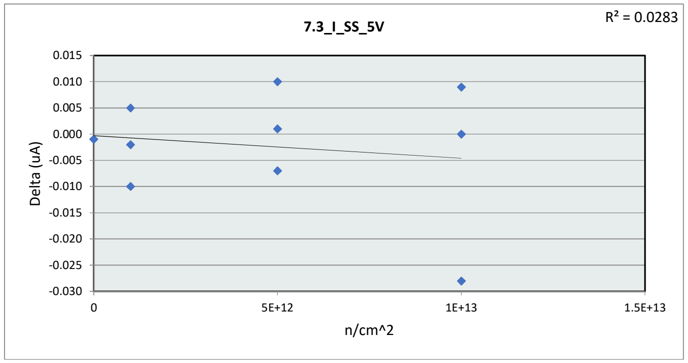


	7.1_I_SS_4V			
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.731	2.951	2.886	2.894
Average	2.818	2.994	2.964	2.916
Max	2.904	3.045	3.009	2.932
UL	3.320	3.320	3.320	3.320

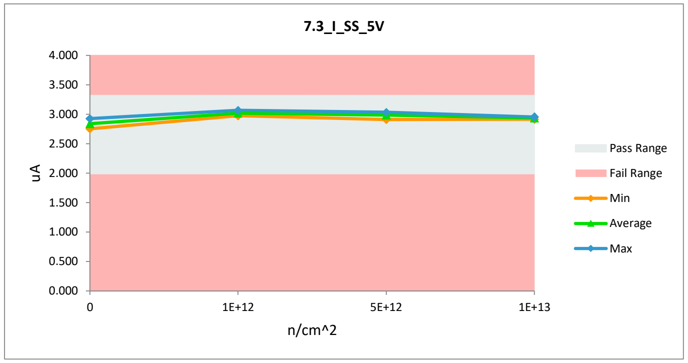


NDD Characterization Report
TPS7H5006-SEP

		7.3_I_SS_5V		
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		3.2	3.32	
Min Limit		2.2	1.98	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2.754	2.753	-0.001
0	49	2.928	2.927	-0.001
1E+12	11	3.063	3.068	0.005
1E+12	12	3.019	3.009	-0.010
1E+12	13	2.976	2.974	-0.002
5E+12	14	2.908	2.909	0.001
5E+12	15	3.011	3.021	0.010
5E+12	16	3.040	3.033	-0.007
1E+13	17	2.917	2.917	0.000
1E+13	18	2.936	2.945	0.009
1E+13	19	2.984	2.956	-0.028
	Max	3.063	3.068	0.010
	Average	2.958	2.956	-0.002
	Min	2.754	2.753	-0.028
	Std Dev	0.085	0.085	0.010

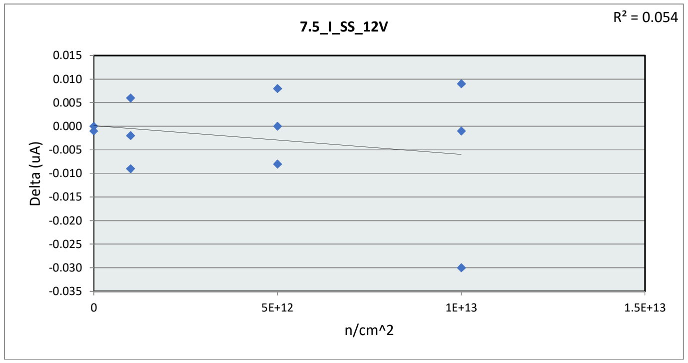


	7.3_I_SS_5V			
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.753	2.974	2.909	2.917
Average	2.840	3.017	2.988	2.939
Max	2.927	3.068	3.033	2.956
UL	3.320	3.320	3.320	3.320

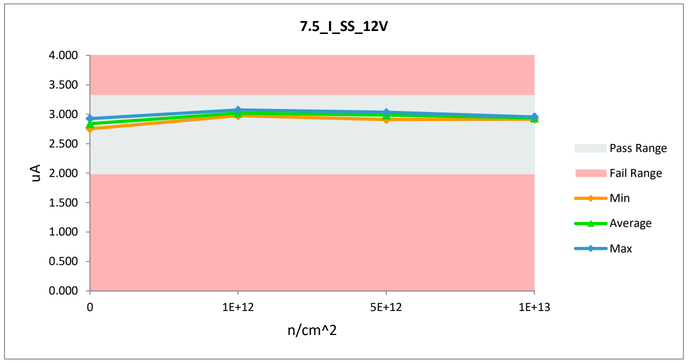


NDD Characterization Report
TPS7H5006-SEP

		7.5_I_SS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	3.2	3.32	
	Min Limit	2.2	1.98	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2.755	2.755	0.000
0	49	2.929	2.928	-0.001
1E+12	11	3.065	3.071	0.006
1E+12	12	3.020	3.011	-0.009
1E+12	13	2.977	2.975	-0.002
5E+12	14	2.910	2.910	0.000
5E+12	15	3.014	3.022	0.008
5E+12	16	3.042	3.034	-0.008
1E+13	17	2.918	2.917	-0.001
1E+13	18	2.936	2.945	0.009
1E+13	19	2.987	2.957	-0.030
	Max	3.065	3.071	0.009
	Average	2.959	2.957	-0.003
	Min	2.755	2.755	-0.030
	Std Dev	0.086	0.085	0.011

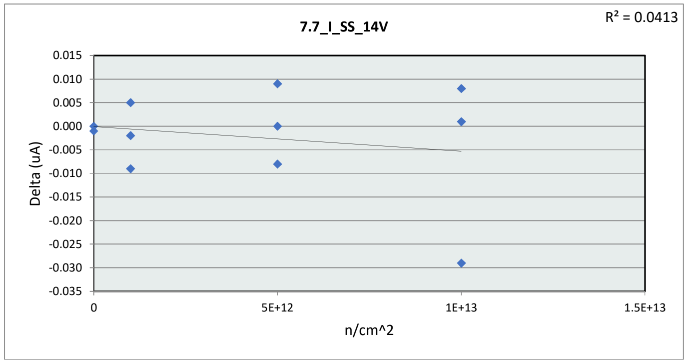


	7.5_I_SS_12V			
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.755	2.975	2.910	2.917
Average	2.842	3.019	2.989	2.940
Max	2.928	3.071	3.034	2.957
UL	3.320	3.320	3.320	3.320

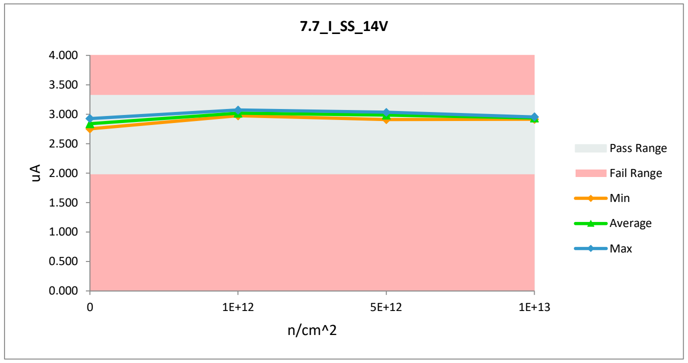


NDD Characterization Report
TPS7H5006-SEP

		7.7_I_SS_14V		
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		3.2	3.32	
Min Limit		2.2	1.98	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2.755	2.755	0.000
0	49	2.929	2.928	-0.001
1E+12	11	3.066	3.071	0.005
1E+12	12	3.020	3.011	-0.009
1E+12	13	2.978	2.976	-0.002
5E+12	14	2.910	2.910	0.000
5E+12	15	3.013	3.022	0.009
5E+12	16	3.041	3.033	-0.008
1E+13	17	2.917	2.918	0.001
1E+13	18	2.937	2.945	0.008
1E+13	19	2.986	2.957	-0.029
	Max	3.066	3.071	0.009
	Average	2.959	2.957	-0.002
	Min	2.755	2.755	-0.029
	Std Dev	0.085	0.085	0.010

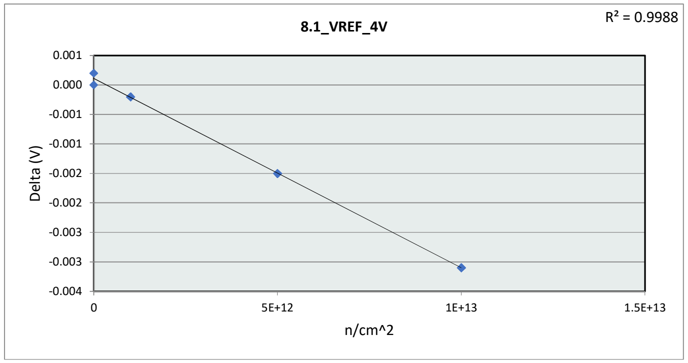


	7.7_I_SS_14V			
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.755	2.976	2.910	2.918
Average	2.842	3.019	2.988	2.940
Max	2.928	3.071	3.033	2.957
UL	3.320	3.320	3.320	3.320

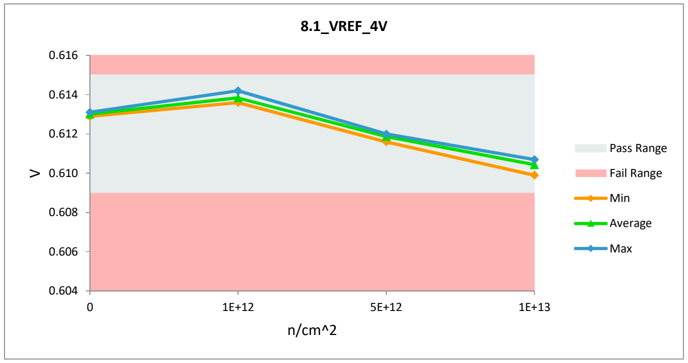


NDD Characterization Report
TPS7H5006-SEP

		8.1_VREF_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.615	0.615	
	Min Limit	0.611	0.609	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.613	0.613	0.000
0	49	0.613	0.613	0.000
1E+12	11	0.614	0.614	0.000
1E+12	12	0.614	0.614	0.000
1E+12	13	0.614	0.614	0.000
5E+12	14	0.613	0.612	-0.002
5E+12	15	0.613	0.612	-0.002
5E+12	16	0.613	0.612	-0.002
1E+13	17	0.613	0.610	-0.003
1E+13	18	0.614	0.611	-0.003
1E+13	19	0.614	0.611	-0.003
	Max	0.614	0.614	0.000
	Average	0.614	0.612	-0.001
	Min	0.613	0.610	-0.003
	Std Dev	0.000	0.001	0.001

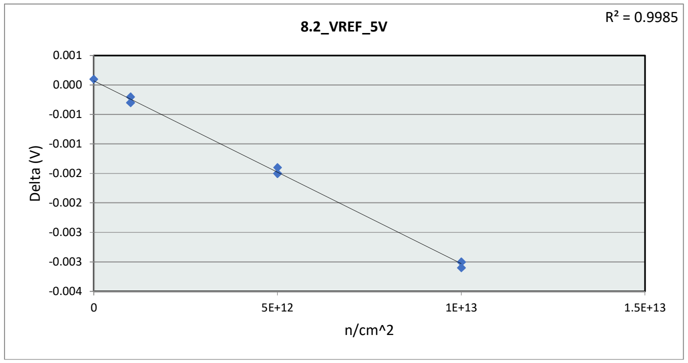


	8.1_VREF_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.615	V		
Min Limit	0.609	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.614	0.612	0.610
Average	0.613	0.614	0.612	0.610
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

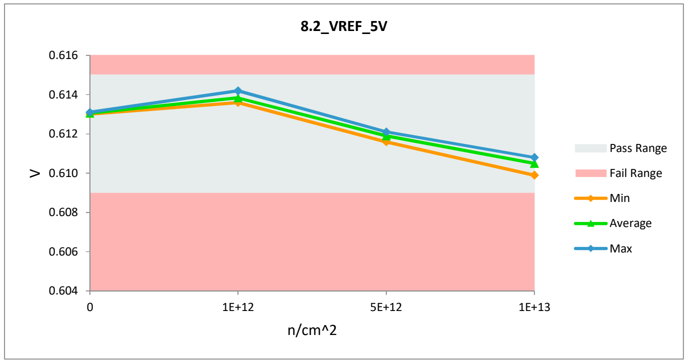


NDD Characterization Report
TPS7H5006-SEP

		8.2_VREF_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.615	0.615	
	Min Limit	0.611	0.609	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.613	0.613	0.000
0	49	0.613	0.613	0.000
1E+12	11	0.614	0.614	0.000
1E+12	12	0.614	0.614	0.000
1E+12	13	0.614	0.614	0.000
5E+12	14	0.613	0.612	-0.002
5E+12	15	0.613	0.612	-0.001
5E+12	16	0.613	0.612	-0.002
1E+13	17	0.613	0.610	-0.003
1E+13	18	0.614	0.611	-0.003
1E+13	19	0.614	0.611	-0.003
	Max	0.614	0.614	0.000
	Average	0.614	0.612	-0.001
	Min	0.613	0.610	-0.003
	Std Dev	0.001	0.001	0.001

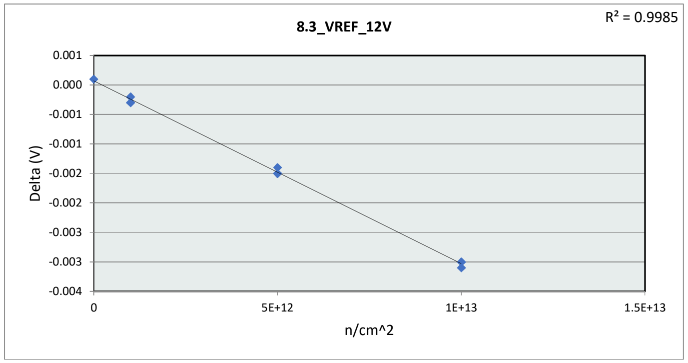


	8.2_VREF_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.615 V			
Min Limit	0.609 V			
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.614	0.612	0.610
Average	0.613	0.614	0.612	0.611
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

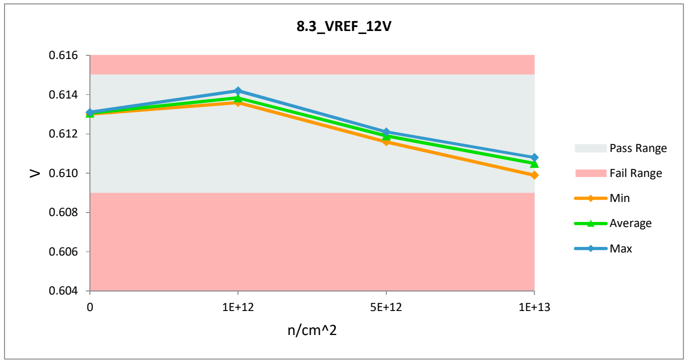


NDD Characterization Report
TPS7H5006-SEP

	8.3_VREF_12V			
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.615	0.615	
	Min Limit	0.611	0.609	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.613	0.613	0.000
0	49	0.613	0.613	0.000
1E+12	11	0.614	0.614	0.000
1E+12	12	0.614	0.614	0.000
1E+12	13	0.614	0.614	0.000
5E+12	14	0.613	0.612	-0.002
5E+12	15	0.613	0.612	-0.001
5E+12	16	0.613	0.612	-0.002
1E+13	17	0.613	0.610	-0.003
1E+13	18	0.614	0.611	-0.003
1E+13	19	0.614	0.611	-0.003
	Max	0.614	0.614	0.000
	Average	0.614	0.612	-0.001
	Min	0.613	0.610	-0.003
	Std Dev	0.001	0.001	0.001

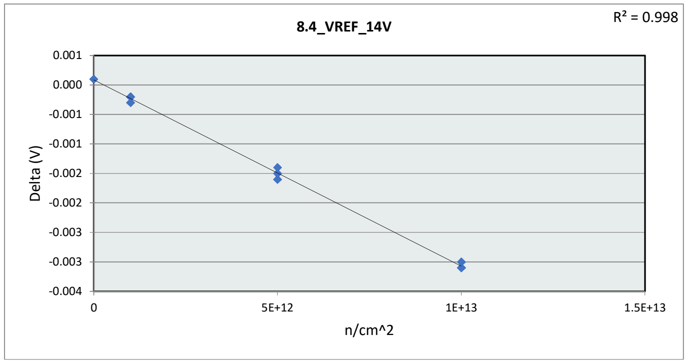


	8.3_VREF_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.615	V		
Min Limit	0.609	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.614	0.612	0.610
Average	0.613	0.614	0.612	0.611
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

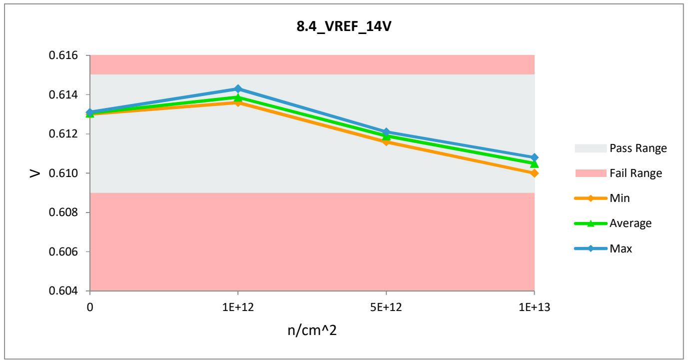


NDD Characterization Report
TPS7H5006-SEP

		8.4_VREF_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.615	0.615	
Min Limit		0.611	0.609	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.613	0.613	0.000
0	49	0.613	0.613	0.000
1E+12	11	0.614	0.614	0.000
1E+12	12	0.614	0.614	0.000
1E+12	13	0.614	0.614	0.000
5E+12	14	0.613	0.612	-0.002
5E+12	15	0.613	0.612	-0.001
5E+12	16	0.613	0.612	-0.002
1E+13	17	0.613	0.610	-0.003
1E+13	18	0.614	0.611	-0.003
1E+13	19	0.614	0.611	-0.003
	Max	0.614	0.614	0.000
	Average	0.614	0.612	-0.001
	Min	0.613	0.610	-0.003
	Std Dev	0.000	0.001	0.001

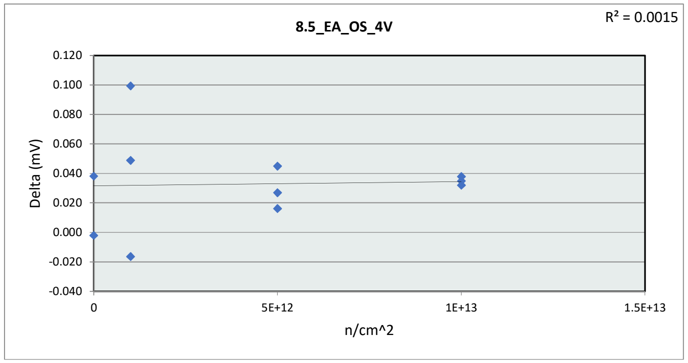


	8.4_VREF_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.615	V		
Min Limit	0.609	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.614	0.612	0.610
Average	0.613	0.614	0.612	0.611
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

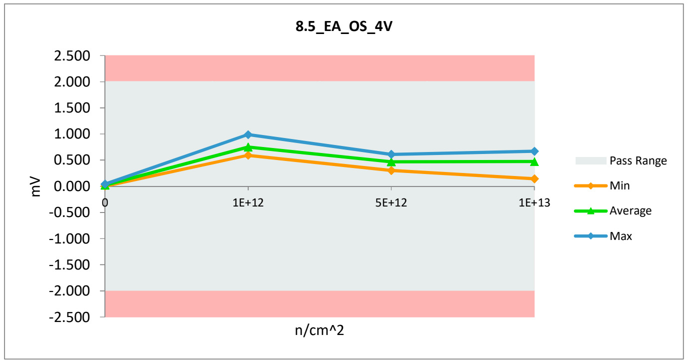


NDD Characterization Report
TPS7H5006-SEP

		8.5_EA_OS_4V		
Test Site				
Tester				
Test Number				
Unit		mV	mV	
Max Limit		1.9	2	
Min Limit		-1.8	-2	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.043	0.041	-0.002
0	49	-0.032	0.006	0.038
1E+12	11	1.008	0.991	-0.016
1E+12	12	0.619	0.668	0.049
1E+12	13	0.495	0.594	0.099
5E+12	14	0.287	0.304	0.016
5E+12	15	0.441	0.486	0.045
5E+12	16	0.584	0.611	0.027
1E+13	17	0.112	0.147	0.035
1E+13	18	0.557	0.595	0.038
1E+13	19	0.640	0.672	0.032
	Max	1.008	0.991	0.099
	Average	0.432	0.465	0.033
	Min	-0.032	0.006	-0.016
	Std Dev	0.307	0.306	0.030

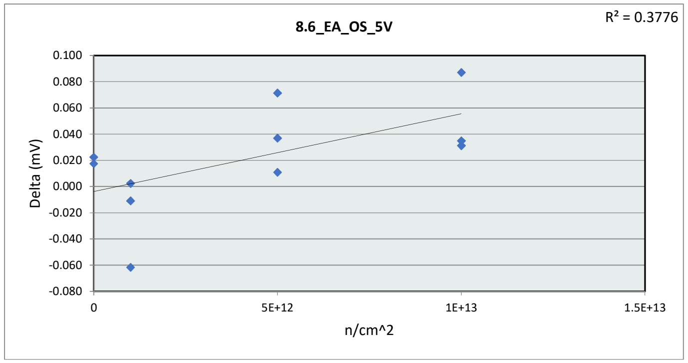


8.5_EA_OS_4V				
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.006	0.594	0.304	0.147
Average	0.023	0.751	0.467	0.471
Max	0.041	0.991	0.611	0.672
UL	2.000	2.000	2.000	2.000

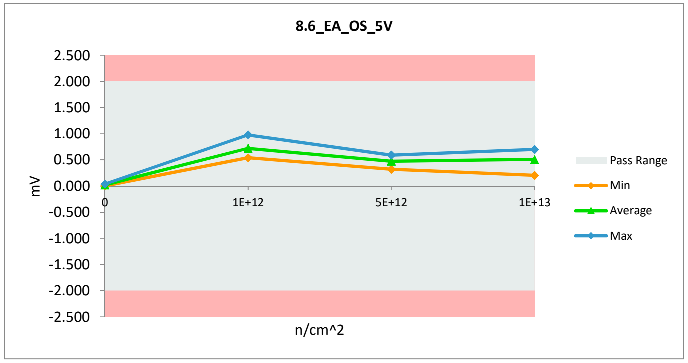


NDD Characterization Report
TPS7H5006-SEP

		8.6_EA_OS_5V		
Test Site				
Tester				
Test Number				
Unit		mV	mV	
Max Limit		1.9	2	
Min Limit		-1.8	-2	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.015	0.037	0.022
0	49	-0.013	0.005	0.018
1E+12	11	1.040	0.978	-0.062
1E+12	12	0.658	0.647	-0.011
1E+12	13	0.540	0.542	0.002
5E+12	14	0.309	0.320	0.011
5E+12	15	0.445	0.517	0.071
5E+12	16	0.555	0.592	0.037
1E+13	17	0.117	0.204	0.087
1E+13	18	0.585	0.620	0.035
1E+13	19	0.668	0.699	0.031
	Max	1.040	0.978	0.087
	Average	0.447	0.469	0.022
	Min	-0.013	0.005	-0.062
	Std Dev	0.318	0.297	0.040

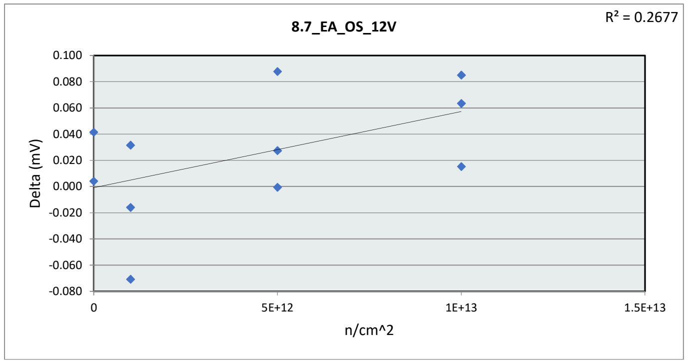


	8.6_EA_OS_5V			
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.005	0.542	0.320	0.204
Average	0.021	0.722	0.476	0.508
Max	0.037	0.978	0.592	0.699
UL	2.000	2.000	2.000	2.000

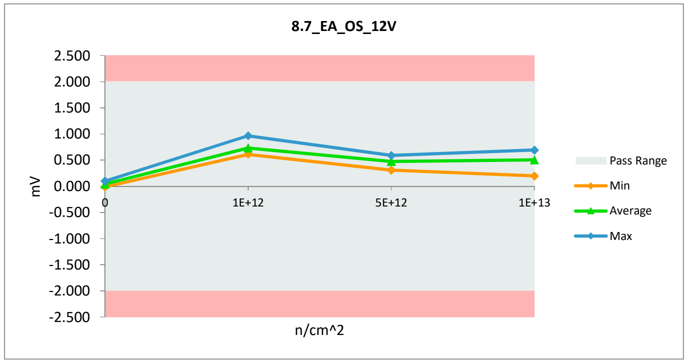


NDD Characterization Report
TPS7H5006-SEP

		8.7_EA_OS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mV	mV	
	Max Limit	1.9	2	
	Min Limit	-1.8	-2	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.058	0.100	0.041
0	49	-0.015	-0.011	0.004
1E+12	11	1.037	0.966	-0.071
1E+12	12	0.641	0.625	-0.016
1E+12	13	0.579	0.610	0.032
5E+12	14	0.309	0.309	0.000
5E+12	15	0.439	0.527	0.088
5E+12	16	0.562	0.589	0.027
1E+13	17	0.133	0.197	0.064
1E+13	18	0.536	0.622	0.085
1E+13	19	0.678	0.693	0.015
	Max	1.037	0.966	0.088
	Average	0.451	0.475	0.024
	Min	-0.015	-0.011	-0.071
	Std Dev	0.310	0.291	0.046

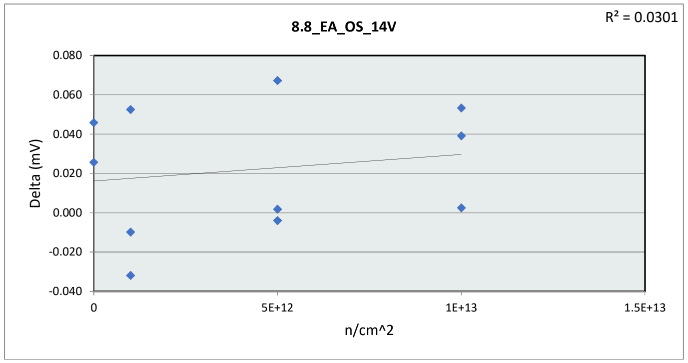


	8.7_EA_OS_12V			
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	-0.011	0.610	0.309	0.197
Average	0.044	0.734	0.475	0.504
Max	0.100	0.966	0.589	0.693
UL	2.000	2.000	2.000	2.000

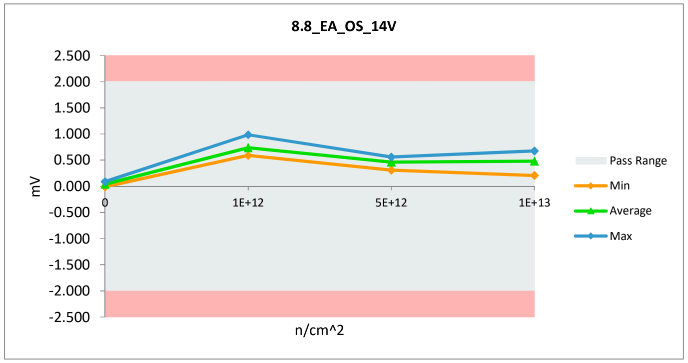


NDD Characterization Report
TPS7H5006-SEP

		8.8_EA_OS_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	mV	mV	
	Max Limit	1.9	2	
	Min Limit	-1.8	-2	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.043	0.089	0.046
0	49	-0.034	-0.008	0.026
1E+12	11	1.018	0.986	-0.032
1E+12	12	0.644	0.634	-0.010
1E+12	13	0.539	0.591	0.052
5E+12	14	0.315	0.311	-0.004
5E+12	15	0.449	0.516	0.067
5E+12	16	0.558	0.560	0.002
1E+13	17	0.154	0.208	0.053
1E+13	18	0.556	0.559	0.002
1E+13	19	0.640	0.679	0.039
	Max	1.018	0.986	0.067
	Average	0.444	0.466	0.022
	Min	-0.034	-0.008	-0.032
	Std Dev	0.305	0.289	0.032

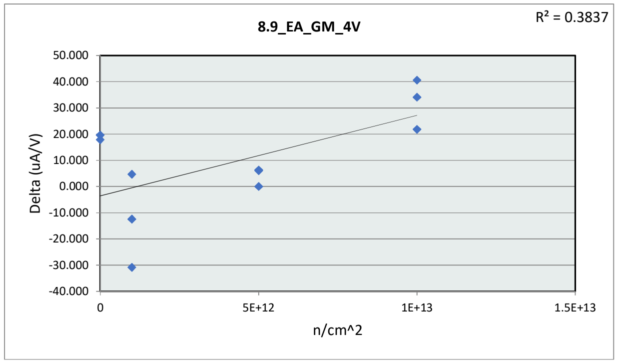


	8.8_EA_OS_14V			
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	-0.008	0.591	0.311	0.208
Average	0.040	0.737	0.463	0.482
Max	0.089	0.986	0.560	0.679
UL	2.000	2.000	2.000	2.000

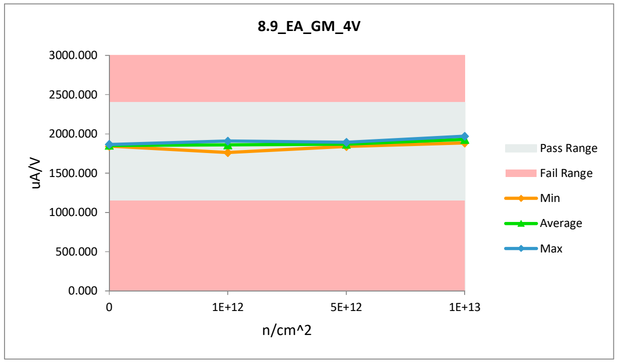


NDD Characterization Report
TPS7H5006-SEP

		8.9_EA_GM_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA/V	uA/V	
	Max Limit	2350	2400	
	Min Limit	1200	1150	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1823.640	1841.556	17.916
0	49	1846.511	1866.188	19.677
1E+12	11	1918.690	1906.253	-12.437
1E+12	12	1940.449	1909.638	-30.811
1E+12	13	1756.409	1761.129	4.720
5E+12	14	1835.009	1841.313	6.304
5E+12	15	1887.944	1894.008	6.064
5E+12	16	1864.042	1864.032	-0.010
1E+13	17	1850.850	1884.932	34.082
1E+13	18	1929.458	1970.035	40.577
1E+13	19	1913.482	1935.300	21.818
	Max	1940.449	1970.035	40.577
	Average	1869.680	1879.489	9.809
	Min	1756.409	1761.129	-30.811
	Std Dev	55.055	55.227	20.339

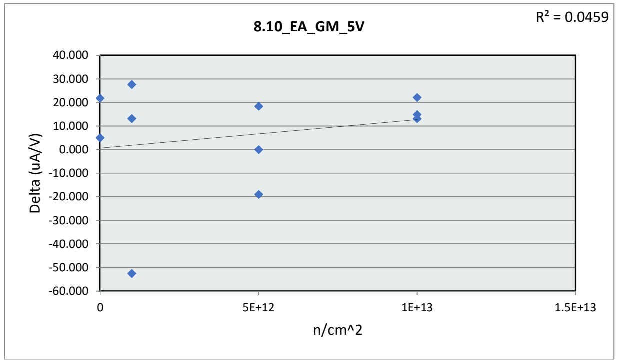


	8.9_EA_GM_4V			
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1841.556	1761.129	1841.313	1884.932
Average	1853.872	1859.007	1866.451	1930.089
Max	1866.188	1909.638	1894.008	1970.035
UL	2400.000	2400.000	2400.000	2400.000

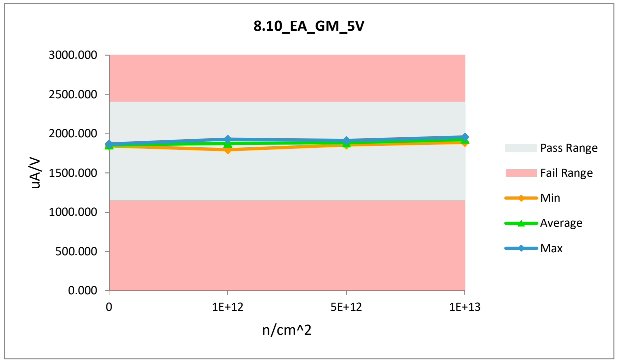


NDD Characterization Report
TPS7H5006-SEP

		8.10_EA_GM_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA/V	uA/V	
	Max Limit	2350	2400	
	Min Limit	1200	1150	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1823.640	1845.465	21.825
0	49	1864.042	1869.057	5.015
1E+12	11	1918.076	1931.257	13.181
1E+12	12	1952.610	1900.121	-52.489
1E+12	13	1768.881	1796.459	27.578
5E+12	14	1875.912	1856.986	-18.926
5E+12	15	1894.019	1912.457	18.438
5E+12	16	1881.909	1881.898	-0.011
1E+13	17	1873.262	1888.125	14.863
1E+13	18	1936.451	1958.571	22.120
1E+13	19	1922.163	1935.245	13.082
	Max	1952.610	1958.571	27.578
	Average	1882.815	1888.695	5.880
	Min	1768.881	1796.459	-52.489
	Std Dev	52.574	46.228	23.217

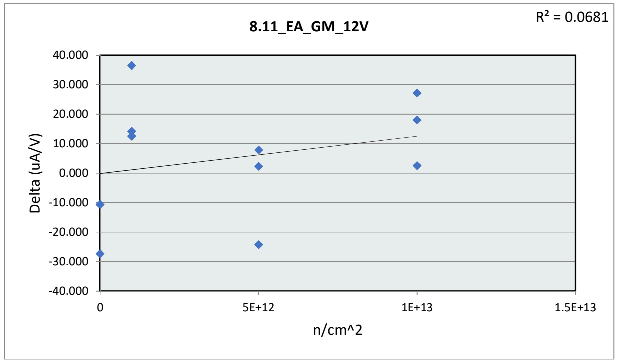


	8.10_EA_GM_5V			
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1845.465	1796.459	1856.986	1888.125
Average	1857.261	1875.946	1883.780	1927.314
Max	1869.057	1931.257	1912.457	1958.571
UL	2400.000	2400.000	2400.000	2400.000

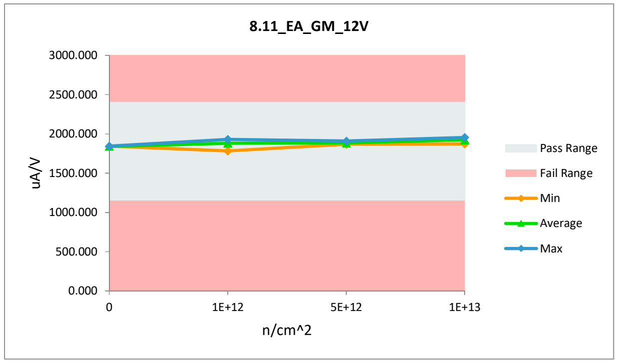


NDD Characterization Report
TPS7H5006-SEP

		8.11_EA_GM_12V		
Test Site				
Tester				
Test Number				
Unit		uA/V	uA/V	
Max Limit		2350	2400	
Min Limit		1200	1150	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1852.321	1841.727	-10.594
0	49	1869.963	1842.658	-27.305
1E+12	11	1894.756	1931.257	36.501
1E+12	12	1918.690	1931.268	12.578
1E+12	13	1768.881	1783.103	14.222
5E+12	14	1864.042	1866.406	2.364
5E+12	15	1901.489	1909.344	7.855
5E+12	16	1900.121	1875.901	-24.220
1E+13	17	1869.963	1872.583	2.620
1E+13	18	1927.308	1954.475	27.167
1E+13	19	1927.264	1945.297	18.033
	Max	1927.308	1954.475	36.501
	Average	1881.345	1886.729	5.384
	Min	1768.881	1783.103	-27.305
	Std Dev	45.391	52.852	19.889

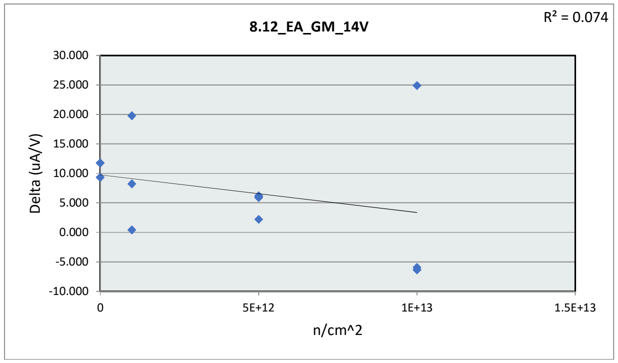


	8.11_EA_GM_12V			
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1841.727	1783.103	1866.406	1872.583
Average	1842.193	1881.876	1883.884	1924.118
Max	1842.658	1931.268	1909.344	1954.475
UL	2400.000	2400.000	2400.000	2400.000

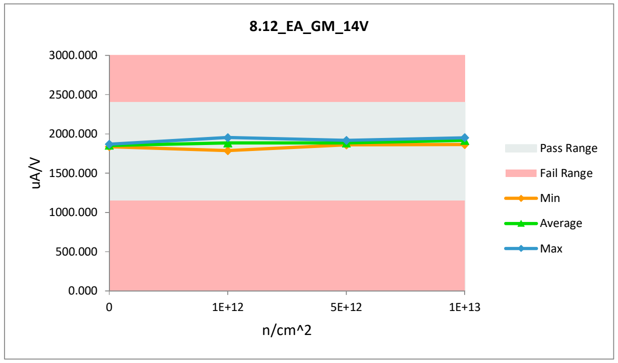


NDD Characterization Report
TPS7H5006-SEP

		8.12_EA_GM_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA/V	uA/V	
	Max Limit	2350	2400	
	Min Limit	1200	1150	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1829.307	1838.659	9.352
0	49	1858.168	1869.942	11.774
1E+12	11	1904.219	1912.457	8.238
1E+12	12	1931.958	1951.747	19.789
1E+12	13	1784.962	1785.380	0.418
5E+12	14	1858.158	1860.363	2.205
5E+12	15	1912.457	1918.679	6.222
5E+12	16	1869.963	1875.901	5.938
1E+13	17	1871.444	1865.524	-5.920
1E+13	18	1927.474	1952.383	24.909
1E+13	19	1938.420	1932.058	-6.362
	Max	1938.420	1952.383	24.909
	Average	1880.594	1887.554	6.960
	Min	1784.962	1785.380	-6.362
	Std Dev	47.678	51.375	9.631

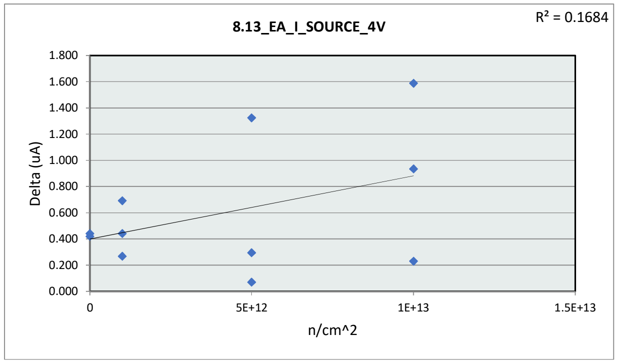


	8.12_EA_GM_14V			
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1838.659	1785.380	1860.363	1865.524
Average	1854.301	1883.195	1884.981	1916.655
Max	1869.942	1951.747	1918.679	1952.383
UL	2400.000	2400.000	2400.000	2400.000

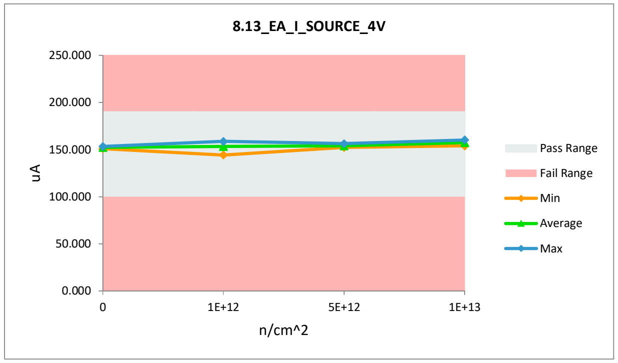


NDD Characterization Report
TPS7H5006-SEP

		8.13_EA_I_SOURCE_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	150.678	151.097	0.419
0	49	152.990	153.431	0.441
1E+12	11	156.353	157.045	0.692
1E+12	12	158.421	158.690	0.269
1E+12	13	143.839	144.280	0.441
5E+12	14	151.997	152.291	0.294
5E+12	15	154.994	156.319	1.325
5E+12	16	153.963	154.033	0.070
1E+13	17	153.077	154.012	0.935
1E+13	18	158.702	160.291	1.589
1E+13	19	157.823	158.053	0.230
	Max	158.702	160.291	1.589
	Average	153.894	154.504	0.610
	Min	143.839	144.280	0.070
	Std Dev	4.276	4.427	0.482

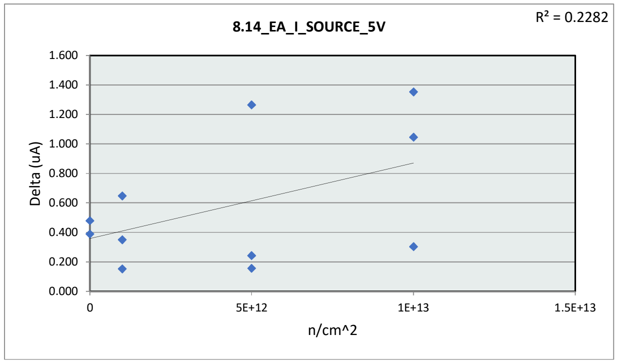


	8.13_EA_I_SOURCE_4V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	151.097	144.280	152.291	154.012
Average	152.264	153.338	154.214	157.452
Max	153.431	158.690	156.319	160.291
UL	190.000	190.000	190.000	190.000

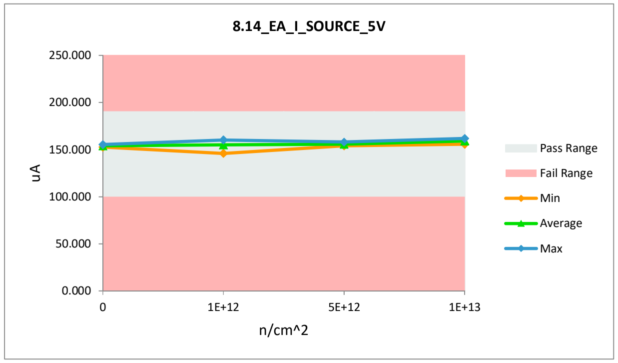


NDD Characterization Report
TPS7H5006-SEP

		8.14_EA_I_SOURCE_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	152.278	152.668	0.390
0	49	154.821	155.300	0.479
1E+12	11	158.058	158.705	0.647
1E+12	12	160.198	160.351	0.153
1E+12	13	145.589	145.939	0.350
5E+12	14	153.654	153.897	0.243
5E+12	15	156.709	157.974	1.265
5E+12	16	155.641	155.798	0.157
1E+13	17	154.767	155.813	1.046
1E+13	18	160.625	161.978	1.353
1E+13	19	159.570	159.874	0.304
	Max	160.625	161.978	1.353
	Average	155.628	156.209	0.581
	Min	145.589	145.939	0.153
	Std Dev	4.310	4.447	0.440

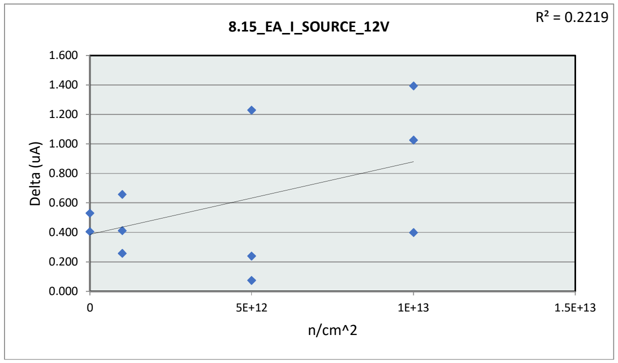


	8.14_EA_I_SOURCE_5V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	152.668	145.939	153.897	155.813
Average	153.984	154.998	155.890	159.222
Max	155.300	160.351	157.974	161.978
UL	190.000	190.000	190.000	190.000

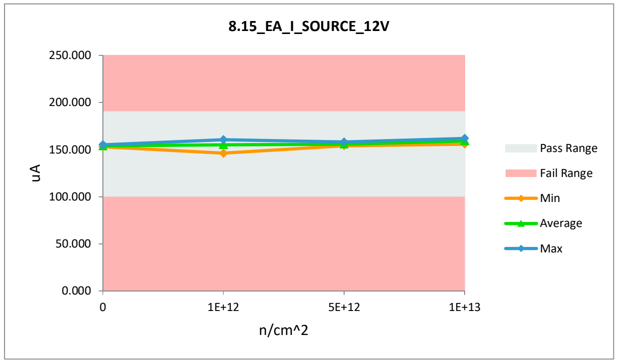


NDD Characterization Report
TPS7H5006-SEP

		8.15_EA_I_SOURCE_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	152.353	152.882	0.529
0	49	154.730	155.134	0.404
1E+12	11	158.179	158.836	0.657
1E+12	12	160.153	160.410	0.257
1E+12	13	145.676	146.086	0.410
5E+12	14	153.695	153.933	0.238
5E+12	15	156.742	157.970	1.228
5E+12	16	155.673	155.746	0.073
1E+13	17	154.790	155.815	1.025
1E+13	18	160.563	161.956	1.393
1E+13	19	159.471	159.869	0.398
	Max	160.563	161.956	1.393
	Average	155.639	156.240	0.601
	Min	145.676	146.086	0.073
	Std Dev	4.270	4.408	0.431

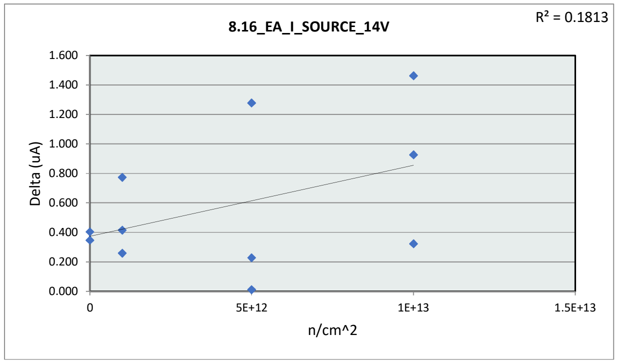


	8.15_EA_I_SOURCE_12V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	152.882	146.086	153.933	155.815
Average	154.008	155.111	155.883	159.213
Max	155.134	160.410	157.970	161.956
UL	190.000	190.000	190.000	190.000

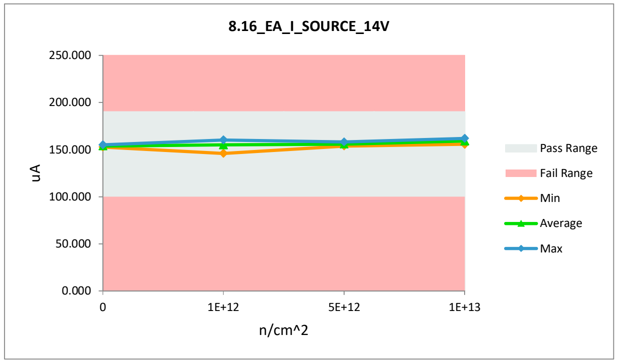


NDD Characterization Report
TPS7H5006-SEP

		8.16_EA_I_SOURCE_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	152.287	152.690	0.403
0	49	154.703	155.048	0.345
1E+12	11	158.066	158.838	0.772
1E+12	12	160.039	160.297	0.258
1E+12	13	145.579	145.993	0.414
5E+12	14	153.622	153.849	0.227
5E+12	15	156.656	157.933	1.277
5E+12	16	155.539	155.550	0.011
1E+13	17	154.744	155.669	0.925
1E+13	18	160.402	161.863	1.461
1E+13	19	159.393	159.715	0.322
	Max	160.402	161.863	1.461
	Average	155.548	156.131	0.583
	Min	145.579	145.993	0.011
	Std Dev	4.256	4.418	0.464

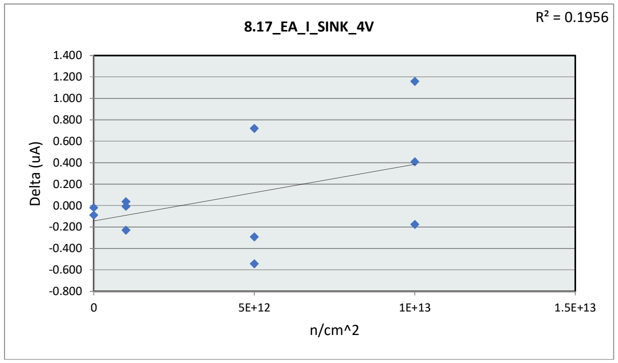


	8.16_EA_I_SOURCE_14V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	152.690	145.993	153.849	155.669
Average	153.869	155.043	155.777	159.082
Max	155.048	160.297	157.933	161.863
UL	190.000	190.000	190.000	190.000

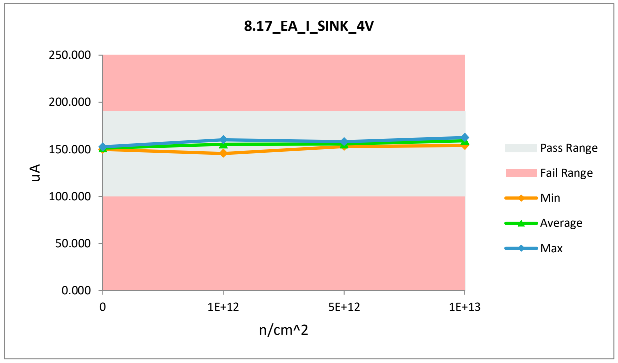


NDD Characterization Report
TPS7H5006-SEP

		8.17_EA_I_SINK_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	150.057	149.967	-0.090
0	49	152.578	152.557	-0.021
1E+12	11	160.076	160.111	0.035
1E+12	12	160.508	160.277	-0.231
1E+12	13	145.723	145.714	-0.009
5E+12	14	153.247	152.954	-0.293
5E+12	15	157.343	158.062	0.719
5E+12	16	156.063	155.519	-0.544
1E+13	17	153.672	154.079	0.407
1E+13	18	161.437	162.594	1.157
1E+13	19	160.762	160.586	-0.176
	Max	161.437	162.594	1.157
	Average	155.588	155.675	0.087
	Min	145.723	145.714	-0.544
	Std Dev	5.047	5.197	0.491

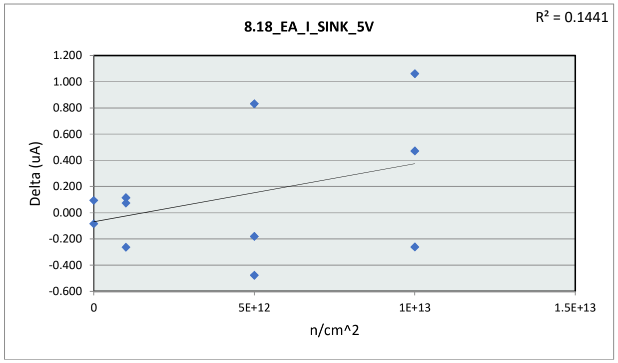


	8.17_EA_I_SINK_4V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	149.967	145.714	152.954	154.079
Average	151.262	155.367	155.512	159.086
Max	152.557	160.277	158.062	162.594
UL	190.000	190.000	190.000	190.000

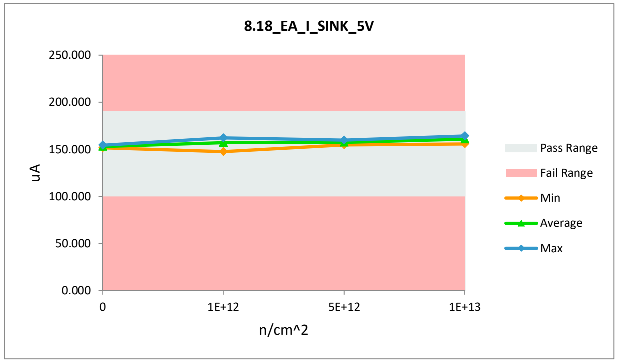


NDD Characterization Report
TPS7H5006-SEP

		8.18_EA_I_SINK_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	151.743	151.658	-0.085
0	49	154.421	154.514	0.093
1E+12	11	161.878	161.992	0.114
1E+12	12	162.402	162.138	-0.264
1E+12	13	147.551	147.624	0.073
5E+12	14	154.952	154.770	-0.182
5E+12	15	159.082	159.913	0.831
5E+12	16	157.921	157.443	-0.478
1E+13	17	155.422	155.892	0.470
1E+13	18	163.339	164.399	1.060
1E+13	19	162.627	162.364	-0.263
	Max	163.339	164.399	1.060
	Average	157.394	157.519	0.124
	Min	147.551	147.624	-0.478
	Std Dev	5.085	5.190	0.480

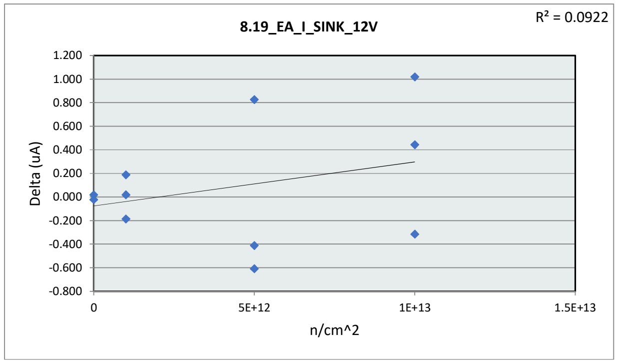


	8.18_EA_I_SINK_5V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	151.658	147.624	154.770	155.892
Average	153.086	157.251	157.375	160.885
Max	154.514	162.138	159.913	164.399
UL	190.000	190.000	190.000	190.000

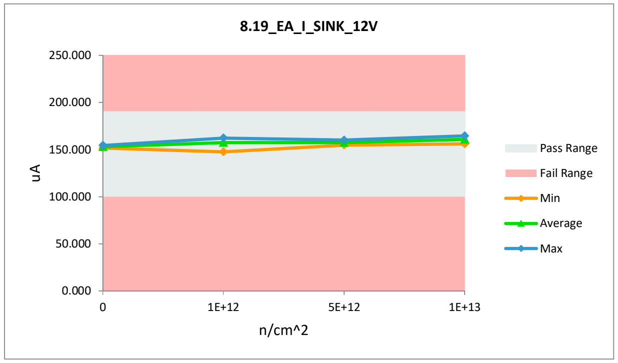


NDD Characterization Report
TPS7H5006-SEP

		8.19_EA_I_SINK_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	151.742	151.719	-0.023
0	49	154.449	154.467	0.018
1E+12	11	162.065	162.252	0.187
1E+12	12	162.394	162.207	-0.187
1E+12	13	147.642	147.660	0.018
5E+12	14	155.085	154.672	-0.413
5E+12	15	159.144	159.969	0.825
5E+12	16	158.073	157.463	-0.610
1E+13	17	155.482	155.925	0.443
1E+13	18	163.457	164.474	1.017
1E+13	19	162.693	162.377	-0.316
	Max	163.457	164.474	1.017
	Average	157.475	157.562	0.087
	Min	147.642	147.660	-0.610
	Std Dev	5.097	5.226	0.504

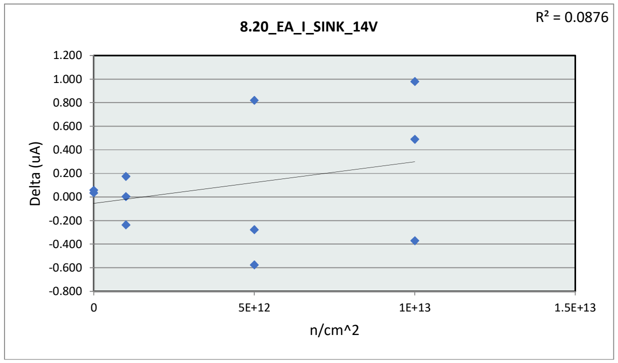


	8.19_EA_I_SINK_12V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	151.719	147.660	154.672	155.925
Average	153.093	157.373	157.368	160.925
Max	154.467	162.252	159.969	164.474
UL	190.000	190.000	190.000	190.000

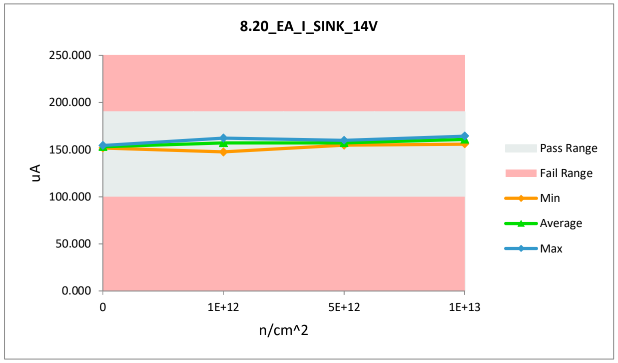


NDD Characterization Report
TPS7H5006-SEP

		8.20_EA_I_SINK_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	185	190	
	Min Limit	105	100	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	151.674	151.708	0.034
0	49	154.378	154.435	0.057
1E+12	11	161.895	162.069	0.174
1E+12	12	162.303	162.065	-0.238
1E+12	13	147.525	147.528	0.003
5E+12	14	154.829	154.550	-0.279
5E+12	15	158.971	159.790	0.819
5E+12	16	157.938	157.361	-0.577
1E+13	17	155.418	155.906	0.488
1E+13	18	163.370	164.348	0.978
1E+13	19	162.623	162.251	-0.372
	Max	163.370	164.348	0.978
	Average	157.357	157.456	0.099
	Min	147.525	147.528	-0.577
	Std Dev	5.098	5.197	0.490

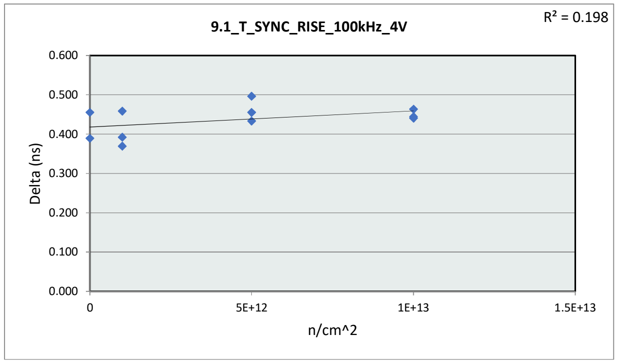


	8.20_EA_I_SINK_14V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	151.708	147.528	154.550	155.906
Average	153.072	157.221	157.234	160.835
Max	154.435	162.069	159.790	164.348
UL	190.000	190.000	190.000	190.000

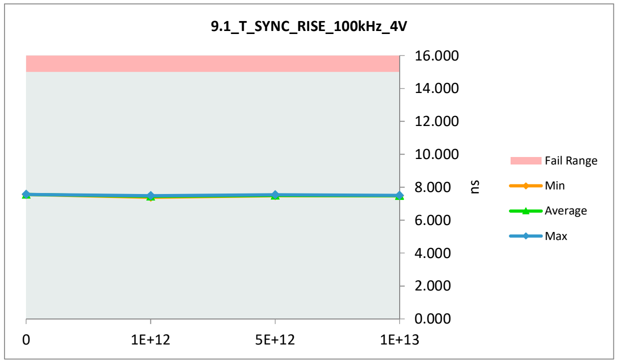


NDD Characterization Report
TPS7H5006-SEP

		9.1_T_SYNC_RISE_100kHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14.5	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.117	7.572	0.455
0	49	7.166	7.555	0.389
1E+12	11	7.055	7.447	0.392
1E+12	12	7.013	7.382	0.369
1E+12	13	7.036	7.494	0.458
5E+12	14	7.062	7.495	0.433
5E+12	15	7.019	7.474	0.455
5E+12	16	7.047	7.543	0.496
1E+13	17	7.044	7.507	0.463
1E+13	18	7.059	7.499	0.440
1E+13	19	7.040	7.484	0.444
	Max	7.166	7.572	0.496
	Average	7.060	7.496	0.436
	Min	7.013	7.382	0.369
	Std Dev	0.045	0.053	0.038

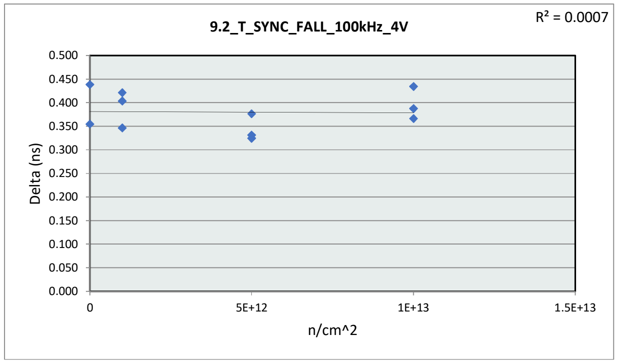


	9.1_T_SYNC_RISE_100kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.555	7.382	7.474	7.484
Average	7.564	7.441	7.504	7.497
Max	7.572	7.494	7.543	7.507
UL	15.000	15.000	15.000	15.000

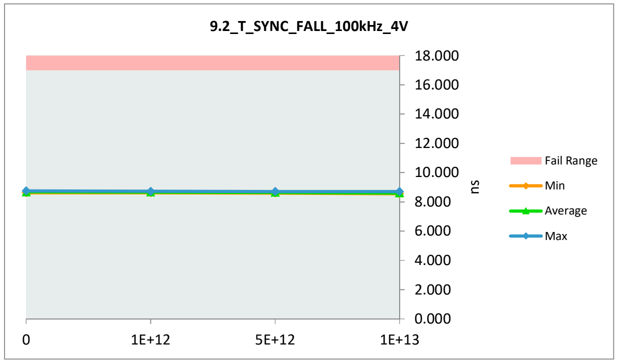


NDD Characterization Report
TPS7H5006-SEP

		9.2_T_SYNC_FALL_100kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14.5	17	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.267	8.621	0.354
0	49	8.302	8.740	0.438
1E+12	11	8.200	8.621	0.421
1E+12	12	8.289	8.635	0.346
1E+12	13	8.317	8.720	0.403
5E+12	14	8.291	8.622	0.331
5E+12	15	8.331	8.707	0.376
5E+12	16	8.279	8.603	0.324
1E+13	17	8.119	8.553	0.434
1E+13	18	8.322	8.709	0.387
1E+13	19	8.188	8.554	0.366
	Max	8.331	8.740	0.438
	Average	8.264	8.644	0.380
	Min	8.119	8.553	0.324
	Std Dev	0.067	0.065	0.040

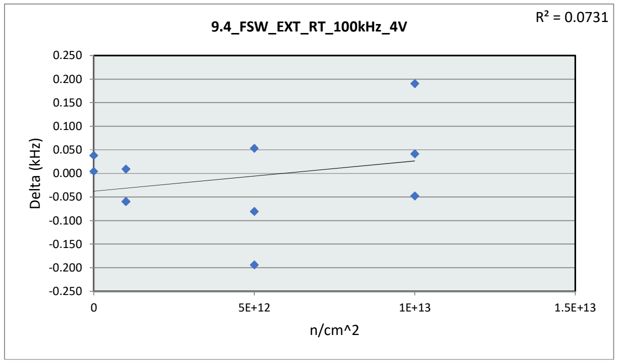


	9.2_T_SYNC_FALL_100kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17 ns			
Min Limit	ns			
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.621	8.621	8.603	8.553
Average	8.681	8.659	8.644	8.605
Max	8.740	8.720	8.707	8.709
UL	17.000	17.000	17.000	17.000

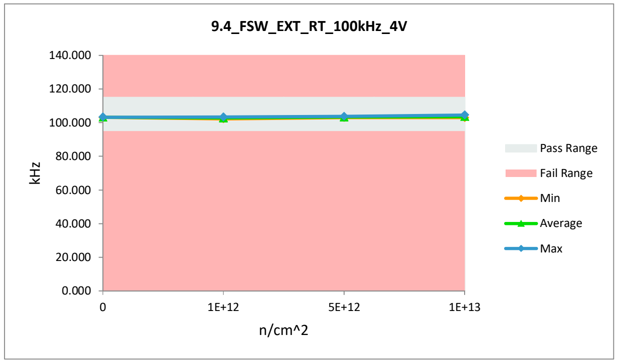


NDD Characterization Report
TPS7H5006-SEP

		9.4_FSW_EXT_RT_100kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	115	115	
	Min Limit	95	95	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	103.279	103.283	0.004
0	49	103.068	103.106	0.038
1E+12	11	102.574	102.583	0.009
1E+12	12	102.348	102.288	-0.060
1E+12	13	103.353	103.293	-0.060
5E+12	14	103.185	102.991	-0.194
5E+12	15	103.060	103.113	0.053
5E+12	16	103.854	103.773	-0.081
1E+13	17	102.838	103.028	0.190
1E+13	18	103.105	103.146	0.041
1E+13	19	104.658	104.610	-0.048
	Max	104.658	104.610	0.190
	Average	103.211	103.201	-0.010
	Min	102.348	102.288	-0.194
	Std Dev	0.623	0.603	0.097

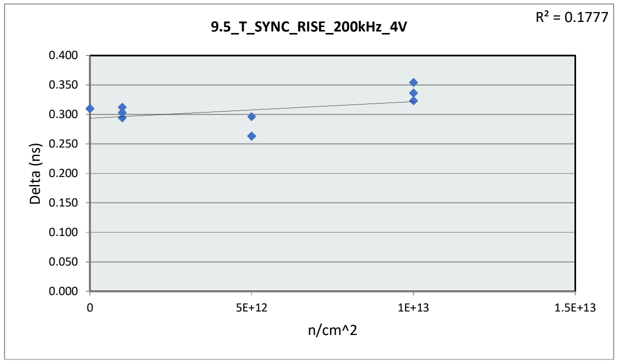


	9.4_FSW_EXT_RT_100kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.106	102.288	102.991	103.028
Average	103.195	102.721	103.292	103.595
Max	103.283	103.293	103.773	104.610
UL	115.000	115.000	115.000	115.000

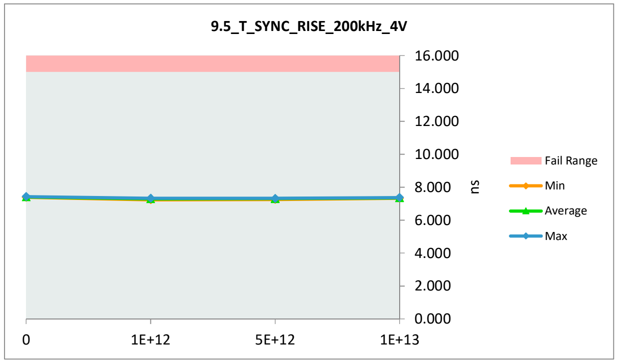


NDD Characterization Report
TPS7H5006-SEP

		9.5_T_SYNC_RISE_200kHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14.5	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.079	7.388	0.309
0	49	7.125	7.435	0.310
1E+12	11	7.015	7.309	0.294
1E+12	12	6.921	7.233	0.312
1E+12	13	7.025	7.328	0.303
5E+12	14	7.056	7.319	0.263
5E+12	15	6.965	7.261	0.296
5E+12	16	7.059	7.322	0.263
1E+13	17	6.990	7.326	0.336
1E+13	18	7.018	7.341	0.323
1E+13	19	7.016	7.370	0.354
	Max	7.125	7.435	0.354
	Average	7.024	7.330	0.306
	Min	6.921	7.233	0.263
	Std Dev	0.056	0.056	0.027

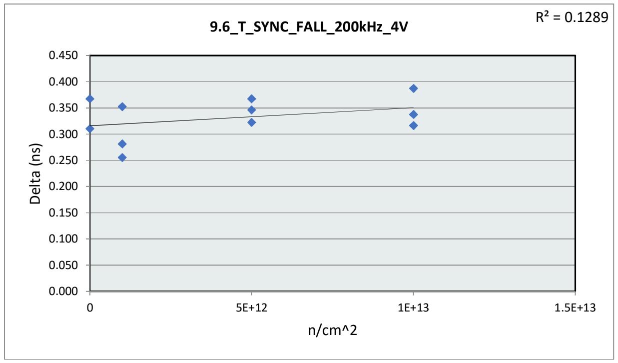


	9.5_T_SYNC_RISE_200kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.388	7.233	7.261	7.326
Average	7.412	7.290	7.301	7.346
Max	7.435	7.328	7.322	7.370
UL	15.000	15.000	15.000	15.000

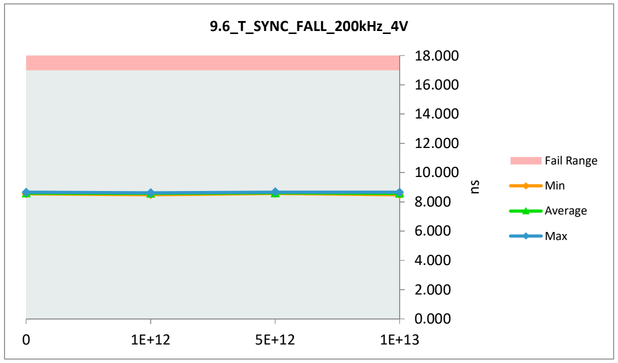


NDD Characterization Report
TPS7H5006-SEP

		9.6_T_SYNC_FALL_200kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.234	8.544	0.310
0	49	8.288	8.655	0.367
1E+12	11	8.244	8.596	0.352
1E+12	12	8.244	8.499	0.255
1E+12	13	8.328	8.609	0.281
5E+12	14	8.255	8.577	0.322
5E+12	15	8.305	8.672	0.367
5E+12	16	8.251	8.597	0.346
1E+13	17	8.163	8.479	0.316
1E+13	18	8.319	8.656	0.337
1E+13	19	8.175	8.562	0.387
	Max	8.328	8.672	0.387
	Average	8.255	8.586	0.331
	Min	8.163	8.479	0.255
	Std Dev	0.053	0.063	0.039

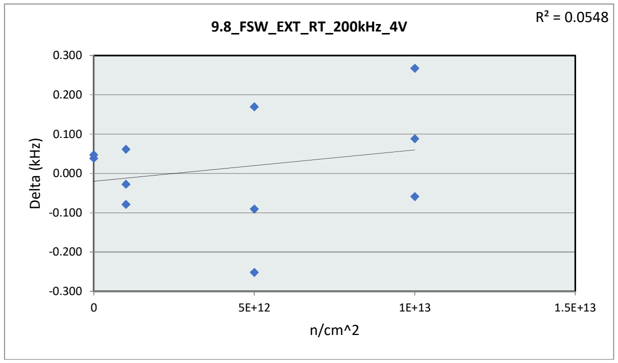


	9.6_T_SYNC_FALL_200kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.544	8.499	8.577	8.479
Average	8.600	8.568	8.615	8.566
Max	8.655	8.609	8.672	8.656
UL	17.000	17.000	17.000	17.000

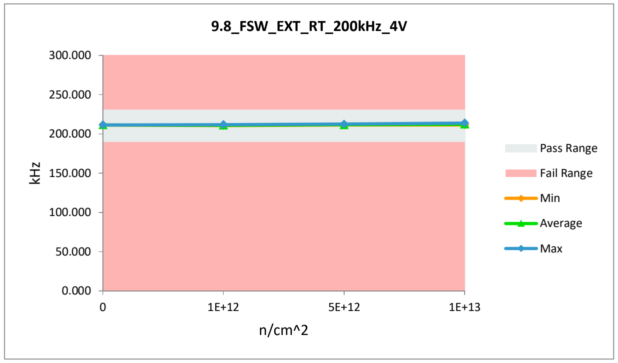


NDD Characterization Report
TPS7H5006-SEP

		9.8_FSW_EXT_RT_200kHz_4V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		230	230	
Min Limit		190	190	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	211.430	211.477	0.047
0	49	211.292	211.330	0.038
1E+12	11	210.469	210.530	0.061
1E+12	12	210.491	210.463	-0.028
1E+12	13	211.763	211.684	-0.079
5E+12	14	211.622	211.370	-0.252
5E+12	15	211.251	211.420	0.169
5E+12	16	212.520	212.429	-0.091
1E+13	17	211.269	211.536	0.267
1E+13	18	211.444	211.532	0.088
1E+13	19	213.855	213.796	-0.059
	Max	213.855	213.796	0.267
	Average	211.582	211.597	0.015
	Min	210.469	210.463	-0.252
	Std Dev	0.940	0.902	0.140

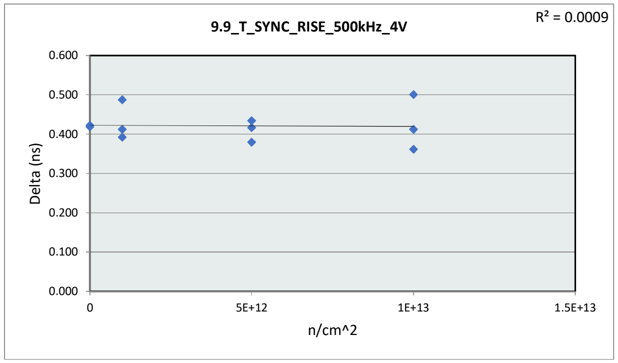


	9.8_FSW_EXT_RT_200kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	211.330	210.463	211.370	211.532
Average	211.404	210.892	211.740	212.288
Max	211.477	211.684	212.429	213.796
UL	230.000	230.000	230.000	230.000

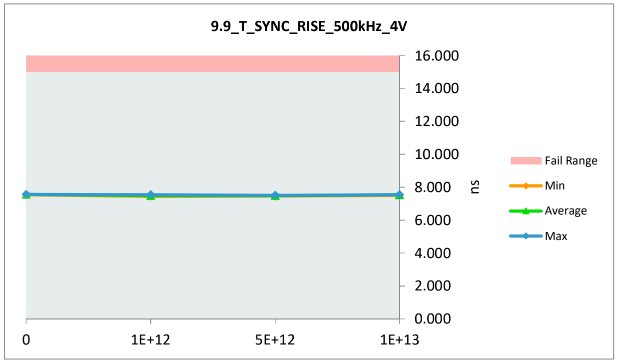


NDD Characterization Report
TPS7H5006-SEP

		9.9_T_SYNC_RISE_500kHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14.5	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.147	7.565	0.418
0	49	7.128	7.550	0.422
1E+12	11	7.091	7.483	0.392
1E+12	12	7.040	7.452	0.412
1E+12	13	7.046	7.533	0.487
5E+12	14	7.078	7.512	0.434
5E+12	15	7.044	7.460	0.416
5E+12	16	7.109	7.488	0.379
1E+13	17	7.144	7.505	0.361
1E+13	18	7.053	7.553	0.500
1E+13	19	7.134	7.546	0.412
	Max	7.147	7.565	0.500
	Average	7.092	7.513	0.421
	Min	7.040	7.452	0.361
	Std Dev	0.042	0.039	0.041

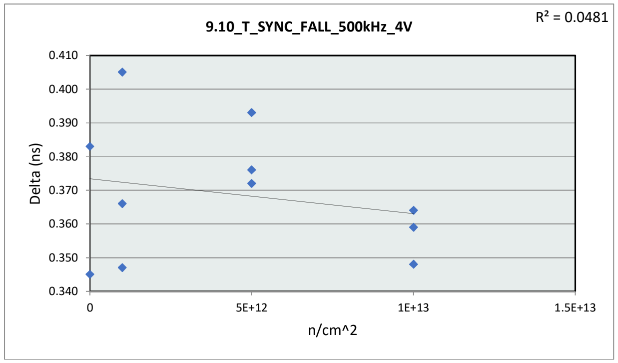


	9.9_T_SYNC_RISE_500kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.550	7.452	7.460	7.505
Average	7.558	7.489	7.487	7.535
Max	7.565	7.533	7.512	7.553
UL	15.000	15.000	15.000	15.000

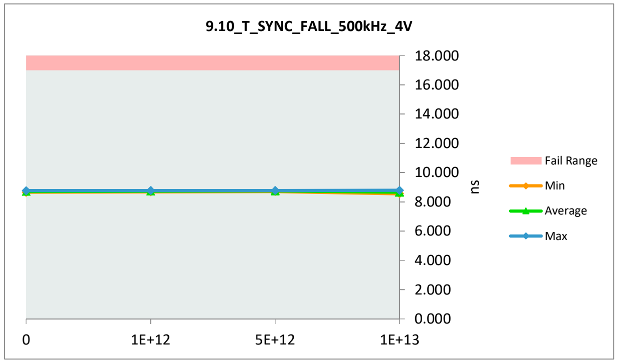


NDD Characterization Report
TPS7H5006-SEP

		9.10_T_SYNC_FALL_500kHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.305	8.650	0.345
0	49	8.377	8.760	0.383
1E+12	11	8.272	8.677	0.405
1E+12	12	8.377	8.724	0.347
1E+12	13	8.408	8.774	0.366
5E+12	14	8.359	8.752	0.393
5E+12	15	8.391	8.763	0.372
5E+12	16	8.324	8.700	0.376
1E+13	17	8.209	8.557	0.348
1E+13	18	8.424	8.783	0.359
1E+13	19	8.268	8.632	0.364
	Max	8.424	8.783	0.405
	Average	8.338	8.707	0.369
	Min	8.209	8.557	0.345
	Std Dev	0.068	0.071	0.019

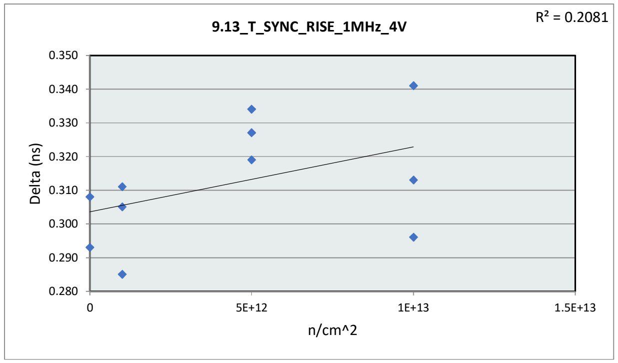


	9.10_T_SYNC_FALL_500kHz_4			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.650	8.677	8.700	8.557
Average	8.705	8.725	8.738	8.657
Max	8.760	8.774	8.763	8.783
UL	17.000	17.000	17.000	17.000

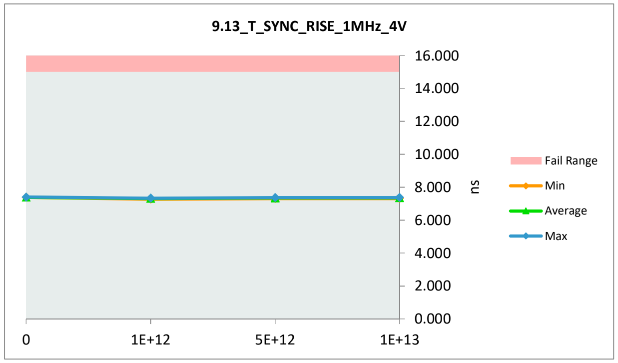


NDD Characterization Report
TPS7H5006-SEP

		9.13_T_SYNC_RISE_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14.5	15	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.090	7.383	0.293
0	49	7.090	7.398	0.308
1E+12	11	7.042	7.327	0.285
1E+12	12	6.975	7.280	0.305
1E+12	13	7.028	7.339	0.311
5E+12	14	7.035	7.354	0.319
5E+12	15	6.965	7.299	0.334
5E+12	16	7.037	7.364	0.327
1E+13	17	7.063	7.376	0.313
1E+13	18	7.018	7.314	0.296
1E+13	19	7.038	7.379	0.341
	Max	7.090	7.398	0.341
	Average	7.035	7.347	0.312
	Min	6.965	7.280	0.285
	Std Dev	0.040	0.038	0.017

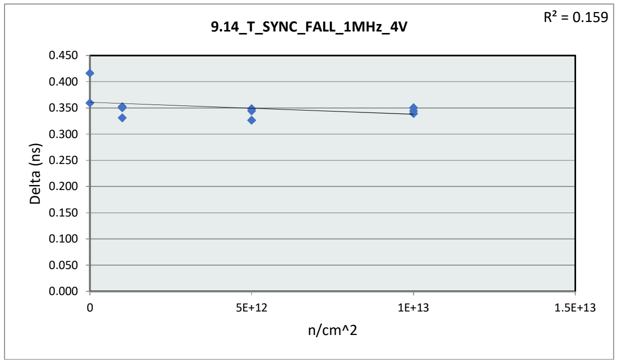


	9.13_T_SYNC_RISE_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.383	7.280	7.299	7.314
Average	7.391	7.315	7.339	7.356
Max	7.398	7.339	7.364	7.379
UL	15.000	15.000	15.000	15.000

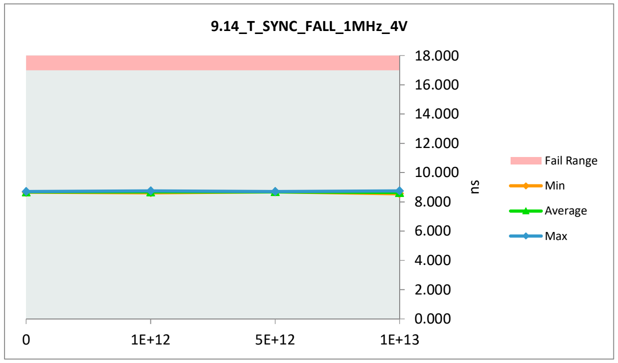


NDD Characterization Report
TPS7H5006-SEP

		9.14_T_SYNC_FALL_1MHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.233	8.649	0.416
0	49	8.341	8.700	0.359
1E+12	11	8.278	8.628	0.350
1E+12	12	8.319	8.671	0.352
1E+12	13	8.410	8.741	0.331
5E+12	14	8.339	8.687	0.348
5E+12	15	8.381	8.707	0.326
5E+12	16	8.335	8.679	0.344
1E+13	17	8.212	8.556	0.344
1E+13	18	8.401	8.740	0.339
1E+13	19	8.246	8.596	0.350
	Max	8.410	8.741	0.416
	Average	8.318	8.669	0.351
	Min	8.212	8.556	0.326
	Std Dev	0.068	0.058	0.024

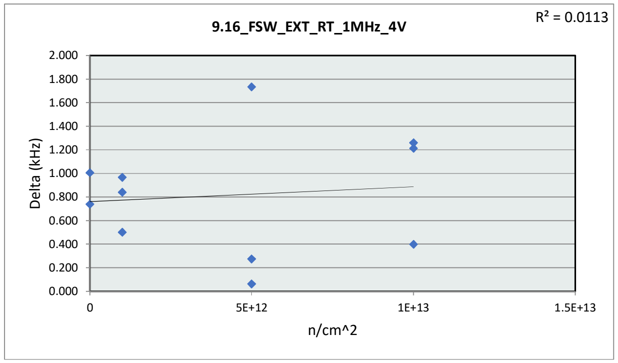


9.14_T_SYNC_FALL_1MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.649	8.628	8.679	8.556
Average	8.675	8.680	8.691	8.631
Max	8.700	8.741	8.707	8.740
UL	17.000	17.000	17.000	17.000

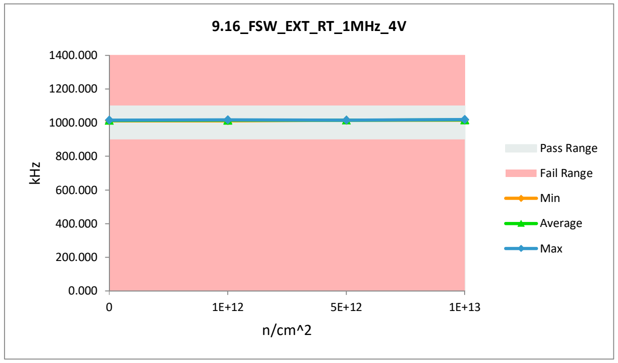


NDD Characterization Report
TPS7H5006-SEP

		9.16_FSW_EXT_RT_1MHz_4V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		1100	1100	
Min Limit		900	900	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1010.364	1011.101	0.737
0	49	1014.509	1015.513	1.004
1E+12	11	1010.436	1011.274	0.838
1E+12	12	1013.306	1014.271	0.965
1E+12	13	1015.233	1015.733	0.500
5E+12	14	1013.513	1013.575	0.062
5E+12	15	1013.653	1015.385	1.732
5E+12	16	1015.091	1015.365	0.274
1E+13	17	1014.036	1015.248	1.212
1E+13	18	1014.634	1015.893	1.259
1E+13	19	1018.260	1018.657	0.397
	Max	1018.260	1018.657	1.732
	Average	1013.912	1014.729	0.816
	Min	1010.364	1011.101	0.062
	Std Dev	2.195	2.148	0.489

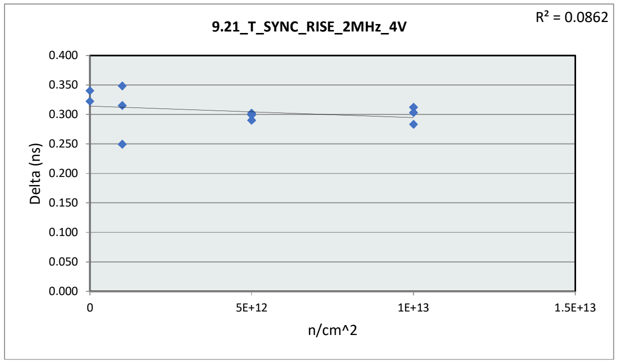


9.16_FSW_EXT_RT_1MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1011.101	1011.274	1013.575	1015.248
Average	1013.307	1013.759	1014.775	1016.599
Max	1015.513	1015.733	1015.385	1018.657
UL	1100.000	1100.000	1100.000	1100.000

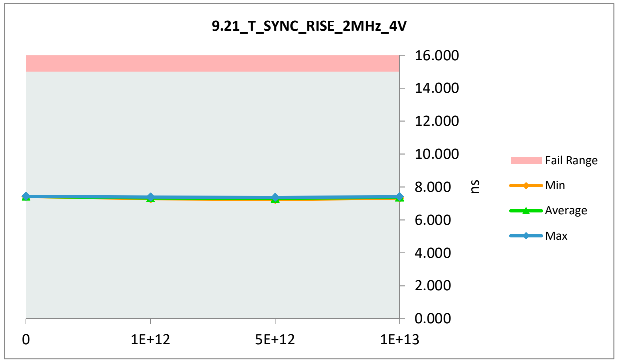


NDD Characterization Report
TPS7H5006-SEP

		9.21_T_SYNC_RISE_2MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.091	7.431	0.340
0	49	7.102	7.424	0.322
1E+12	11	7.069	7.384	0.315
1E+12	12	6.959	7.307	0.348
1E+12	13	7.031	7.280	0.249
5E+12	14	7.058	7.360	0.302
5E+12	15	6.947	7.237	0.290
5E+12	16	7.032	7.331	0.299
1E+13	17	7.096	7.408	0.312
1E+13	18	7.048	7.331	0.283
1E+13	19	7.095	7.398	0.303
	Max	7.102	7.431	0.348
	Average	7.048	7.354	0.306
	Min	6.947	7.237	0.249
	Std Dev	0.053	0.062	0.027

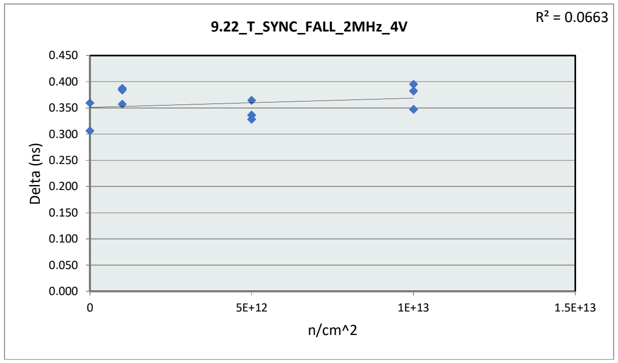


	9.21_T_SYNC_RISE_2MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.424	7.280	7.237	7.331
Average	7.428	7.324	7.309	7.379
Max	7.431	7.384	7.360	7.408
UL	15.000	15.000	15.000	15.000

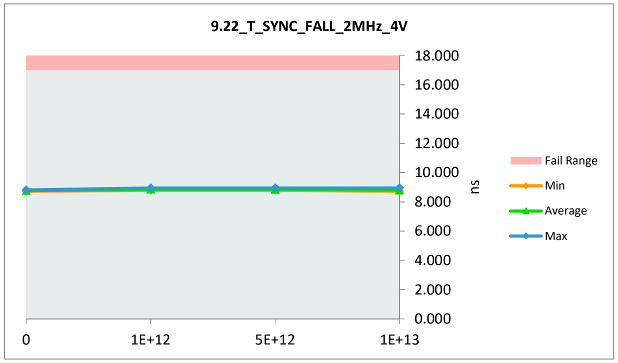


NDD Characterization Report
TPS7H5006-SEP

		9.22_T_SYNC_FALL_2MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.363	8.722	0.359
0	49	8.501	8.807	0.306
1E+12	11	8.439	8.796	0.357
1E+12	12	8.484	8.871	0.387
1E+12	13	8.551	8.935	0.384
5E+12	14	8.461	8.797	0.336
5E+12	15	8.585	8.949	0.364
5E+12	16	8.468	8.796	0.328
1E+13	17	8.369	8.751	0.382
1E+13	18	8.553	8.948	0.395
1E+13	19	8.382	8.729	0.347
	Max	8.585	8.949	0.395
	Average	8.469	8.827	0.359
	Min	8.363	8.722	0.306
	Std Dev	0.076	0.085	0.028

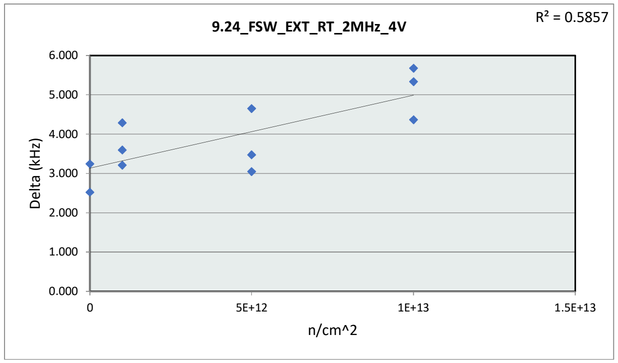


	9.22_T_SYNC_FALL_2MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17 ns			
Min Limit	ns			
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.722	8.796	8.796	8.729
Average	8.765	8.867	8.847	8.809
Max	8.807	8.935	8.949	8.948
UL	17.000	17.000	17.000	17.000

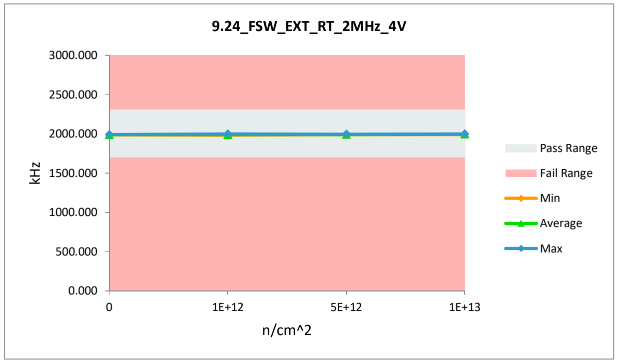


NDD Characterization Report
TPS7H5006-SEP

		9.24_FSW_EXT_RT_2MHz_4V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		2300	2300	
Min Limit		1700	1700	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1988.291	1990.807	2.516
0	49	1984.655	1987.895	3.240
1E+12	11	1978.903	1982.107	3.204
1E+12	12	1985.352	1989.635	4.283
1E+12	13	1995.899	1999.490	3.591
5E+12	14	1992.487	1995.531	3.044
5E+12	15	1985.544	1990.191	4.647
5E+12	16	1989.406	1992.874	3.468
1E+13	17	1986.200	1991.869	5.669
1E+13	18	1994.020	1999.351	5.331
1E+13	19	1990.826	1995.187	4.361
	Max	1995.899	1999.490	5.669
	Average	1988.326	1992.267	3.941
	Min	1978.903	1982.107	2.516
	Std Dev	4.877	5.077	0.996

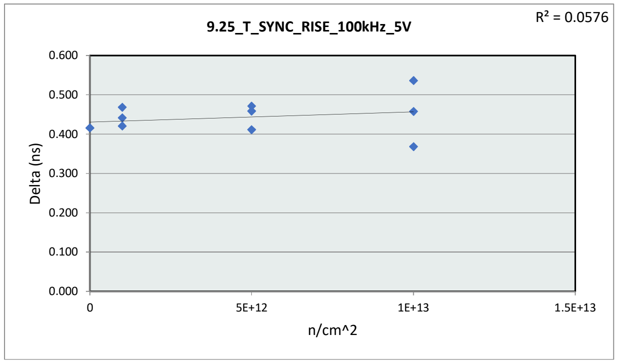


9.24_FSW_EXT_RT_2MHz_4V				
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	1987.895	1982.107	1990.191	1991.869
Average	1989.351	1990.411	1992.865	1995.469
Max	1990.807	1999.490	1995.531	1999.351
UL	2300.000	2300.000	2300.000	2300.000

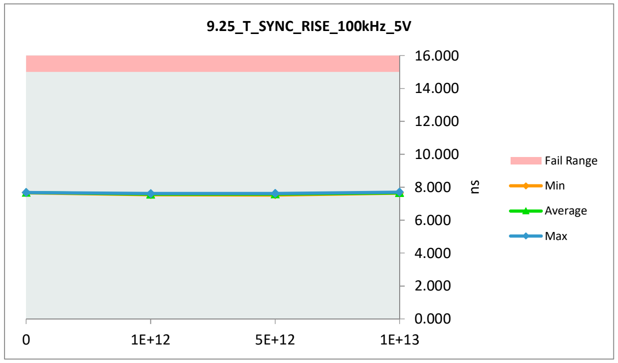


NDD Characterization Report
TPS7H5006-SEP

		9.25_T_SYNC_RISE_100kHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.253	7.668	0.415
0	49	7.266	7.681	0.415
1E+12	11	7.145	7.613	0.468
1E+12	12	7.111	7.552	0.441
1E+12	13	7.144	7.564	0.420
5E+12	14	7.163	7.621	0.458
5E+12	15	7.122	7.533	0.411
5E+12	16	7.145	7.616	0.471
1E+13	17	7.163	7.699	0.536
1E+13	18	7.185	7.642	0.457
1E+13	19	7.277	7.645	0.368
	Max	7.277	7.699	0.536
	Average	7.179	7.621	0.442
	Min	7.111	7.533	0.368
	Std Dev	0.059	0.054	0.044

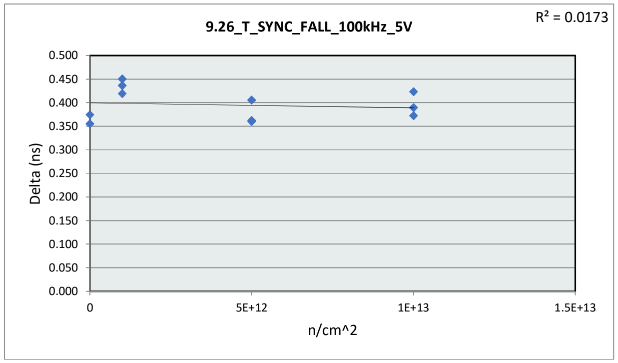


	9.25_T_SYNC_RISE_100kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.668	7.552	7.533	7.642
Average	7.675	7.576	7.590	7.662
Max	7.681	7.613	7.621	7.699
UL	15.000	15.000	15.000	15.000

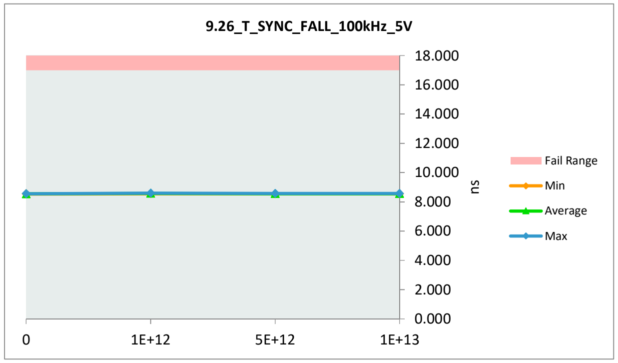


NDD Characterization Report
TPS7H5006-SEP

		9.26_T_SYNC_FALL_100kHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.185	8.540	0.355
0	49	8.183	8.557	0.374
1E+12	11	8.126	8.562	0.436
1E+12	12	8.177	8.596	0.419
1E+12	13	8.137	8.587	0.450
5E+12	14	8.188	8.548	0.360
5E+12	15	8.204	8.566	0.362
5E+12	16	8.162	8.567	0.405
1E+13	17	8.155	8.578	0.423
1E+13	18	8.171	8.560	0.389
1E+13	19	8.175	8.547	0.372
	Max	8.204	8.596	0.450
	Average	8.169	8.564	0.395
	Min	8.126	8.540	0.355
	Std Dev	0.023	0.017	0.033

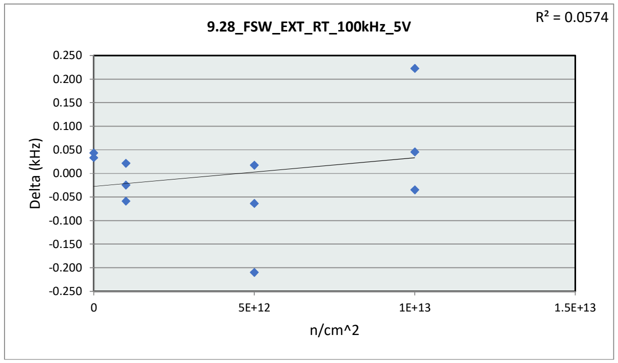


	9.26_T_SYNC_FALL_100kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.540	8.562	8.548	8.547
Average	8.549	8.582	8.560	8.562
Max	8.557	8.596	8.567	8.578
UL	17.000	17.000	17.000	17.000

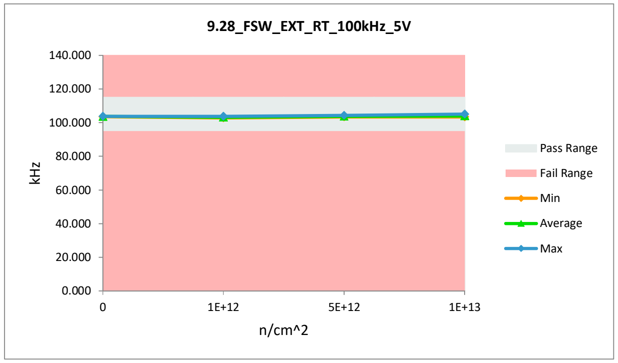


NDD Characterization Report
TPS7H5006-SEP

		9.28_FSW_EXT_RT_100kHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	115	115	
	Min Limit	95	95	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	103.778	103.811	0.033
0	49	103.521	103.564	0.043
1E+12	11	103.048	103.069	0.021
1E+12	12	102.846	102.821	-0.025
1E+12	13	103.830	103.771	-0.059
5E+12	14	103.665	103.455	-0.210
5E+12	15	103.540	103.557	0.017
5E+12	16	104.376	104.312	-0.064
1E+13	17	103.259	103.481	0.222
1E+13	18	103.544	103.589	0.045
1E+13	19	105.093	105.058	-0.035
	Max	105.093	105.058	0.222
	Average	103.682	103.681	-0.001
	Min	102.846	102.821	-0.210
	Std Dev	0.620	0.597	0.104

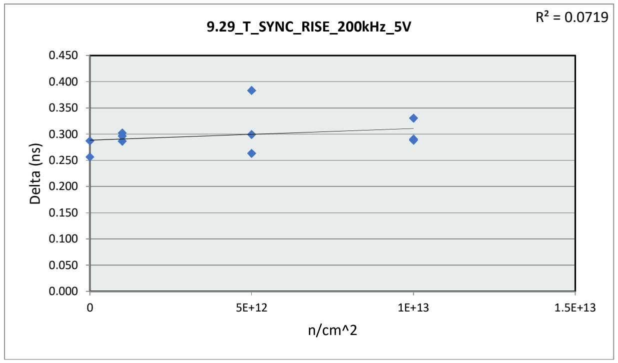


	9.28_FSW_EXT_RT_100kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.564	102.821	103.455	103.481
Average	103.688	103.220	103.775	104.043
Max	103.811	103.771	104.312	105.058
UL	115.000	115.000	115.000	115.000

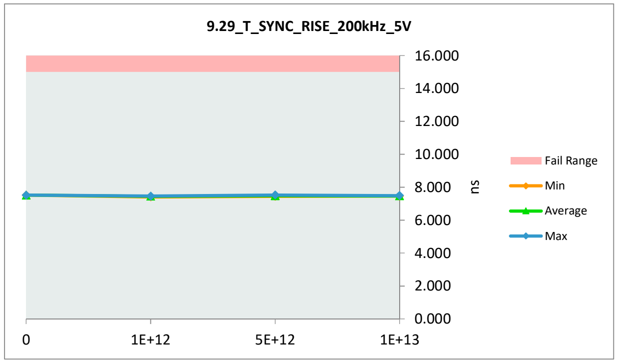


NDD Characterization Report
TPS7H5006-SEP

		9.29_T_SYNC_RISE_200kHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.264	7.520	0.256
0	49	7.232	7.519	0.287
1E+12	11	7.155	7.451	0.296
1E+12	12	7.109	7.411	0.302
1E+12	13	7.172	7.458	0.286
5E+12	14	7.158	7.457	0.299
5E+12	15	7.145	7.528	0.383
5E+12	16	7.181	7.444	0.263
1E+13	17	7.183	7.473	0.290
1E+13	18	7.163	7.451	0.288
1E+13	19	7.165	7.495	0.330
	Max	7.264	7.528	0.383
	Average	7.175	7.473	0.298
	Min	7.109	7.411	0.256
	Std Dev	0.042	0.037	0.034



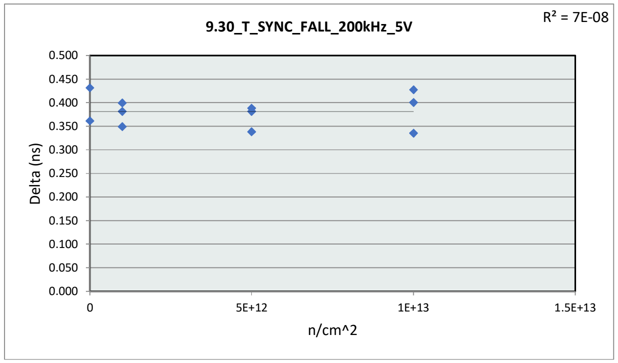
	9.29_T_SYNC_RISE_200kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.519	7.411	7.444	7.451
Average	7.520	7.440	7.476	7.473
Max	7.520	7.458	7.528	7.495
UL	15.000	15.000	15.000	15.000



NDD Characterization Report
TPS7H5006-SEP

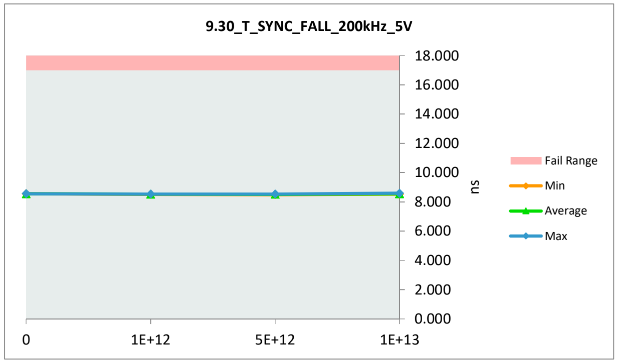
	9.30_T_SYNC_FALL_200kHz_5V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	14	17
Min Limit	0	

n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.123	8.554	0.431
0	49	8.190	8.551	0.361
1E+12	11	8.184	8.533	0.349
1E+12	12	8.121	8.502	0.381
1E+12	13	8.117	8.516	0.399
5E+12	14	8.149	8.537	0.388
5E+12	15	8.155	8.493	0.338
5E+12	16	8.122	8.503	0.381
1E+13	17	8.135	8.535	0.400
1E+13	18	8.160	8.587	0.427
1E+13	19	8.190	8.525	0.335
	Max	8.190	8.587	0.431
	Average	8.150	8.531	0.381
	Min	8.117	8.493	0.335
	Std Dev	0.029	0.027	0.033



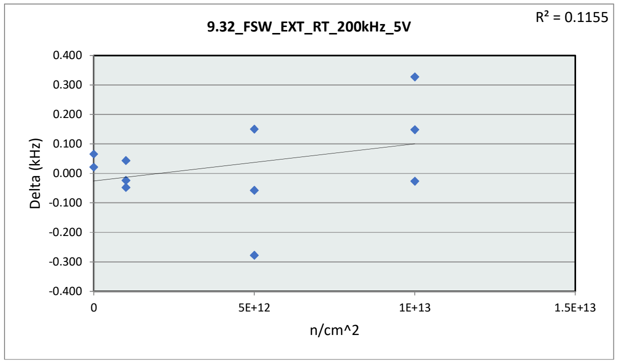
	9.30_T_SYNC_FALL_200kHz_5	
Test Site		
Tester		
Test Number		
Max Limit	17	ns
Min Limit		ns

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.551	8.502	8.493	8.525
Average	8.553	8.517	8.511	8.549
Max	8.554	8.533	8.537	8.587
UL	17.000	17.000	17.000	17.000

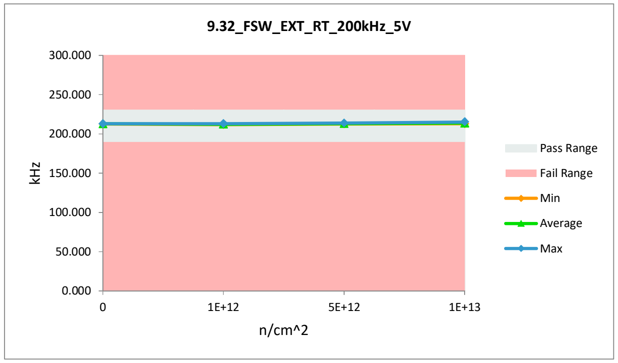


NDD Characterization Report
TPS7H5006-SEP

		9.32_FSW_EXT_RT_200kHz_5V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		230	230	
Min Limit		190	190	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	212.889	212.910	0.021
0	49	212.633	212.698	0.065
1E+12	11	211.870	211.913	0.043
1E+12	12	211.954	211.930	-0.024
1E+12	13	213.135	213.087	-0.048
5E+12	14	212.972	212.694	-0.278
5E+12	15	212.617	212.767	0.150
5E+12	16	214.018	213.960	-0.058
1E+13	17	212.598	212.925	0.327
1E+13	18	212.723	212.871	0.148
1E+13	19	215.224	215.197	-0.027
	Max	215.224	215.197	0.327
	Average	212.967	212.996	0.029
	Min	211.870	211.913	-0.278
	Std Dev	0.943	0.914	0.153

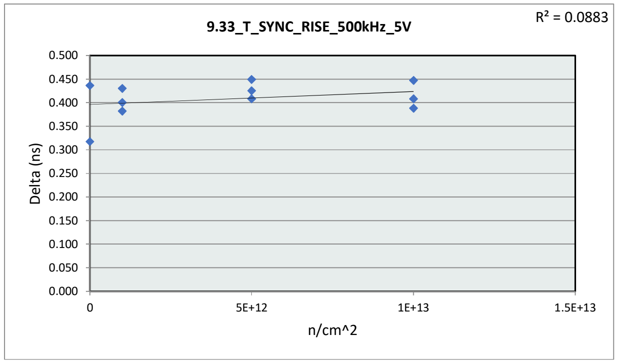


	9.32_FSW_EXT_RT_200kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	212.698	211.913	212.694	212.871
Average	212.804	212.310	213.140	213.664
Max	212.910	213.087	213.960	215.197
UL	230.000	230.000	230.000	230.000

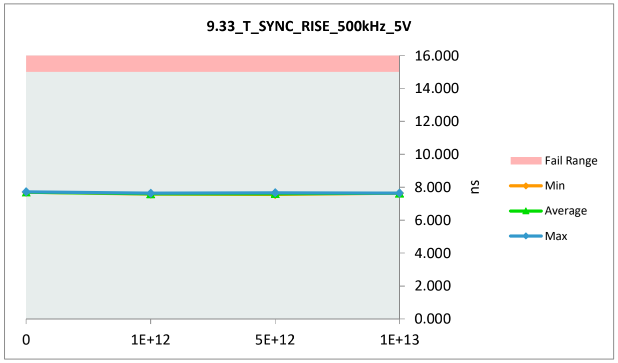


NDD Characterization Report
TPS7H5006-SEP

		9.33_T_SYNC_RISE_500kHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.279	7.715	0.436
0	49	7.374	7.691	0.317
1E+12	11	7.201	7.631	0.430
1E+12	12	7.180	7.580	0.400
1E+12	13	7.196	7.578	0.382
5E+12	14	7.200	7.649	0.449
5E+12	15	7.146	7.554	0.408
5E+12	16	7.204	7.629	0.425
1E+13	17	7.197	7.644	0.447
1E+13	18	7.245	7.633	0.388
1E+13	19	7.226	7.634	0.408
	Max	7.374	7.715	0.449
	Average	7.223	7.631	0.408
	Min	7.146	7.554	0.317
	Std Dev	0.061	0.047	0.038

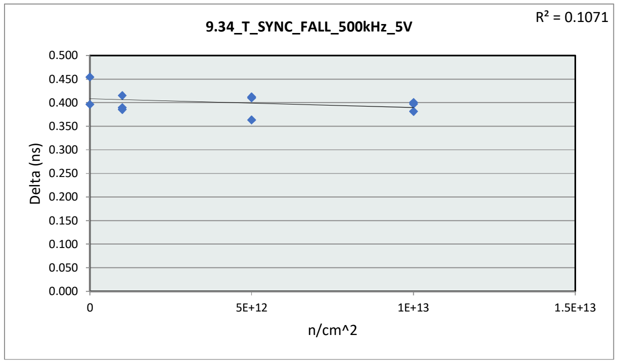


	9.33_T_SYNC_RISE_500kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.691	7.578	7.554	7.633
Average	7.703	7.596	7.611	7.637
Max	7.715	7.631	7.649	7.644
UL	15.000	15.000	15.000	15.000

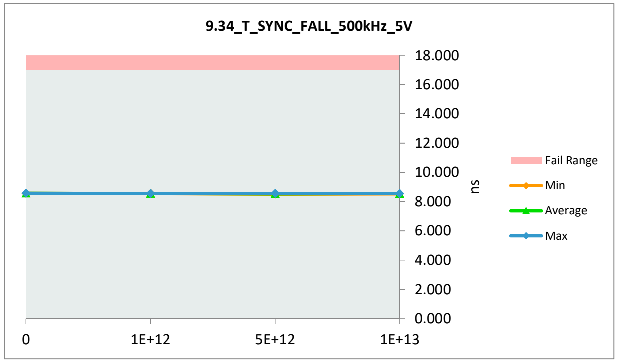


NDD Characterization Report
TPS7H5006-SEP

		9.34_T_SYNC_FALL_500kHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.122	8.576	0.454
0	49	8.174	8.570	0.396
1E+12	11	8.161	8.550	0.389
1E+12	12	8.165	8.550	0.385
1E+12	13	8.148	8.563	0.415
5E+12	14	8.150	8.562	0.412
5E+12	15	8.149	8.512	0.363
5E+12	16	8.131	8.541	0.410
1E+13	17	8.131	8.528	0.397
1E+13	18	8.160	8.541	0.381
1E+13	19	8.150	8.550	0.400
	Max	8.174	8.576	0.454
	Average	8.149	8.549	0.400
	Min	8.122	8.512	0.363
	Std Dev	0.016	0.019	0.023

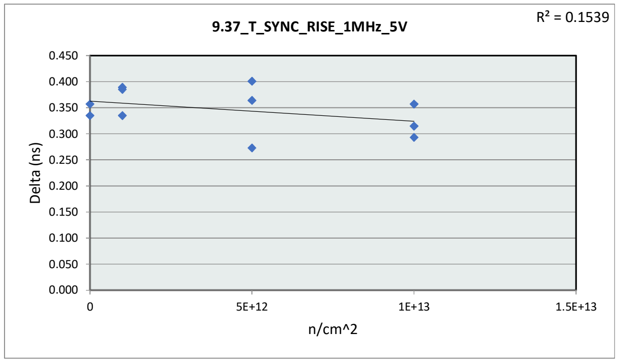


	9.34_T_SYNC_FALL_500kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.570	8.550	8.512	8.528
Average	8.573	8.554	8.538	8.540
Max	8.576	8.563	8.562	8.550
UL	17.000	17.000	17.000	17.000

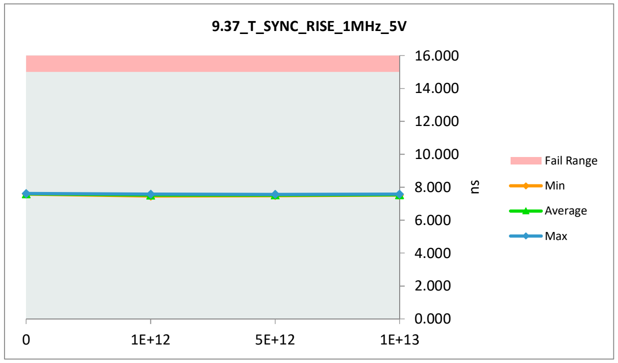


NDD Characterization Report
TPS7H5006-SEP

		9.37_T_SYNC_RISE_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.229	7.586	0.357
0	49	7.278	7.613	0.335
1E+12	11	7.181	7.516	0.335
1E+12	12	7.076	7.461	0.385
1E+12	13	7.189	7.578	0.389
5E+12	14	7.260	7.533	0.273
5E+12	15	7.096	7.497	0.401
5E+12	16	7.195	7.559	0.364
1E+13	17	7.284	7.577	0.293
1E+13	18	7.163	7.520	0.357
1E+13	19	7.215	7.530	0.315
	Max	7.284	7.613	0.401
	Average	7.197	7.543	0.346
	Min	7.076	7.461	0.273
	Std Dev	0.068	0.044	0.040

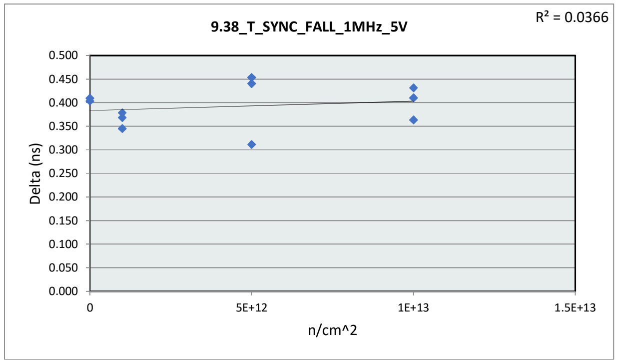


	9.37_T_SYNC_RISE_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.586	7.461	7.497	7.520
Average	7.600	7.518	7.530	7.542
Max	7.613	7.578	7.559	7.577
UL	15.000	15.000	15.000	15.000

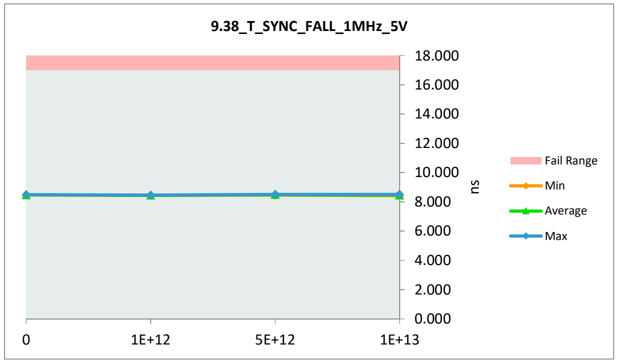


NDD Characterization Report
TPS7H5006-SEP

		9.38_T_SYNC_FALL_1MHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.077	8.480	0.403
0	49	8.061	8.470	0.409
1E+12	11	8.088	8.456	0.368
1E+12	12	8.105	8.450	0.345
1E+12	13	8.057	8.435	0.378
5E+12	14	8.148	8.459	0.311
5E+12	15	8.068	8.508	0.440
5E+12	16	8.058	8.511	0.453
1E+13	17	8.030	8.440	0.410
1E+13	18	8.056	8.419	0.363
1E+13	19	8.075	8.506	0.431
	Max	8.148	8.511	0.453
	Average	8.075	8.467	0.392
	Min	8.030	8.419	0.311
	Std Dev	0.031	0.031	0.043

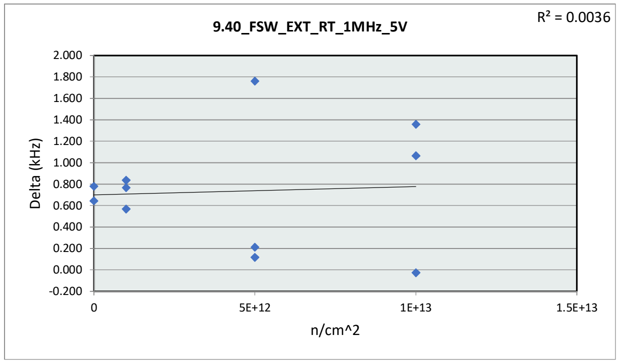


9.38_T_SYNC_FALL_1MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.470	8.435	8.459	8.419
Average	8.475	8.447	8.493	8.455
Max	8.480	8.456	8.511	8.506
UL	17.000	17.000	17.000	17.000

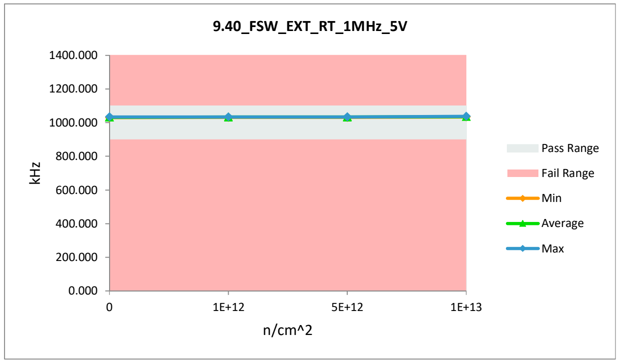


NDD Characterization Report
TPS7H5006-SEP

		9.40_FSW_EXT_RT_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	1100	1100	
	Min Limit	900	900	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1028.667	1029.309	0.642
0	49	1033.862	1034.640	0.778
1E+12	11	1029.855	1030.691	0.836
1E+12	12	1032.644	1033.410	0.766
1E+12	13	1033.702	1034.269	0.567
5E+12	14	1031.362	1031.573	0.211
5E+12	15	1032.665	1034.424	1.759
5E+12	16	1034.408	1034.523	0.115
1E+13	17	1032.994	1034.056	1.062
1E+13	18	1032.793	1034.149	1.356
1E+13	19	1037.559	1037.532	-0.027
	Max	1037.559	1037.532	1.759
	Average	1032.774	1033.507	0.733
	Min	1028.667	1029.309	-0.027
	Std Dev	2.347	2.235	0.532

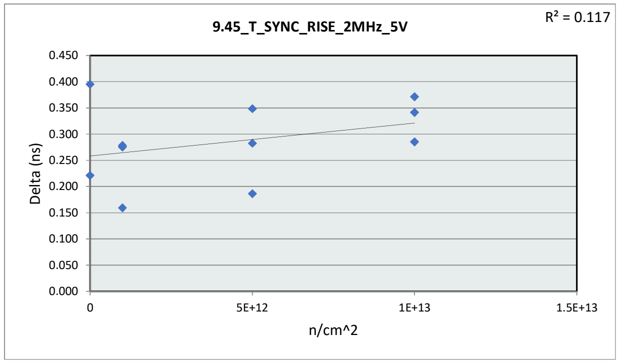


	9.40_FSW_EXT_RT_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1029.309	1030.691	1031.573	1034.056
Average	1031.975	1032.790	1033.507	1035.246
Max	1034.640	1034.269	1034.523	1037.532
UL	1100.000	1100.000	1100.000	1100.000

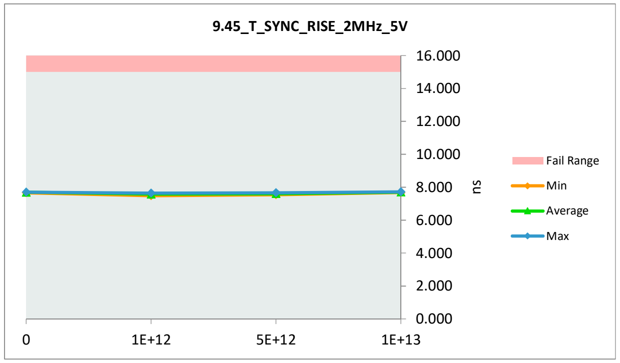


NDD Characterization Report
TPS7H5006-SEP

		9.45_T_SYNC_RISE_2MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.311	7.706	0.395
0	49	7.446	7.667	0.221
1E+12	11	7.324	7.602	0.278
1E+12	12	7.320	7.479	0.159
1E+12	13	7.367	7.642	0.275
5E+12	14	7.331	7.613	0.282
5E+12	15	7.349	7.535	0.186
5E+12	16	7.313	7.661	0.348
1E+13	17	7.416	7.701	0.285
1E+13	18	7.341	7.682	0.341
1E+13	19	7.338	7.709	0.371
	Max	7.446	7.709	0.395
	Average	7.351	7.636	0.286
	Min	7.311	7.479	0.159
	Std Dev	0.043	0.074	0.075

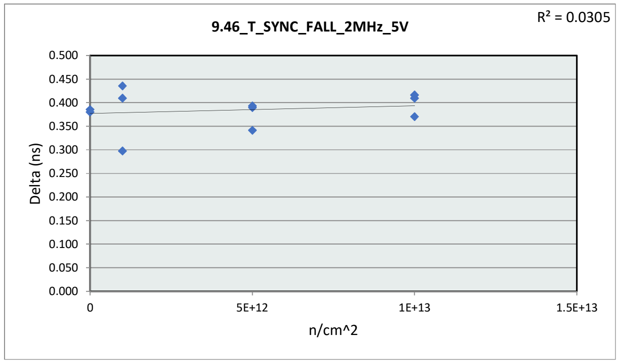


	9.45_T_SYNC_RISE_2MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.667	7.479	7.535	7.682
Average	7.687	7.574	7.603	7.697
Max	7.706	7.642	7.661	7.709
UL	15.000	15.000	15.000	15.000

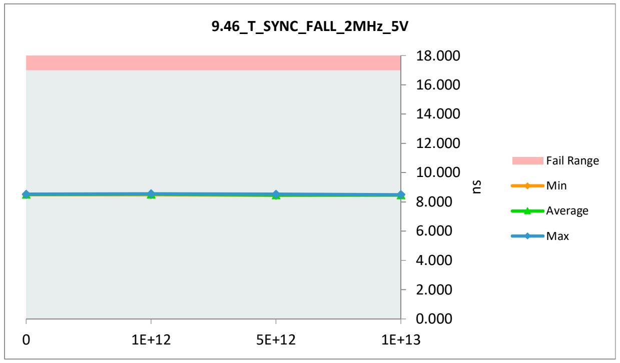


NDD Characterization Report
TPS7H5006-SEP

		9.46_T_SYNC_FALL_2MHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.094	8.479	0.385
0	49	8.144	8.524	0.380
1E+12	11	8.138	8.547	0.409
1E+12	12	8.187	8.484	0.297
1E+12	13	8.095	8.530	0.435
5E+12	14	8.071	8.464	0.393
5E+12	15	8.127	8.516	0.389
5E+12	16	8.092	8.433	0.341
1E+13	17	8.053	8.469	0.416
1E+13	18	8.093	8.463	0.370
1E+13	19	8.080	8.489	0.409
	Max	8.187	8.547	0.435
	Average	8.107	8.491	0.384
	Min	8.053	8.433	0.297
	Std Dev	0.038	0.035	0.038

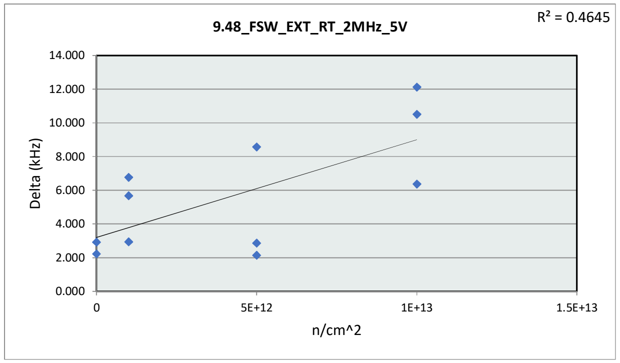


9.46_T_SYNC_FALL_2MHz_5V				
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.479	8.484	8.433	8.463
Average	8.502	8.520	8.471	8.474
Max	8.524	8.547	8.516	8.489
UL	17.000	17.000	17.000	17.000

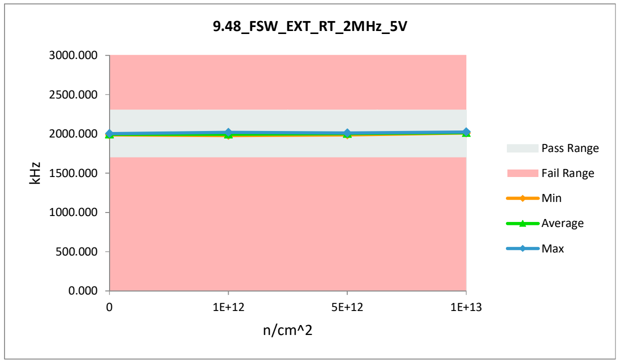


NDD Characterization Report
TPS7H5006-SEP

		9.48_FSW_EXT_RT_2MHz_5V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		2300	2300	
Min Limit		1700	1700	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2002.150	2004.367	2.217
0	49	1983.602	1986.514	2.912
1E+12	11	1977.461	1980.395	2.934
1E+12	12	1984.282	1991.047	6.765
1E+12	13	2012.981	2018.650	5.669
5E+12	14	2006.776	2008.911	2.135
5E+12	15	1984.607	1987.462	2.855
5E+12	16	2003.388	2011.945	8.557
1E+13	17	1999.997	2012.114	12.117
1E+13	18	2018.828	2025.186	6.358
1E+13	19	1999.725	2010.220	10.495
	Max	2018.828	2025.186	12.117
	Average	1997.618	2003.346	5.729
	Min	1977.461	1980.395	2.135
	Std Dev	13.355	14.680	3.496

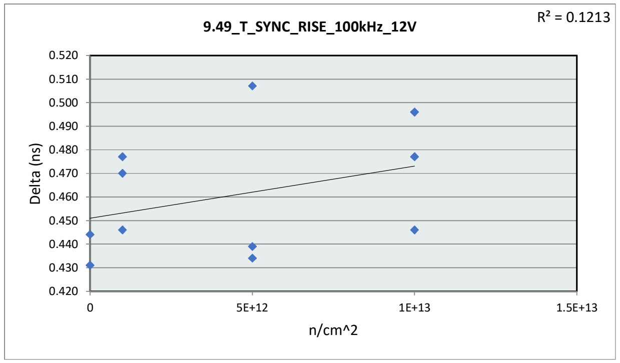


	9.48_FSW_EXT_RT_2MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	1986.514	1980.395	1987.462	2010.220
Average	1995.441	1996.697	2002.773	2015.840
Max	2004.367	2018.650	2011.945	2025.186
UL	2300.000	2300.000	2300.000	2300.000

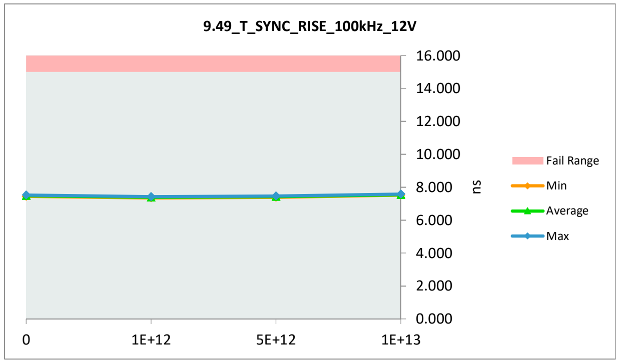


NDD Characterization Report
TPS7H5006-SEP

		9.49_T_SYNC_RISE_100kHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.015	7.446	0.431
0	49	7.086	7.530	0.444
1E+12	11	6.888	7.365	0.477
1E+12	12	6.906	7.352	0.446
1E+12	13	6.956	7.426	0.470
5E+12	14	7.039	7.473	0.434
5E+12	15	6.942	7.381	0.439
5E+12	16	6.954	7.461	0.507
1E+13	17	7.111	7.588	0.477
1E+13	18	7.075	7.521	0.446
1E+13	19	7.050	7.546	0.496
	Max	7.111	7.588	0.507
	Average	7.002	7.463	0.461
	Min	6.888	7.352	0.431
	Std Dev	0.076	0.078	0.026

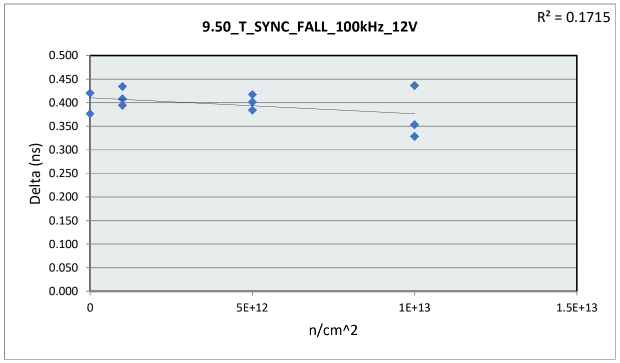


	9.49_T_SYNC_RISE_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.446	7.352	7.381	7.521
Average	7.488	7.381	7.438	7.552
Max	7.530	7.426	7.473	7.588
UL	15.000	15.000	15.000	15.000

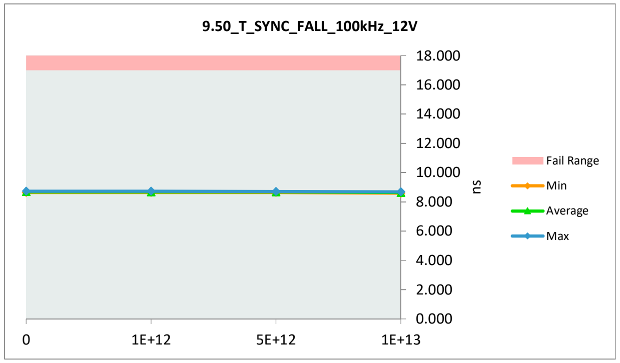


NDD Characterization Report
TPS7H5006-SEP

		9.50_T_SYNC_FALL_100kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.309	8.729	0.420
0	49	8.263	8.639	0.376
1E+12	11	8.296	8.730	0.434
1E+12	12	8.267	8.675	0.408
1E+12	13	8.248	8.642	0.394
5E+12	14	8.252	8.636	0.384
5E+12	15	8.283	8.684	0.401
5E+12	16	8.285	8.702	0.417
1E+13	17	8.234	8.587	0.353
1E+13	18	8.242	8.678	0.436
1E+13	19	8.294	8.622	0.328
	Max	8.309	8.730	0.436
	Average	8.270	8.666	0.396
	Min	8.234	8.587	0.328
	Std Dev	0.025	0.045	0.034

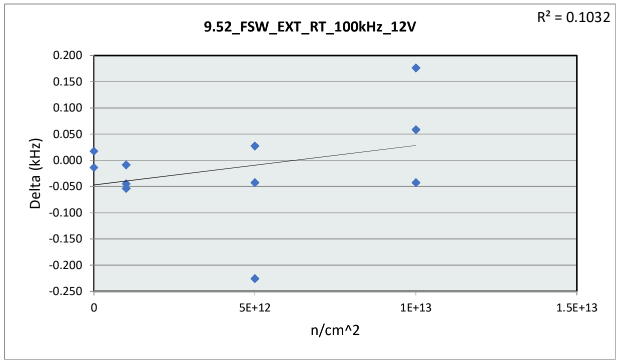


	9.50_T_SYNC_FALL_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.639	8.642	8.636	8.587
Average	8.684	8.682	8.674	8.629
Max	8.729	8.730	8.702	8.678
UL	17.000	17.000	17.000	17.000

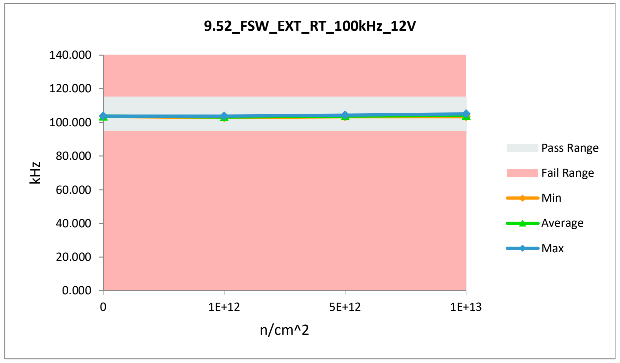


NDD Characterization Report
TPS7H5006-SEP

		9.52_FSW_EXT_RT_100kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	115	115	
	Min Limit	95	95	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	103.832	103.818	-0.014
0	49	103.533	103.550	0.017
1E+12	11	103.113	103.104	-0.009
1E+12	12	102.888	102.843	-0.045
1E+12	13	103.835	103.781	-0.054
5E+12	14	103.706	103.480	-0.226
5E+12	15	103.558	103.585	0.027
5E+12	16	104.397	104.354	-0.043
1E+13	17	103.323	103.499	0.176
1E+13	18	103.540	103.598	0.058
1E+13	19	105.127	105.084	-0.043
	Max	105.127	105.084	0.176
	Average	103.714	103.700	-0.014
	Min	102.888	102.843	-0.226
	Std Dev	0.614	0.599	0.097

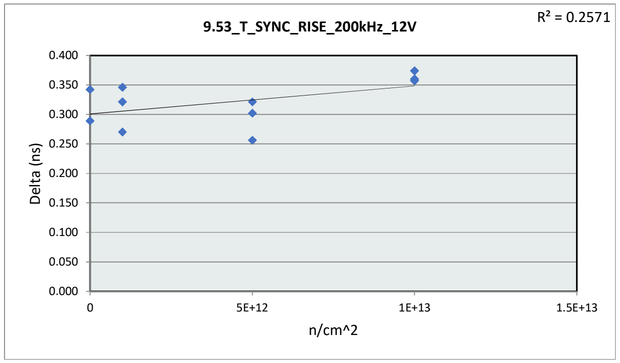


	9.52_FSW_EXT_RT_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.550	102.843	103.480	103.499
Average	103.684	103.243	103.806	104.060
Max	103.818	103.781	104.354	105.084
UL	115.000	115.000	115.000	115.000



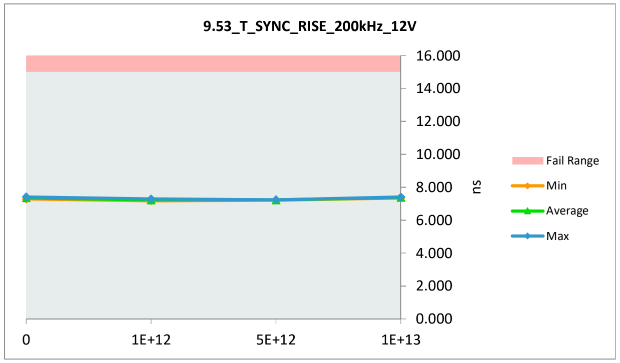
NDD Characterization Report
TPS7H5006-SEP

		9.53_T_SYNC_RISE_200kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.992	7.281	0.289
0	49	7.069	7.411	0.342
1E+12	11	6.906	7.176	0.270
1E+12	12	6.870	7.216	0.346
1E+12	13	6.964	7.285	0.321
5E+12	14	6.982	7.238	0.256
5E+12	15	6.889	7.210	0.321
5E+12	16	6.926	7.228	0.302
1E+13	17	7.019	7.393	0.374
1E+13	18	7.017	7.377	0.360
1E+13	19	6.992	7.349	0.357
	Max	7.069	7.411	0.374
	Average	6.966	7.288	0.322
	Min	6.870	7.176	0.256
	Std Dev	0.062	0.082	0.039



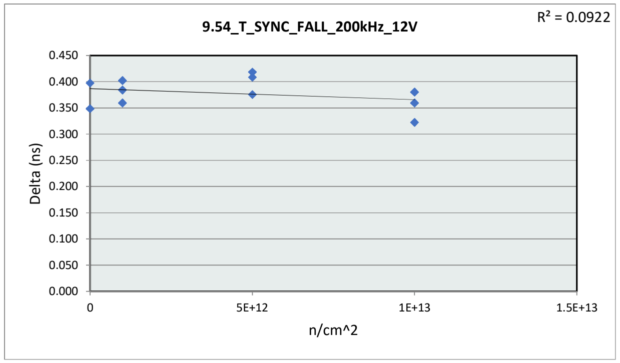
9.53_T_SYNC_RISE_200kHz_1		
Test Site		
Tester		
Test Number		
Max Limit	15	ns
Min Limit		ns

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.281	7.176	7.210	7.349
Average	7.346	7.226	7.225	7.373
Max	7.411	7.285	7.238	7.393
UL	15.000	15.000	15.000	15.000

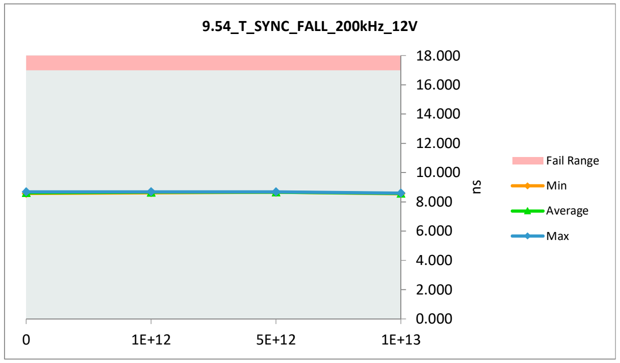


NDD Characterization Report
TPS7H5006-SEP

		9.54_T_SYNC_FALL_200kHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.285	8.682	0.397
0	49	8.229	8.577	0.348
1E+12	11	8.306	8.690	0.384
1E+12	12	8.272	8.631	0.359
1E+12	13	8.237	8.639	0.402
5E+12	14	8.258	8.676	0.418
5E+12	15	8.244	8.652	0.408
5E+12	16	8.284	8.659	0.375
1E+13	17	8.225	8.605	0.380
1E+13	18	8.204	8.563	0.359
1E+13	19	8.235	8.557	0.322
	Max	8.306	8.690	0.418
	Average	8.253	8.630	0.377
	Min	8.204	8.557	0.322
	Std Dev	0.031	0.048	0.029

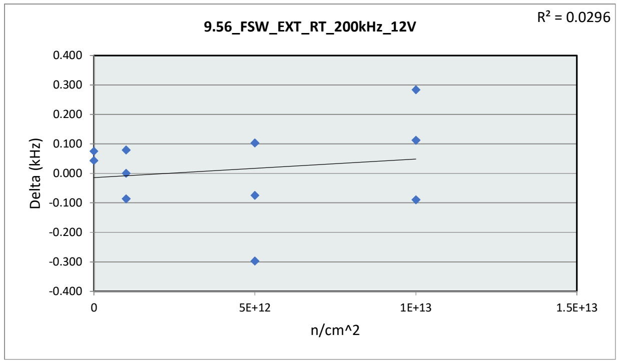


	9.54_T_SYNC_FALL_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.577	8.631	8.652	8.557
Average	8.630	8.653	8.662	8.575
Max	8.682	8.690	8.676	8.605
UL	17.000	17.000	17.000	17.000

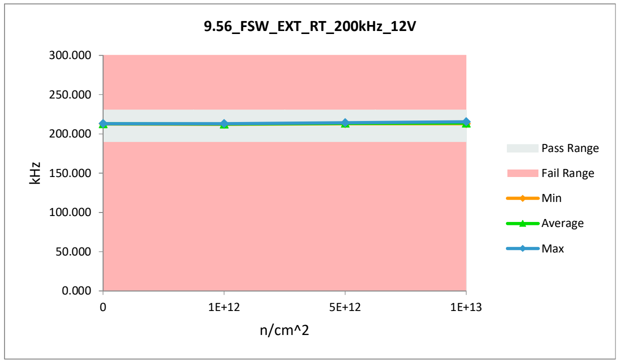


NDD Characterization Report
TPS7H5006-SEP

		9.56_FSW_EXT_RT_200kHz_12V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		230	230	
Min Limit		190	190	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	212.955	212.998	0.043
0	49	212.662	212.737	0.075
1E+12	11	211.950	212.029	0.079
1E+12	12	212.027	212.027	0.000
1E+12	13	213.221	213.134	-0.087
5E+12	14	213.081	212.783	-0.298
5E+12	15	212.738	212.841	0.103
5E+12	16	214.158	214.083	-0.075
1E+13	17	212.663	212.946	0.283
1E+13	18	212.770	212.882	0.112
1E+13	19	215.310	215.220	-0.090
	Max	215.310	215.220	0.283
	Average	213.049	213.062	0.013
	Min	211.950	212.027	-0.298
	Std Dev	0.954	0.901	0.150

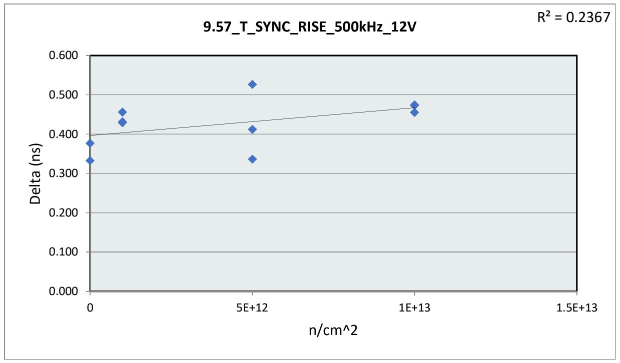


	9.56_FSW_EXT_RT_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	212.737	212.027	212.783	212.882
Average	212.868	212.397	213.236	213.683
Max	212.998	213.134	214.083	215.220
UL	230.000	230.000	230.000	230.000

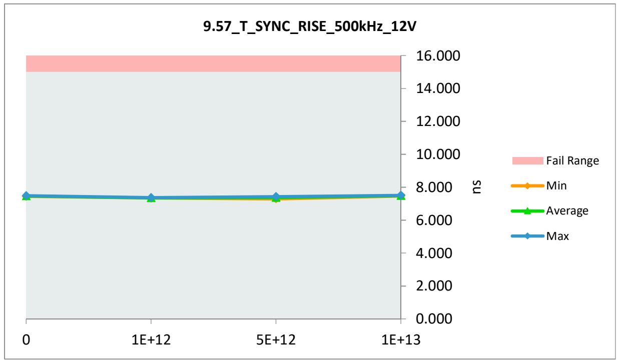


NDD Characterization Report
TPS7H5006-SEP

		9.57_T_SYNC_RISE_500kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.072	7.448	0.376
0	49	7.153	7.485	0.332
1E+12	11	6.885	7.341	0.456
1E+12	12	6.935	7.364	0.429
1E+12	13	6.937	7.368	0.431
5E+12	14	7.023	7.435	0.412
5E+12	15	6.957	7.293	0.336
5E+12	16	6.887	7.413	0.526
1E+13	17	7.002	7.475	0.473
1E+13	18	7.059	7.514	0.455
1E+13	19	7.001	7.475	0.474
	Max	7.153	7.514	0.526
	Average	6.992	7.419	0.427
	Min	6.885	7.293	0.332
	Std Dev	0.082	0.070	0.060

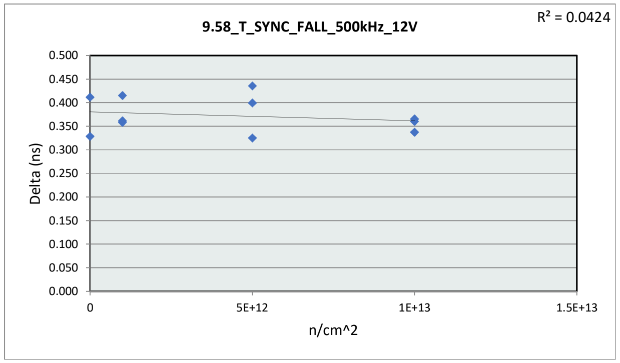


9.57_T_SYNC_RISE_500kHz_1				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.448	7.341	7.293	7.475
Average	7.467	7.358	7.380	7.488
Max	7.485	7.368	7.435	7.514
UL	15.000	15.000	15.000	15.000

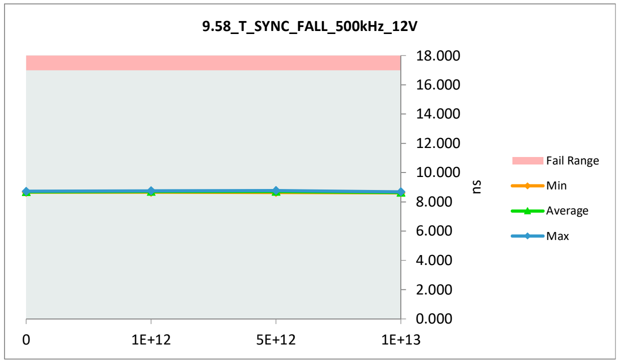


NDD Characterization Report
TPS7H5006-SEP

		9.58_T_SYNC_FALL_500kHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.391	8.719	0.328
0	49	8.238	8.649	0.411
1E+12	11	8.343	8.758	0.415
1E+12	12	8.319	8.680	0.361
1E+12	13	8.298	8.656	0.358
5E+12	14	8.308	8.633	0.325
5E+12	15	8.337	8.736	0.399
5E+12	16	8.333	8.768	0.435
1E+13	17	8.276	8.613	0.337
1E+13	18	8.285	8.650	0.365
1E+13	19	8.313	8.673	0.360
	Max	8.391	8.768	0.435
	Average	8.313	8.685	0.372
	Min	8.238	8.613	0.325
	Std Dev	0.040	0.052	0.037

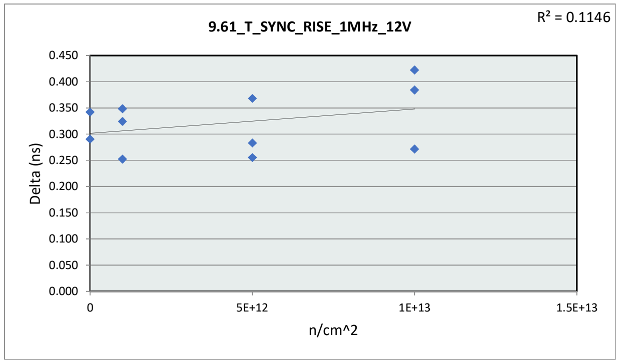


	9.58_T_SYNC_FALL_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.649	8.656	8.633	8.613
Average	8.684	8.698	8.712	8.645
Max	8.719	8.758	8.768	8.673
UL	17.000	17.000	17.000	17.000

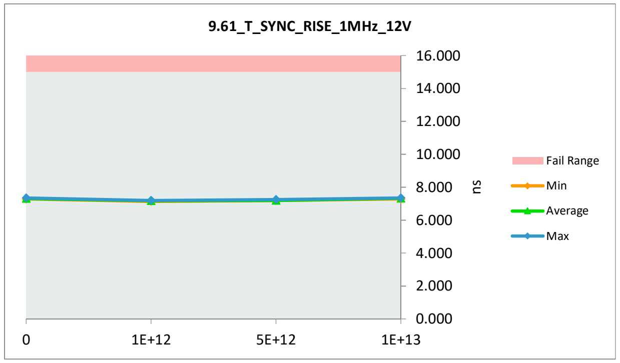


NDD Characterization Report
TPS7H5006-SEP

		9.61_T_SYNC_RISE_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.942	7.284	0.342
0	49	7.067	7.357	0.290
1E+12	11	6.791	7.139	0.348
1E+12	12	6.859	7.183	0.324
1E+12	13	6.950	7.202	0.252
5E+12	14	6.986	7.241	0.255
5E+12	15	6.821	7.189	0.368
5E+12	16	6.903	7.186	0.283
1E+13	17	7.010	7.281	0.271
1E+13	18	6.963	7.347	0.384
1E+13	19	6.919	7.341	0.422
	Max	7.067	7.357	0.422
	Average	6.928	7.250	0.322
	Min	6.791	7.139	0.252
	Std Dev	0.082	0.076	0.056

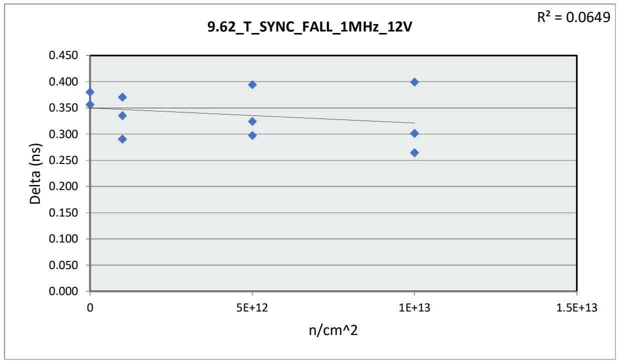


9.61_T_SYNC_RISE_1MHz_12V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.284	7.139	7.186	7.281
Average	7.321	7.175	7.205	7.323
Max	7.357	7.202	7.241	7.347
UL	15.000	15.000	15.000	15.000

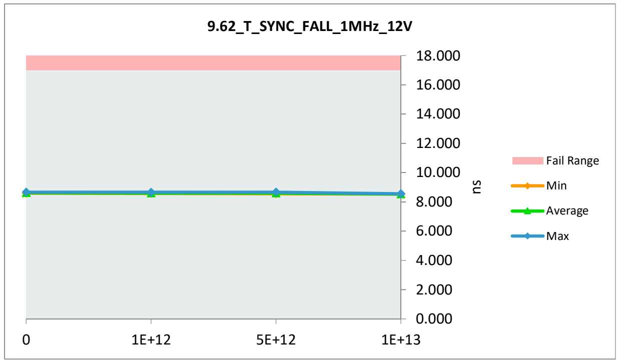


NDD Characterization Report
TPS7H5006-SEP

		9.62_T_SYNC_FALL_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	17	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.279	8.659	0.380
0	49	8.233	8.589	0.356
1E+12	11	8.286	8.656	0.370
1E+12	12	8.250	8.585	0.335
1E+12	13	8.280	8.570	0.290
5E+12	14	8.278	8.575	0.297
5E+12	15	8.265	8.659	0.394
5E+12	16	8.222	8.546	0.324
1E+13	17	8.138	8.537	0.399
1E+13	18	8.265	8.529	0.264
1E+13	19	8.246	8.547	0.301
	Max	8.286	8.659	0.399
	Average	8.249	8.587	0.337
	Min	8.138	8.529	0.264
	Std Dev	0.042	0.050	0.046

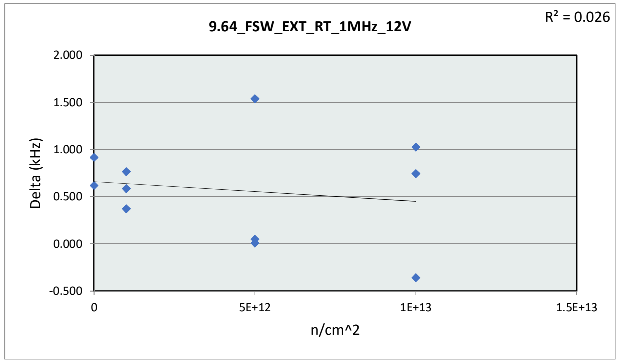


	9.62_T_SYNC_FALL_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.589	8.570	8.546	8.529
Average	8.624	8.604	8.593	8.538
Max	8.659	8.656	8.659	8.547
UL	17.000	17.000	17.000	17.000

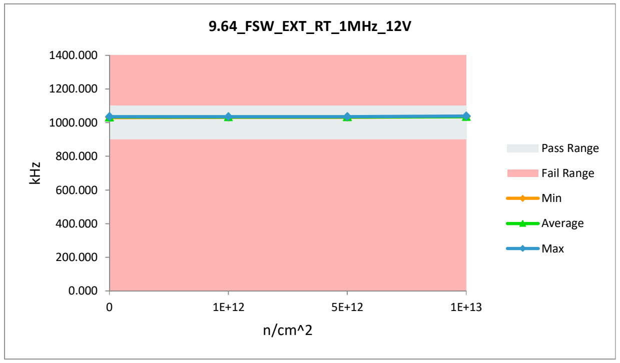


NDD Characterization Report
TPS7H5006-SEP

		9.64_FSW_EXT_RT_1MHz_12V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		1100	1100	
Min Limit		900	900	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1030.177	1030.794	0.617
0	49	1035.219	1036.134	0.915
1E+12	11	1031.892	1032.655	0.763
1E+12	12	1034.282	1034.867	0.585
1E+12	13	1035.204	1035.576	0.372
5E+12	14	1032.655	1032.702	0.047
5E+12	15	1034.247	1035.784	1.537
5E+12	16	1036.072	1036.079	0.007
1E+13	17	1034.408	1035.152	0.744
1E+13	18	1034.094	1035.119	1.025
1E+13	19	1039.002	1038.642	-0.360
	Max	1039.002	1038.642	1.537
	Average	1034.296	1034.864	0.568
	Min	1030.177	1030.794	-0.360
	Std Dev	2.291	2.121	0.532

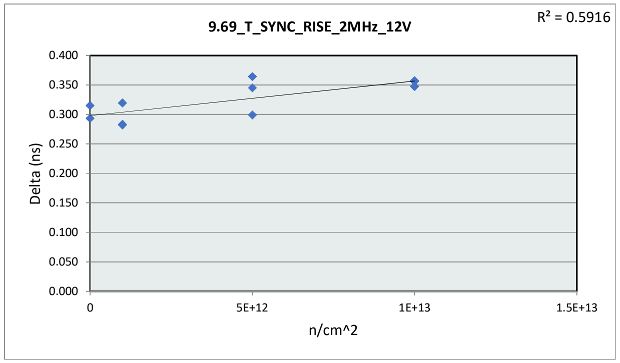


	9.64_FSW_EXT_RT_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1030.794	1032.655	1032.702	1035.119
Average	1033.464	1034.366	1034.855	1036.304
Max	1036.134	1035.576	1036.079	1038.642
UL	1100.000	1100.000	1100.000	1100.000

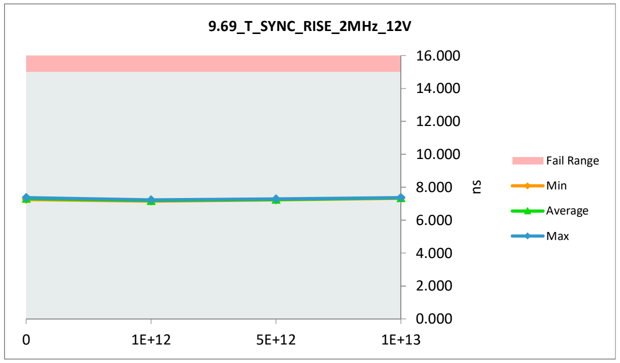


NDD Characterization Report
TPS7H5006-SEP

		9.69_T_SYNC_RISE_2MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.946	7.261	0.315
0	49	7.083	7.376	0.293
1E+12	11	6.866	7.148	0.282
1E+12	12	6.860	7.179	0.319
1E+12	13	6.956	7.239	0.283
5E+12	14	6.934	7.298	0.364
5E+12	15	6.883	7.228	0.345
5E+12	16	6.955	7.254	0.299
1E+13	17	7.013	7.369	0.356
1E+13	18	7.000	7.347	0.347
1E+13	19	6.980	7.337	0.357
	Max	7.083	7.376	0.364
	Average	6.952	7.276	0.324
	Min	6.860	7.148	0.282
	Std Dev	0.067	0.076	0.031

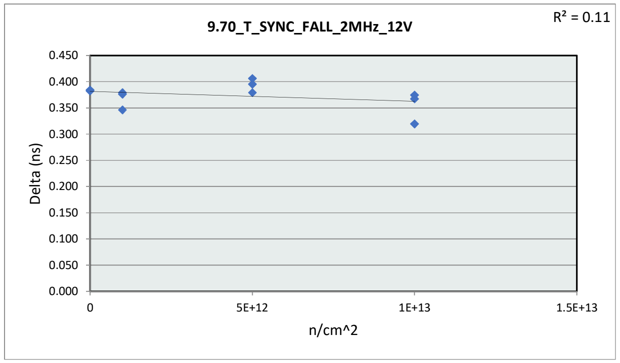


	9.69_T_SYNC_RISE_2MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.261	7.148	7.228	7.337
Average	7.319	7.189	7.260	7.351
Max	7.376	7.239	7.298	7.369
UL	15.000	15.000	15.000	15.000

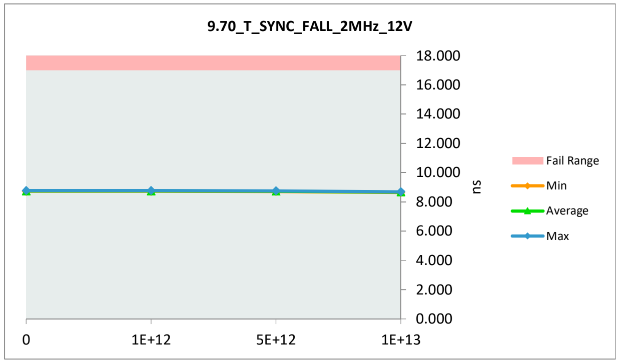


NDD Characterization Report
TPS7H5006-SEP

		9.70_T_SYNC_FALL_2MHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.382	8.766	0.384
0	49	8.337	8.719	0.382
1E+12	11	8.422	8.768	0.346
1E+12	12	8.342	8.718	0.376
1E+12	13	8.355	8.734	0.379
5E+12	14	8.323	8.702	0.379
5E+12	15	8.345	8.751	0.406
5E+12	16	8.349	8.744	0.395
1E+13	17	8.328	8.647	0.319
1E+13	18	8.320	8.687	0.367
1E+13	19	8.308	8.682	0.374
	Max	8.422	8.768	0.406
	Average	8.346	8.720	0.373
	Min	8.308	8.647	0.319
	Std Dev	0.032	0.038	0.024

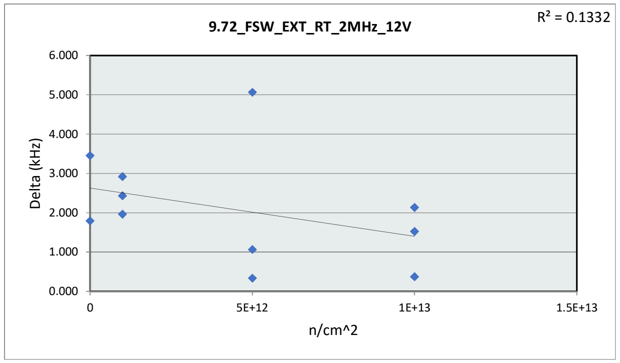


	9.70_T_SYNC_FALL_2MHz_12			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.719	8.718	8.702	8.647
Average	8.743	8.740	8.732	8.672
Max	8.766	8.768	8.751	8.687
UL	17.000	17.000	17.000	17.000

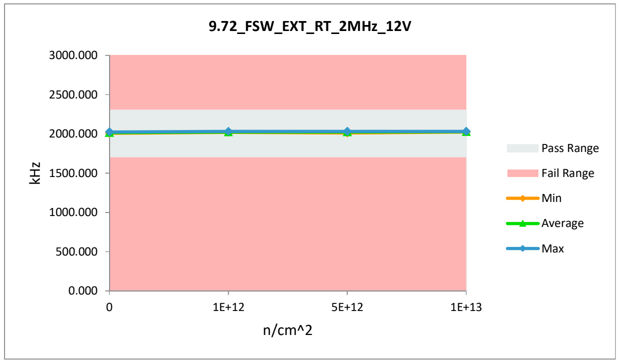


NDD Characterization Report
TPS7H5006-SEP

		9.72_FSW_EXT_RT_2MHz_12V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		2300	2300	
Min Limit		1700	1700	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2006.342	2008.131	1.789
0	49	2021.882	2025.330	3.448
1E+12	11	2014.990	2017.418	2.428
1E+12	12	2019.835	2022.752	2.917
1E+12	13	2028.171	2030.128	1.957
5E+12	14	2012.140	2012.471	0.331
5E+12	15	2023.236	2028.296	5.060
5E+12	16	2029.798	2030.859	1.061
1E+13	17	2026.866	2028.387	1.521
1E+13	18	2022.649	2024.778	2.129
1E+13	19	2029.341	2029.709	0.368
	Max	2029.798	2030.859	5.060
	Average	2021.386	2023.478	2.092
	Min	2006.342	2008.131	0.331
	Std Dev	7.553	7.641	1.379

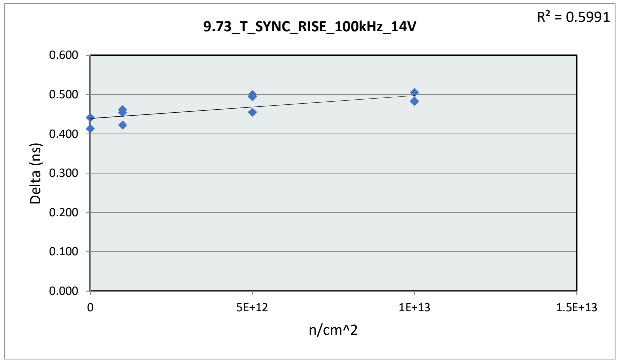


	9.72_FSW_EXT_RT_2MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	2008.131	2017.418	2012.471	2024.778
Average	2016.731	2023.433	2023.875	2027.625
Max	2025.330	2030.128	2030.859	2029.709
UL	2300.000	2300.000	2300.000	2300.000

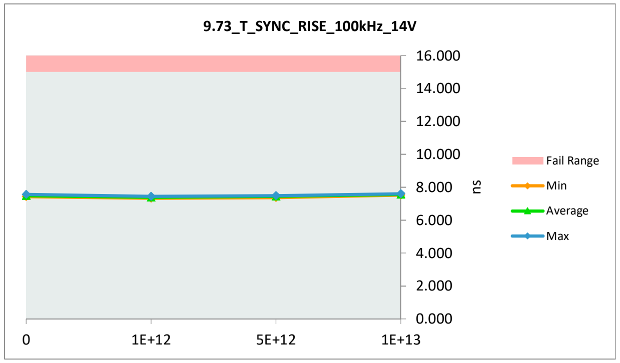


NDD Characterization Report
TPS7H5006-SEP

		9.73_T_SYNC_RISE_100kHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.019	7.432	0.413
0	49	7.117	7.558	0.441
1E+12	11	6.916	7.377	0.461
1E+12	12	6.911	7.333	0.422
1E+12	13	6.995	7.449	0.454
5E+12	14	7.003	7.497	0.494
5E+12	15	6.920	7.375	0.455
5E+12	16	6.963	7.462	0.499
1E+13	17	7.124	7.606	0.482
1E+13	18	7.044	7.527	0.483
1E+13	19	7.067	7.572	0.505
	Max	7.124	7.606	0.505
	Average	7.007	7.472	0.464
	Min	6.911	7.333	0.413
	Std Dev	0.076	0.089	0.031

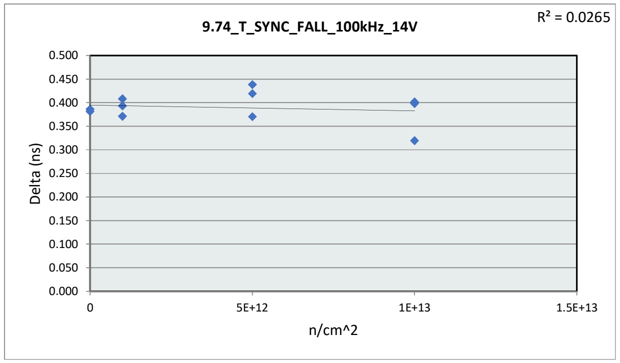


9.73_T_SYNC_RISE_100kHz_1				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.432	7.333	7.375	7.527
Average	7.495	7.386	7.445	7.568
Max	7.558	7.449	7.497	7.606
UL	15.000	15.000	15.000	15.000

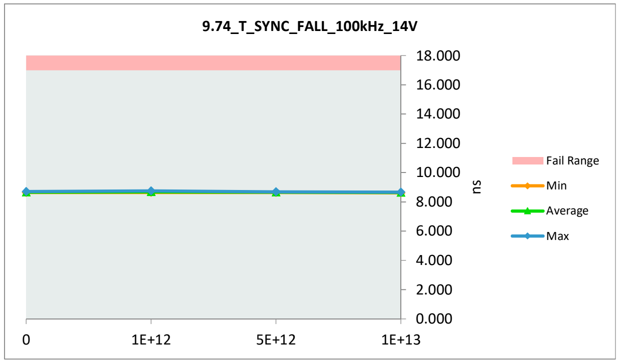


NDD Characterization Report
TPS7H5006-SEP

		9.74_T_SYNC_FALL_100kHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.316	8.697	0.381
0	49	8.246	8.632	0.386
1E+12	11	8.339	8.747	0.408
1E+12	12	8.288	8.659	0.371
1E+12	13	8.256	8.649	0.393
5E+12	14	8.267	8.637	0.370
5E+12	15	8.257	8.695	0.438
5E+12	16	8.241	8.660	0.419
1E+13	17	8.296	8.615	0.319
1E+13	18	8.225	8.626	0.401
1E+13	19	8.262	8.660	0.398
	Max	8.339	8.747	0.438
	Average	8.272	8.662	0.389
	Min	8.225	8.615	0.319
	Std Dev	0.034	0.038	0.031

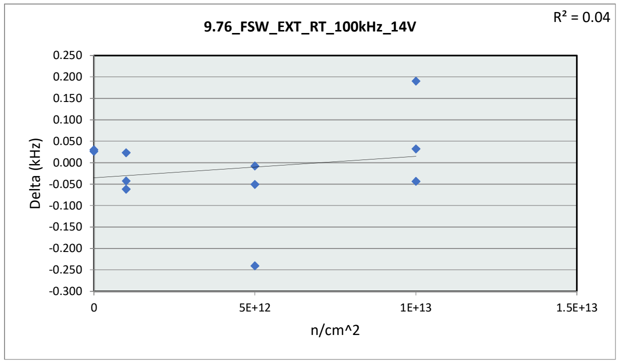


	9.74_T_SYNC_FALL_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.632	8.649	8.637	8.615
Average	8.665	8.685	8.664	8.634
Max	8.697	8.747	8.695	8.660
UL	17.000	17.000	17.000	17.000

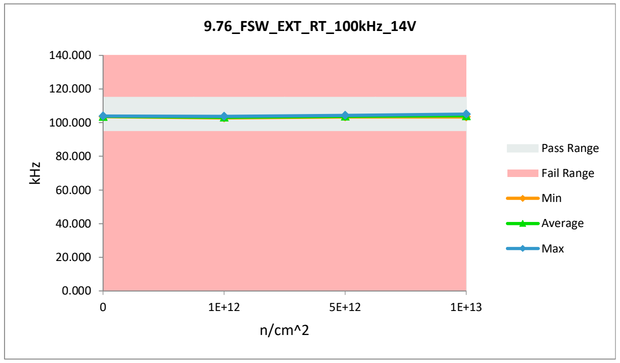


NDD Characterization Report
TPS7H5006-SEP

		9.76_FSW_EXT_RT_100kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	115	115	
	Min Limit	95	95	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	103.821	103.847	0.026
0	49	103.521	103.551	0.030
1E+12	11	103.112	103.135	0.023
1E+12	12	102.860	102.817	-0.043
1E+12	13	103.841	103.779	-0.062
5E+12	14	103.702	103.461	-0.241
5E+12	15	103.564	103.556	-0.008
5E+12	16	104.393	104.342	-0.051
1E+13	17	103.301	103.491	0.190
1E+13	18	103.557	103.589	0.032
1E+13	19	105.114	105.070	-0.044
	Max	105.114	105.070	0.190
	Average	103.708	103.694	-0.013
	Min	102.860	102.817	-0.241
	Std Dev	0.616	0.598	0.103



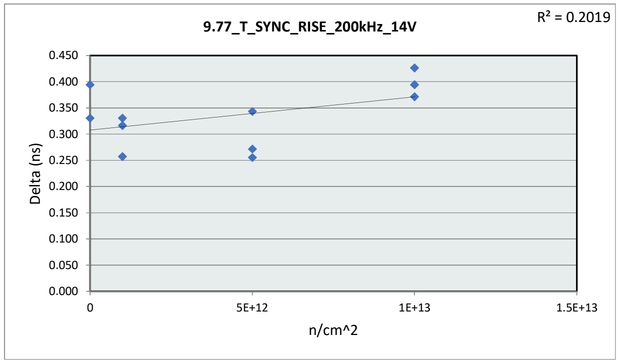
	9.76_FSW_EXT_RT_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	103.551	102.817	103.461	103.491
Average	103.699	103.244	103.786	104.050
Max	103.847	103.779	104.342	105.070
UL	115.000	115.000	115.000	115.000



NDD Characterization Report
TPS7H5006-SEP

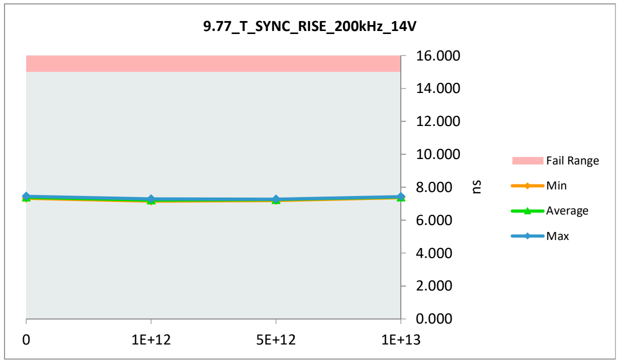
	9.77_T_SYNC_RISE_200kHz_14V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	14	15
Min Limit	0	

n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.001	7.331	0.330
0	49	7.059	7.453	0.394
1E+12	11	6.899	7.156	0.257
1E+12	12	6.876	7.206	0.330
1E+12	13	6.974	7.290	0.316
5E+12	14	7.002	7.273	0.271
5E+12	15	6.939	7.194	0.255
5E+12	16	6.933	7.276	0.343
1E+13	17	6.994	7.388	0.394
1E+13	18	7.003	7.429	0.426
1E+13	19	7.007	7.378	0.371
	Max	7.059	7.453	0.426
	Average	6.972	7.307	0.335
	Min	6.876	7.156	0.255
	Std Dev	0.054	0.098	0.058



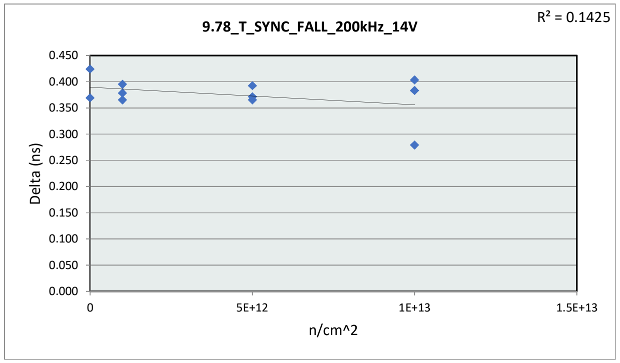
	9.77_T_SYNC_RISE_200kHz_1	
Test Site		
Tester		
Test Number		
Max Limit	15	ns
Min Limit		ns

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.331	7.156	7.194	7.378
Average	7.392	7.217	7.248	7.398
Max	7.453	7.290	7.276	7.429
UL	15.000	15.000	15.000	15.000

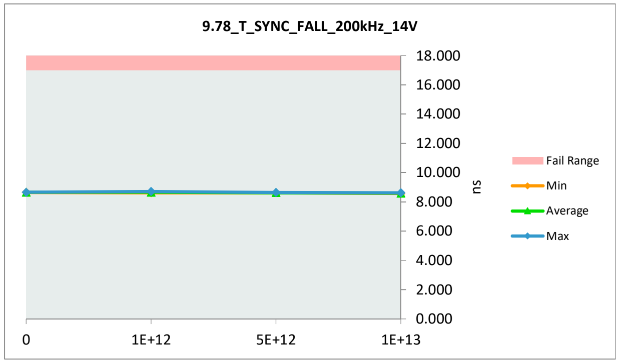


NDD Characterization Report
TPS7H5006-SEP

		9.78_T_SYNC_FALL_200kHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.281	8.650	0.369
0	49	8.230	8.654	0.424
1E+12	11	8.302	8.697	0.395
1E+12	12	8.271	8.636	0.365
1E+12	13	8.234	8.612	0.378
5E+12	14	8.243	8.635	0.392
5E+12	15	8.246	8.617	0.371
5E+12	16	8.249	8.614	0.365
1E+13	17	8.191	8.574	0.383
1E+13	18	8.303	8.582	0.279
1E+13	19	8.204	8.607	0.403
	Max	8.303	8.697	0.424
	Average	8.250	8.625	0.375
	Min	8.191	8.574	0.279
	Std Dev	0.036	0.035	0.037

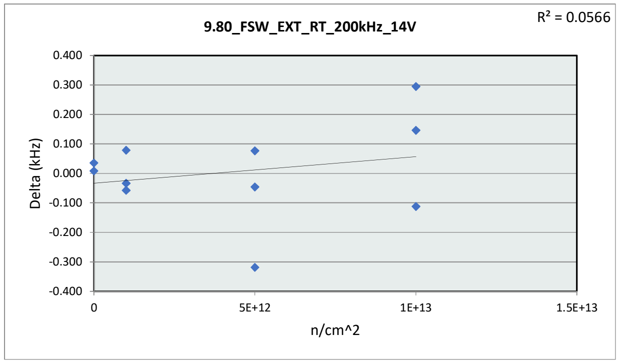


9.78_T_SYNC_FALL_200kHz_1				
Test Site				
Tester				
Test Number				
Max Limit	17 ns			
Min Limit	ns			
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.650	8.612	8.614	8.574
Average	8.652	8.648	8.622	8.588
Max	8.654	8.697	8.635	8.607
UL	17.000	17.000	17.000	17.000

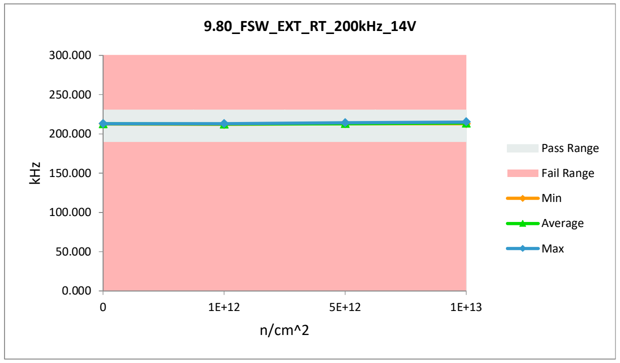


NDD Characterization Report
TPS7H5006-SEP

		9.80_FSW_EXT_RT_200kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	230	230	
	Min Limit	190	190	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	212.997	213.005	0.008
0	49	212.661	212.696	0.035
1E+12	11	211.958	212.036	0.078
1E+12	12	212.011	211.977	-0.034
1E+12	13	213.187	213.129	-0.058
5E+12	14	213.069	212.750	-0.319
5E+12	15	212.733	212.809	0.076
5E+12	16	214.125	214.079	-0.046
1E+13	17	212.638	212.932	0.294
1E+13	18	212.730	212.876	0.146
1E+13	19	215.317	215.204	-0.113
	Max	215.317	215.204	0.294
	Average	213.039	213.045	0.006
	Min	211.958	211.977	-0.319
	Std Dev	0.955	0.906	0.155

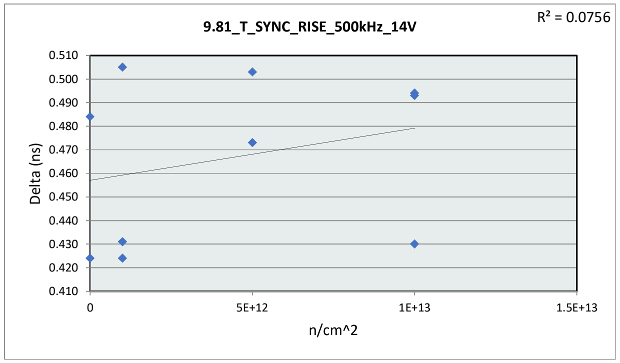


	9.80_FSW_EXT_RT_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	212.696	211.977	212.750	212.876
Average	212.851	212.381	213.213	213.671
Max	213.005	213.129	214.079	215.204
UL	230.000	230.000	230.000	230.000

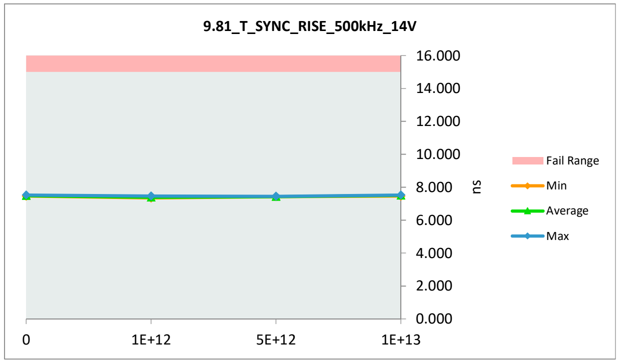


NDD Characterization Report
TPS7H5006-SEP

		9.81_T_SYNC_RISE_500kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	14	15	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.971	7.455	0.484
0	49	7.100	7.524	0.424
1E+12	11	6.911	7.342	0.431
1E+12	12	6.920	7.344	0.424
1E+12	13	6.958	7.463	0.505
5E+12	14	6.982	7.455	0.473
5E+12	15	6.958	7.431	0.473
5E+12	16	6.920	7.423	0.503
1E+13	17	7.030	7.523	0.493
1E+13	18	7.032	7.462	0.430
1E+13	19	7.029	7.523	0.494
	Max	7.100	7.524	0.505
	Average	6.983	7.450	0.467
	Min	6.911	7.342	0.424
	Std Dev	0.059	0.064	0.033

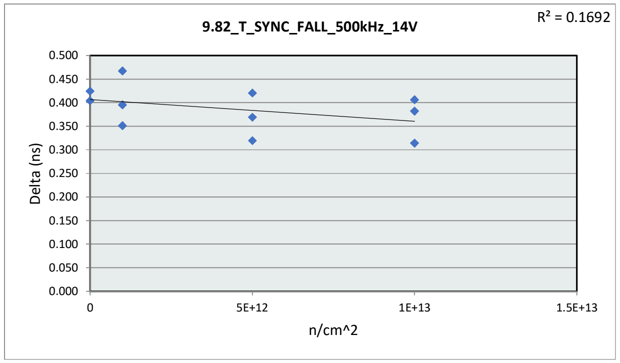


	9.81_T_SYNC_RISE_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.455	7.342	7.423	7.462
Average	7.490	7.383	7.436	7.503
Max	7.524	7.463	7.455	7.523
UL	15.000	15.000	15.000	15.000

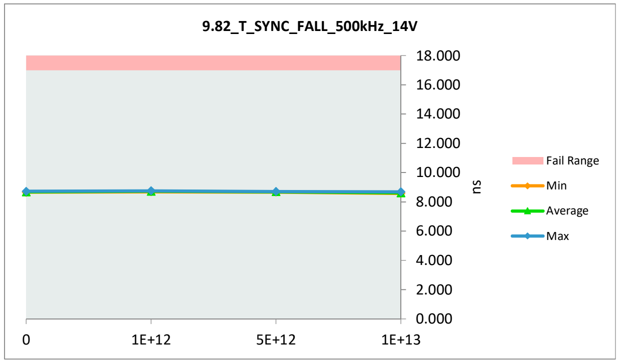


NDD Characterization Report
TPS7H5006-SEP

		9.82_T_SYNC_FALL_500kHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.289	8.713	0.424
0	49	8.244	8.648	0.404
1E+12	11	8.356	8.751	0.395
1E+12	12	8.334	8.685	0.351
1E+12	13	8.250	8.717	0.467
5E+12	14	8.298	8.667	0.369
5E+12	15	8.289	8.709	0.420
5E+12	16	8.385	8.704	0.319
1E+13	17	8.218	8.600	0.382
1E+13	18	8.265	8.579	0.314
1E+13	19	8.267	8.673	0.406
	Max	8.385	8.751	0.467
	Average	8.290	8.677	0.386
	Min	8.218	8.579	0.314
	Std Dev	0.050	0.052	0.046

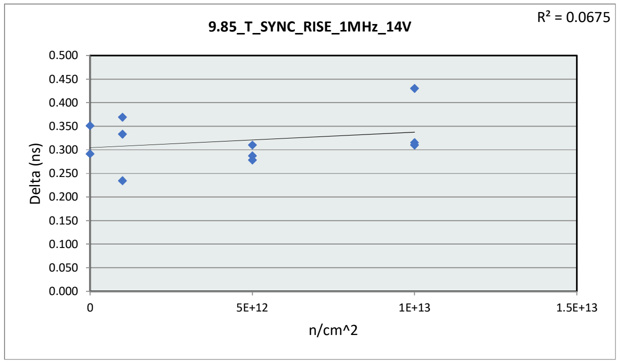


	9.82_T_SYNC_FALL_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.648	8.685	8.667	8.579
Average	8.681	8.718	8.693	8.617
Max	8.713	8.751	8.709	8.673
UL	17.000	17.000	17.000	17.000

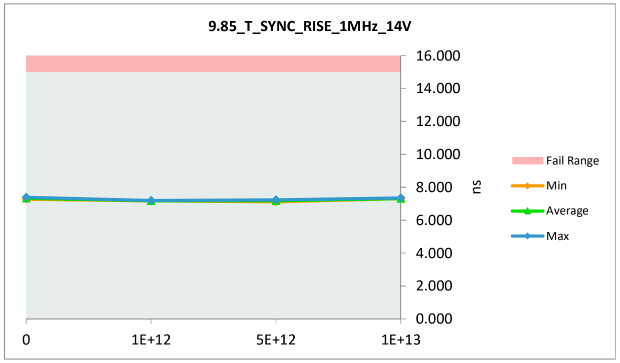


NDD Characterization Report
TPS7H5006-SEP

		9.85_T_SYNC_RISE_1MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.976	7.267	0.291
0	49	7.040	7.391	0.351
1E+12	11	6.827	7.160	0.333
1E+12	12	6.823	7.192	0.369
1E+12	13	6.955	7.189	0.234
5E+12	14	6.929	7.239	0.310
5E+12	15	6.844	7.122	0.278
5E+12	16	6.888	7.175	0.287
1E+13	17	6.925	7.355	0.430
1E+13	18	6.995	7.305	0.310
1E+13	19	6.988	7.303	0.315
	Max	7.040	7.391	0.430
	Average	6.926	7.245	0.319
	Min	6.823	7.122	0.234
	Std Dev	0.073	0.086	0.052



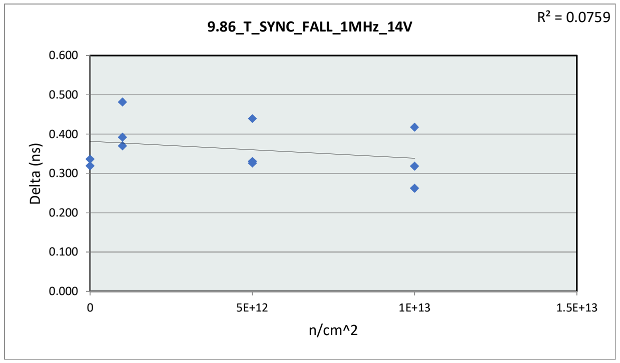
	9.85_T_SYNC_RISE_1MHz_14			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.267	7.160	7.122	7.303
Average	7.329	7.180	7.179	7.321
Max	7.391	7.192	7.239	7.355
UL	15.000	15.000	15.000	15.000



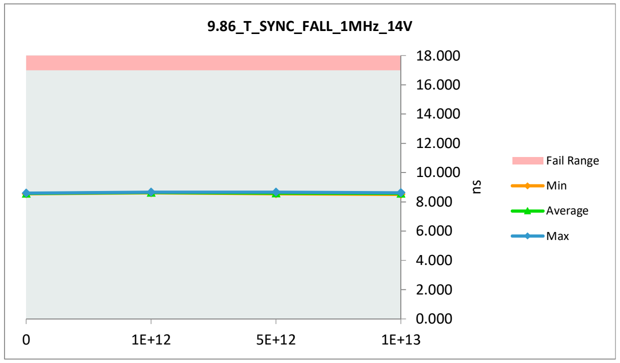
NDD Characterization Report
TPS7H5006-SEP

	9.86_T_SYNC_FALL_1MHz_14V		
Test Site			
Tester			
Test Number			
Unit	ns	ns	
Max Limit	14	17	
Min Limit	0		

n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.281	8.600	0.319
0	49	8.214	8.550	0.336
1E+12	11	8.266	8.658	0.392
1E+12	12	8.238	8.608	0.370
1E+12	13	8.176	8.657	0.481
5E+12	14	8.264	8.594	0.330
5E+12	15	8.223	8.662	0.439
5E+12	16	8.220	8.546	0.326
1E+13	17	8.257	8.519	0.262
1E+13	18	8.213	8.630	0.417
1E+13	19	8.236	8.554	0.318
	Max	8.281	8.662	0.481
	Average	8.235	8.598	0.363
	Min	8.176	8.519	0.262
	Std Dev	0.030	0.051	0.064

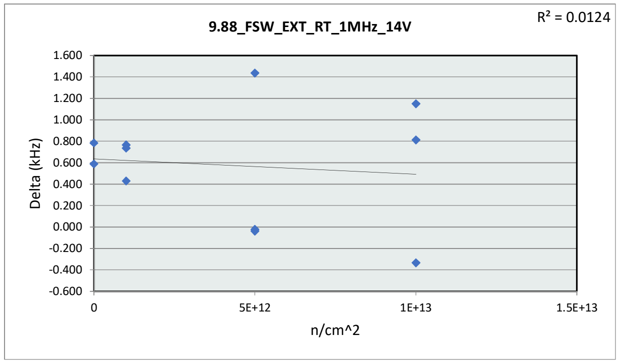


	9.86_T_SYNC_FALL_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.550	8.608	8.546	8.519
Average	8.575	8.641	8.601	8.568
Max	8.600	8.658	8.662	8.630
UL	17.000	17.000	17.000	17.000

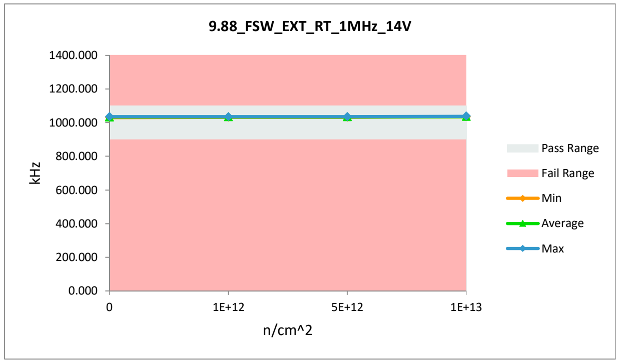


NDD Characterization Report
TPS7H5006-SEP

		9.88_FSW_EXT_RT_1MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	1100	1100	
	Min Limit	900	900	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1030.166	1030.754	0.588
0	49	1035.121	1035.903	0.782
1E+12	11	1031.878	1032.612	0.734
1E+12	12	1034.107	1034.872	0.765
1E+12	13	1035.096	1035.525	0.429
5E+12	14	1032.672	1032.632	-0.040
5E+12	15	1034.310	1035.745	1.435
5E+12	16	1036.098	1036.075	-0.023
1E+13	17	1034.287	1035.099	0.812
1E+13	18	1033.989	1035.138	1.149
1E+13	19	1038.878	1038.543	-0.335
	Max	1038.878	1038.543	1.435
	Average	1034.237	1034.809	0.572
	Min	1030.166	1030.754	-0.335
	Std Dev	2.263	2.106	0.531

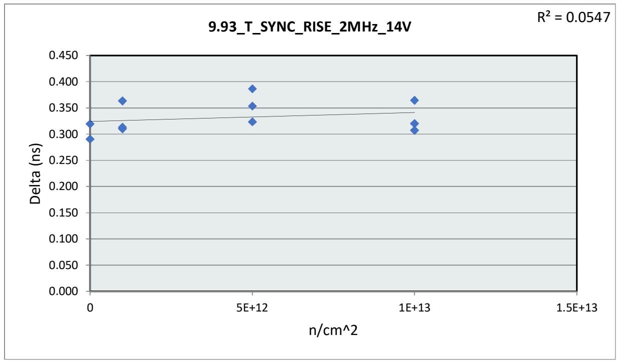


	9.88_FSW_EXT_RT_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1030.754	1032.612	1032.632	1035.099
Average	1033.329	1034.336	1034.817	1036.260
Max	1035.903	1035.525	1036.075	1038.543
UL	1100.000	1100.000	1100.000	1100.000

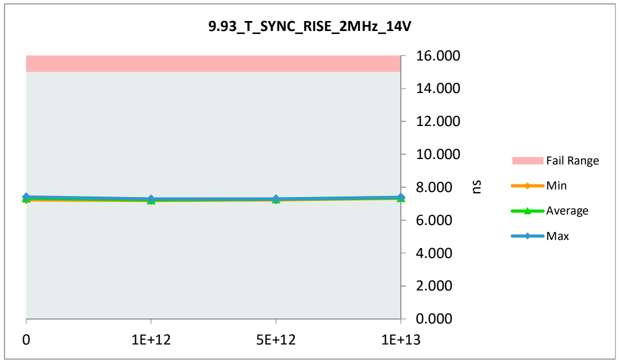


NDD Characterization Report
TPS7H5006-SEP

		9.93_T_SYNC_RISE_2MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	15	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.950	7.240	0.290
0	49	7.088	7.407	0.319
1E+12	11	6.829	7.192	0.363
1E+12	12	6.887	7.200	0.313
1E+12	13	6.971	7.281	0.310
5E+12	14	6.921	7.274	0.353
5E+12	15	6.905	7.228	0.323
5E+12	16	6.906	7.292	0.386
1E+13	17	7.022	7.386	0.364
1E+13	18	7.017	7.324	0.307
1E+13	19	7.029	7.349	0.320
	Max	7.088	7.407	0.386
	Average	6.957	7.288	0.332
	Min	6.829	7.192	0.290
	Std Dev	0.076	0.072	0.030

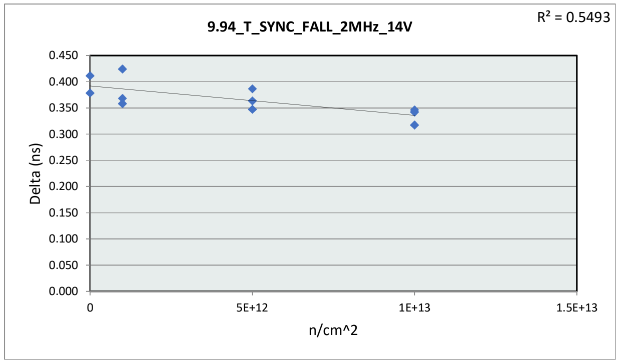


	9.93_T_SYNC_RISE_2MHz_14			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.240	7.192	7.228	7.324
Average	7.324	7.224	7.265	7.353
Max	7.407	7.281	7.292	7.386
UL	15.000	15.000	15.000	15.000

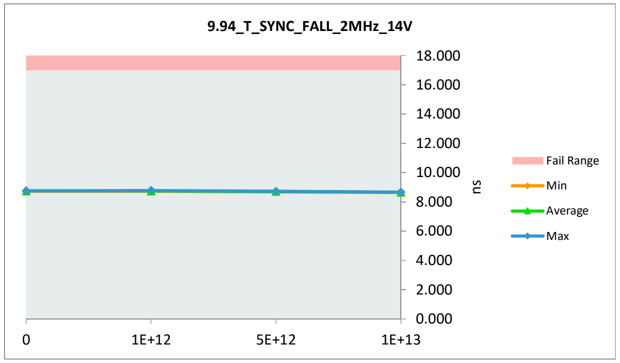


NDD Characterization Report
TPS7H5006-SEP

		9.94_T_SYNC_FALL_2MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		14	17	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.338	8.749	0.411
0	49	8.351	8.729	0.378
1E+12	11	8.418	8.776	0.358
1E+12	12	8.360	8.728	0.368
1E+12	13	8.309	8.733	0.424
5E+12	14	8.309	8.695	0.386
5E+12	15	8.360	8.723	0.363
5E+12	16	8.333	8.680	0.347
1E+13	17	8.307	8.649	0.342
1E+13	18	8.317	8.663	0.346
1E+13	19	8.335	8.652	0.317
	Max	8.418	8.776	0.424
	Average	8.340	8.707	0.367
	Min	8.307	8.649	0.317
	Std Dev	0.033	0.042	0.031

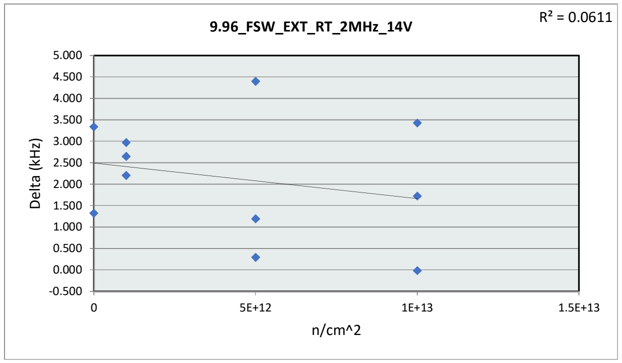


	9.94_T_SYNC_FALL_2MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.729	8.728	8.680	8.649
Average	8.739	8.746	8.699	8.655
Max	8.749	8.776	8.723	8.663
UL	17.000	17.000	17.000	17.000

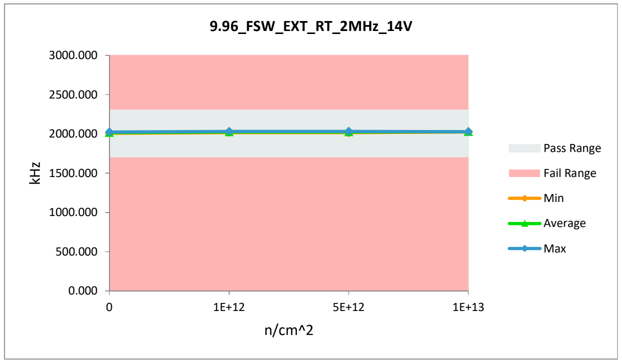


NDD Characterization Report
TPS7H5006-SEP

		9.96_FSW_EXT_RT_2MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	2300	2300	
	Min Limit	1700	1700	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2006.417	2007.735	1.318
0	49	2021.265	2024.596	3.331
1E+12	11	2014.374	2017.016	2.642
1E+12	12	2019.467	2022.435	2.968
1E+12	13	2027.733	2029.934	2.201
5E+12	14	2012.367	2012.654	0.287
5E+12	15	2023.434	2027.827	4.393
5E+12	16	2029.403	2030.592	1.189
1E+13	17	2026.541	2028.260	1.719
1E+13	18	2021.809	2025.231	3.422
1E+13	19	2029.347	2029.325	-0.022
	Max	2029.403	2030.592	4.393
	Average	2021.105	2023.237	2.132
	Min	2006.417	2007.735	-0.022
	Std Dev	7.459	7.614	1.376

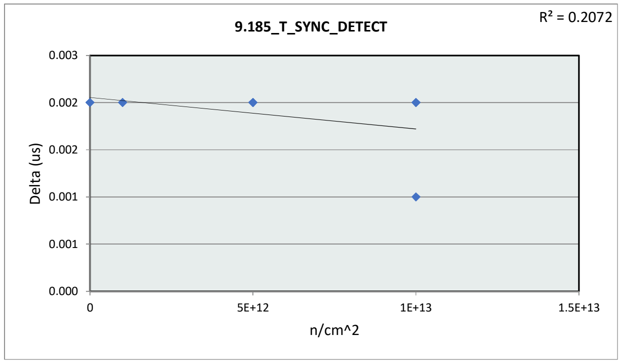


	9.96_FSW_EXT_RT_2MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	2007.735	2017.016	2012.654	2025.231
Average	2016.166	2023.128	2023.691	2027.605
Max	2024.596	2029.934	2030.592	2029.325
UL	2300.000	2300.000	2300.000	2300.000

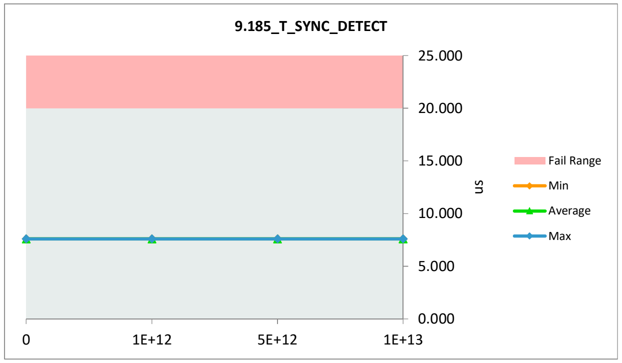


NDD Characterization Report
TPS7H5006-SEP

		9.185_T_SYNC_DETECT		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	12	20	
	Min Limit	4		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.587	7.589	0.002
0	49	7.587	7.589	0.002
1E+12	11	7.586	7.588	0.002
1E+12	12	7.586	7.588	0.002
1E+12	13	7.587	7.589	0.002
5E+12	14	7.587	7.589	0.002
5E+12	15	7.586	7.588	0.002
5E+12	16	7.587	7.589	0.002
1E+13	17	7.587	7.589	0.002
1E+13	18	7.587	7.589	0.002
1E+13	19	7.587	7.588	0.001
	Max	7.587	7.589	0.002
	Average	7.587	7.589	0.002
	Min	7.586	7.588	0.001
	Std Dev	0.000	0.001	0.000

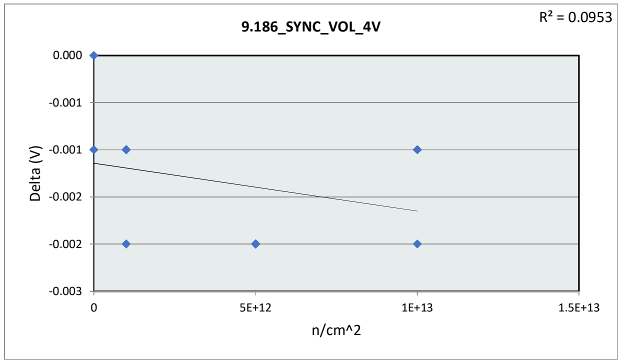


	9.185_T_SYNC_DETECT			
Test Site				
Tester				
Test Number				
Max Limit	20	us		
Min Limit		us		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.589	7.588	7.588	7.588
Average	7.589	7.588	7.589	7.589
Max	7.589	7.589	7.589	7.589
UL	20.000	20.000	20.000	20.000

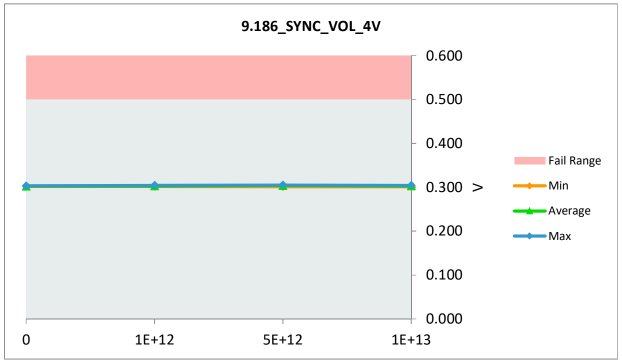


NDD Characterization Report
TPS7H5006-SEP

		9.186_SYNC_VOL_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.5	0.5	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.303	0.303	0.000
0	49	0.303	0.302	-0.001
1E+12	11	0.304	0.302	-0.002
1E+12	12	0.305	0.304	-0.001
1E+12	13	0.303	0.302	-0.001
5E+12	14	0.307	0.305	-0.002
5E+12	15	0.307	0.305	-0.002
5E+12	16	0.303	0.301	-0.002
1E+13	17	0.302	0.301	-0.001
1E+13	18	0.305	0.304	-0.001
1E+13	19	0.306	0.304	-0.002
	Max	0.307	0.305	0.000
	Average	0.304	0.303	-0.001
	Min	0.302	0.301	-0.002
	Std Dev	0.002	0.001	0.001



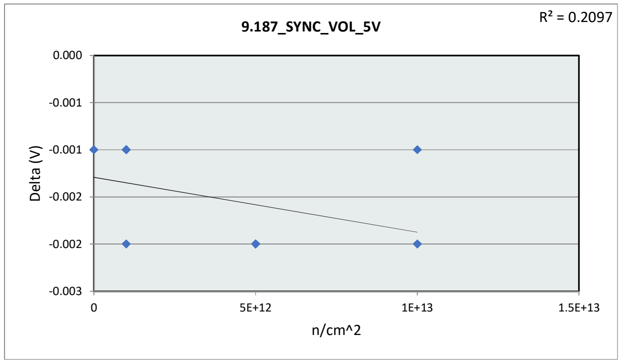
9.186_SYNC_VOL_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.302	0.302	0.301	0.301
Average	0.303	0.303	0.304	0.303
Max	0.303	0.304	0.305	0.304
UL	0.500	0.500	0.500	0.500



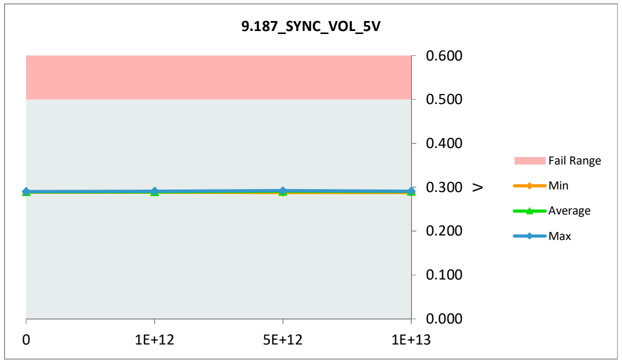
NDD Characterization Report
TPS7H5006-SEP

	9.187_SYNC_VOL_5V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.5	0.5
Min Limit	0	

n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.291	0.290	-0.001
0	49	0.290	0.289	-0.001
1E+12	11	0.291	0.289	-0.002
1E+12	12	0.292	0.291	-0.001
1E+12	13	0.290	0.289	-0.001
5E+12	14	0.294	0.292	-0.002
5E+12	15	0.294	0.292	-0.002
5E+12	16	0.290	0.288	-0.002
1E+13	17	0.290	0.288	-0.002
1E+13	18	0.292	0.291	-0.001
1E+13	19	0.293	0.291	-0.002
	Max	0.294	0.292	-0.001
	Average	0.292	0.290	-0.002
	Min	0.290	0.288	-0.002
	Std Dev	0.002	0.001	0.001

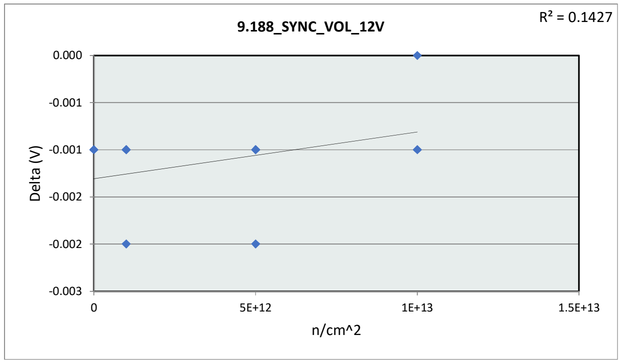


	9.187_SYNC_VOL_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.289	0.289	0.288	0.288
Average	0.290	0.290	0.291	0.290
Max	0.290	0.291	0.292	0.291
UL	0.500	0.500	0.500	0.500

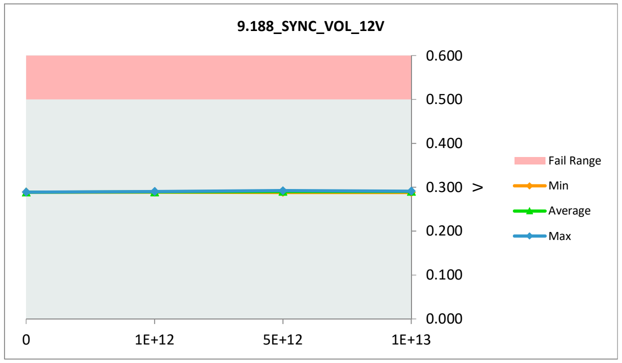


NDD Characterization Report
TPS7H5006-SEP

		9.188_SYNC_VOL_12V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.5	0.5	
Min Limit		0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.290	0.289	-0.001
0	49	0.290	0.289	-0.001
1E+12	11	0.290	0.289	-0.001
1E+12	12	0.292	0.290	-0.002
1E+12	13	0.290	0.289	-0.001
5E+12	14	0.293	0.291	-0.002
5E+12	15	0.293	0.292	-0.001
5E+12	16	0.289	0.288	-0.001
1E+13	17	0.289	0.288	-0.001
1E+13	18	0.291	0.291	0.000
1E+13	19	0.292	0.291	-0.001
	Max	0.293	0.292	0.000
	Average	0.291	0.290	-0.001
	Min	0.289	0.288	-0.002
	Std Dev	0.001	0.001	0.001

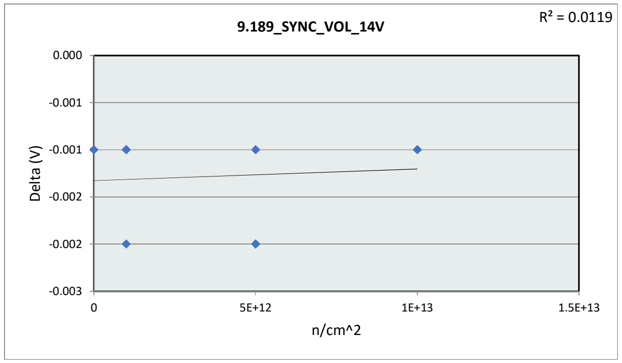


	9.188_SYNC_VOL_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.289	0.289	0.288	0.288
Average	0.289	0.289	0.290	0.290
Max	0.289	0.290	0.292	0.291
UL	0.500	0.500	0.500	0.500

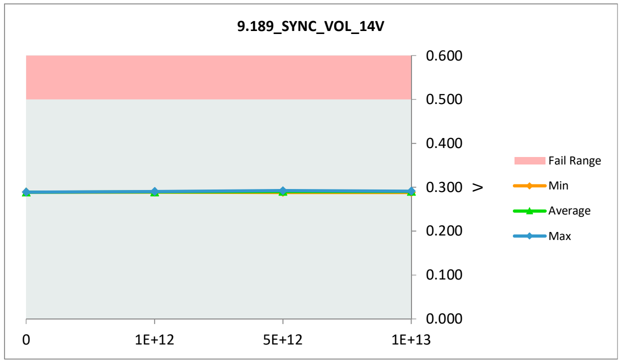


NDD Characterization Report
TPS7H5006-SEP

		9.189_SYNC_VOL_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.5	0.5	
	Min Limit	0		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.290	0.289	-0.001
0	49	0.290	0.289	-0.001
1E+12	11	0.290	0.289	-0.001
1E+12	12	0.292	0.290	-0.002
1E+12	13	0.290	0.289	-0.001
5E+12	14	0.293	0.291	-0.002
5E+12	15	0.293	0.292	-0.001
5E+12	16	0.290	0.288	-0.002
1E+13	17	0.289	0.288	-0.001
1E+13	18	0.292	0.291	-0.001
1E+13	19	0.292	0.291	-0.001
	Max	0.293	0.292	-0.001
	Average	0.291	0.290	-0.001
	Min	0.289	0.288	-0.002
	Std Dev	0.001	0.001	0.000

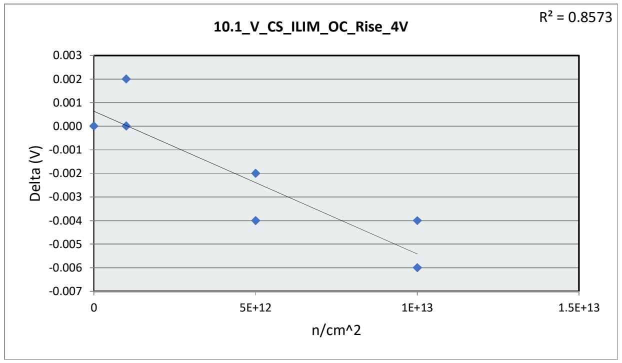


	9.189_SYNC_VOL_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.289	0.289	0.288	0.288
Average	0.289	0.289	0.290	0.290
Max	0.289	0.290	0.292	0.291
UL	0.500	0.500	0.500	0.500

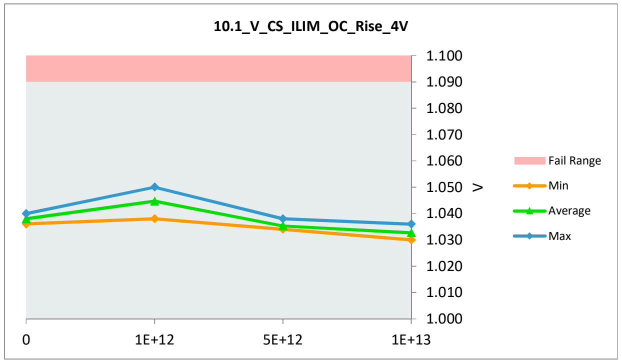


NDD Characterization Report
TPS7H5006-SEP

		10.1_V_CS_ILIM_OC_Rise_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.08	1.09	
	Min Limit	0.95		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.036	1.036	0.000
0	49	1.040	1.040	0.000
1E+12	11	1.038	1.038	0.000
1E+12	12	1.044	1.046	0.002
1E+12	13	1.050	1.050	0.000
5E+12	14	1.036	1.034	-0.002
5E+12	15	1.040	1.038	-0.002
5E+12	16	1.038	1.034	-0.004
1E+13	17	1.038	1.032	-0.006
1E+13	18	1.042	1.036	-0.006
1E+13	19	1.034	1.030	-0.004
	Max	1.050	1.050	0.002
	Average	1.040	1.038	-0.002
	Min	1.034	1.030	-0.006
	Std Dev	0.004	0.006	0.003

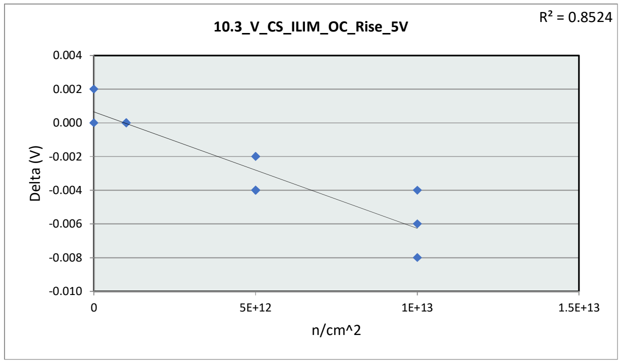


	10.1_V_CS_ILIM_OC_Rise_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.036	1.038	1.034	1.030
Average	1.038	1.045	1.035	1.033
Max	1.040	1.050	1.038	1.036
UL	1.090	1.090	1.090	1.090

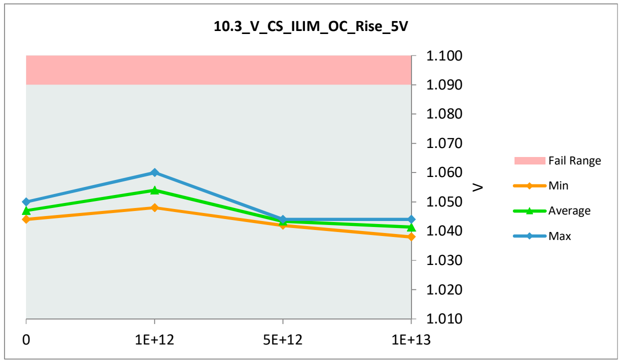


NDD Characterization Report
TPS7H5006-SEP

		10.3_V_CS_ILIM_OC_Rise_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.08	1.09	
Min Limit		0.95		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.042	1.044	0.002
0	49	1.050	1.050	0.000
1E+12	11	1.048	1.048	0.000
1E+12	12	1.054	1.054	0.000
1E+12	13	1.060	1.060	0.000
5E+12	14	1.044	1.042	-0.002
5E+12	15	1.048	1.044	-0.004
5E+12	16	1.048	1.044	-0.004
1E+13	17	1.046	1.042	-0.004
1E+13	18	1.052	1.044	-0.008
1E+13	19	1.044	1.038	-0.006
	Max	1.060	1.060	0.002
	Average	1.049	1.046	-0.002
	Min	1.042	1.038	-0.008
	Std Dev	0.005	0.006	0.003

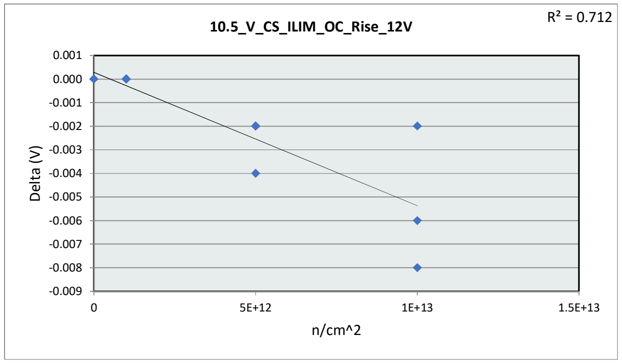


	10.3_V_CS_ILIM_OC_Rise_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.044	1.048	1.042	1.038
Average	1.047	1.054	1.043	1.041
Max	1.050	1.060	1.044	1.044
UL	1.090	1.090	1.090	1.090

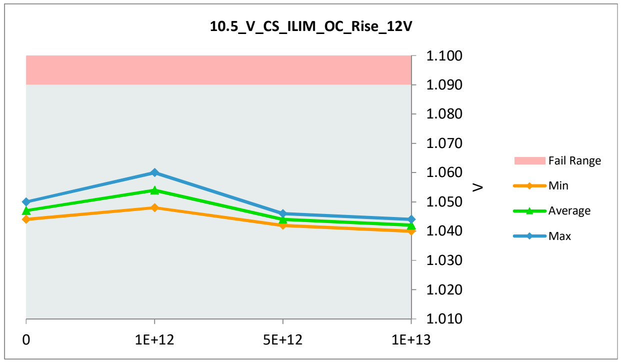


NDD Characterization Report
TPS7H5006-SEP

		10.5_V_CS_ILIM_OC_Rise_12V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.08	1.09	
Min Limit		0.95		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.044	1.044	0.000
0	49	1.050	1.050	0.000
1E+12	11	1.048	1.048	0.000
1E+12	12	1.054	1.054	0.000
1E+12	13	1.060	1.060	0.000
5E+12	14	1.044	1.042	-0.002
5E+12	15	1.048	1.046	-0.002
5E+12	16	1.048	1.044	-0.004
1E+13	17	1.048	1.042	-0.006
1E+13	18	1.052	1.044	-0.008
1E+13	19	1.042	1.040	-0.002
	Max	1.060	1.060	0.000
	Average	1.049	1.047	-0.002
	Min	1.042	1.040	-0.008
	Std Dev	0.005	0.006	0.003

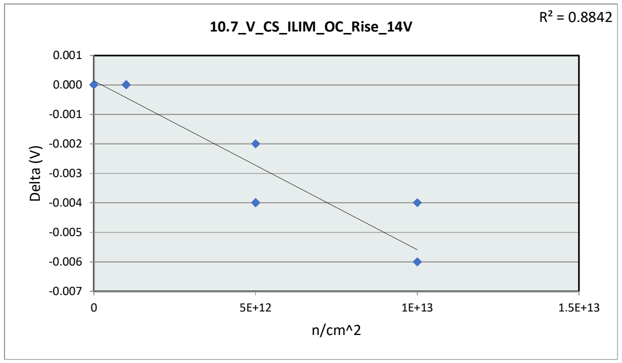


	10.5_V_CS_ILIM_OC_Rise_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.044	1.048	1.042	1.040
Average	1.047	1.054	1.044	1.042
Max	1.050	1.060	1.046	1.044
UL	1.090	1.090	1.090	1.090

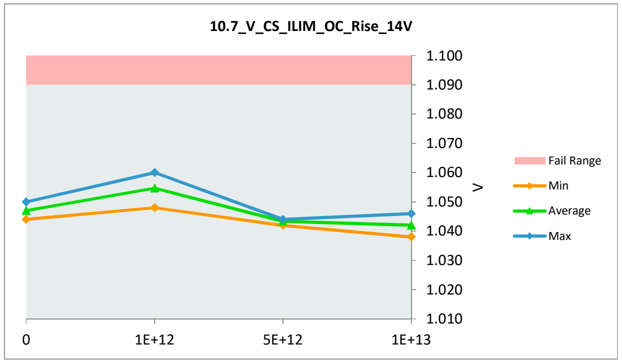


NDD Characterization Report
TPS7H5006-SEP

		10.7_V_CS_ILIM_OC_Rise_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.08	1.09	
Min Limit		0.95		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	1.044	1.044	0.000
0	49	1.050	1.050	0.000
1E+12	11	1.048	1.048	0.000
1E+12	12	1.056	1.056	0.000
1E+12	13	1.060	1.060	0.000
5E+12	14	1.044	1.042	-0.002
5E+12	15	1.048	1.044	-0.004
5E+12	16	1.048	1.044	-0.004
1E+13	17	1.048	1.042	-0.006
1E+13	18	1.052	1.046	-0.006
1E+13	19	1.042	1.038	-0.004
	Max	1.060	1.060	0.000
	Average	1.049	1.047	-0.002
	Min	1.042	1.038	-0.006
	Std Dev	0.005	0.006	0.003

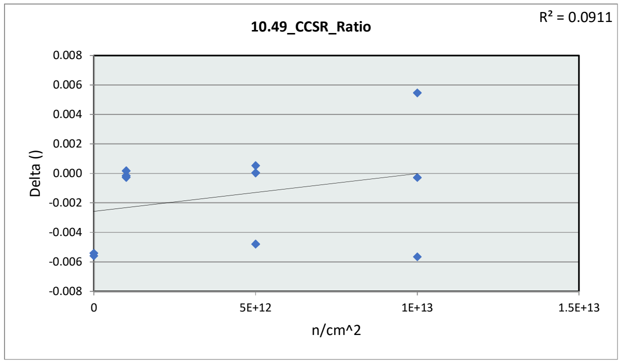


	10.7_V_CS_ILIM_OC_Rise_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.044	1.048	1.042	1.038
Average	1.047	1.055	1.043	1.042
Max	1.050	1.060	1.044	1.046
UL	1.090	1.090	1.090	1.090

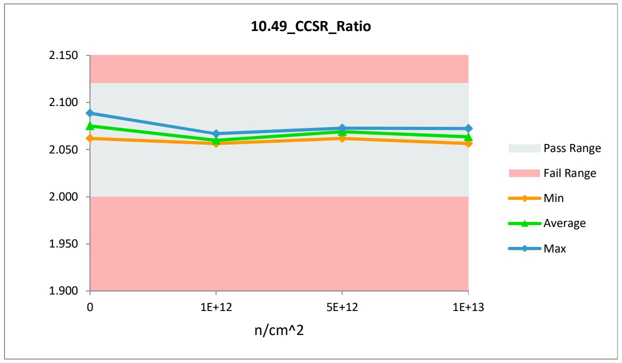


NDD Characterization Report
TPS7H5006-SEP

		10.49_CCSR_Ratio		
	Test Site			
	Tester			
	Test Number			
	Unit			
	Max Limit	2.12	2.12	
	Min Limit	2	2	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	2.094	2.089	-0.006
0	49	2.067	2.062	-0.005
1E+12	11	2.067	2.067	0.000
1E+12	12	2.057	2.057	0.000
1E+12	13	2.057	2.056	0.000
5E+12	14	2.067	2.062	-0.005
5E+12	15	2.072	2.073	0.001
5E+12	16	2.073	2.073	0.000
1E+13	17	2.062	2.056	-0.006
1E+13	18	2.073	2.072	0.000
1E+13	19	2.056	2.062	0.005
	Max	2.094	2.089	0.005
	Average	2.068	2.066	-0.001
	Min	2.056	2.056	-0.006
	Std Dev	0.011	0.010	0.004

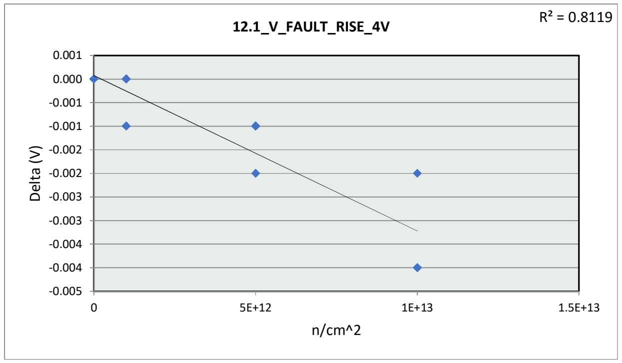


	10.49_CCSR_Ratio			
Test Site				
Tester				
Test Number				
Max Limit	2.12			
Min Limit	2			
n/cm^2	0	1E+12	5E+12	1E+13
LL	2.000	2.000	2.000	2.000
Min	2.062	2.056	2.062	2.056
Average	2.075	2.060	2.069	2.063
Max	2.089	2.067	2.073	2.072
UL	2.120	2.120	2.120	2.120

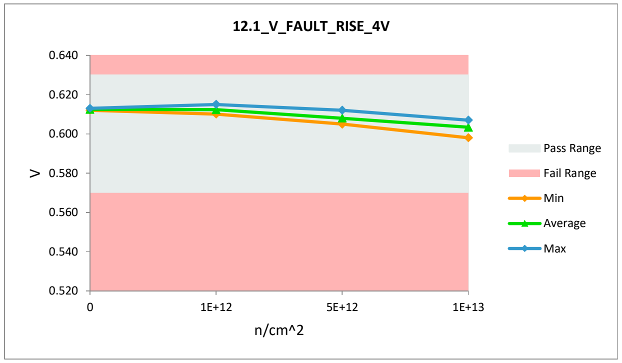


NDD Characterization Report
TPS7H5006-SEP

		12.1_V_FAULT_RISE_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.613	0.613	0.000
0	49	0.612	0.612	0.000
1E+12	11	0.612	0.612	0.000
1E+12	12	0.615	0.615	0.000
1E+12	13	0.611	0.610	-0.001
5E+12	14	0.608	0.607	-0.001
5E+12	15	0.606	0.605	-0.001
5E+12	16	0.614	0.612	-0.002
1E+13	17	0.607	0.605	-0.002
1E+13	18	0.611	0.607	-0.004
1E+13	19	0.602	0.598	-0.004
	Max	0.615	0.615	0.000
	Average	0.610	0.609	-0.001
	Min	0.602	0.598	-0.004
	Std Dev	0.004	0.005	0.002

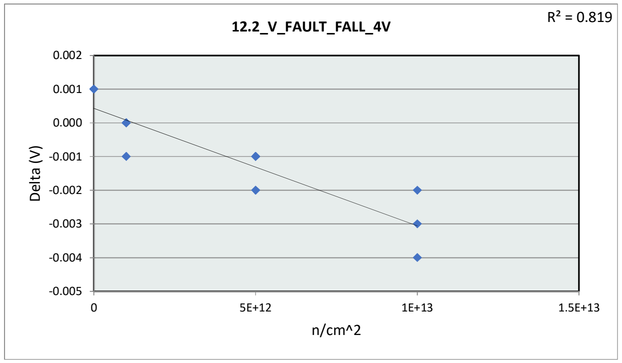


	12.1_V_FAULT_RISE_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.612	0.610	0.605	0.598
Average	0.613	0.612	0.608	0.603
Max	0.613	0.615	0.612	0.607
UL	0.630	0.630	0.630	0.630

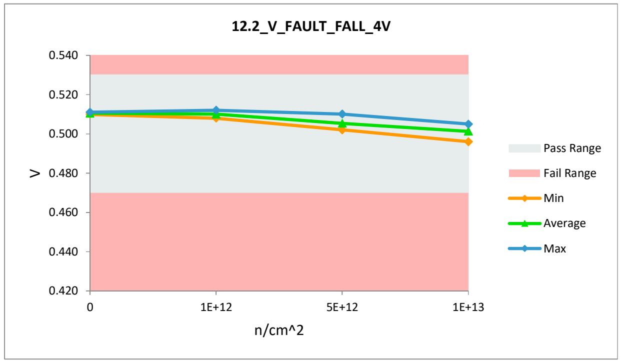


NDD Characterization Report
TPS7H5006-SEP

		12.2_V_FAULT_FALL_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.510	0.511	0.001
0	49	0.509	0.510	0.001
1E+12	11	0.510	0.510	0.000
1E+12	12	0.512	0.512	0.000
1E+12	13	0.509	0.508	-0.001
5E+12	14	0.506	0.504	-0.002
5E+12	15	0.503	0.502	-0.001
5E+12	16	0.511	0.510	-0.001
1E+13	17	0.505	0.503	-0.002
1E+13	18	0.508	0.505	-0.003
1E+13	19	0.500	0.496	-0.004
	Max	0.512	0.512	0.001
	Average	0.508	0.506	-0.001
	Min	0.500	0.496	-0.004
	Std Dev	0.004	0.005	0.002

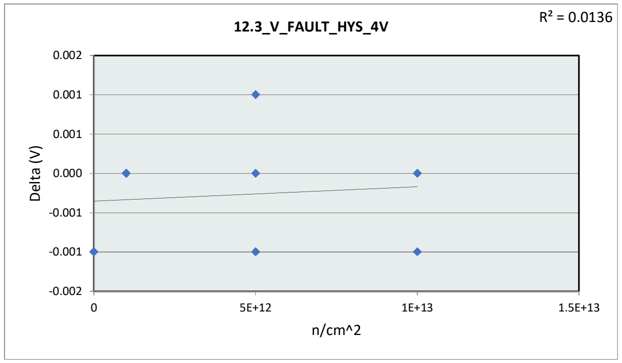


	12.2_V_FAULT_FALL_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.53 V			
Min Limit	0.47 V			
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.510	0.508	0.502	0.496
Average	0.511	0.510	0.505	0.501
Max	0.511	0.512	0.510	0.505
UL	0.530	0.530	0.530	0.530

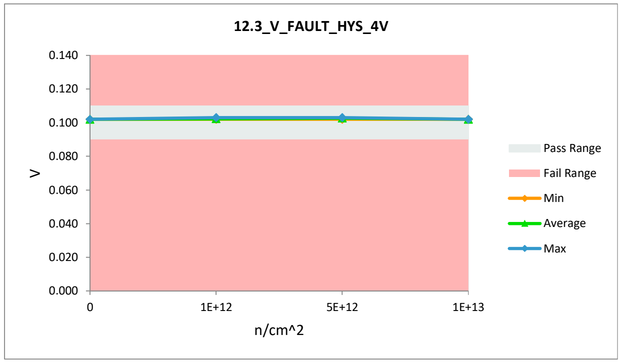


NDD Characterization Report
TPS7H5006-SEP

		12.3_V_FAULT_HYS_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.108	0.11	
	Min Limit	0.092	0.09	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.103	0.102	-0.001
0	49	0.103	0.102	-0.001
1E+12	11	0.102	0.102	0.000
1E+12	12	0.103	0.103	0.000
1E+12	13	0.102	0.102	0.000
5E+12	14	0.102	0.103	0.001
5E+12	15	0.103	0.103	0.000
5E+12	16	0.103	0.102	-0.001
1E+13	17	0.102	0.102	0.000
1E+13	18	0.103	0.102	-0.001
1E+13	19	0.102	0.102	0.000
	Max	0.103	0.103	0.001
	Average	0.103	0.102	0.000
	Min	0.102	0.102	-0.001
	Std Dev	0.001	0.000	0.001

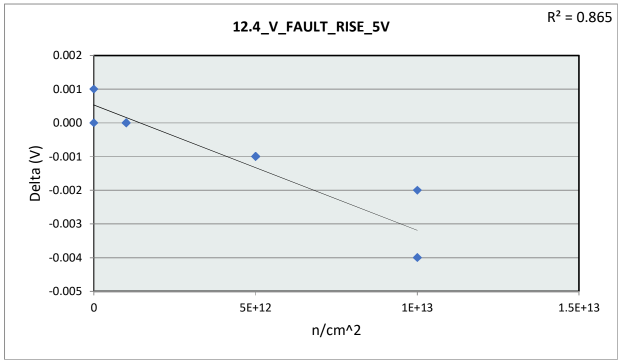


	12.3_V_FAULT_HYS_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.102	0.102
Average	0.102	0.102	0.103	0.102
Max	0.102	0.103	0.103	0.102
UL	0.110	0.110	0.110	0.110

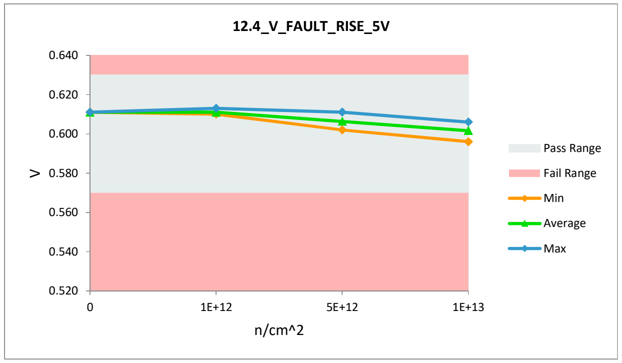


NDD Characterization Report
TPS7H5006-SEP

		12.4_V_FAULT_RISE_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.610	0.611	0.001
0	49	0.611	0.611	0.000
1E+12	11	0.610	0.610	0.000
1E+12	12	0.613	0.613	0.000
1E+12	13	0.610	0.610	0.000
5E+12	14	0.607	0.606	-0.001
5E+12	15	0.603	0.602	-0.001
5E+12	16	0.612	0.611	-0.001
1E+13	17	0.605	0.603	-0.002
1E+13	18	0.610	0.606	-0.004
1E+13	19	0.600	0.596	-0.004
	Max	0.613	0.613	0.001
	Average	0.608	0.607	-0.001
	Min	0.600	0.596	-0.004
	Std Dev	0.004	0.005	0.002

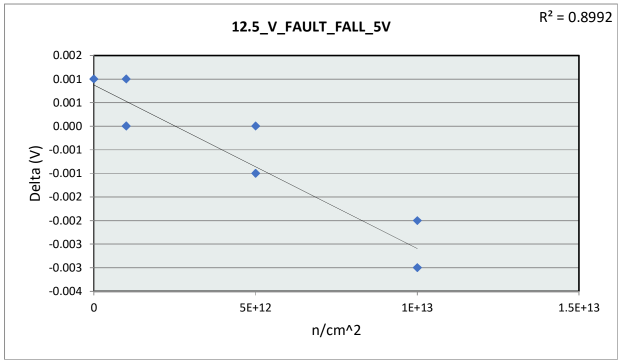


	12.4_V_FAULT_RISE_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.611	0.610	0.602	0.596
Average	0.611	0.611	0.606	0.602
Max	0.611	0.613	0.611	0.606
UL	0.630	0.630	0.630	0.630

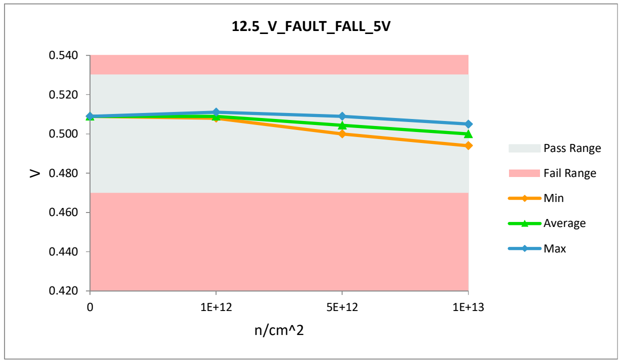


NDD Characterization Report
TPS7H5006-SEP

		12.5_V_FAULT_FALL_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.508	0.509	0.001
0	49	0.508	0.509	0.001
1E+12	11	0.508	0.508	0.000
1E+12	12	0.510	0.511	0.001
1E+12	13	0.508	0.508	0.000
5E+12	14	0.505	0.504	-0.001
5E+12	15	0.500	0.500	0.000
5E+12	16	0.510	0.509	-0.001
1E+13	17	0.503	0.501	-0.002
1E+13	18	0.508	0.505	-0.003
1E+13	19	0.497	0.494	-0.003
	Max	0.510	0.511	0.001
	Average	0.506	0.505	-0.001
	Min	0.497	0.494	-0.003
	Std Dev	0.004	0.005	0.002

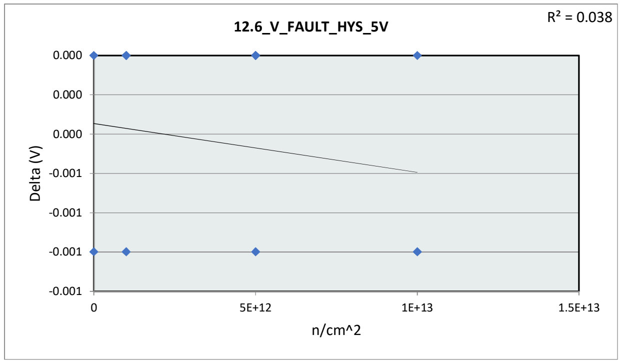


	12.5_V_FAULT_FALL_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.509	0.508	0.500	0.494
Average	0.509	0.509	0.504	0.500
Max	0.509	0.511	0.509	0.505
UL	0.530	0.530	0.530	0.530

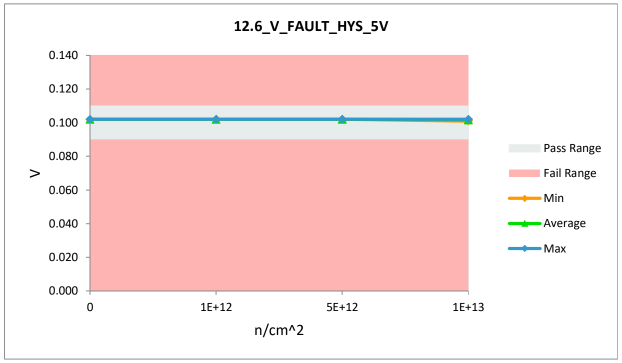


NDD Characterization Report
TPS7H5006-SEP

		12.6_V_FAULT_HYS_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.108	0.11	
	Min Limit	0.092	0.09	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.102	0.102	0.000
0	49	0.103	0.102	-0.001
1E+12	11	0.102	0.102	0.000
1E+12	12	0.103	0.102	-0.001
1E+12	13	0.102	0.102	0.000
5E+12	14	0.102	0.102	0.000
5E+12	15	0.103	0.102	-0.001
5E+12	16	0.102	0.102	0.000
1E+13	17	0.102	0.102	0.000
1E+13	18	0.102	0.101	-0.001
1E+13	19	0.103	0.102	-0.001
	Max	0.103	0.102	0.000
	Average	0.102	0.102	0.000
	Min	0.102	0.101	-0.001
	Std Dev	0.001	0.000	0.001

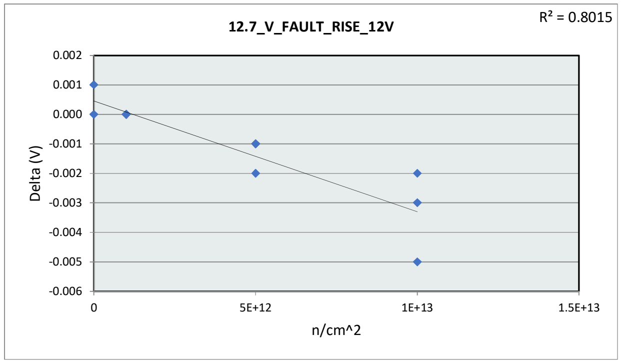


	12.6_V_FAULT_HYS_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.102	0.101
Average	0.102	0.102	0.102	0.102
Max	0.102	0.102	0.102	0.102
UL	0.110	0.110	0.110	0.110

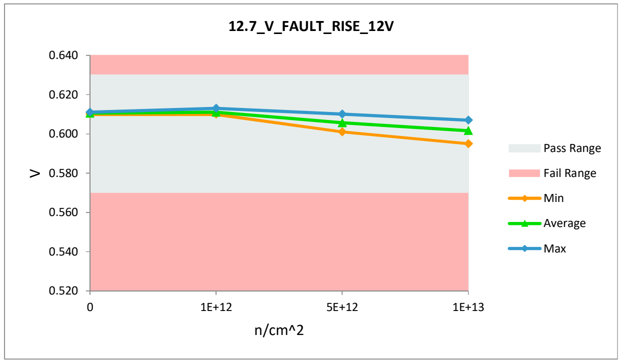


NDD Characterization Report
TPS7H5006-SEP

		12.7_V_FAULT_RISE_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.610	0.610	0.000
0	49	0.610	0.611	0.001
1E+12	11	0.610	0.610	0.000
1E+12	12	0.613	0.613	0.000
1E+12	13	0.610	0.610	0.000
5E+12	14	0.607	0.606	-0.001
5E+12	15	0.602	0.601	-0.001
5E+12	16	0.612	0.610	-0.002
1E+13	17	0.605	0.603	-0.002
1E+13	18	0.610	0.607	-0.003
1E+13	19	0.600	0.595	-0.005
	Max	0.613	0.613	0.001
	Average	0.608	0.607	-0.001
	Min	0.600	0.595	-0.005
	Std Dev	0.004	0.005	0.002

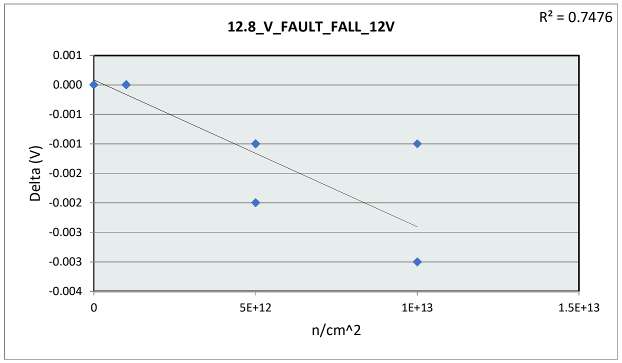


	12.7_V_FAULT_RISE_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.63 V			
Min Limit	0.57 V			
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.610	0.610	0.601	0.595
Average	0.611	0.611	0.606	0.602
Max	0.611	0.613	0.610	0.607
UL	0.630	0.630	0.630	0.630

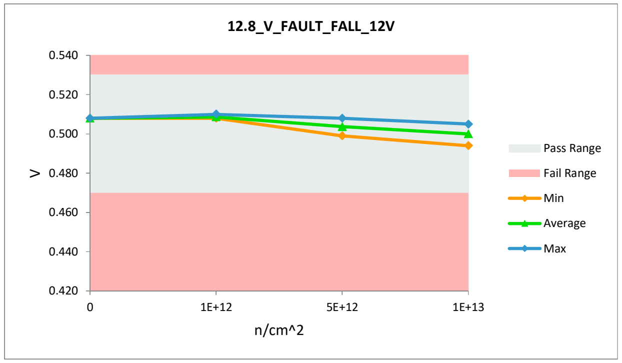


NDD Characterization Report
TPS7H5006-SEP

		12.8_V_FAULT_FALL_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.508	0.508	0.000
0	49	0.508	0.508	0.000
1E+12	11	0.508	0.508	0.000
1E+12	12	0.510	0.510	0.000
1E+12	13	0.508	0.508	0.000
5E+12	14	0.505	0.504	-0.001
5E+12	15	0.500	0.499	-0.001
5E+12	16	0.510	0.508	-0.002
1E+13	17	0.502	0.501	-0.001
1E+13	18	0.508	0.505	-0.003
1E+13	19	0.497	0.494	-0.003
	Max	0.510	0.510	0.000
	Average	0.506	0.505	-0.001
	Min	0.497	0.494	-0.003
	Std Dev	0.004	0.005	0.001

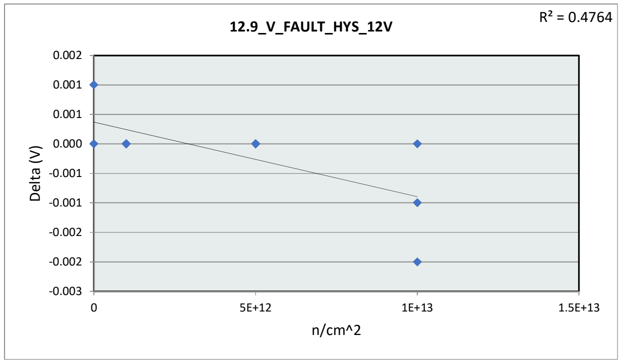


	12.8_V_FAULT_FALL_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.508	0.508	0.499	0.494
Average	0.508	0.509	0.504	0.500
Max	0.508	0.510	0.508	0.505
UL	0.530	0.530	0.530	0.530

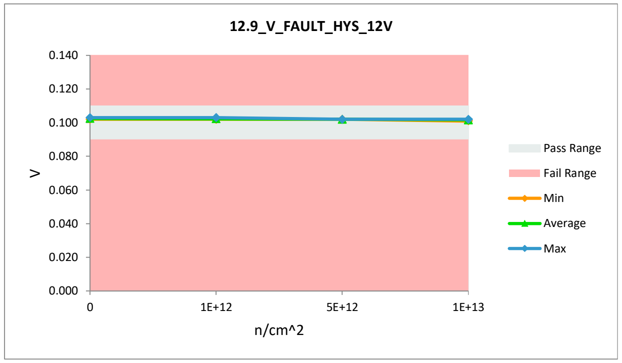


NDD Characterization Report
TPS7H5006-SEP

		12.9_V_FAULT_HYS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.108	0.11	
	Min Limit	0.092	0.09	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.102	0.102	0.000
0	49	0.102	0.103	0.001
1E+12	11	0.102	0.102	0.000
1E+12	12	0.103	0.103	0.000
1E+12	13	0.102	0.102	0.000
5E+12	14	0.102	0.102	0.000
5E+12	15	0.102	0.102	0.000
5E+12	16	0.102	0.102	0.000
1E+13	17	0.103	0.102	-0.001
1E+13	18	0.102	0.102	0.000
1E+13	19	0.103	0.101	-0.002
	Max	0.103	0.103	0.001
	Average	0.102	0.102	0.000
	Min	0.102	0.101	-0.002
	Std Dev	0.000	0.001	0.001

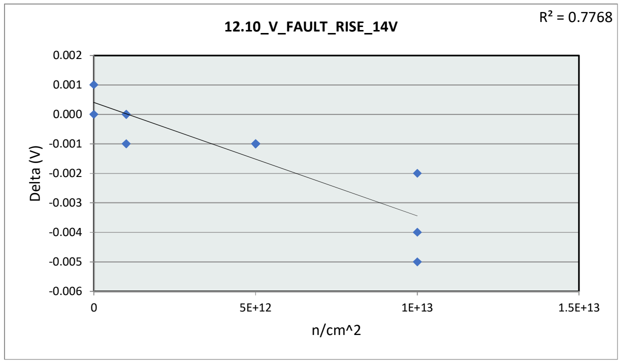


	12.9_V_FAULT_HYS_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.102	0.101
Average	0.103	0.102	0.102	0.102
Max	0.103	0.103	0.102	0.102
UL	0.110	0.110	0.110	0.110

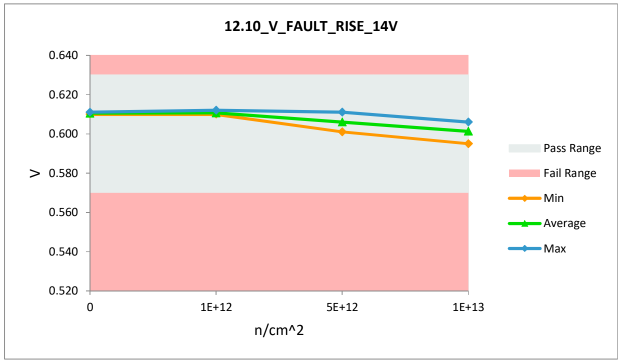


NDD Characterization Report
TPS7H5006-SEP

		12.10_V_FAULT_RISE_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.63	0.63	
Min Limit		0.58	0.57	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.610	0.610	0.000
0	49	0.610	0.611	0.001
1E+12	11	0.610	0.610	0.000
1E+12	12	0.613	0.612	-0.001
1E+12	13	0.610	0.610	0.000
5E+12	14	0.607	0.606	-0.001
5E+12	15	0.602	0.601	-0.001
5E+12	16	0.612	0.611	-0.001
1E+13	17	0.605	0.603	-0.002
1E+13	18	0.610	0.606	-0.004
1E+13	19	0.600	0.595	-0.005
	Max	0.613	0.612	0.001
	Average	0.608	0.607	-0.001
	Min	0.600	0.595	-0.005
	Std Dev	0.004	0.005	0.002

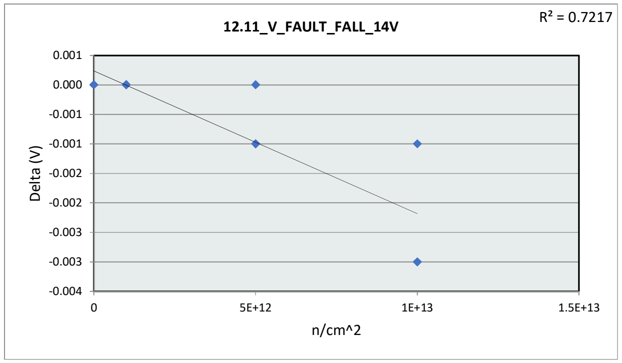


	12.10_V_FAULT_RISE_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.610	0.610	0.601	0.595
Average	0.611	0.611	0.606	0.601
Max	0.611	0.612	0.611	0.606
UL	0.630	0.630	0.630	0.630

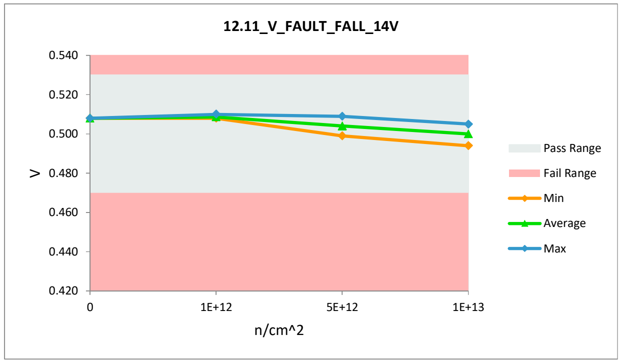


NDD Characterization Report
TPS7H5006-SEP

		12.11_V_FAULT_FALL_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.53	0.53	
Min Limit		0.48	0.47	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.508	0.508	0.000
0	49	0.508	0.508	0.000
1E+12	11	0.508	0.508	0.000
1E+12	12	0.510	0.510	0.000
1E+12	13	0.508	0.508	0.000
5E+12	14	0.504	0.504	0.000
5E+12	15	0.500	0.499	-0.001
5E+12	16	0.510	0.509	-0.001
1E+13	17	0.502	0.501	-0.001
1E+13	18	0.508	0.505	-0.003
1E+13	19	0.497	0.494	-0.003
	Max	0.510	0.510	0.000
	Average	0.506	0.505	-0.001
	Min	0.497	0.494	-0.003
	Std Dev	0.004	0.005	0.001

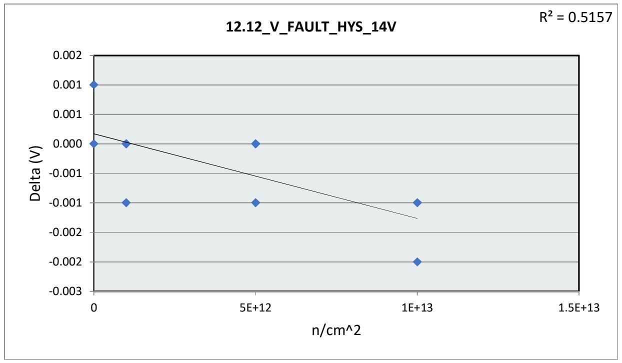


	12.11_V_FAULT_FALL_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.53 V			
Min Limit	0.47 V			
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.508	0.508	0.499	0.494
Average	0.508	0.509	0.504	0.500
Max	0.508	0.510	0.509	0.505
UL	0.530	0.530	0.530	0.530

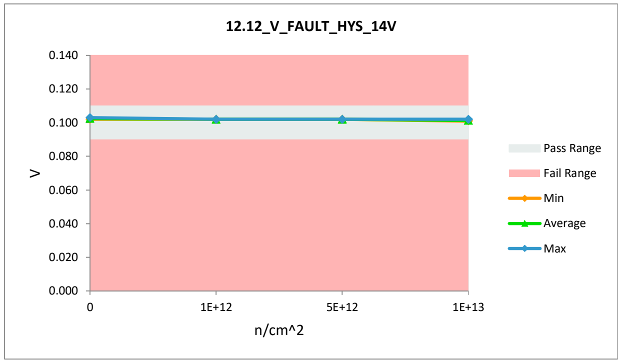


NDD Characterization Report
TPS7H5006-SEP

		12.12_V_FAULT_HYS_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.108	0.11	
	Min Limit	0.092	0.09	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.102	0.102	0.000
0	49	0.102	0.103	0.001
1E+12	11	0.102	0.102	0.000
1E+12	12	0.103	0.102	-0.001
1E+12	13	0.102	0.102	0.000
5E+12	14	0.103	0.102	-0.001
5E+12	15	0.102	0.102	0.000
5E+12	16	0.102	0.102	0.000
1E+13	17	0.103	0.102	-0.001
1E+13	18	0.102	0.101	-0.001
1E+13	19	0.103	0.101	-0.002
	Max	0.103	0.103	0.001
	Average	0.102	0.102	0.000
	Min	0.102	0.101	-0.002
	Std Dev	0.001	0.001	0.001

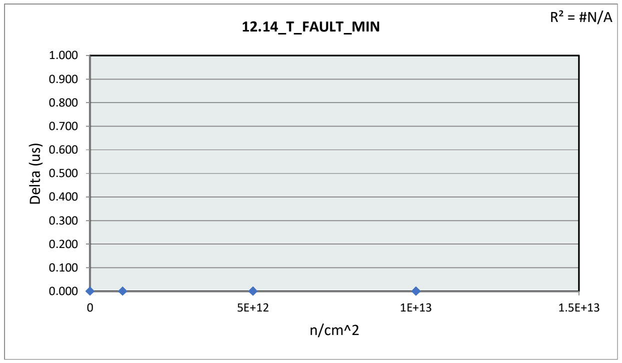


	12.12_V_FAULT_HYS_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.102	0.101
Average	0.103	0.102	0.102	0.101
Max	0.103	0.102	0.102	0.102
UL	0.110	0.110	0.110	0.110

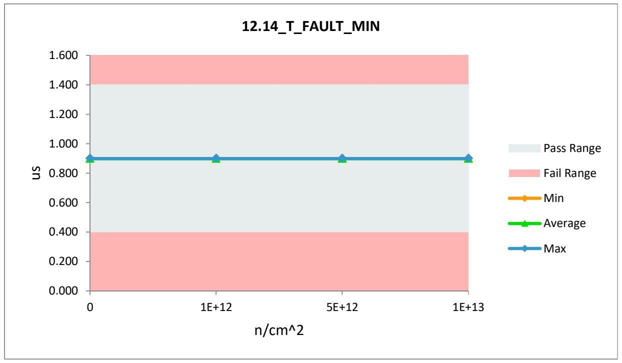


NDD Characterization Report
TPS7H5006-SEP

		12.14_T_FAULT_MIN		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	1.2	1.4	
	Min Limit	0.6	0.4	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	0.900	0.900	0.000
0	49	0.900	0.900	0.000
1E+12	11	0.900	0.900	0.000
1E+12	12	0.900	0.900	0.000
1E+12	13	0.900	0.900	0.000
5E+12	14	0.900	0.900	0.000
5E+12	15	0.900	0.900	0.000
5E+12	16	0.900	0.900	0.000
1E+13	17	0.900	0.900	0.000
1E+13	18	0.900	0.900	0.000
1E+13	19	0.900	0.900	0.000
	Max	0.900	0.900	0.000
	Average	0.900	0.900	0.000
	Min	0.900	0.900	0.000
	Std Dev	0.000	0.000	0.000

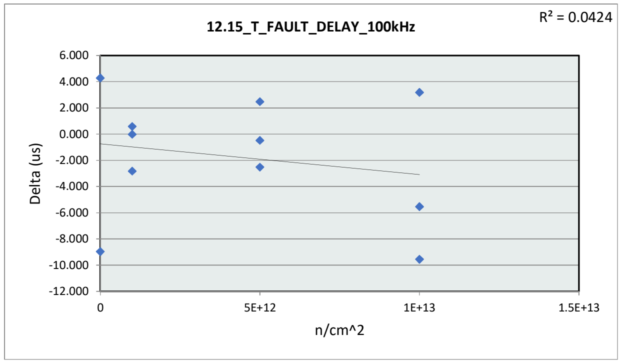


	12.14_T_FAULT_MIN			
Test Site				
Tester				
Test Number				
Max Limit	1.4	us		
Min Limit	0.4	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.400	0.400	0.400	0.400
Min	0.900	0.900	0.900	0.900
Average	0.900	0.900	0.900	0.900
Max	0.900	0.900	0.900	0.900
UL	1.400	1.400	1.400	1.400

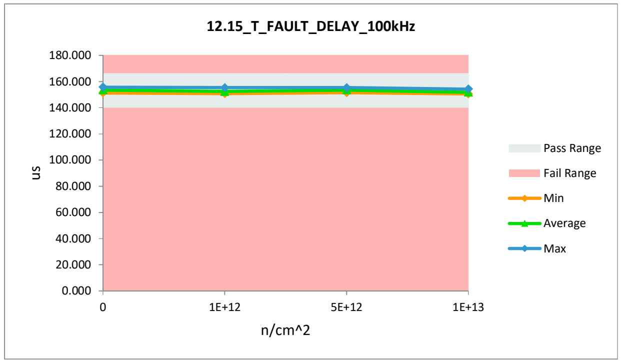


NDD Characterization Report
TPS7H5006-SEP

		12.15_T_FAULT_DELAY_100kHz		
Test Site				
Tester				
Test Number				
Unit		us	us	
Max Limit		166	166	
Min Limit		140	140	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	160.311	151.330	-8.981
0	49	151.433	155.700	4.267
1E+12	11	153.528	150.692	-2.836
1E+12	12	154.748	155.327	0.579
1E+12	13	150.935	150.911	-0.024
5E+12	14	157.909	155.377	-2.532
5E+12	15	151.252	153.712	2.460
5E+12	16	151.914	151.425	-0.489
1E+13	17	160.029	150.467	-9.562
1E+13	18	151.114	154.282	3.168
1E+13	19	156.232	150.683	-5.549
	Max	160.311	155.700	4.267
	Average	154.491	152.719	-1.773
	Min	150.935	150.467	-9.562
	Std Dev	3.616	2.154	4.665

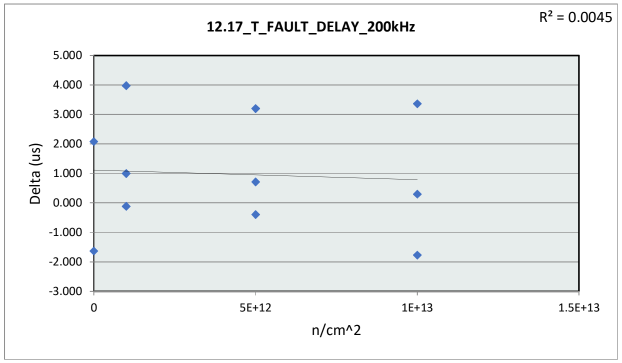


	12.15_T_FAULT_DELAY_100kH			
Test Site				
Tester				
Test Number				
Max Limit	166	us		
Min Limit	140	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	140.000	140.000	140.000	140.000
Min	151.330	150.692	151.425	150.467
Average	153.515	152.310	153.505	151.811
Max	155.700	155.327	155.377	154.282
UL	166.000	166.000	166.000	166.000

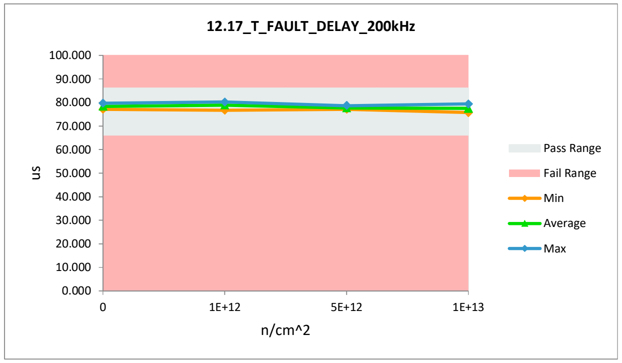


NDD Characterization Report
TPS7H5006-SEP

		12.17_T_FAULT_DELAY_200kHz		
Test Site				
Tester				
Test Number				
Unit		us	us	
Max Limit		86	86	
Min Limit		70	66	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	78.669	77.034	-1.635
0	49	77.582	79.658	2.076
1E+12	11	76.770	76.646	-0.124
1E+12	12	76.209	80.181	3.972
1E+12	13	78.747	79.738	0.991
5E+12	14	76.345	77.054	0.709
5E+12	15	75.475	78.668	3.193
5E+12	16	77.683	77.281	-0.402
1E+13	17	77.209	77.496	0.287
1E+13	18	75.997	79.354	3.357
1E+13	19	77.474	75.698	-1.776
	Max	78.747	80.181	3.972
	Average	77.105	78.073	0.968
	Min	75.475	75.698	-1.776
	Std Dev	1.060	1.499	1.970

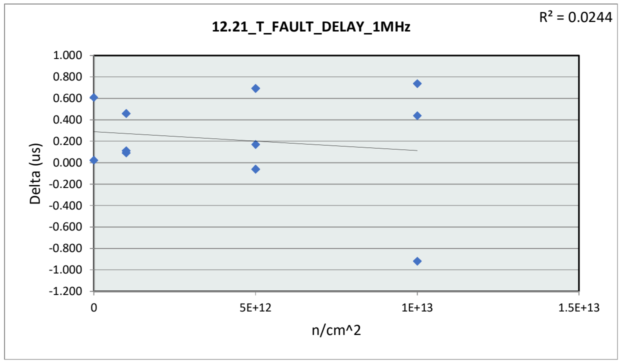


	12.17_T_FAULT_DELAY_200kH			
Test Site				
Tester				
Test Number				
Max Limit	86	us		
Min Limit	66	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	66.000	66.000	66.000	66.000
Min	77.034	76.646	77.054	75.698
Average	78.346	78.855	77.668	77.516
Max	79.658	80.181	78.668	79.354
UL	86.000	86.000	86.000	86.000

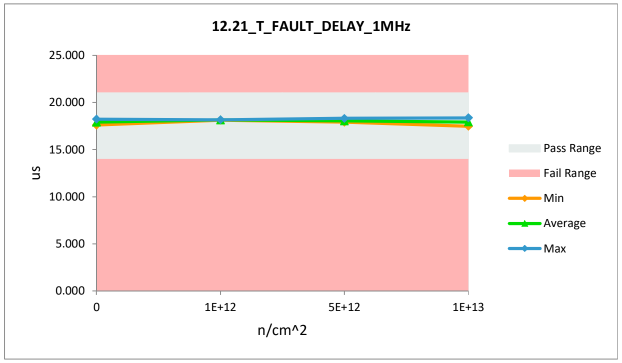


NDD Characterization Report
TPS7H5006-SEP

		12.21_T_FAULT_DELAY_1MHz		
Test Site				
Tester				
Test Number				
Unit		us	us	
Max Limit		21	21	
Min Limit		14	14	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	17.568	17.590	0.022
0	49	17.617	18.224	0.607
1E+12	11	18.081	18.170	0.089
1E+12	12	17.674	18.130	0.456
1E+12	13	18.044	18.153	0.109
5E+12	14	17.980	17.918	-0.062
5E+12	15	17.733	17.901	0.168
5E+12	16	17.618	18.309	0.691
1E+13	17	18.387	17.467	-0.920
1E+13	18	17.637	18.374	0.737
1E+13	19	17.515	17.953	0.438
	Max	18.387	18.374	0.737
	Average	17.805	18.017	0.212
	Min	17.515	17.467	-0.920
	Std Dev	0.276	0.287	0.468

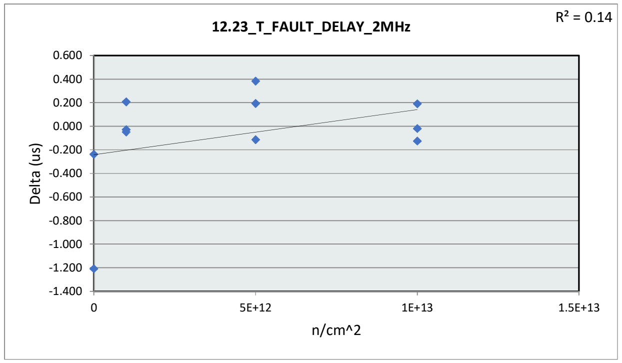


	12.21_T_FAULT_DELAY_1MHz			
Test Site				
Tester				
Test Number				
Max Limit	21	us		
Min Limit	14	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	14.000	14.000	14.000	14.000
Min	17.590	18.130	17.901	17.467
Average	17.907	18.151	18.043	17.931
Max	18.224	18.170	18.309	18.374
UL	21.000	21.000	21.000	21.000

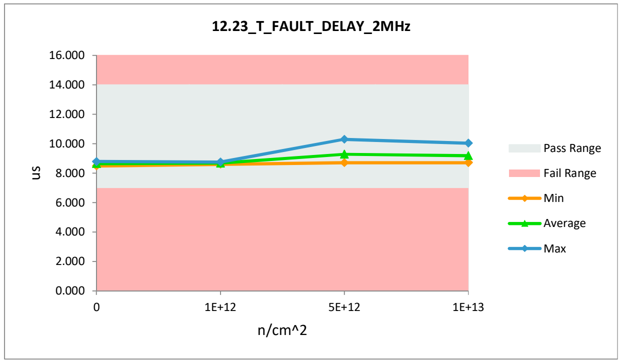


NDD Characterization Report
TPS7H5006-SEP

n/cm^2		12.23_T_FAULT_DELAY_2MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	14	14	
	Min Limit	7	7	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.728	8.489	-0.239
0	49	9.991	8.782	-1.209
1E+12	11	8.551	8.756	0.205
1E+12	12	8.693	8.663	-0.030
1E+12	13	8.655	8.605	-0.050
5E+12	14	8.508	8.700	0.192
5E+12	15	8.464	8.845	0.381
5E+12	16	10.419	10.303	-0.116
1E+13	17	10.051	10.031	-0.020
1E+13	18	8.946	8.819	-0.127
1E+13	19	8.526	8.715	0.189
	Max	10.419	10.303	0.381
	Average	9.048	8.973	-0.075
	Min	8.464	8.489	-1.209
	Std Dev	0.729	0.602	0.418

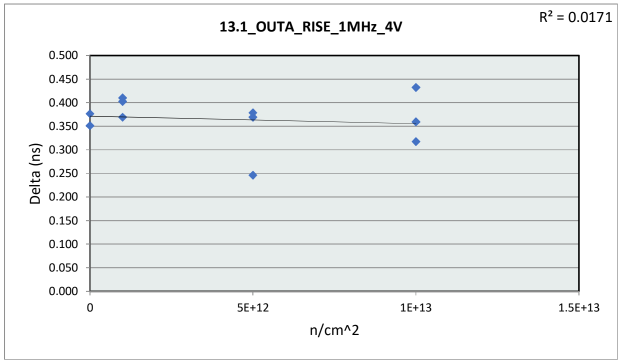


	12.23_T_FAULT_DELAY_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	14	us		
Min Limit	7	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	7.000	7.000	7.000	7.000
Min	8.489	8.605	8.700	8.715
Average	8.636	8.675	9.283	9.188
Max	8.782	8.756	10.303	10.031
UL	14.000	14.000	14.000	14.000

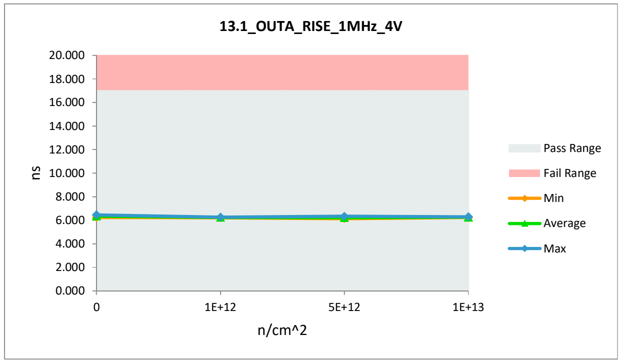


NDD Characterization Report
TPS7H5006-SEP

		13.1_OUTA_RISE_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	5.891	6.242	0.351
0	49	6.065	6.441	0.376
1E+12	11	5.892	6.261	0.369
1E+12	12	5.810	6.220	0.410
1E+12	13	5.812	6.214	0.402
5E+12	14	5.941	6.187	0.246
5E+12	15	5.758	6.136	0.378
5E+12	16	5.965	6.334	0.369
1E+13	17	5.883	6.242	0.359
1E+13	18	5.817	6.249	0.432
1E+13	19	5.963	6.280	0.317
	Max	6.065	6.441	0.432
	Average	5.891	6.255	0.364
	Min	5.758	6.136	0.246
	Std Dev	0.089	0.080	0.050

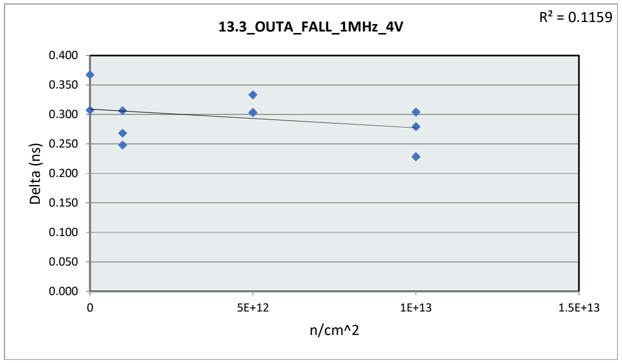


	13.1_OUTA_RISE_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.242	6.214	6.136	6.242
Average	6.342	6.232	6.219	6.257
Max	6.441	6.261	6.334	6.280
UL	17.000	17.000	17.000	17.000

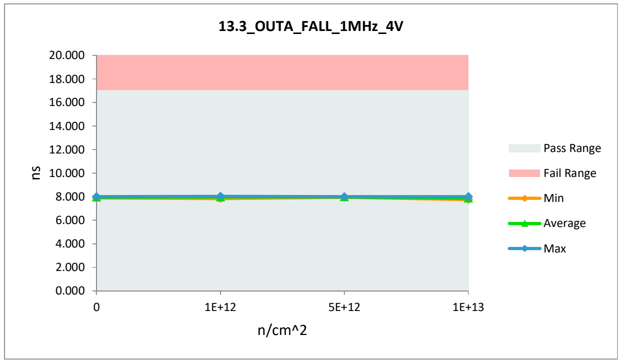


NDD Characterization Report
TPS7H5006-SEP

		13.3_OUTA_FALL_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.514	7.881	0.367
0	49	7.693	8.000	0.307
1E+12	11	7.579	7.847	0.268
1E+12	12	7.736	8.042	0.306
1E+12	13	7.751	7.999	0.248
5E+12	14	7.694	7.997	0.303
5E+12	15	7.662	7.995	0.333
5E+12	16	7.659	7.962	0.303
1E+13	17	7.527	7.755	0.228
1E+13	18	7.696	8.000	0.304
1E+13	19	7.579	7.858	0.279
	Max	7.751	8.042	0.367
	Average	7.645	7.940	0.295
	Min	7.514	7.755	0.228
	Std Dev	0.082	0.090	0.038

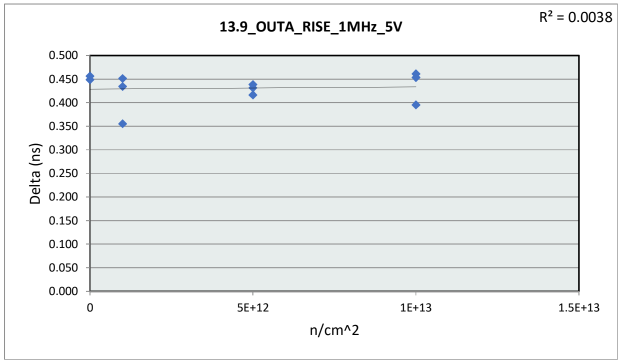


	13.3_OUTA_FALL_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.881	7.847	7.962	7.755
Average	7.941	7.963	7.985	7.871
Max	8.000	8.042	7.997	8.000
UL	17.000	17.000	17.000	17.000

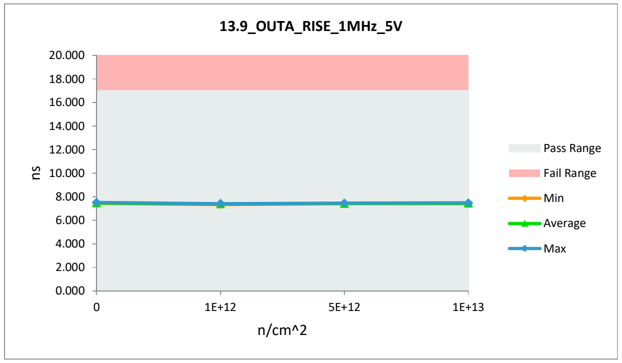


NDD Characterization Report
TPS7H5006-SEP

		13.9_OUTA_RISE_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.963	7.419	0.456
0	49	7.065	7.513	0.448
1E+12	11	6.959	7.393	0.434
1E+12	12	6.967	7.418	0.451
1E+12	13	6.980	7.335	0.355
5E+12	14	7.034	7.450	0.416
5E+12	15	6.949	7.387	0.438
5E+12	16	7.003	7.434	0.431
1E+13	17	7.021	7.416	0.395
1E+13	18	6.979	7.432	0.453
1E+13	19	7.017	7.478	0.461
	Max	7.065	7.513	0.461
	Average	6.994	7.425	0.431
	Min	6.949	7.335	0.355
	Std Dev	0.037	0.047	0.032

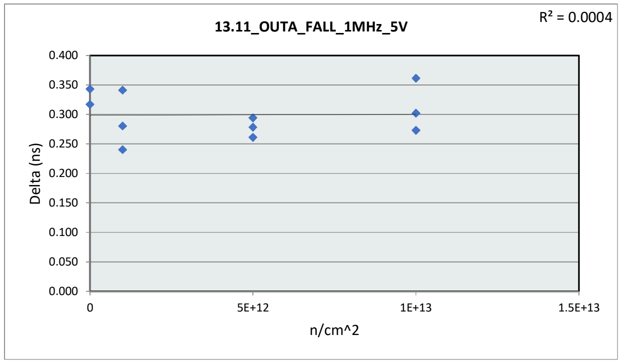


	13.9_OUTA_RISE_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.419	7.335	7.387	7.416
Average	7.466	7.382	7.424	7.442
Max	7.513	7.418	7.450	7.478
UL	17.000	17.000	17.000	17.000

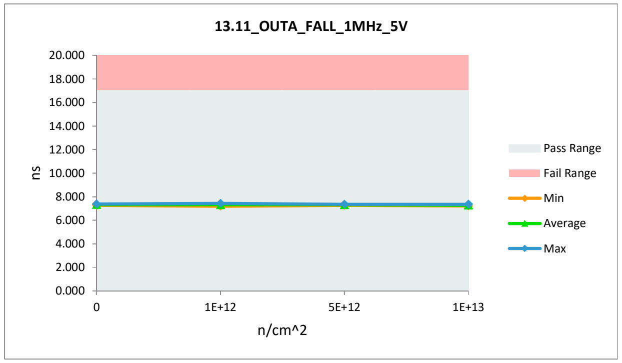


NDD Characterization Report
TPS7H5006-SEP

		13.11_OUTA_FALL_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.964	7.281	0.317
0	49	7.030	7.373	0.343
1E+12	11	6.937	7.177	0.240
1E+12	12	7.081	7.422	0.341
1E+12	13	7.057	7.337	0.280
5E+12	14	7.059	7.353	0.294
5E+12	15	7.030	7.291	0.261
5E+12	16	7.004	7.282	0.278
1E+13	17	6.942	7.215	0.273
1E+13	18	6.994	7.355	0.361
1E+13	19	6.940	7.242	0.302
	Max	7.081	7.422	0.361
	Average	7.003	7.303	0.299
	Min	6.937	7.177	0.240
	Std Dev	0.052	0.073	0.038

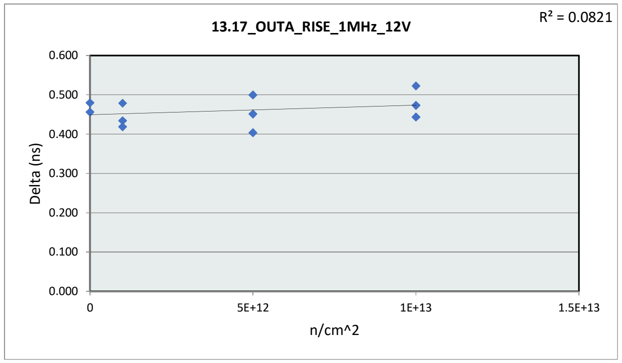


	13.11_OUTA_FALL_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.281	7.177	7.282	7.215
Average	7.327	7.312	7.309	7.271
Max	7.373	7.422	7.353	7.355
UL	17.000	17.000	17.000	17.000

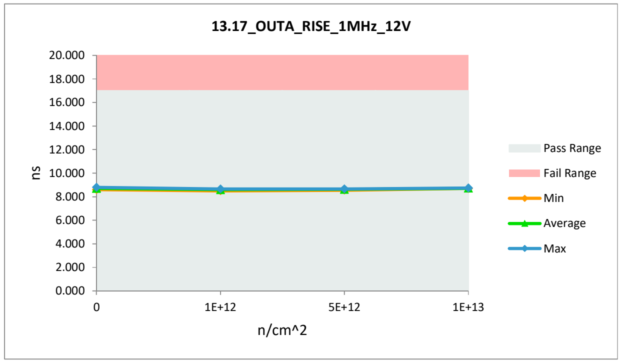


NDD Characterization Report
TPS7H5006-SEP

		13.17_OUTA_RISE_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.151	8.607	0.456
0	49	8.317	8.796	0.479
1E+12	11	8.086	8.504	0.418
1E+12	12	8.179	8.613	0.434
1E+12	13	8.169	8.647	0.478
5E+12	14	8.199	8.650	0.451
5E+12	15	8.140	8.543	0.403
5E+12	16	8.162	8.661	0.499
1E+13	17	8.212	8.734	0.522
1E+13	18	8.235	8.708	0.473
1E+13	19	8.254	8.697	0.443
	Max	8.317	8.796	0.522
	Average	8.191	8.651	0.460
	Min	8.086	8.504	0.403
	Std Dev	0.062	0.084	0.035

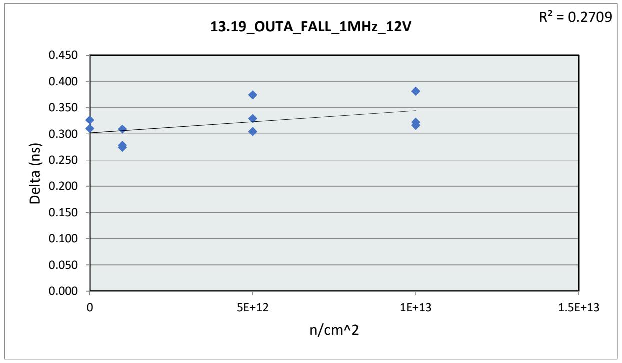


	13.17_OUTA_RISE_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.607	8.504	8.543	8.697
Average	8.702	8.588	8.618	8.713
Max	8.796	8.647	8.661	8.734
UL	17.000	17.000	17.000	17.000

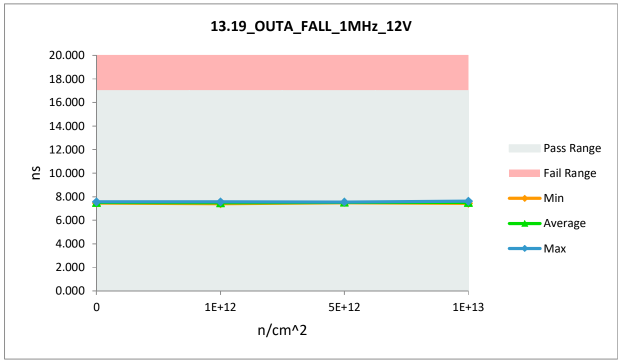


NDD Characterization Report
TPS7H5006-SEP

		13.19_OUTA_FALL_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.124	7.450	0.326
0	49	7.249	7.559	0.310
1E+12	11	7.084	7.393	0.309
1E+12	12	7.281	7.555	0.274
1E+12	13	7.217	7.495	0.278
5E+12	14	7.240	7.544	0.304
5E+12	15	7.158	7.532	0.374
5E+12	16	7.162	7.491	0.329
1E+13	17	7.107	7.429	0.322
1E+13	18	7.229	7.610	0.381
1E+13	19	7.172	7.488	0.316
	Max	7.281	7.610	0.381
	Average	7.184	7.504	0.320
	Min	7.084	7.393	0.274
	Std Dev	0.064	0.064	0.033

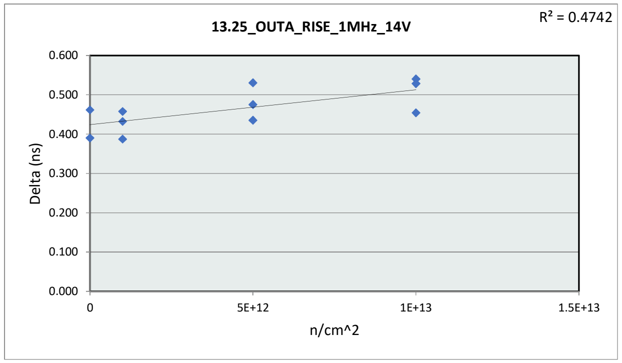


	13.19_OUTA_FALL_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.450	7.393	7.491	7.429
Average	7.505	7.481	7.522	7.509
Max	7.559	7.555	7.544	7.610
UL	17.000	17.000	17.000	17.000

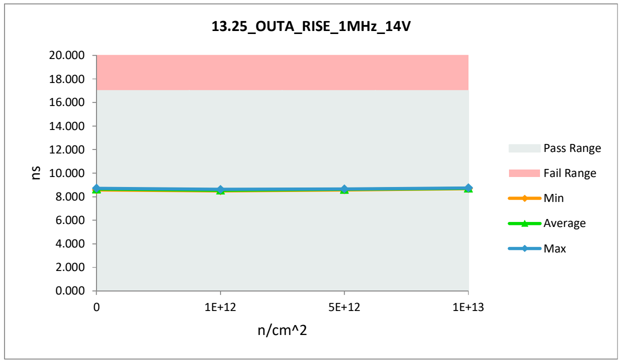


NDD Characterization Report
TPS7H5006-SEP

		13.25_OUTA_RISE_1MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	16.5	17	
	Min Limit	4	0	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.108	8.569	0.461
0	49	8.322	8.712	0.390
1E+12	11	8.032	8.489	0.457
1E+12	12	8.151	8.538	0.387
1E+12	13	8.185	8.617	0.432
5E+12	14	8.184	8.619	0.435
5E+12	15	8.113	8.588	0.475
5E+12	16	8.121	8.651	0.530
1E+13	17	8.210	8.750	0.540
1E+13	18	8.188	8.716	0.528
1E+13	19	8.238	8.692	0.454
	Max	8.322	8.750	0.540
	Average	8.168	8.631	0.463
	Min	8.032	8.489	0.387
	Std Dev	0.077	0.082	0.053

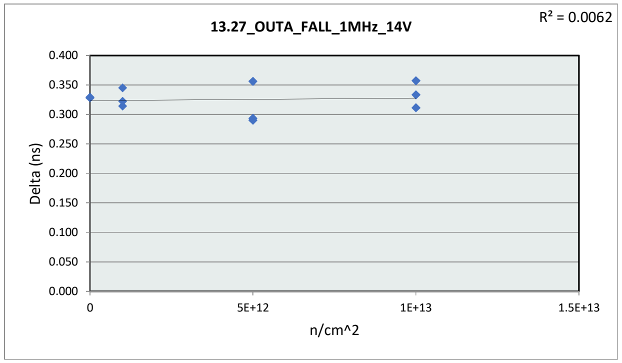


	13.25_OUTA_RISE_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.569	8.489	8.588	8.692
Average	8.641	8.548	8.619	8.719
Max	8.712	8.617	8.651	8.750
UL	17.000	17.000	17.000	17.000



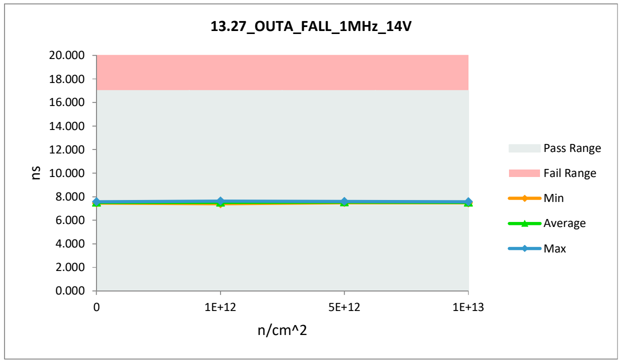
NDD Characterization Report
TPS7H5006-SEP

		13.27_OUTA_FALL_1MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		16.5	17	
Min Limit		4	0	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.135	7.463	0.328
0	49	7.248	7.577	0.329
1E+12	11	7.077	7.399	0.322
1E+12	12	7.285	7.630	0.345
1E+12	13	7.228	7.542	0.314
5E+12	14	7.290	7.583	0.293
5E+12	15	7.214	7.570	0.356
5E+12	16	7.206	7.496	0.290
1E+13	17	7.119	7.476	0.357
1E+13	18	7.253	7.564	0.311
1E+13	19	7.173	7.506	0.333
	Max	7.290	7.630	0.357
	Average	7.203	7.528	0.325
	Min	7.077	7.399	0.290
	Std Dev	0.069	0.066	0.022



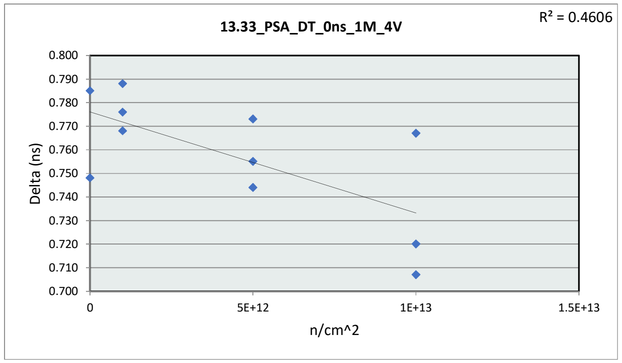
	13.27_OUTA_FALL_1MHz_14V	
Test Site		
Tester		
Test Number		
Max Limit	17	ns
Min Limit	0	ns

n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.463	7.399	7.496	7.476
Average	7.520	7.524	7.550	7.515
Max	7.577	7.630	7.583	7.564
UL	17.000	17.000	17.000	17.000

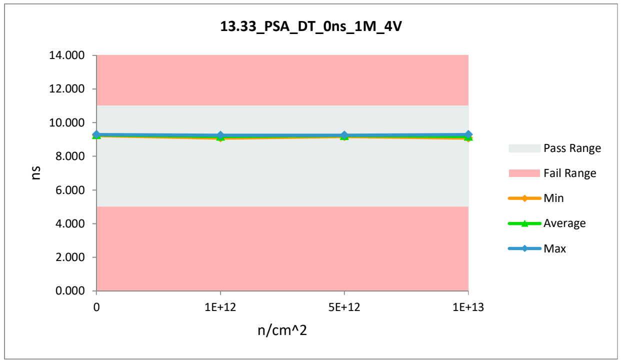


NDD Characterization Report
TPS7H5006-SEP

		13.33_PSA_DT_0ns_1M_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		11	11	
Min Limit		5	5	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	8.495	9.243	0.748
0	49	8.509	9.294	0.785
1E+12	11	8.465	9.253	0.788
1E+12	12	8.436	9.204	0.768
1E+12	13	8.311	9.087	0.776
5E+12	14	8.504	9.259	0.755
5E+12	15	8.425	9.169	0.744
5E+12	16	8.485	9.258	0.773
1E+13	17	8.450	9.170	0.720
1E+13	18	8.381	9.088	0.707
1E+13	19	8.527	9.294	0.767
	Max	8.527	9.294	0.788
	Average	8.453	9.211	0.757
	Min	8.311	9.087	0.707
	Std Dev	0.064	0.074	0.026

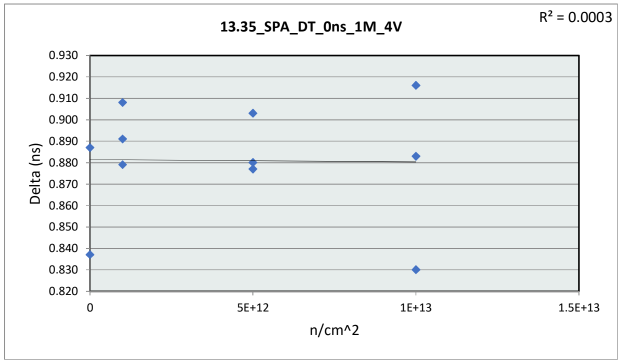


	13.33_PSA_DT_0ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	9.243	9.087	9.169	9.088
Average	9.269	9.181	9.229	9.184
Max	9.294	9.253	9.259	9.294
UL	11.000	11.000	11.000	11.000

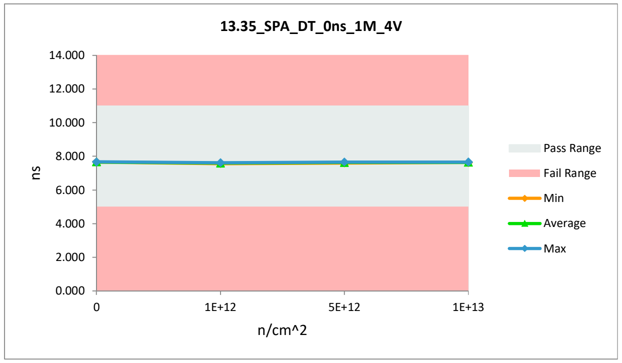


NDD Characterization Report
TPS7H5006-SEP

		13.35_SPA_DT_0ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.829	7.666	0.837
0	49	6.775	7.662	0.887
1E+12	11	6.706	7.614	0.908
1E+12	12	6.715	7.606	0.891
1E+12	13	6.681	7.560	0.879
5E+12	14	6.718	7.621	0.903
5E+12	15	6.723	7.600	0.877
5E+12	16	6.769	7.649	0.880
1E+13	17	6.810	7.640	0.830
1E+13	18	6.713	7.629	0.916
1E+13	19	6.763	7.646	0.883
	Max	6.829	7.666	0.916
	Average	6.746	7.627	0.881
	Min	6.681	7.560	0.830
	Std Dev	0.047	0.031	0.027

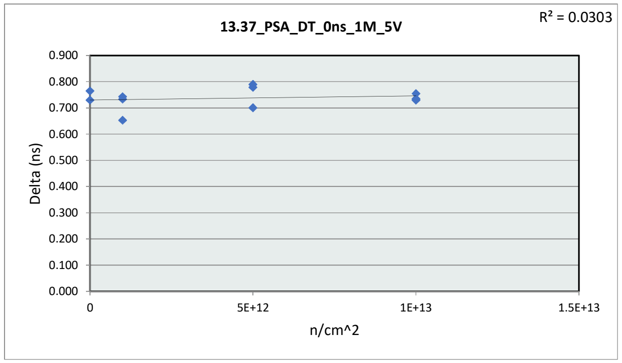


	13.35_SPA_DT_0ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	7.662	7.560	7.600	7.629
Average	7.664	7.593	7.623	7.638
Max	7.666	7.614	7.649	7.646
UL	11.000	11.000	11.000	11.000

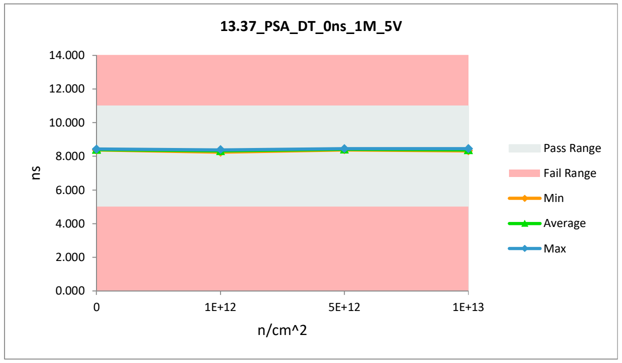


NDD Characterization Report
TPS7H5006-SEP

		13.37_PSA_DT_0ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.609	8.373	0.764
0	49	7.703	8.432	0.729
1E+12	11	7.646	8.388	0.742
1E+12	12	7.625	8.358	0.733
1E+12	13	7.585	8.237	0.652
5E+12	14	7.702	8.402	0.700
5E+12	15	7.604	8.382	0.778
5E+12	16	7.664	8.453	0.789
1E+13	17	7.650	8.379	0.729
1E+13	18	7.593	8.327	0.734
1E+13	19	7.701	8.455	0.754
	Max	7.703	8.455	0.789
	Average	7.644	8.381	0.737
	Min	7.585	8.237	0.652
	Std Dev	0.044	0.062	0.038

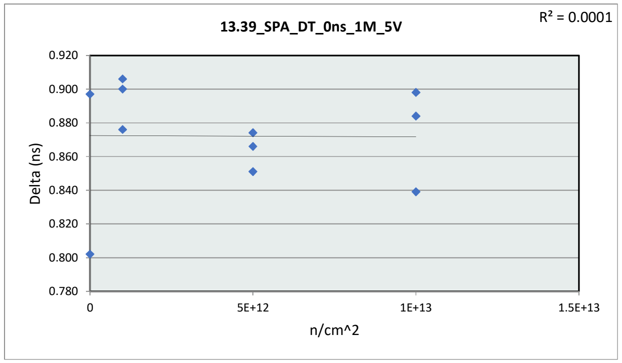


	13.37_PSA_DT_0ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.373	8.237	8.382	8.327
Average	8.403	8.328	8.412	8.387
Max	8.432	8.388	8.453	8.455
UL	11.000	11.000	11.000	11.000

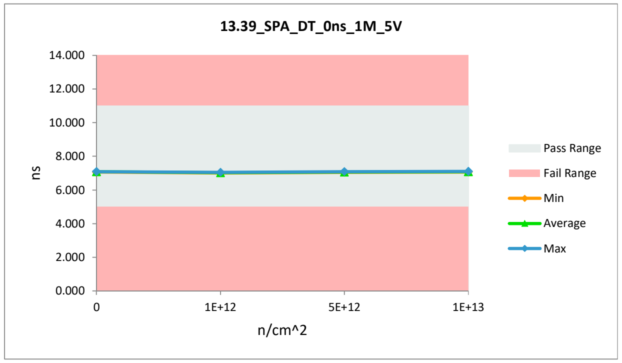


NDD Characterization Report
TPS7H5006-SEP

		13.39_SPA_DT_0ns_1M_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		11	11	
Min Limit		5	5	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.254	7.056	0.802
0	49	6.200	7.097	0.897
1E+12	11	6.108	7.008	0.900
1E+12	12	6.153	7.029	0.876
1E+12	13	6.136	7.042	0.906
5E+12	14	6.170	7.044	0.874
5E+12	15	6.182	7.048	0.866
5E+12	16	6.239	7.090	0.851
1E+13	17	6.216	7.100	0.884
1E+13	18	6.192	7.090	0.898
1E+13	19	6.227	7.066	0.839
	Max	6.254	7.100	0.906
	Average	6.189	7.061	0.872
	Min	6.108	7.008	0.802
	Std Dev	0.045	0.030	0.031

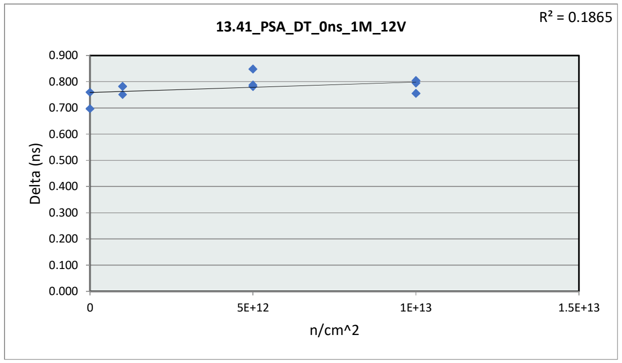


	13.39_SPA_DT_0ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	7.056	7.008	7.044	7.066
Average	7.077	7.026	7.061	7.085
Max	7.097	7.042	7.090	7.100
UL	11.000	11.000	11.000	11.000

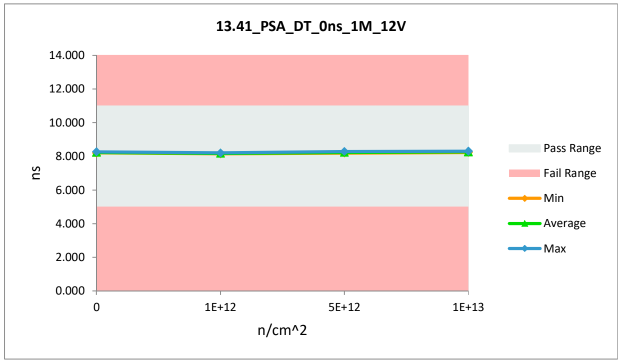


NDD Characterization Report
TPS7H5006-SEP

		13.41_PSA_DT_0ns_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.502	8.198	0.696
0	49	7.510	8.269	0.759
1E+12	11	7.393	8.143	0.750
1E+12	12	7.423	8.204	0.781
1E+12	13	7.390	8.172	0.782
5E+12	14	7.427	8.275	0.848
5E+12	15	7.406	8.187	0.781
5E+12	16	7.457	8.244	0.787
1E+13	17	7.477	8.232	0.755
1E+13	18	7.431	8.235	0.804
1E+13	19	7.507	8.301	0.794
	Max	7.510	8.301	0.848
	Average	7.448	8.224	0.776
	Min	7.390	8.143	0.696
	Std Dev	0.045	0.048	0.038

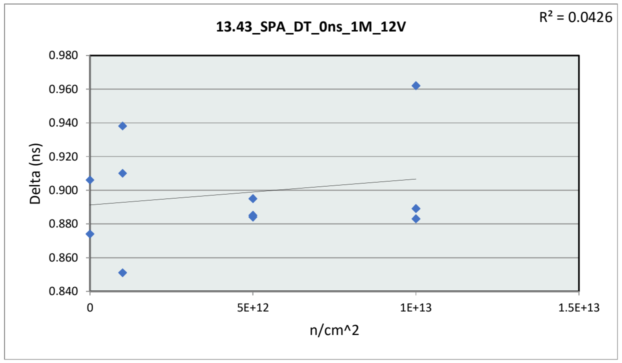


	13.41_PSA_DT_0ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.198	8.143	8.187	8.232
Average	8.234	8.173	8.235	8.256
Max	8.269	8.204	8.275	8.301
UL	11.000	11.000	11.000	11.000

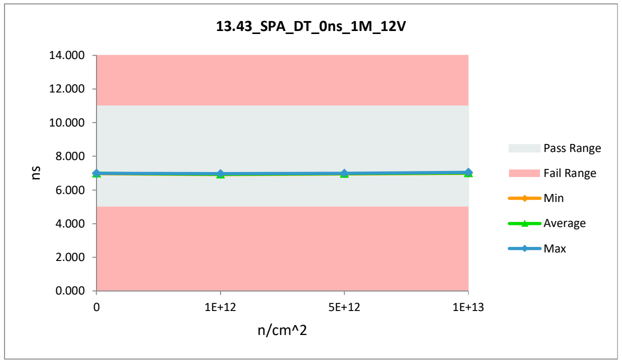


NDD Characterization Report
TPS7H5006-SEP

		13.43_SPA_DT_0ns_1M_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		11	11	
Min Limit		5	5	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.085	6.991	0.906
0	49	6.105	6.979	0.874
1E+12	11	5.984	6.922	0.938
1E+12	12	6.067	6.918	0.851
1E+12	13	6.057	6.967	0.910
5E+12	14	6.073	6.958	0.885
5E+12	15	6.097	6.992	0.895
5E+12	16	6.087	6.971	0.884
1E+13	17	6.120	7.003	0.883
1E+13	18	6.085	7.047	0.962
1E+13	19	6.095	6.984	0.889
	Max	6.120	7.047	0.962
	Average	6.078	6.976	0.898
	Min	5.984	6.918	0.851
	Std Dev	0.036	0.036	0.031

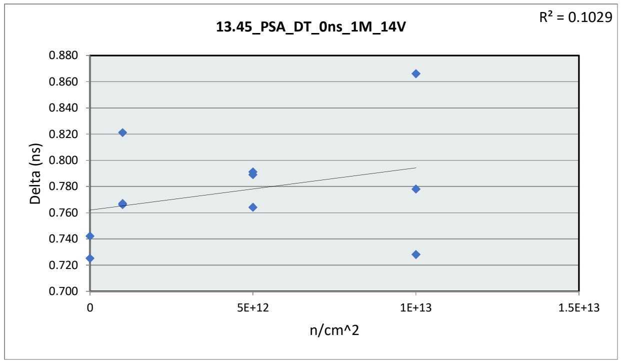


	13.43_SPA_DT_0ns_1M_12V			
Test Site				
Tester				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	6.979	6.918	6.958	6.984
Average	6.985	6.936	6.974	7.011
Max	6.991	6.967	6.992	7.047
UL	11.000	11.000	11.000	11.000

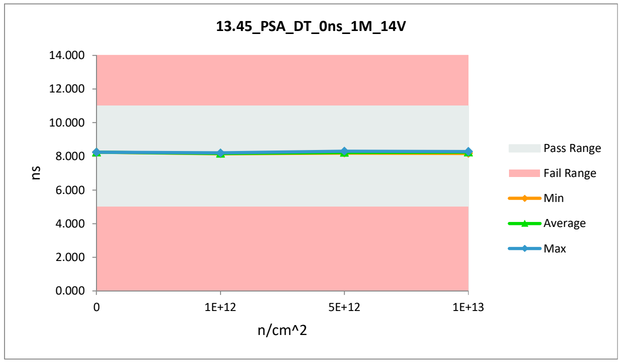


NDD Characterization Report
TPS7H5006-SEP

		13.45_PSA_DT_0ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	7.500	8.242	0.742
0	49	7.515	8.240	0.725
1E+12	11	7.392	8.159	0.767
1E+12	12	7.380	8.201	0.821
1E+12	13	7.392	8.158	0.766
5E+12	14	7.507	8.298	0.791
5E+12	15	7.404	8.193	0.789
5E+12	16	7.460	8.224	0.764
1E+13	17	7.446	8.174	0.728
1E+13	18	7.401	8.267	0.866
1E+13	19	7.503	8.281	0.778
	Max	7.515	8.298	0.866
	Average	7.445	8.222	0.776
	Min	7.380	8.158	0.725
	Std Dev	0.054	0.049	0.041

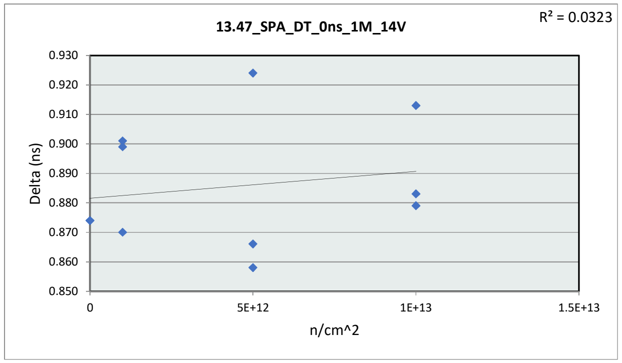


	13.45_PSA_DT_0ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.240	8.158	8.193	8.174
Average	8.241	8.173	8.238	8.241
Max	8.242	8.201	8.298	8.281
UL	11.000	11.000	11.000	11.000

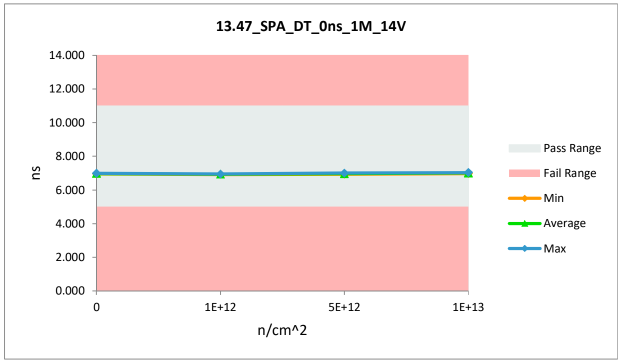


NDD Characterization Report
TPS7H5006-SEP

		13.47_SPA_DT_0ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	6.085	6.959	0.874
0	49	6.115	6.989	0.874
1E+12	11	6.022	6.923	0.901
1E+12	12	6.060	6.930	0.870
1E+12	13	6.048	6.947	0.899
5E+12	14	6.097	6.963	0.866
5E+12	15	6.075	6.933	0.858
5E+12	16	6.074	6.998	0.924
1E+13	17	6.147	7.030	0.883
1E+13	18	6.125	7.004	0.879
1E+13	19	6.067	6.980	0.913
	Max	6.147	7.030	0.924
	Average	6.083	6.969	0.886
	Min	6.022	6.923	0.858
	Std Dev	0.036	0.034	0.021

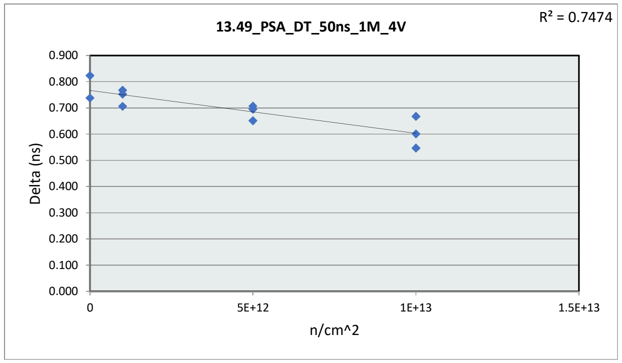


	13.47_SPA_DT_0ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	6.959	6.923	6.933	6.980
Average	6.974	6.933	6.965	7.005
Max	6.989	6.947	6.998	7.030
UL	11.000	11.000	11.000	11.000

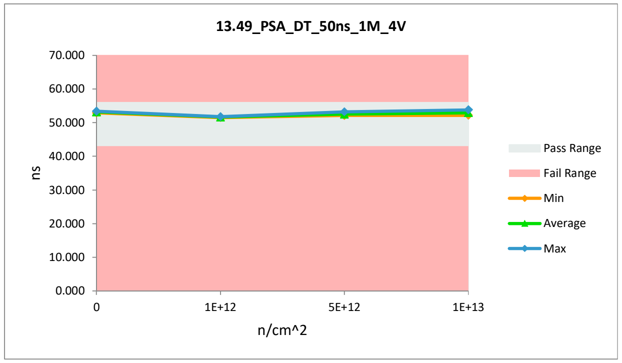


NDD Characterization Report
TPS7H5006-SEP

		13.49_PSA_DT_50ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	56	56	
	Min Limit	44	43	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	52.665	53.402	0.737
0	49	52.120	52.943	0.823
1E+12	11	51.013	51.765	0.752
1E+12	12	50.737	51.504	0.767
1E+12	13	51.094	51.800	0.706
5E+12	14	51.579	52.285	0.706
5E+12	15	51.465	52.116	0.651
5E+12	16	52.518	53.213	0.695
1E+13	17	53.270	53.816	0.546
1E+13	18	52.117	52.784	0.667
1E+13	19	51.575	52.175	0.600
	Max	53.270	53.816	0.823
	Average	51.832	52.528	0.695
	Min	50.737	51.504	0.546
	Std Dev	0.779	0.751	0.078

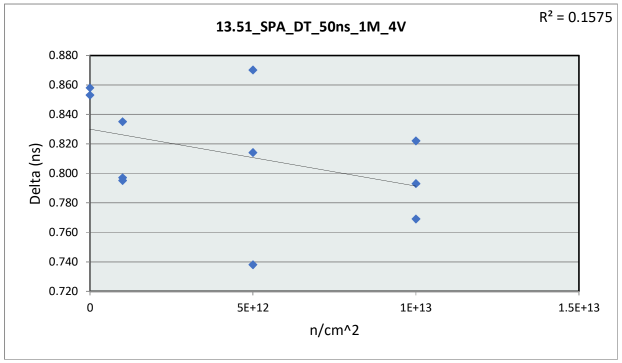


	13.49_PSA_DT_50ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	56	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	52.943	51.504	52.116	52.175
Average	53.173	51.690	52.538	52.925
Max	53.402	51.800	53.213	53.816
UL	56.000	56.000	56.000	56.000

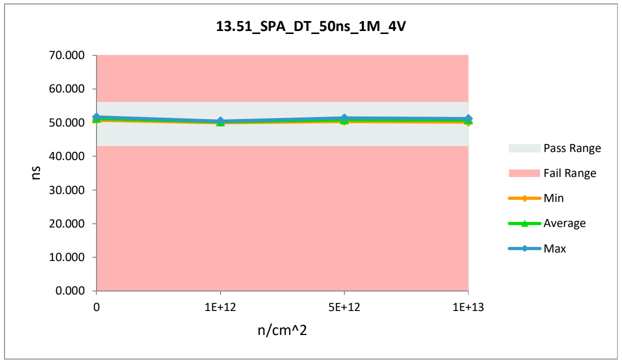


NDD Characterization Report
TPS7H5006-SEP

		13.51_SPA_DT_50ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	56	56	
	Min Limit	44	43	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	50.810	51.668	0.858
0	49	49.931	50.784	0.853
1E+12	11	49.227	50.024	0.797
1E+12	12	49.318	50.153	0.835
1E+12	13	49.705	50.500	0.795
5E+12	14	49.826	50.640	0.814
5E+12	15	49.613	50.351	0.738
5E+12	16	50.538	51.408	0.870
1E+13	17	50.199	51.021	0.822
1E+13	18	50.433	51.202	0.769
1E+13	19	49.328	50.121	0.793
	Max	50.810	51.668	0.870
	Average	49.903	50.716	0.813
	Min	49.227	50.024	0.738
	Std Dev	0.534	0.553	0.040

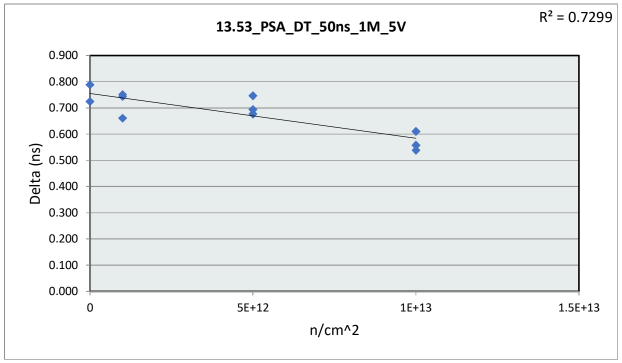


	13.51_SPA_DT_50ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	56	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	50.784	50.024	50.351	50.121
Average	51.226	50.226	50.800	50.781
Max	51.668	50.500	51.408	51.202
UL	56.000	56.000	56.000	56.000

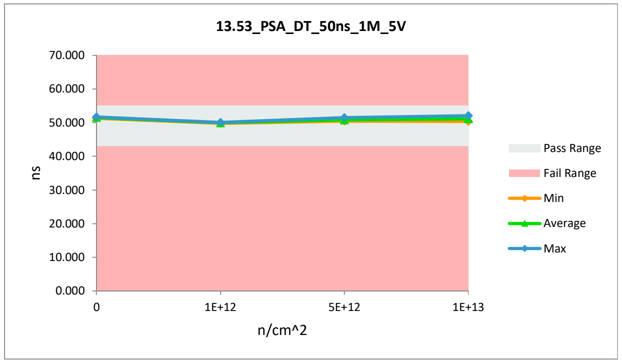


NDD Characterization Report
TPS7H5006-SEP

		13.53_PSA_DT_50ns_1M_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		45	43	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	50.902	51.690	0.788
0	49	50.550	51.274	0.724
1E+12	11	49.314	50.064	0.750
1E+12	12	49.005	49.748	0.743
1E+12	13	49.388	50.048	0.660
5E+12	14	49.785	50.531	0.746
5E+12	15	49.711	50.387	0.676
5E+12	16	50.783	51.476	0.693
1E+13	17	51.437	52.047	0.610
1E+13	18	50.580	51.137	0.557
1E+13	19	49.819	50.357	0.538
	Max	51.437	52.047	0.788
	Average	50.116	50.796	0.680
	Min	49.005	49.748	0.538
	Std Dev	0.773	0.761	0.082

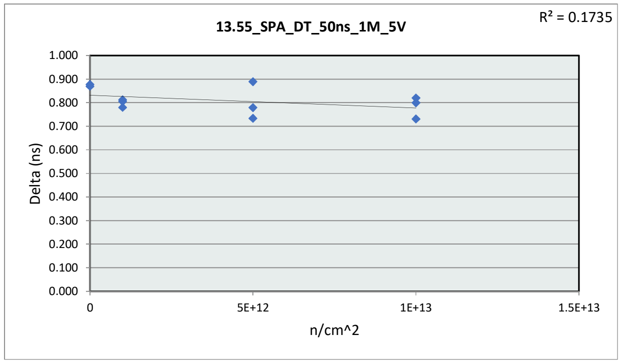


	13.53_PSA_DT_50ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	51.274	49.748	50.387	50.357
Average	51.482	49.953	50.798	51.180
Max	51.690	50.064	51.476	52.047
UL	55.000	55.000	55.000	55.000

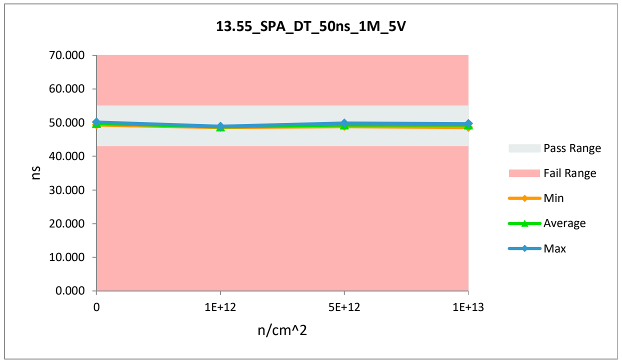


NDD Characterization Report
TPS7H5006-SEP

		13.55_SPA_DT_50ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	45	43	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	49.289	50.158	0.869
0	49	48.464	49.341	0.877
1E+12	11	47.731	48.543	0.812
1E+12	12	47.803	48.607	0.804
1E+12	13	48.162	48.941	0.779
5E+12	14	48.339	49.117	0.778
5E+12	15	48.130	48.863	0.733
5E+12	16	49.027	49.915	0.888
1E+13	17	48.726	49.545	0.819
1E+13	18	48.916	49.715	0.799
1E+13	19	47.848	48.578	0.730
	Max	49.289	50.158	0.888
	Average	48.403	49.211	0.808
	Min	47.731	48.543	0.730
	Std Dev	0.529	0.565	0.053

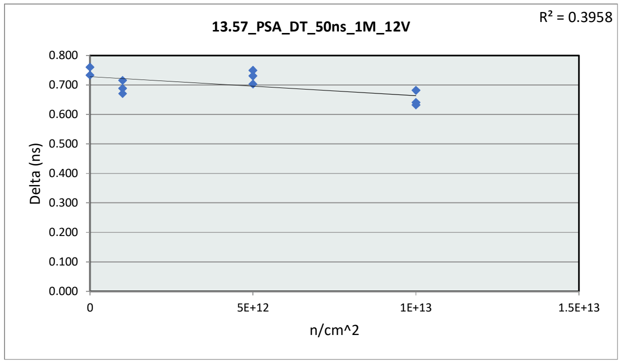


	13.55_SPA_DT_50ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	49.341	48.543	48.863	48.578
Average	49.750	48.697	49.298	49.279
Max	50.158	48.941	49.915	49.715
UL	55.000	55.000	55.000	55.000

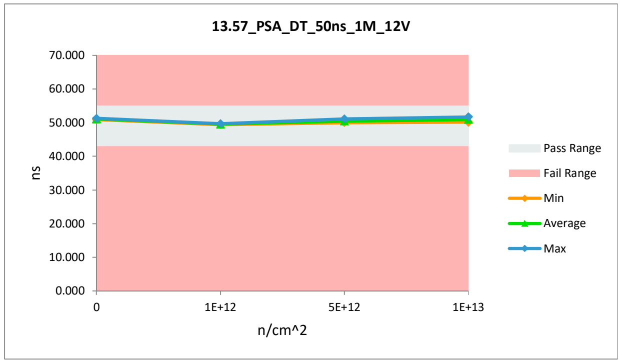


NDD Characterization Report
TPS7H5006-SEP

		13.57_PSA_DT_50ns_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	45	43	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	50.485	51.245	0.760
0	49	50.189	50.922	0.733
1E+12	11	48.928	49.643	0.715
1E+12	12	48.685	49.373	0.688
1E+12	13	49.007	49.677	0.670
5E+12	14	49.468	50.198	0.730
5E+12	15	49.327	50.030	0.703
5E+12	16	50.367	51.116	0.749
1E+13	17	51.100	51.732	0.632
1E+13	18	50.234	50.874	0.640
1E+13	19	49.448	50.129	0.681
	Max	51.100	51.732	0.760
	Average	49.749	50.449	0.700
	Min	48.685	49.373	0.632
	Std Dev	0.767	0.766	0.042

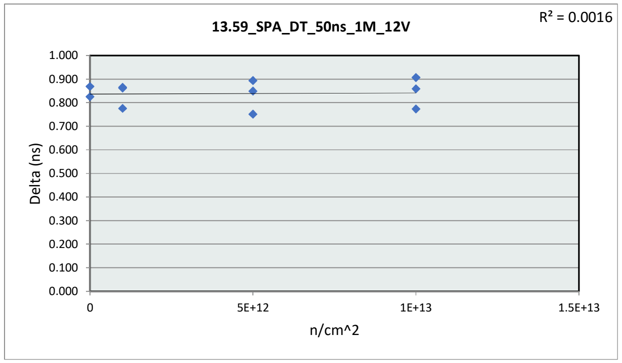


	13.57_PSA_DT_50ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	50.922	49.373	50.030	50.129
Average	51.084	49.564	50.448	50.912
Max	51.245	49.677	51.116	51.732
UL	55.000	55.000	55.000	55.000

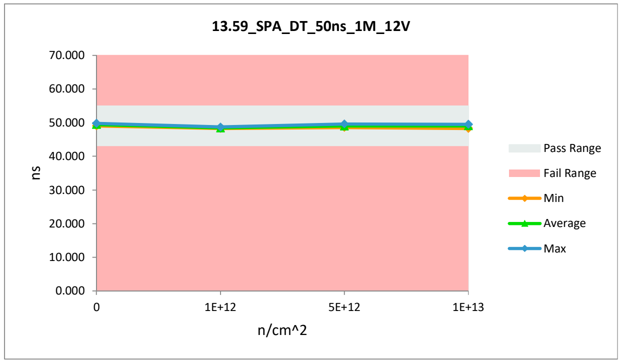


NDD Characterization Report
TPS7H5006-SEP

		13.59_SPA_DT_50ns_1M_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		45	43	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	48.983	49.808	0.825
0	49	48.201	49.069	0.868
1E+12	11	47.376	48.237	0.861
1E+12	12	47.540	48.315	0.775
1E+12	13	47.833	48.698	0.865
5E+12	14	48.005	48.853	0.848
5E+12	15	47.815	48.566	0.751
5E+12	16	48.704	49.597	0.893
1E+13	17	48.421	49.327	0.906
1E+13	18	48.640	49.498	0.858
1E+13	19	47.527	48.300	0.773
	Max	48.983	49.808	0.906
	Average	48.095	48.933	0.838
	Min	47.376	48.237	0.751
	Std Dev	0.536	0.562	0.051

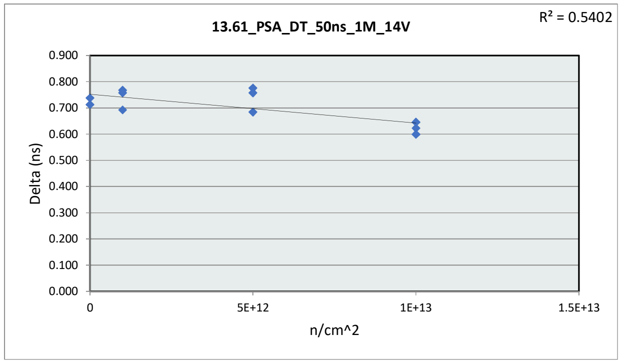


	13.59_SPA_DT_50ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	49.069	48.237	48.566	48.300
Average	49.439	48.417	49.005	49.042
Max	49.808	48.698	49.597	49.498
UL	55.000	55.000	55.000	55.000

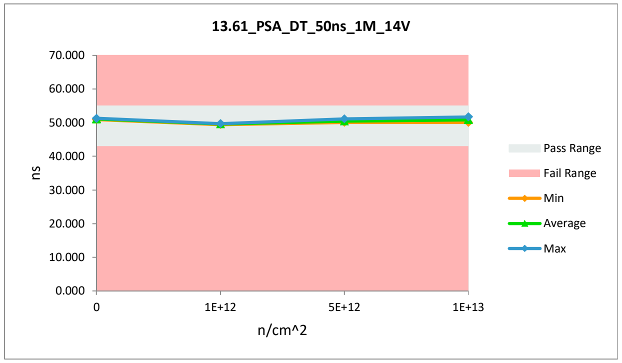


NDD Characterization Report
TPS7H5006-SEP

		13.61_PSA_DT_50ns_1M_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		45	43	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	50.555	51.267	0.712
0	49	50.192	50.929	0.737
1E+12	11	48.874	49.641	0.767
1E+12	12	48.665	49.422	0.757
1E+12	13	49.021	49.713	0.692
5E+12	14	49.433	50.190	0.757
5E+12	15	49.370	50.054	0.684
5E+12	16	50.320	51.095	0.775
1E+13	17	51.054	51.699	0.645
1E+13	18	50.226	50.825	0.599
1E+13	19	49.464	50.086	0.622
	Max	51.054	51.699	0.775
	Average	49.743	50.447	0.704
	Min	48.665	49.422	0.599
	Std Dev	0.768	0.750	0.061

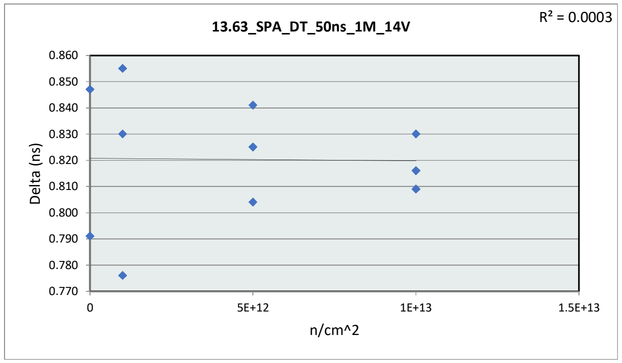


	13.61_PSA_DT_50ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	50.929	49.422	50.054	50.086
Average	51.098	49.592	50.446	50.870
Max	51.267	49.713	51.095	51.699
UL	55.000	55.000	55.000	55.000

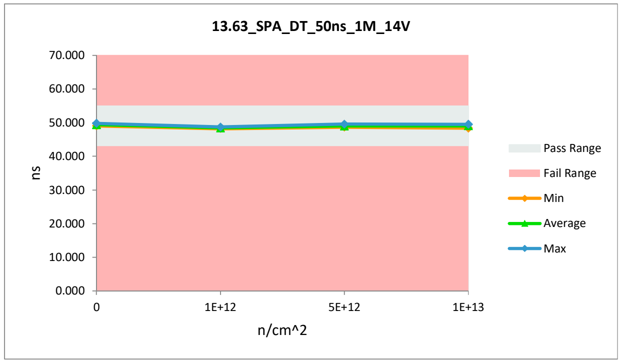


NDD Characterization Report
TPS7H5006-SEP

		13.63_SPA_DT_50ns_1M_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		45	43	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	48.941	49.788	0.847
0	49	48.241	49.032	0.791
1E+12	11	47.360	48.215	0.855
1E+12	12	47.579	48.355	0.776
1E+12	13	47.879	48.709	0.830
5E+12	14	48.029	48.833	0.804
5E+12	15	47.804	48.629	0.825
5E+12	16	48.710	49.551	0.841
1E+13	17	48.505	49.321	0.816
1E+13	18	48.672	49.481	0.809
1E+13	19	47.523	48.353	0.830
	Max	48.941	49.788	0.855
	Average	48.113	48.933	0.820
	Min	47.360	48.215	0.776
	Std Dev	0.537	0.540	0.024

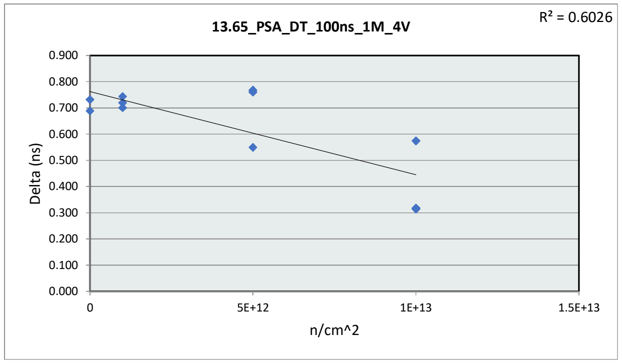


	13.63_SPA_DT_50ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	49.032	48.215	48.629	48.353
Average	49.410	48.426	49.004	49.052
Max	49.788	48.709	49.551	49.481
UL	55.000	55.000	55.000	55.000

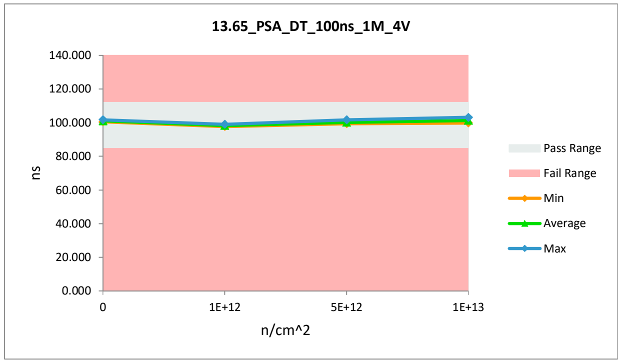


NDD Characterization Report
TPS7H5006-SEP

		13.65_PSA_DT_100ns_1M_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		112	112	
Min Limit		87	85	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	101.010	101.741	0.731
0	49	99.750	100.438	0.688
1E+12	11	97.342	98.085	0.743
1E+12	12	97.026	97.745	0.719
1E+12	13	98.269	98.969	0.700
5E+12	14	98.639	99.399	0.760
5E+12	15	98.746	99.295	0.549
5E+12	16	100.805	101.572	0.767
1E+13	17	102.828	103.145	0.317
1E+13	18	100.435	100.749	0.314
1E+13	19	99.223	99.797	0.574
	Max	102.828	103.145	0.767
	Average	99.461	100.085	0.624
	Min	97.026	97.745	0.314
	Std Dev	1.722	1.636	0.168

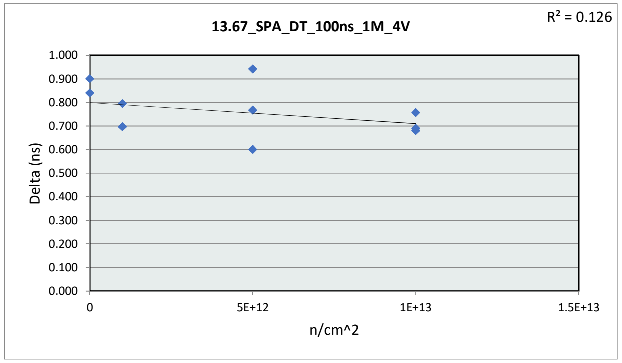


	13.65_PSA_DT_100ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	112	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	100.438	97.745	99.295	99.797
Average	101.090	98.266	100.089	101.230
Max	101.741	98.969	101.572	103.145
UL	112.000	112.000	112.000	112.000

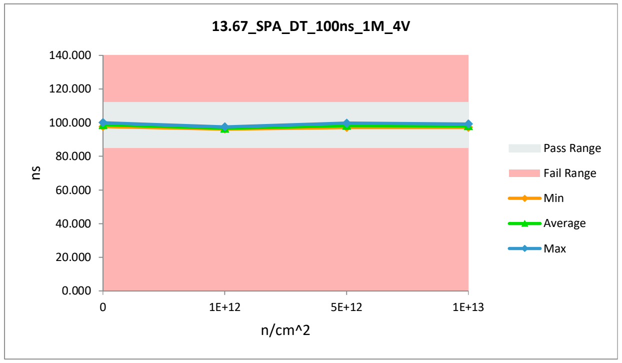


NDD Characterization Report
TPS7H5006-SEP

		13.67_SPA_DT_100ns_1M_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		112	112	
Min Limit		87	85	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	99.097	99.997	0.900
0	49	96.812	97.651	0.839
1E+12	11	95.423	96.218	0.795
1E+12	12	95.476	96.172	0.696
1E+12	13	96.810	97.506	0.696
5E+12	14	97.216	97.983	0.767
5E+12	15	96.533	97.133	0.600
5E+12	16	98.772	99.713	0.941
1E+13	17	97.162	97.918	0.756
1E+13	18	98.562	99.252	0.690
1E+13	19	96.473	97.153	0.680
	Max	99.097	99.997	0.941
	Average	97.121	97.881	0.760
	Min	95.423	96.172	0.600
	Std Dev	1.236	1.292	0.102

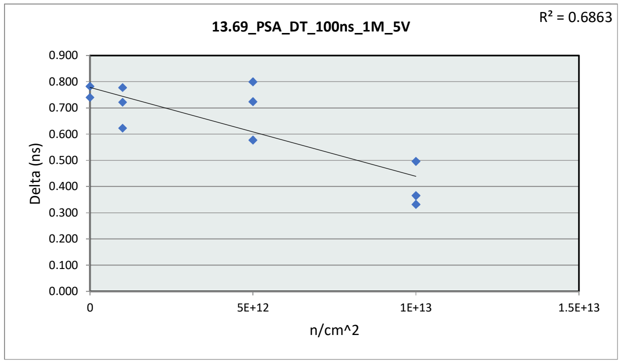


	13.67_SPA_DT_100ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	112	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	97.651	96.172	97.133	97.153
Average	98.824	96.632	98.276	98.108
Max	99.997	97.506	99.713	99.252
UL	112.000	112.000	112.000	112.000

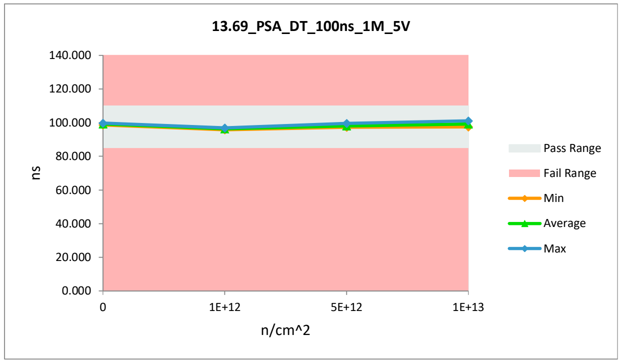


NDD Characterization Report
TPS7H5006-SEP

		13.69_PSA_DT_100ns_1M_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		110	110	
Min Limit		89	85	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	98.980	99.719	0.739
0	49	97.869	98.651	0.782
1E+12	11	95.409	96.186	0.777
1E+12	12	95.076	95.797	0.721
1E+12	13	96.241	96.863	0.622
5E+12	14	96.652	97.375	0.723
5E+12	15	96.761	97.338	0.577
5E+12	16	98.819	99.618	0.799
1E+13	17	100.662	101.027	0.365
1E+13	18	98.547	98.878	0.331
1E+13	19	96.993	97.488	0.495
	Max	100.662	101.027	0.799
	Average	97.455	98.085	0.630
	Min	95.076	95.797	0.331
	Std Dev	1.688	1.624	0.168

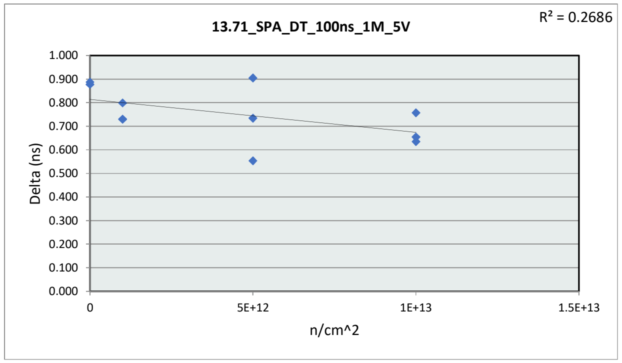


	13.69_PSA_DT_100ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	98.651	95.797	97.338	97.488
Average	99.185	96.282	98.110	99.131
Max	99.719	96.863	99.618	101.027
UL	110.000	110.000	110.000	110.000

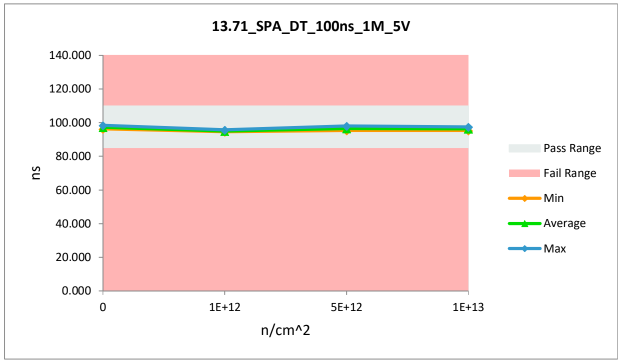


NDD Characterization Report
TPS7H5006-SEP

		13.71_SPA_DT_100ns_1M_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		110	110	
Min Limit		89	85	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	97.515	98.394	0.879
0	49	95.366	96.255	0.889
1E+12	11	93.795	94.595	0.800
1E+12	12	93.889	94.620	0.731
1E+12	13	95.003	95.735	0.732
5E+12	14	95.480	96.216	0.736
5E+12	15	94.945	95.500	0.555
5E+12	16	97.158	98.064	0.906
1E+13	17	95.668	96.427	0.759
1E+13	18	96.917	97.554	0.637
1E+13	19	94.634	95.290	0.656
	Max	97.515	98.394	0.906
	Average	95.488	96.241	0.753
	Min	93.795	94.595	0.555
	Std Dev	1.252	1.295	0.111

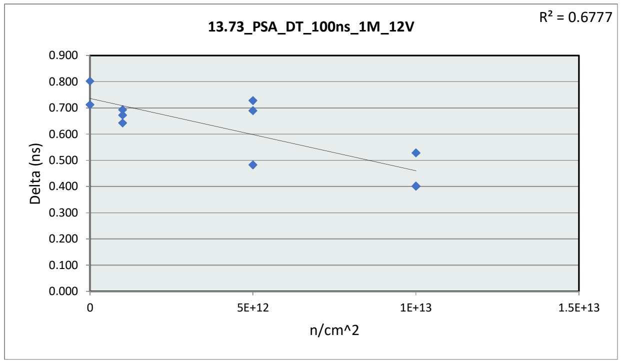


	13.71_SPA_DT_100ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	96.255	94.595	95.500	95.290
Average	97.325	94.983	96.593	96.424
Max	98.394	95.735	98.064	97.554
UL	110.000	110.000	110.000	110.000

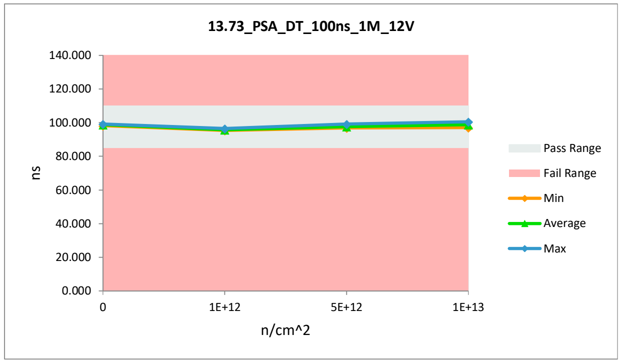


NDD Characterization Report
TPS7H5006-SEP

		13.73_PSA_DT_100ns_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	89	85	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	98.454	99.258	0.804
0	49	97.489	98.203	0.714
1E+12	11	94.998	95.642	0.644
1E+12	12	94.661	95.356	0.695
1E+12	13	95.790	96.464	0.674
5E+12	14	96.180	96.910	0.730
5E+12	15	96.335	96.819	0.484
5E+12	16	98.409	99.100	0.691
1E+13	17	100.191	100.594	0.403
1E+13	18	98.140	98.543	0.403
1E+13	19	96.554	97.084	0.530
	Max	100.191	100.594	0.804
	Average	97.018	97.634	0.616
	Min	94.661	95.356	0.403
	Std Dev	1.676	1.634	0.138

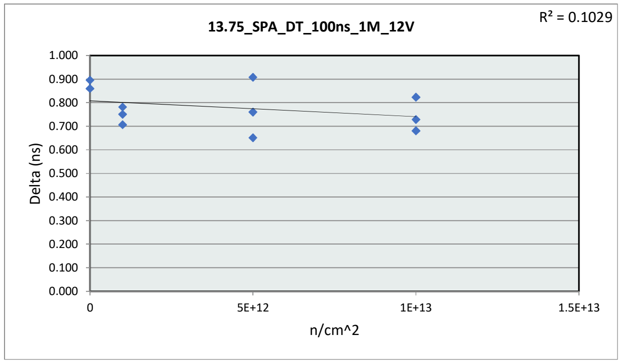


	13.73_PSA_DT_100ns_1M_12			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	98.203	95.356	96.819	97.084
Average	98.731	95.821	97.610	98.740
Max	99.258	96.464	99.100	100.594
UL	110.000	110.000	110.000	110.000

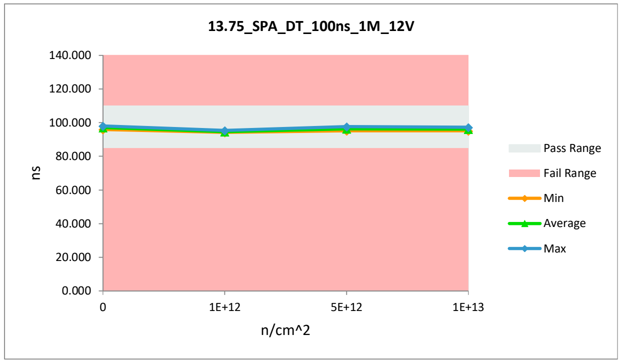


NDD Characterization Report
TPS7H5006-SEP

		13.75_SPA_DT_100ns_1M_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		110	110	
Min Limit		89	85	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	97.174	98.035	0.861
0	49	95.110	96.007	0.897
1E+12	11	93.467	94.250	0.783
1E+12	12	93.634	94.342	0.708
1E+12	13	94.694	95.446	0.752
5E+12	14	95.200	95.962	0.762
5E+12	15	94.608	95.261	0.653
5E+12	16	96.834	97.743	0.909
1E+13	17	95.367	96.192	0.825
1E+13	18	96.589	97.319	0.730
1E+13	19	94.393	95.075	0.682
	Max	97.174	98.035	0.909
	Average	95.188	95.967	0.778
	Min	93.467	94.250	0.653
	Std Dev	1.235	1.283	0.086



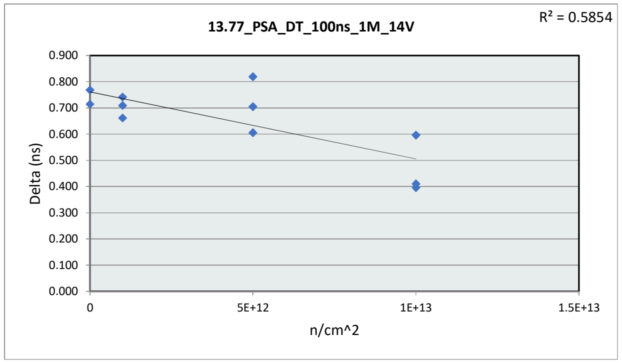
	13.75_SPA_DT_100ns_1M_12			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	96.007	94.250	95.261	95.075
Average	97.021	94.679	96.322	96.195
Max	98.035	95.446	97.743	97.319
UL	110.000	110.000	110.000	110.000



NDD Characterization Report
TPS7H5006-SEP

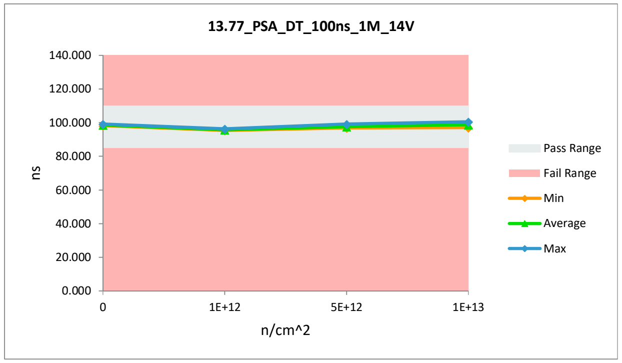
	13.77_PSA_DT_100ns_1M_14V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	110	110
Min Limit	89	85

n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	98.441	99.211	0.770
0	49	97.460	98.176	0.716
1E+12	11	94.962	95.673	0.711
1E+12	12	94.604	95.347	0.743
1E+12	13	95.758	96.421	0.663
5E+12	14	96.197	96.903	0.706
5E+12	15	96.261	96.868	0.607
5E+12	16	98.321	99.142	0.821
1E+13	17	100.198	100.595	0.397
1E+13	18	98.110	98.522	0.412
1E+13	19	96.505	97.103	0.598
	Max	100.198	100.595	0.821
	Average	96.983	97.633	0.649
	Min	94.604	95.347	0.397
	Std Dev	1.684	1.630	0.137



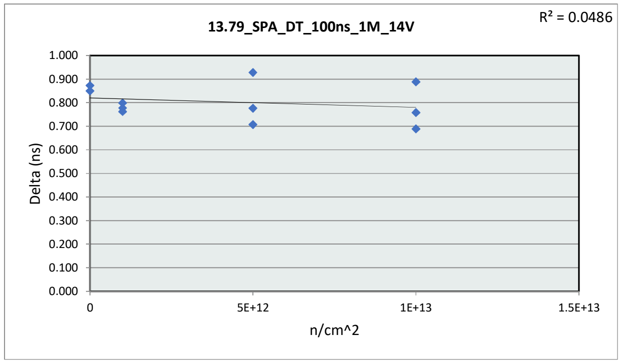
	13.77_PSA_DT_100ns_1M_14	
Test Site		
Tester		
Test Number		
Max Limit	110	ns
Min Limit	85	ns

n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	98.176	95.347	96.868	97.103
Average	98.694	95.814	97.638	98.740
Max	99.211	96.421	99.142	100.595
UL	110.000	110.000	110.000	110.000

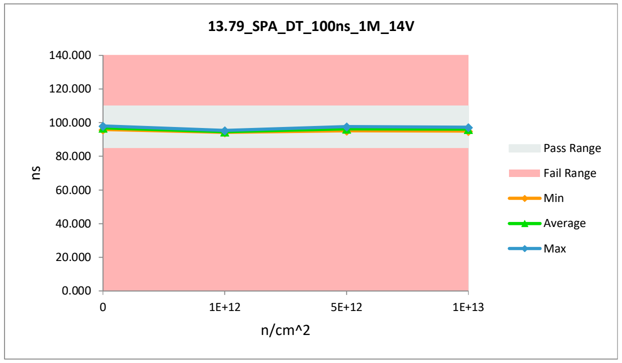


NDD Characterization Report
TPS7H5006-SEP

		13.79_SPA_DT_100ns_1M_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		110	110	
Min Limit		89	85	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	97.173	98.047	0.874
0	49	95.092	95.944	0.852
1E+12	11	93.428	94.207	0.779
1E+12	12	93.593	94.357	0.764
1E+12	13	94.661	95.461	0.800
5E+12	14	95.177	95.955	0.778
5E+12	15	94.563	95.272	0.709
5E+12	16	96.805	97.735	0.930
1E+13	17	95.348	96.238	0.890
1E+13	18	96.558	97.318	0.760
1E+13	19	94.349	95.039	0.690
	Max	97.173	98.047	0.930
	Average	95.159	95.961	0.802
	Min	93.428	94.207	0.690
	Std Dev	1.244	1.290	0.076

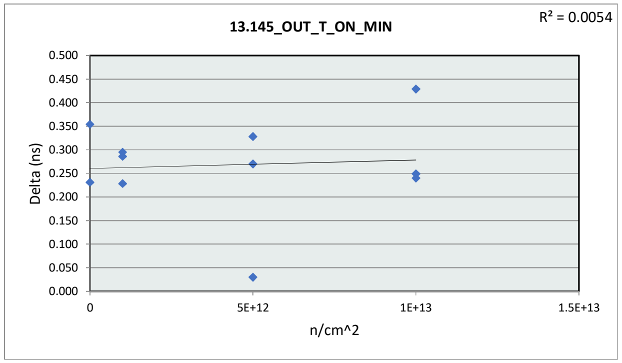


	13.79_SPA_DT_100ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	95.944	94.207	95.272	95.039
Average	96.996	94.675	96.321	96.198
Max	98.047	95.461	97.735	97.318
UL	110.000	110.000	110.000	110.000

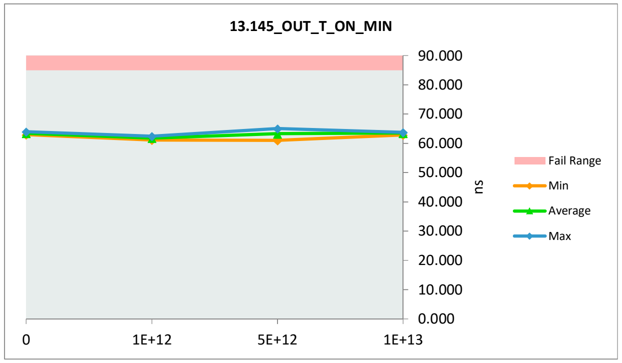


NDD Characterization Report
TPS7H5006-SEP

		13.145_OUT_T_ON_MIN		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		85	85	
Min Limit		20		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	63.608	63.963	0.355
0	49	62.727	62.959	0.232
1E+12	11	60.944	61.173	0.229
1E+12	12	61.278	61.574	0.296
1E+12	13	62.178	62.465	0.287
5E+12	14	64.765	65.036	0.271
5E+12	15	60.967	60.998	0.031
5E+12	16	63.399	63.728	0.329
1E+13	17	63.485	63.735	0.250
1E+13	18	62.663	62.904	0.241
1E+13	19	63.393	63.823	0.430
	Max	64.765	65.036	0.430
	Average	62.673	62.942	0.268
	Min	60.944	60.998	0.031
	Std Dev	1.227	1.283	0.099

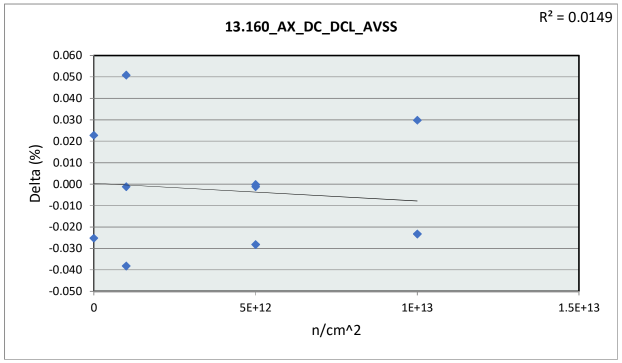


	13.145_OUT_T_ON_MIN			
Test Site				
Tester				
Test Number				
Max Limit	85	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	62.959	61.173	60.998	62.904
Average	63.461	61.737	63.254	63.487
Max	63.963	62.465	65.036	63.823
UL	85.000	85.000	85.000	85.000

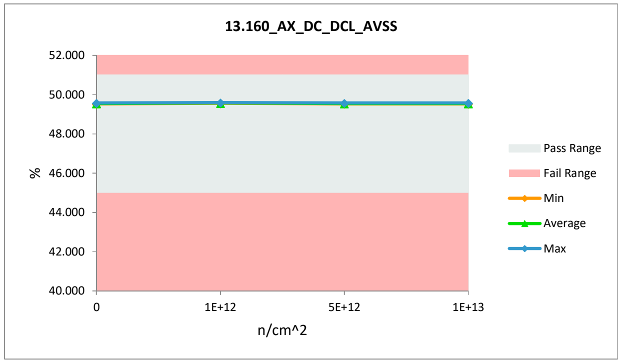


NDD Characterization Report
TPS7H5006-SEP

		13.160_AX_DC_DCL_AVSS		
Test Site				
Tester				
Test Number				
Unit		%	%	
Max Limit		51	51	
Min Limit		45	45	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	49.550	49.525	-0.025
0	49	49.550	49.573	0.023
1E+12	11	49.547	49.598	0.051
1E+12	12	49.593	49.555	-0.038
1E+12	13	49.563	49.562	-0.001
5E+12	14	49.546	49.546	0.000
5E+12	15	49.574	49.573	-0.001
5E+12	16	49.563	49.535	-0.028
1E+13	17	49.551	49.528	-0.023
1E+13	18	49.561	49.538	-0.023
1E+13	19	49.544	49.574	0.030
	Max	49.593	49.598	0.051
	Average	49.558	49.555	-0.003
	Min	49.544	49.525	-0.038
	Std Dev	0.015	0.023	0.028

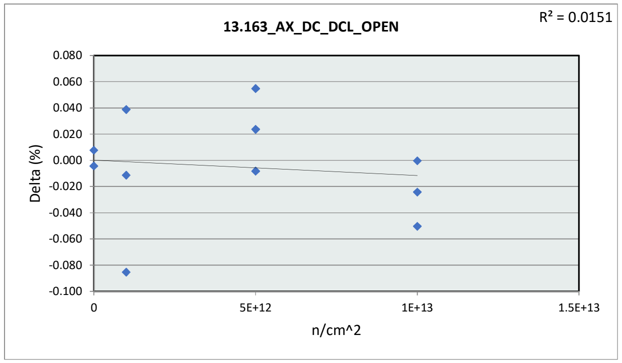


	13.160_AX_DC_DCL_AVSS			
Test Site				
Tester				
Test Number				
Max Limit	51	%		
Min Limit	45	%		
n/cm^2	0	1E+12	5E+12	1E+13
LL	45.000	45.000	45.000	45.000
Min	49.525	49.555	49.535	49.528
Average	49.549	49.572	49.551	49.547
Max	49.573	49.598	49.573	49.574
UL	51.000	51.000	51.000	51.000

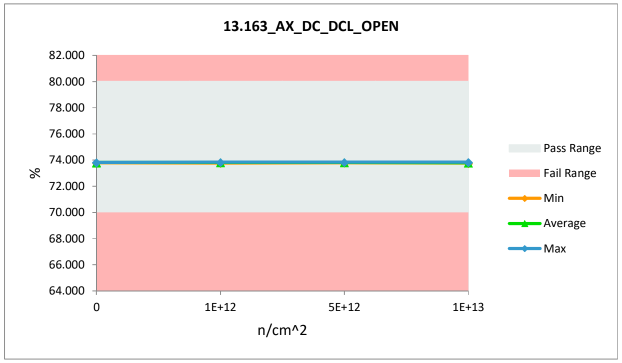


NDD Characterization Report
TPS7H5006-SEP

		13.163_AX_DC_DCL_OPEN		
	Test Site			
	Tester			
	Test Number			
	Unit	%	%	
	Max Limit	80	80	
	Min Limit	70	70	
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	73.810	73.818	0.008
0	49	73.794	73.790	-0.004
1E+12	11	73.867	73.782	-0.085
1E+12	12	73.795	73.834	0.039
1E+12	13	73.854	73.843	-0.011
5E+12	14	73.831	73.823	-0.008
5E+12	15	73.783	73.838	0.055
5E+12	16	73.775	73.799	0.024
1E+13	17	73.837	73.837	0.000
1E+13	18	73.813	73.763	-0.050
1E+13	19	73.815	73.791	-0.024
	Max	73.867	73.843	0.055
	Average	73.816	73.811	-0.005
	Min	73.775	73.763	-0.085
	Std Dev	0.029	0.027	0.039

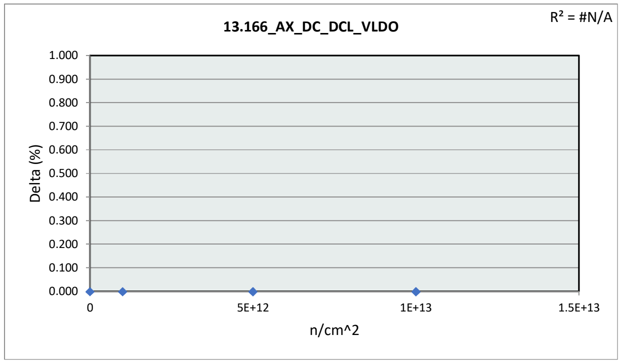


	13.163_AX_DC_DCL_OPEN			
Test Site				
Tester				
Test Number				
Max Limit	80	%		
Min Limit	70	%		
n/cm^2	0	1E+12	5E+12	1E+13
LL	70.000	70.000	70.000	70.000
Min	73.790	73.782	73.799	73.763
Average	73.804	73.820	73.820	73.797
Max	73.818	73.843	73.838	73.837
UL	80.000	80.000	80.000	80.000

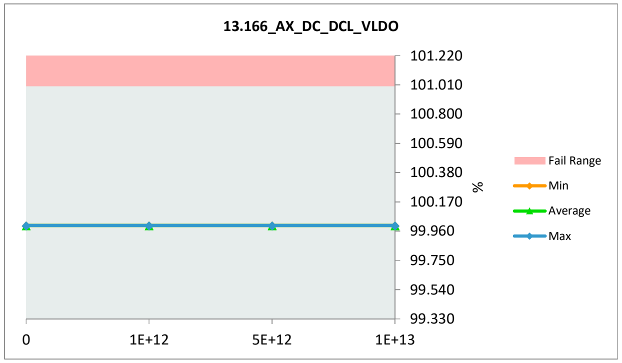


NDD Characterization Report
TPS7H5006-SEP

		13.166_AX_DC_DCL_VLDO		
	Test Site			
	Tester			
	Test Number			
	Unit	%	%	
	Max Limit	101	101	
	Min Limit	95		
n/cm^2	Serial #	Pre_NDD_5006-SEP	Post_NDD_5006-SEP	Delta
0	48	100.000	100.000	0.000
0	49	100.000	100.000	0.000
1E+12	11	100.000	100.000	0.000
1E+12	12	100.000	100.000	0.000
1E+12	13	100.000	100.000	0.000
5E+12	14	100.000	100.000	0.000
5E+12	15	100.000	100.000	0.000
5E+12	16	100.000	100.000	0.000
1E+13	17	100.000	100.000	0.000
1E+13	18	100.000	100.000	0.000
1E+13	19	100.000	100.000	0.000
	Max	100.000	100.000	0.000
	Average	100.000	100.000	0.000
	Min	100.000	100.000	0.000
	Std Dev	0.000	0.000	0.000



	13.166_AX_DC_DCL_VLDO			
Test Site				
Tester				
Test Number				
Max Limit	101	%		
Min Limit		%		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	100.000	100.000	100.000	100.000
Average	100.000	100.000	100.000	100.000
Max	100.000	100.000	100.000	100.000
UL	101.000	101.000	101.000	101.000



6 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision * (August 2022) to Revision A (August 2024)	Page
• Updated document title	1
• Updated document to include information for TPS7H5002-SP QMLP	1

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